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THE ANALYSIS OF TRACE IMPURITIES IN URANIUM COMPOUNDS USING SPARK-SOURCE MASS SPECTRO-METRY

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1991



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USING SPARK-SOURCE MASS SPECTROMETRY

by

DAVID CHARLES HUDSON-LAMB, B.Sc (HONS) (UPE)

A dissertation submitted in partial

fulfilment of the requirements

for the degree of

MAGISTER SCIENTIAE

in the Faculty of Science

at the University of Pretoria, South Africa

MAY 1991

PROMOTOR : PROFESSOR R G BÖHMER CO-PROMOTOR : DR W C A VAN NIEKERK



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ATOMIC ENERGY CORPORATION OF SOUTH AFRICA, LIMITED

PRETORIA



CHAPTER FIVE

QUANTITATIVE ANALYSIS

5.1 Calculation Methods

The calculation method used to derive the formula for determination of relative sensitivity factors (RSF's) for impurity elements in different matrices relative to an internal standard is discussed in detail on page 138.

For clarity, the essential formulae are also given here:



where:

 K_{x}/K_{y} is the RSF for element X relative to the internal standard, X (see page 28).

Equation (1) can be rewritten as follows:



where:

 C_x is the unknown concentration of an element X, C_y is the known concentration of the internal standard,



 Q_x/Q_y^- is the ratio between the exposure values of an element X and the internal standard at 50% transmission, and K_x/K_y is the relative sensitivity factor for element X relative to the internal standard, which is derived from calibration plots as the slope of the regression line.

Equation (1) can be used to determine the RSF of any element X relative to any internal standard (IS) in any matrix Z. Rewriting equation (1) into the above notation gives:

$$(RSF_{IS}^{X})_{Z} = \begin{bmatrix} \frac{Q_{X}}{Q_{IS}} \\ \frac{Q_{IS}}{C_{X}} \\ \frac{C_{IS}}{C_{X}} \end{bmatrix}_{Z}$$
(3)

This formula is directly related to the general formula for a RSF, namely:

where:

 C_{ms} is the concentration of an element X relative to an internal standard determined experimentally with the mass spectrometer, and

 C_{true} is the true concentration of an element X relative to an internal standard where both concentrations are known.

The calculation method used to derive the formula which is used to determine the unknown background concentration of an element X in different matrices, Z, using different standards is given below. The general spark-source mass spectrometry equation applies:



where:

 $\begin{pmatrix} C_{X} \end{pmatrix}_{Z}$ is the unknown concentration of element X in matrix Z, K_X is a constant for element X, and $\begin{pmatrix} Q_{X} \end{pmatrix}_{Z}$ is the instrument signal for element X in matrix Z.

Equation (5) also applies when a known standard (STD) is added to the matrix Z:

where:

 $(C_{x})_{z+std}$ is the unknown concentration of element X in the matrix Z plus the known concentration of element X in the standard, K_{x} is a constant (see equation (5)), and $(Q_{x})_{z+std}$ is the combined instrument signal for element X and the standard in the matrix Z.

In order to determine the unknown background concentration $\binom{C}{x'z}$ of element X in matrix Z, equations (5) and (6) are combined as follows:

$$(C_{\mathbf{x}})_{z+std} - (C_{\mathbf{x}})_{z} = K_{\mathbf{x}} \left[\frac{1}{(Q_{\mathbf{x}})_{z+std}} - \frac{1}{(Q_{\mathbf{x}})_{z}} \right]$$

This difference is equal to the concentration of the added standard, expressed as $\binom{C}{x}_{std}$:



 $\binom{(Q_x)_z}{z}$ and $\binom{(Q_x)_z}{z+std}$ values can be determined as outlined on page 105 below.

 $\binom{C}{x}_{std}$ values are known and K_x can be calculated. Inserting the K_x value for element X in equation (5) enables the determination of $\binom{C}{x}_z$. This leads to the following equation:

$$(C_{x})_{z} = (C_{x})_{std} \cdot \frac{(Q_{x})_{z+std}}{(Q_{x})_{z} - (Q_{x})_{z+std}} \dots \dots \dots (8)$$

Equation (8) is the fundamental formula used to determine the background concentration of an element X in a matrix Z, using known prepared graphite standards. This formula will be used to determine background concentrations of impurity elements in U_3O_8 and UF_4 matrices in the following sections. The instrument signals of element X in both the matrix Z and the combination of matrix plus standard can be expressed relative to an internal reference standard (IS) (see page 28). $Q_{\rm IS}$ values are the same in the Z and Z+STD matrices for a particular choice of Y concentration.

Equation (8) then converts to:

$$(C_x)_z = (C_x)_{std} \cdot \frac{(Q_x/Q_{IS})_{z+std}}{(Q_x/Q_{IS})_z - (Q_x/Q_{IS})_{z+std}} \dots \dots (9)$$



This formula only holds true when $(Q_x/Q_{IS})_z$ is larger than $(Q_x/Q_{IS})_{z+std}$. The opposite can never happen in spark-source mass spectrometry because the concentration is inversely proportional to the instrument signal. Thus, the higher the concentration, i.e. when the standard is added to the matrix Z, the resultant instrument signal will be smaller than that for only the matrix Z.

5.2 <u>U₃O₈/graphite matrix quantitation</u>

5.2.1 Blank correction

In order to determine relative sensitivity factors (RSF's) for impurity elements in a U₃O₈/graphite matrix, the blank U₃O₈ sample must first be quantified. Considerable effort was initiated to obtain a blank U_3O_8 sample with few impurity elements to ensure a background spectrum relatively free from spectral lines. This blank base U_3O_8 sample (ES 0) was then mixed with a graphite powder, spiked with Y as an internal reference standard, in the ratio of five parts U_3O_8 to one part graphite by mass. The choice of this ratio has been discussed on page 30. The sample was then analysed several times to obtain an instrument signal, $(Q_x / Q_y)_{U_1 O_4}$ for element X relative to the internal standard, Y, in a U_3O_8 /graphite matrix. The exposure value for Y, Q_v^- , is the mean of the singly and doubly charged species. The blank base U₃O₈ sample used for this purpose is stoichiometric i.e. 100 per cent U_3O_8 .

To be able to quantify the impurity elements present in the blank base U_3O_8 sample, a range of graphite standards were prepared



which contained the impurity elements under investigation in different concentrations, together with Y as internal reference standard. The method followed to prepare these graphite standards has been described on page 26. UCAR SP1 graphite powder was used for these standards. The concentration range of the standards is as follows:

U₃O₈ used: stoichiometric i.e. 84,8 per cent U. Concentrations: 4 μg X /gC 20 μg X /gC 40 μg X /gC 100 μg X /gC 200 μg X /gC

Expressed relative to U, the concentrations $(C_x)_{x \text{ std}}$ for each impurity element X, become:

1 μg X /gU 5 μg X /gU 10 μg X /gU 25 μg X /gU 50 μg X /gU

The concentration of Y added to each of the above graphite standards as internal standard is 20 μ g Y/gC or 5 μ g Y/gU.

In addition to the above range of graphite standards using UCAR SP1 graphite, a range of check standards were also prepared using Ultra 'F' graphite. The main reason for preparing these check standards was to see whether results obtained for certain elements using UCAR SP1 graphite could not be improved by using Ultra 'F' graphite. The difference between these two graphite powders' background spectra for certain elements was used to



check the results obtained from the UCAR SP1 range of graphite standards. This was especially useful for Fe, which has a high background concentration in UCAR SP1 compared to Ultra 'F'. Additional impurity elements not incorporated in the UCAR SPI graphite standards were now added to these check standards using Ultra 'F' graphite. These elements could not be added to the UCAR SP1 graphite because of spectral line interferences from elements already added. However due to the absence of these interfering elements in Ultra 'F' graphite these additional impurity elements could be added and analysed without any interference. Elements falling into this category were Li, W, P, Na, K and S. This fact also accounts for the low value for the number of analyses in Table 5.2 (see page 111) where the calibration curve parameters are listed.

The concentration range of these check graphite standards is as follows:

Concentrations: 20 μg X /gC 40 μg X /gC 80 μg X /gC 200 μg X /gC

Expressed relative to U, the concentration, $(C_x)_{std}$, becomes:

5 μg X /gU 10 μg X /gU 20 μg X /gU 50 μg X /gU



The concentration of Y added to each of the above graphite check standards as internal standard is 80 µgY/gC or 20 µgY/gU.

Using standard addition methods, each of the above graphite standards are mixed with the blank base U_3O_8 sample in the ratio of five parts U_3O_8 to one part graphite by mass. Similarly, as for the blank base U_3O_8 /graphite matrix sample, each sample is analysed several times to obtain an instrument signal, $(Q_x/Q_y^-)_{U_3O_8+std}$, for element X relative to the internal standard in the blank base U_3O_8 plus the graphite standard. These instrument signals are used in equation (9) to calculate the concentration of element X in the blank base U_3O_8 , $(C_x)_{U_3O_8}$.

$$(C_{x})_{U_{3}O_{8}} = (C_{x})_{std} \qquad \frac{(Q_{x}/Q_{y}^{-})_{U_{3}O_{8}} + std}{(Q_{x}/Q_{y}^{-})_{U_{3}O_{8}} - (Q_{x}/Q_{y}^{-})_{U_{3}O_{8}} + std}$$

The results obtained to quantify the impurity elements in the blank base U_3O_8 sample are given in Table 5.1 as $C_{\chi}(SSMS)$ in $\mu g \chi / g U$.

The concentration values for Na (20,9), Mg (26,0), Si (18,3) and Fe (20,3) are all very high in comparison to the concentrations of the graphite standards e.g. the 1, 5, 10 and 25 μ gX/gU standards. This fact greatly influences the gradient of the calibration line. This is shown as follows:

On the x-axis of the calibration curve, the ratio C_y/C_x is plotted where $C_x = (C_x)_{std} + (C_x)_{30}$. Thus when $(C_x)_{030}$ is large, the ratio C_y/C_x becomes smaller where C_y is taken as constant. This makes the gradient, m, of the regression line



<u>Table 5.1</u>: Blank Base U_3O_8 (ES 0) quantification

Element	Charge State(+)	n	Std Error at 95 % CL (%)	C _x (SSMS) (µg X /gU)	Certified conc (µg X /gU)
В	1	18	10,4	9,8	0,07
Na	1	5	42,1	20,9	5
Mg	2	12	31,2	26,0	0,5
A1	2	18	13,3	9,6	1
Si	2	16	33,6	18,3	17
Р	1&2	12	18,4	3,5	-
Ca	2	35	16,1	6,0	2,2
K	1&2	6	25,2	5,6	4
Ti	1&2	14	12,6	0,42	0,3
V	1&2	38	18,0	0,38	0,31
Cr	1&2	45	10,0	5,3	2
Mn	1&2	34	12,6	0,35	0,14
Fe	1&2	22	9,7	20,3	13
Со	1&2	26	8,1	0,30	0,1
Ni	1	28	10,5	2,4	0,8
Cu	1&2	26	12,3	0,5	0,3
Zn	1	31	7,3	1,78	1,66
Zr	1&2	36	12,9	3,5	0,5
Мо	2	12	18,7	2,5	0,3
Sb	1	25	14,1	1,22	1,2
Li	1	3	19,3	0,19	0,21



inaccurate and limits the calibration range. In this way the RSF is influenced directly by a high background concentration. Even elements with lower background concentrations e.g. B (9,8) and A1 (9,6) influence the Q-values of the lower graphite standards with concentrations of 1, 5 and 10 μ gX/gU. The same can be said for Ca (6,0), K (5,6) and Cr (5,3) which influence the two lowest graphite standards with concentrations of 1 and 5 μ gX/gU. The rest of the elements in Table 5.1 have background concentrations which do not influence the calculation of relative sensitivity factors significantly.

The $C_{_X}$ values in Table 5.1 determined for impurity elements in the blank base U_3O_8 are only for the elements in their elemental state. The hydrogenated and oxygenated species of the elements have not been considered. When analysing unknown U_3O_8 samples with the spark-source mass spectrometer, it is assumed that the same degree of hydrogenation and oxygenation of elements in the sample takes place as with the U_3O_8 calibration standard samples. This assumption is reasonable if the unknown sample is also stoichiometric U_3O_8 and the sparking parameters used to generate ions are identical for the U_3O_8 sample as for the U_3O_8 calibration standard samples.

The chemical composition of the impurity elements within the U_3O_8 samples are also assumed to be similar to those in the U_3O_8 calibration standard samples. The plasma generated between the two electrodes in the ion source provides the equalising locality for such differences. In this plasma the chemical structures are atomised and ionised and recombination of species takes place.

The high standard errors at 95% confidence level (CL) for Na (42,1%) and K (25,2%) can be ascribed to the small number of data



points (n = 5 for Na and n = 6 for K). The fact that the concentration of Na in the blank base U_3O_8 sample is quite high ($C_x = 20,9 \ \mu g \ Na/gU$) also plays a direct role in the relatively high uncertainty.

Similarly, the high standard errors at 95% CL for Mg (31,2%) and Si (33,6%) can also be ascribed to the high concentrations of these two elements in the blank base U_3O_8 sample ($C_x = 26,0$ for Mg and $C_x = 18,3$ for Si). This explains why the $(C_x)_{U_3O_8}$ values for these two elements fluctuated over the concentration range of the graphite standards. This fluctuation can further be enhanced by the position on the photoplate where the spectral lines of Mg at m/e 12,5 and of Si at m/e 14,5 are influenced by background emulsion fogging due to the strong spectral line of the major component, ¹²C at m/e 12. This interference directly affects the results obtained for Mg and Si and can lead to large standard errors.

For the remainder of the impurity elements in the blank base U_3O_8 sample, the standard errors at a 95% CL show typical values comparable to the precision of the method, namely approximately 20%. The large values of n for these elements also ensures the reliability of the lower (C_X) U_3O_8 values over the concentration range of the graphite standards.

In Table 5.1 concentration values of impurities in the base U_3O_8 material obtained with the spark-source mass spectrometer are compared with values obtained using different analytical techniques (see certified concentration column). These techniques are described on page 158. The main reason for some of the differences is the fact that the $C_{_{\rm X}}$ (SSMS) values include the concent



tration of that particular element present in the graphite powder used. In other words, the C_x (SSMS) value reported is a combination of the concentration of that particular element in the blank base U_3O_8 sample as well as the concentration of that particular element in the UCAR SP1 graphite or Ultra 'F' graphite used. In this way, the impurities in the graphite powder have been quantified and should be kept in mind when using these graphite powders for future analyses.

Differences can also be due to contamination picked up from a variety of sources. An important source of contamination, especially at trace level concentrations, is from ordinary dust in the laboratory environment [24]. Typical elements found in dust samples collected in the laboratory and analysed for impurities included such elements as B, Mg, Al, Si and Ca. It has also been shown that the Na from NaCl in human perspiration is a significant source of Na contamination. Another source of contamination is from the stainless steel tools which are used in the preparation of the electrodes. Possible impurity elements include Al, Cr, Fe, Ni, Zr and Mo. It is thus difficult at this stage to identify the exact sources of contamination and to quantify these impurities. Proposals to prevent or minimise such contamination are discussed in Chapter 7 on page 166.

5.2.2 Calibration Curves

Calibration curves are constructed according to equation (1) on page 98. Q_x/Q_y^- is plotted on the y-axis. The value of C_x in C_y/C_x is taken as the sum of the concentrations of an element X in the prepared graphite standard plus the value in the blank base U_3O_8 . Expressed as symbols, $C_x = C_{std} + C_{U_3O_8}$ where $C_{U_3O_8}$ is obtained from Table 5.1 on page 106.



The slope, K_{χ}/K_{γ} , of the calibration curve is the relative sensitivity factor (RSF) of that particular impurity element X present in the matrix $U_{3}O_{8}$ relative to an internal standard, Y. Calibration curve parameters are listed in Table 5.2. The parameters c, r and n are discussed below. The standard error, s_{m} , in the slope is expressed in the form of the confidence limits of the slope, α , at a 95% confidence level (CL). These two parameters are discussed on pages 115 and 148 in terms of the statistical significance of the results.

The values of the intercept on the y-axis (c) are, with only a few exceptions, relatively close to the origin (0;0). The value of c must be evaluated in perspective with the magnitude of the scale of the y-axis. Elements with high RSF's have large absolute values for c. Examples of such elements are K²⁺ (c = -0,6448) and Bi^{2+} (c = -1,0788). Furthermore, elements with large a's also tend to have large values for c. This follows from the uncertainty in the slope of the regression line. Elements classified into this category are Mo¹⁺ and W²⁺. The intercept on the y-axis is reflected in the correlation coefficient of the fit of data to a regression line. A bad fit suggests that there are unreliable data points which, when included, would affect the intercept on the y-axis. Elements falling into this category are Mo¹⁺ and Ba¹⁺. The value of c is not of importance as it is not incorporated directly into any calculations regarding concentration or RSF's.

However, the value obtained for r is an indication of the fit of the data to the regression line. Ideally, r should be unity. The values of r obtained in Table 5.2 are generally quite good. The rather poor fits of data for Fe^{1+} (r = 0,8529), Ba^{1+} (r = 0,8972) and Mg^{2+} (r = 0,9278) are also apparent from the



Table 5.2: U₃O₈ Calibration curve parameters

	T		•			
Element	Charge State(+)	m (RSF)	a (%)	с	r	п
В	1	1,1468	4,6	-0,0122	0,9961	19
Na	1	0,2483	28,2	0,0016	0,9716	7
Mg	2	1,7725	19,3	-0,0898	0,9278	21
A1	2	1,2399	10,9	0,0083	0,9740	22
Si	2	1,2836	15,1	-0,0197	0,9273	32
P	1	0,2178	20,8	0,0121	0,9839	7
P	2	1,3978	37,8	0,0511	0,9649	6
Ca	2	0,3035	12,2	-0,0216	0,9317	44
K	1	0,1073	15,7	-0,0014	0,9883	8
K	2	18,3676	24,2	-0,6448	0,9910	5
Ti	1	0,2598	16,0	0,0004	0,9660	15
Ti	2	0,4684	5,3	-0,0061	0,9969	12
V	1	0,3025	2,4	0,0248	0,9955	24
V	2	0,5004	19,9	0,0489	0,9580	13
Cr	1	0,2408	9,9	0,0087	0,9622	36
Cr	2	0,7199	9,4	-0,0082	0,9847	18
Mn	1	0,1529	10,3	0,0357	0,9753	23
Mn	2	1,0094	17,8	0,0324	0,9660	13
Fe	1	0,2301	23,6	0,0041	0,8529	30
Fe	2	1,1867	13,1	-0,0039	0,9809	13
Co	1	0,2697	4,0	-0,0049	0,9957	25
Co	2	1,2153	12,9	0,0362	0,9836	12
Ni	1	0,2397	5,7	0,0099	0,9898	29
Cu	1	0,2987	7,3	0,0215	0,9840	28
Cu	2	3,9934	8,2	0,0669	0,9924	13
Zn	1	0,6078	7,4	0,0074	0,9857	25
Sr	1	0,4877	10,0	0,1405	0,9767	23
Sr	2	0,3316	11,7	0,0109	0,9848	13

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Table 5.2: Continued

	Y					
Element	Charge State(+)	m (RSF)	α (%)	с	r	n
Zr	1	1,3375	7,8	0,0501	0,9839	25
Zr	2	0,6769	8,9	-0,0154	0,9911	13
Nb	1	1,3581	8,5	0,0273	0,9814	25
Nb	2	0,9780	10,1	-0,0180	0,9886	13
Мо	1	2,8176	19,2	-0,3758	0,9249	22
Мо	2	1,4294	9,1	-0,0468	0,9907	13
Ru	1	2,8572	6,0	-0,0171	0,9927	20
Rů	2	5,1368	19,2	0,0095	0,9609	13
Cd	1	1,1031	13,2	0,1175	0,9702	25
In	1	0,5853	12,5	0,1331	0,9607	25
In	2	7,7360	11,9	0,0027	0,9842	13
Sb	1	1,7565	16,9	0,0113	0,9342	24
Sb	2	7,0408	7,5	-0,1386	0,9937	13
Ba	1	0,5416	23,0	0,6769	0,8972	22
Ba	2	0,4784	10,5	0,0230	0,9879	13
Sm	1	4,2008	45,0	0,0000	0,9310	7
Sm	2	0,6019	4,9	0,0437	0,9945	26
Eu	1	4,6455	6,2	0,0082	0,9962	12
Eu	2	0,6633	9,7	0,0179	0,9743	26
Gd	1	3,6455	7,4	-0,0127	0,9960	12
Gd	2	0,9391	5,5	-0,0087	0,9939	20
Dy	1	7,2053	6,3	-0,1353	0,9960	12
Dy	2	0,6998	5,5	0,0883	0,9922	24
W	2	2,1239	40,3	0,5395	0,9604	6
Bi	2	20,1841	14,8	-1,0788	0,9681	16
Th	2	2,0486	7,7	-0,0852	0,9889	19
Li	1	0,0243	7,1	0,0002	1,0000	5



large errors in the slopes where a for $Fe^{1+} = 23,6\%$, a for $Ba^+ = 23,0\%$ and a for $Mg^{2+} = 19,3\%$. Another explanation for the poor calibration lines for Fe^{1+} and Mg^{2+} is the high values of these elements in the blank base U_3O_8 , where $C_{U_3O_8} = 20,3 \ \mu g \ Fe/gU$ for Fe^{1+} and $C_{U_3O_8} = 26,0 \ \mu g \ Mg/gU$ for Mg^{2+} . This is in spite of the large number of data points (n) used to draw the calibration curves for these elements. The calibration graph for Fe^{1+} in a U_3O_8 matrix is given in Figure 5.1 as an example of a poor calibration curve.

Good calibration curves were obtained for Co1+ and V1+ as indicated by the correlation coefficients obtained for these elements where r = 0,9957 and r = 0,9955, respectively. Factors contributing to the good fit of data points for these elements is the fact that they both have very small a values where a = 4,0% for Co^{1+} and $\alpha = 2,4\%$ for V¹⁺. Another reason is the fact that they both have small concentrations in the blank base U_3O_8 where $C_{U_3O_8} = 0,3 \ \mu gCo/gU$ for Co^{1+} and $C_{U_3O_8} = 0,38 \ \mu gV/gU$ for V^{1+} . In both cases the value of n is large where n = 25 for Co^{1+} and n = 24 for V^{1+} . A typical example of a good calibration curve is given in Figure 5.2 for Co^{1+} in a U_3O_8 matrix. Another good calibration curve is obtained for B1+ where the concentration obtained in the blank base U_3O_8 is fairly high where $C_{U_3O_8} = 9,8$ $\mu gB/gU$ for B^{1+} . The other parameters coupled to this calibration curve are: r = 0,9961; n = 19 and $\alpha = 4,6\%$. This calibration line is also given in Figure 5.3 as a good line where a large background concentration is present.

The value of n in Table 5.2 is the number of data points where each analysis was taken as a separate data point. The value for the blank is also incorporated in n as a data point.







<u>Figure 5.2</u>: Calibration curve for Co^{1+} in U_3O_8 /graphite matrix







5.2.3 Relative sensitivity factors (RSF's) - U₃O₈

The instrument sensitivity for a particular element is totally unique for a specific spark-source mass spectrometer and detection system. Different RSF's will be obtained for an element using a radio frequency (RF) spark compared to a triggered lowvoltage discharge spark as was used in this investigation.

Another important factor to be considered is that a RSF for a particular element X will differ from matrix to matrix [25]. This is illustrated when comparing RSF's obtained for mutual elements (e.g. A1, P, Ca, Si and Zn) for both a UF₄ and a U_3O_8 matrix. Differences in this case could be ascribed, among other reasons, to the fact that in a UF₄ matrix, fluorination occurs within the plasma resulting in less elemental species of ions. © University of Pretoria



A RSF is also unique with regard to a particular internal reference standard.

It was beyond the scope of this investigation to determine whether a RSF for an element in a U_3O_8 matrix will differ from that for another uranium oxide matrix, for example UO_2 or UO_3 . It is the author's opinion that there would not be a significant difference because the combinations of uranium and oxygen would create very similar plasma conditions [11]. In all uranium oxide matrices, there is an over-abundance of oxygen species generated within the plasma.

Correlations between physico-chemical properties of various elements as impurities and relative sensitivity factors have been published [23, 26]. Instead of using standards to determine RSF's, some authors have determined theoretical RSF's from making use of various combinations of physico-chemical properies of the elements. For the purpose of this investigation, an attempt will only be made to explain certain of the anomalies observed in the experimentally determined RSF's.

Physico-chemical properties such as heats of vaporisation, electrical resistivity, thermal conductivity, ionisation potentials, atomic radii and melting points were studied and some correlations drawn. These correlations are qualitative at their best. Due to the complexity of plasmas in relation to the physico-chemical properties, anomalies cannot be adequately explained in this qualitative fashion. It would require computer simulations involving chemical and physical studies in order to relate the properties to RSF's. This is a very complex task which has not been described in the literature and is beyond the scope of this



thesis. Qualitative comments will nevertheless be offered for some of the observations.

The high relative sensitivity factors (RSF's) obtained for a few of the impurity elements in a U_3O_8 /graphite matrix can be related to their physico-chemical properties with some degree of confidence. Elements which do not readily form ions of a particular species tend to have high RSF's for this species. A prime example is K²⁺ which has a very low ion yield for doubly charged species. A factor in this regard is the fact that potassium has only one valence electron in its outermost shell (4s orbital). This valence electron is readily lost to form the singly charged state having the noble gas structure of argon. Thereafter, it would require far more energy to remove a second electron to form the doubly charged species. This fact could be related to the second ionisation potential (I_p^{II}) for K which, together with the other alkali-earth metals, has the highest I_P^{II} of all the ele-The RSF of 18,3676 obtained for K²⁺ differs consideraments. bly from that obtained for K^+ (RSF = 0,1073). It is evident that K⁺ ions are formed in great abundance in the mass spectrometer. Another element which has a small RSF is Li (RSF = 0,0243). Both Li and K are alkali-earth metals of group IA which readily lose an electron to have a noble gas structure. In the case of Li, this would be helium. Na also has a relatively small RSF namely All the group IA elements have of the lowest melting 0.2483. points which would contribute to the high yield of ions for these elements and the subsequent low RSF's. These elements also have of the lowest electrical resistivity of all the elements present. This fact could also contribute to these elements being atomised and ionised more easily.



Bismuth has a high electrical resistance which could account for the very poor ion yield for the Bi²⁺ ion and the subsequent high RSF value. Only the doubly charged Bi²⁺ was recorded (see page 71). Bismuth is also the most diamagnetic of all the metals and the thermal conductivity is lower than any metal, except for Hg. Both the electrical resistivity and the thermal conductivity are physico-chemical properties which play a role in the generation of the plasma between the two electrodes in the ion-source.

Another group of elements having relatively high RSF's are the singly charged species of the rare-earth metals e.g. Sm, Eu, Gd and Dy. These all have relatively high electrical resistivities and large atomic radii. It was found that the ion yield for doubly charged species was greater than for the singly charged species. This can be demonstrated by plotting the number of ions yielded against the charge state [27].

It would seem that the larger the atom becomes, the fewer ions reach the photoplate, probably due to their momentum and collisions in the flight tube. Elements falling into this category are W^{2+} , Th^{2+} , Sb^{2+} , In^{2+} , Ru^{2+} , Ru^{1+} and Mo^{1+} , and high RSF's could be expected. However, it should be taken into account that the number of ions generated in the ion source also plays a determining role.

The relatively high RSF for Cu^{2+} (RSF = 3,9934) is of interest as it is the highest of the 3d transition elements. Cu and Ag



have of the lowest electrical resistance as well as the highest thermal conductivity. They both are group IB elements having electron configurations such that their d-orbitals are filled and having one electron in the outermost s-orbital. The filled dorbitals lead to stability and an electron is readily lost from the half filled s-orbital. In order to lose another electron to form Cu²⁺ species, more energy is required to remove an electron from a paired 3d orbital resulting in a high RSF for Cu²⁺.

Only a few of the physico-chemical properties of the elements have been referred to in order to explain some of the anomalies obtained with RSF's for impurities in a $U_3O_8/graphite$ matrix. Properties such as bond strengths in diatomic molecules and heats of formation of gaseous atoms from elements in their standard states should also be included when attempting to explain these anomalies.

The RSF's obtained from calibration curves can be checked by making use of the instrument signals obtained. The ratio between the instrument signal for the singly charged state of an element and the instrument signal for the doubly charged state of the same element at a concentration level should be the same as the ratio between the RSF of the singly charged state of the particular element and the RSF for the doubly charged state of that ele-The ratio X^{1+}/X^{2+} is independent of the concentration of ment. element X. A number of elements were measured both in the singly and doubly charged states at two different concentration The means of the ratio X^{1+}/X^{2+} between these two concenlevels. trations were compared and good correlation was obtained. This ratio was used to test the ratio RSF X1+/RSF X2+ for the same element using the RSF's obtained in Table 5.3. Good agreement was obtained for most of the elements, which confirmed that outliers did not seriously influence the determination of RSF's. The ratio X^{1+}/X^{2+} can be used with a RSF for X^{1+} to get an estimate of the RSF for X^{2+} and vice versa.



Table 5.3: Relative Sensitivity Factors: U₃O₈/Graphite Matrix

RSF Singly	Element	RSF Doubly	RSF X1+	X1+/X2+	X1+/X2+
charged Species		charged Species	$\frac{RST}{RSF}$ X ²⁺	C _x =10µgX/gU	C _x =50µgX/gU
0,0243	Li				
1,1468	В				
0,2483	Na				
	Mg	1,7725			
	A1	1,2399			
	Si	1,2836			
0,2178	Р	1,3978			
	Ca	0,3035			
0,1073	K	18,3676			
0,2598	Ti	0,4684			
0,3025	v	0,5004	0,60	0,60	0,58
0,2408	Cr	0,7199	0,33	0,34	0,37
ò,1529	Mn	1,0094	0,15	0,15	0,15
0,2301	Fe	1,1867	0,19	0,20	0,20
0,2697	Со	1,2153	0,22	0,22	0,21
0,2397	Ni				
0,2987	Cu	3,9934	0,07	0,08	0,09
0,6078	Zn				
0,4877	Sr	0,3316	1,47	1,55	1,85
1,3375	Zr	0,6769	1,98	2,03	2,06
1,3581	Nb	0,9780	1,39	1,42	1,27
2,8176	Мо	1,4294	1,97	2,02	2,02
2,8572	Ru	5,1368	0,56	1,37	0,67



Table 5.3: Continued

RSF Singly charged Species	Element	RSF Doubly charged Species	RSF X ¹⁺ RSF X ²⁺	X ¹⁺ /X ²⁺ C _x =10μgX/gU	X ¹⁺ /X ²⁺ C _x =50µgX/gU
1,1031	Cd				
0,5853	In	7,7360	0,08	0,08	0,09
1,7565	Sb	7,0408	0,25	0,25	0,24
0,5416	Ba	0,4784	1,13	1,08	1,19
4,2008	Sm	0,6019	6,98	6,63	6,55
4,6455	Eu	0,6633	7,00	7,05	7,58
3;6455	Gd	0,9391	3,88	3,97	3,89
7,2053	Dy	0,6998	10,30	10,64	9,76
	W	2,1239			
	Bi	20,1841			
	Th	2,0486			

5.3 UF₄-graphite matrix quantitation

5.3.1 Blank correction

In order to determine relative sensitivity factors (RSF's) for impurity elements in a UF₄/graphite matrix, the blank UF₄ sample which was to be used to simulate the matrix material first had to be quantified. Considerable effort was initiated to obtain a blank UF₄ sample with the least impurity elements to ensure a background spectrum relatively free from spectral lines. This blank UF₄ sample was mixed with graphite powder, spiked with Y as an internal reference standard, in the ratio of one to one by



mass. The sample was then analysed several times to obtain an instrument signal $(Q_x/Q_y^-)_{UF_4}$ for element X relative to the internal standard, Y. The exposure value for Y, Q_y^- , is the mean for the singly and doubly charged species. The blank UF₄ sample used for this purpose is stoichiometric i.e. 100 per cent UF₄.

A range of graphite standards were prepared with the impurity elements of interest at different concentrations, together with Y as internal reference standard. The method followed to prepare these graphite standards is given on page 26. The concentration range of these graphite standards is as follows:

UF₄ used: stoichiometric i.e. 75,8% per cent U. Concentrations: 100 µg X /g UF₄ 200 µg X /g UF₄ 500 µg X /g UF₄ 700 µg X /g UF₄ 1 000 µg X /g UF₄

Expressed relative to U, the concentrations $\begin{pmatrix} C \\ x \end{pmatrix}$ for each impurity element X, become:

132 μg X /gU 264 μg X /gU 660 μg X /gU 924 μg X /gU 1 319 μg X /gU

The concentration of Y added to each of the above graphite standards as internal standard is 132 µgY/gU.



These standards were used to quantify the impurity elements in the blank UF₄. Using standard addition methods, each of the above graphite standards was mixed with the blank UF₄ sample in the ratio of one to one by mass. Similar to the blank UF₄ graphite matrix sample, each spiked sample is analysed several times to obtain an instrument signal, $(Q_x/Q_y^-)_{UF_4}$, for element X relative to the internal standard, Y. The concentration of each element X can be determined on the basis of equation (9) discussed on page 101:

$$(C_x)_{UF_4} = (C_x)_{std} \cdot \frac{(Q_x/Q_y)_{UF_4+std}}{(Q_x/Q_y)_{UF_4} - (Q_x/Q_y)_{UF_4+std}}$$

Results are given in Table 5.4 as C_{x} in $\mu gX/gU$.

Table 5.4: Blank UF₄ quantification

Element	Isotope	Isotopic Abundance(%)	Charge State	n	Std Error at 95% CL (%)	C _x (µg X/gU)
A1	27	100	2	8	21,36	5,6
Р	31	100	2	5	34,85	76,7
Ca	40 42	96,94 0,65	2 2	9	12,48	25,2
Si	30	3,09	1	5	13,59	77,4
S	32	95,0	1	5	38,74	385,4
C1	35 37	75,72 24,28	1 1	10	21,35	52,5
Zn	64 67	48,89 27,77	1 1	8	23,78	4,0



The concentration value for S is quite high (385,4 μ gS/gU). This greatly influences the calibration line. On the x-axis of the calibration curve, the ratio C_y/C_x is plotted where $C_x = (C_x)_{std}$ + $(C_x)_{UF_4}$. When the background concentration of an element X in the blank UF₄, $(C_x)_{UF_4}$, is large, the ratio C_y/C_x becomes smaller, where C_y is taken as constant. This makes the gradient of the regression line inaccurate and limits the calibration range. The other impurity elements have background concentrations which do not influence the calibration.

The $C_{_X}$ values in Table 5.4 determined for impurity elements in the blank UF₄ are only for the elemental states. The fluorinated species of the elements have not been considered. When analysing UF₄ samples with the spark-source mass spectrometer, it can be assumed that the same degree of fluorination of the elements takes place in the sample as with the UF₄ calibration samples. This assumption is valid if the unknown sample is also stoichiometric UF₄ and the sparking parameters used to generate ions are identical for the UF₄ sample as for the UF₄ calibration samples.

The chemical structures of the impurity elements in the UF₄ sample are assumed to be similar to those in the UF₄ calibration samples. The plasma generated between the two electrodes in the ion source provides the equalising locality for such differences. In this plasma the chemical structures are broken in the process of atomisation and ionisation and recombination of species can take place.

The preparation and characterisation of graphite standards to obtain relative sensitivity factors (RSF's) for impurity elements



in a UF₄ sample were done under serious production pressures due to the study of reactions in the uranium fuel production process and time was not allowed to analyse the blank UF₄ sample more comprehensively. It was nevertheless decided to include the results in this thesis as they were reasonable in terms of the precision of the method and made a major contribution to the solving of the production problems at the time. The fact that the UF₄ work was done as an additional project under severe time constraints must be kept in mind when accessing the small number of data points on which the principles have been demonstrated.

The high standard errors at 95 % confidence level (CL) for P (34,85%) and S (38,74%) can be ascribed to the small number of data points which were statistically acceptable. This shows how the $(C_x)_{UF_4}$ values for these two elements fluctuated over the concentration range of the standards resulting in the C_x values at higher concentrations being rejected leaving n = 5 with still a larger error in the remaining $(C_x)_{UF_4}$ values. The standard error at 95 % CL obtained for Si (13,59%) with n = 5 seems to be the exception where the remaining $(C_x)_{UF_4}$ values show a better standard error at lower concentration levels of the graphite standards. For the above three elements, namely P, Si and S, their concentrations present in the UF₄ sample are the highest, which has a direct influence in the standard errors at 95 % CL.

For the remainder of the impurity elements in the blank UF₄ sample, the standard errors at a 95 % CL show typical values comparable to the precision of the method, namely ~ 20 %. The larger value of n for these elements also shows the reliability of the lower $(C_x)_{UF_4}$ values over the concentration range of the graphite standards.



5.3.2 Calibration curves

The procedure used to construct calibration curves is given in detail on page 137. A few interesting observations are high-lighted below.

Similar to procedures followed for the U_3O_8 matrix (see page 109), the instrument signal, Q_x/Q_y^- , is plotted on the y-axis and the ratio between the concentrations, C_y/C_x , is plotted on the x-axis. The value of C_x in C_y/C_x is taken as the sum of the concentrations of an element X in the prepared graphite standard plus the value of the blank UF₄, expressed as, $C_x = C_{std} + C_{UF_4}$, where C_{UF_4} is obtained from Table 5.4.

The slope of the resultant curve is the relative sensitivity factor (RSF) of that particular impurity element X present in the matrix UF_4 relative to an internal reference standard, Y.

Theoretically, the calibration curve should pass through the origin (see page 139). The values of the intercept on the y-axis, c, listed in Table 5.5 are in accordance with this fact for most of the elements. The values obtained for P and Cl must be kept in perspective as the values of m for these two elements are also large in magnitude compared to the rest. Negative values for c on the y-axis could indicate a minimum detection value for C_{x} on the x-axis. Below this minimum detection value, non-linearity is evident. For the purpose of this investigation, the highest concentration measured was 1319 μ g X/gU. A1 and Zn display good linearity over the entire concentration range.



Table 5.5: UF, Calibration curve parameters

Element	Isotope	Isotopic Abundance(%)	Charge State	m (RSF)	α (%)	с	r	n
A1	27	100	2	2,0059	0,84	0,0008	0,9999	10
Р	31	100	2	25,7454	10,6	-0,9496	0,9917	10
Ca	40 42	96,94 0,65	2 2	0,6104	3,64	-0,0169	0,9980	16
Si	30	3,09	1	0,9438	8,38	-0,0490	0,9948	10
S	32	95,0	1	0,6891	26,9	-0,0123	0,9575	9
C1	35 37	75,72 24,28	1 1	20,0095	4,82	-0,9232	0,9965	16
Zn	64 67	48,89 27,77	1 1	0,4946	0,87	0,0279	0,9999	10

The calibration graph for Zn in the UF_4 matrix is given in Figure 5.4 as an example of a good calibration curve.

The calibration graph for S in a UF_4 matrix is given in Figure 5.5 as an example of a poor calibration curve.



Figure 5.4: Calibration curve for Zn^{1+} in a UF₄/graphite matrix



Figure 5.5: Calibration curve for S^{1+} in UF₄/graphite matrix



The poor fit of data for S is manifested through the relatively large error in the slope ($\alpha = 26,9\%$) and the high value obtained for S in the blank UF₄. Where blank values are reasonably high, uncertainties in these values are reflected in all other data points. This also happens when standards are added to a quantity which is not known in absolute terms.

The value of n in Table 5.5 is an indication of the number of data points used to construct the calibration curves, where each data point is taken as a single analysis. The value for the blank is also incorporated as a data point.

5.3.3 <u>Relative Sensitivity Factors (RSF's) - UF</u>4

For the impurity elements investigated in a UF₄ matrix, various physico-chemical properties were studied in order to find a qualitative solution for the very high RSF's obtained for P (25,7454) and C1 (20,0095) listed in Table 5.5. Properties such as first and second ionisation potentials (I_p) , bond strength (B_s) of the F-X species, heats of formation (H_f°) of gaseous atoms from elements in their standard states, heat of vaporisation $({\rm H}^{\circ}_{vap}),$ electronegativity (E $_{\rm neg}),$ melting points (M $_{\rm p})$ and boiling points (B_p) were studied [28]. No specific physico-chemical property can be singled out to explain anomalies in RSF's as each property plays a role within the plasma. When the melting points and heats of vaporisation are compared between the various elements, it is apparent that P and Cl have the lowest values. However, these elements also have of the highest E and ionisation potentials.



5.4 <u>Semi-quantitative</u> analysis

5.4.1 50% Transmission intercept method

This method is more time consuming than the appearance level method (see page 132) but is still quicker than setting up the MD100 microdensitometer to obtain analytical data. Instruments required to perform this method are a Hilger & Watts^{*} microphotometer Model L-500-2 equipped with a carriage to hold a photographic plate and a Fluk[#] multimeter. Many of the principles and preliminary procedures discussed in detail for the appearance level method also apply to this method. However, only the operational procedure will be discussed below.

The marked photographic plate is positioned and the lens focused, once the light of the photocell has been switched on. A clear plate region of at least 5mm in diameter is made on the photographic plate where there are no spectral lines of interest, by scraping away the emulsion on the photographic plate. This spot will serve as the 100% transmission region in order to calibrate the multimeter.

The intensity of the light is adjusted by means of the photocell amperage so that when the beam of light is mechanically shut off

- * Hilger & Watts Ltd, 98 St Pancras Way, Camden Road, London NW1.
- # John Fluke MFG. Co. INC, P.O. Box 43210, Mountlake Terrace, Everett, Washington, 98043, U.S.A.


there is 0% transmission of light and when the beam of light passes through the clear plate region there is a 100% transmission of light through the photoplate. The Fluke digital multimeter is coupled to the photocell output using its 1 volt scale so that 0% transmission is zero volt on the multimeter and 100% transmission is 1,0 volt on the multimeter. The second decimal scale is sufficient for this method as a reading of 0,65 volt on the multimeter gives a reading of 65% transmission of light through the spectral line. Dark spectral lines on the photoplate will have lower percentage transmission of light through them than lighter spectral lines. The 50 % transmission intercept method can now be implemented.

An element of known concentration is used to obtain a k-factor The ²³⁴U²⁺ spectral line at m/e 117 is used as e.g. U or Y. internal standard or the ⁸'Y¹⁺ or ⁸'Y²⁺ spectral lines at m/e 89 and 44,5, respectively, can be used as internal standard if Y is present in the sample. A transmission curve is obtained by plotting on the y-axis, using ordinary graph paper, the multimeter reading multiplied by 100 to obtain a percentage transmission for each spectral line on the photographic plate. This is plotted against the natural logarithm on the x-axis of the applicable exposure value of each spectral line on the photographic plate i.e. % T on the y-axis and In Q on the x-axis. From this transmission curve, the exposure value at 50 % transmission is read off the graph paper and is used in the general formula to obtain a k-factor.

The same procedure is followed as above to obtain a transmission curve for an element X of interest. The exposure value at 50 % transmission is used, together with the k-factor obtained from



the internal reference to obtain the concentration value, C_x , of element X. However, this concentration is only for that particular isotope of element X. In order to obtain the total concentration C_x of element in the sample, the isotopic abundance of the applicable isotope measured must be incorporated.

This method is suitable to obtain concentration values for impurity elements in a sample where no relative sensitivity factors are available. In this case the RSF is taken as unity and the final result obtained differs from the true value by about a factor of two or three. The fact that no background correction has been incorporated must be borne in mind. This method can be utilised with high and low concentrations of impurity elements as long as there is a spectral line that can produce a workable transmission curve. Both the semi-quantitative methods are extremely useful for analysing uranium samples where no standard is available. In this case the uranium is taken as the internal standard and used to quantify impurity elements.

5.4.2 Appearance level method

This method is the more reliable method of the two used for semiquantitative analysis. However, its interpretation differs from analyst to analyst as will be illustrated below. The only instrument required to perform this method is a microscope which is equipped with a carriage to hold a photographic plate. Whilst looking through the eye-piece of the microscope, the analyst must be able to move the carriage holding the photographic plate, along both the x- and y-axes. The x-direction gives the analyst the opportunity to view the spectrum on the photographic plate in its entirety whereas movement in the y-direction focuses on a specific area of the photoplate and the number of different exposures in the form of spectral lines can be counted. This last step is the essence of the method.



If an uranium oxide sample, for example U_3O_8 , has been mixed with graphite powder spiked with the internal reference standard, Y, of known concentration, then the U and/or Y are used as the elements of known concentration. A prerequisite for using the U line as reference, is that the isotopic composition is known. If the U is natural, then the concentrations of the various isotopes are known and can be used as reference concentrations. This is shown below as an example.

Uranium used: natural isotopic abundance (converted to mass percent): 238 = 99,286 235 = 0,710 234 = 0,0055 thus concentration of: ²³⁸U = 992 860 µg ²³⁸U/g U₃O₈ ²³⁵U = 7 100 µg ²³⁵U/g U₃O₈ ²³⁴U = 55 µg ²³⁴U/g U₃O₈

The concentration of the ^{234}U isotope of uranium is normally used as it has a value similar to impurity levels in the U_3O_8 .

The above concentrations can be expressed in general ppm terms as μg of the U isotope per total mass of U (in grams). For natural uranium in U₃O₈ the concentrations are:

² ³ ⁸ U = 882 425 ppm ² ³ ⁵ U = 6 167 ppm ² ³ ⁴ U = 47,8 ppm

When graphite powder spiked with a known concentration of Y is mixed with the U_3O_8 , it is done in the ratio of five parts U_3O_8 to one part graphite by mass. This was shown on page 30. The concentration of the Y in the graphite is typically 80 µg Y/gC. When mixed with U_3O_8 , the concentration of Y relative to uranium is approximately 20 µg Y/gU. These two concentrations are used when applying the appearance level method.



When a set of spectral lines belonging to a specific element on the photographic plate is investigated under the microscope, dark lines at longer exposures up to light lines at shorter exposures, are observed. At very short exposures, no spectral lines are detected depending on the concentration level of that element in the sample.

The faintest detectable spectral line is called the appearance line. According to the exposure pattern used, this appearance line thus has a specific appearance exposure. The appearance exposure can thus be defined as that exposure necessary for a specific impurity element present at a certain concentration level to become visible to the analyst. This is where the difference in interpretation of the appearance level method varies from analyst to analyst. What might be the appearance exposure for one analyst is not necessarily that for the other analyst.

When performing semi-quantitative analyses with this method, both the Y^{1+} and Y^{2+} lines at masses 89 and 44,5, respectively, are scrutinized to obtain appearance exposures. Similar to quantitative analysis procedures, the mean of these two values is obtained:

$$Q_{\overline{y}} = \frac{Q_{y^{1+}} + Q_{y^{2+}}}{2}$$

When applying the general formula for spark-source mass spectrometry,

k-factor $concentration (C) = -------, \qquad \dots \dots \dots \dots \dots \dots (1)$ exposure (Q) $the k-factor for Y , K_y, can be obtained:$ $K_y = C_y Q_y^- \qquad \dots \dots \dots \dots \dots (2)$



where:

C is the concentration of the internal standard Y, relative to the U content, i.e. typically 20 μ g Y/gU in the above example, and

 $Q_{_{m V}}^-$ is the mean appearance exposure of the internal standard.

For an unknown impurity element X present in the U_3O_8 sample, the appearance exposure, Q_X , is determined using the same method as described above.

Using the above Q_x and K_y from equation (2) in equation (1), the concentration C_x of element X relative to the internal standard is determined:

$$C_{\mathbf{X}} = \frac{K_{\mathbf{Y}}}{Q_{\mathbf{X}}}$$
(3)

If the internal standard is not present, the U spectral lines are used in exactly the same way. However, only the 23 $^{4}U^{2+}$ spectral line at m/e 117 is suitable for use. The concentration of an element X is then expressed relative to the 23 ^{4}U isotope.

This method is a quick way to obtain a concentration for an element without using relative sensitivity factors. The result can differ by a factor of two or three compared to the use of relative sensitivity factors (RSF's). In the above case, the sensitivity of an element X relative to an internal standard is taken as unity. If a RSF does exist for an element X relative to Y in a specific matrix, then it can be used together with the usual formula given below which was derived on page 98:



$$C_{\mathbf{x}} = \frac{RSF \cdot C_{\mathbf{y}}}{\frac{Q_{\mathbf{x}}}{\frac{Q_{\mathbf{y}}}$$

The appearance exposure of element X, Q_x , is expressed as a ratio together with the mean appearance exposure of the internal standard, Q_y^- . The concentration C_x obtained for element X is only the concentration of that particular isotope of element X. In order to obtain the total concentration of the element, the concentration obtained for that particular isotope measured, is divided by its isotopic abundance and multiplied by 100 to cancel the percentage.



CHAPTER SIX

EVALUATION OF THE METHOD

6.1 <u>Statistical significance of results</u>

6.1.1 Statistical approach

Data interpretation is based on the graphic method [29, 30]. This incorporates the use of calibration lines which are obtained from plotting the instrument signal, y, against the concentration, x, of an element. The relationship between x and y can be derived by linear regression using the standard formula:

where:

m is the slope of the calibration line, and c is the intercept of the y-axis.

The general spark-source mass spectrometry formula [8] can be interpreted on this basis:

$$C_{\mathbf{x}} = \frac{K_{\mathbf{x}}}{Q_{\mathbf{x}}} \qquad (2)$$

where:

 C_x is the concentration of element X, K_x is a constant and Q_x is the exposure value at 50% transmission of element X.

Equation (2) can be rewritten in the form of equation (1) as follows:

$$\frac{1}{Q_x} = K_x \cdot C_x$$

The intercept c, on the y-axis of equation (1) is taken as zero and is explained later on in this section (see page 139). © University of Pretoria



The same general formula applies for the internal standard Y, namely:

$$C_{y} = \frac{K_{y}}{Q_{-}}$$
(3)

 Q_y^- is the mean exposure value of Y for the charge states 1+ and 2+ (see page 29).

Combining equations (2) and (3) gives:

$$\frac{Q_{\mathbf{x}}}{Q_{\mathbf{y}}^{-}} = \frac{K_{\mathbf{x}}}{K_{\mathbf{y}}} \cdot \frac{C_{\mathbf{y}}}{C_{\mathbf{x}}} \qquad \dots \dots \dots \dots (4)$$

where:

 $\frac{Q_x}{Q_y^-}$ is the instrument signal, expressed as the ratio between the exposure value, Q_x , of element X at 50% transmission and the exposure value Q_y^- , of the internal reference standard, Y, at 50% transmission; $\frac{C_y}{C}$ is the ratio between the concentration of the internal

reference standard, Y, and the concentration of element X which is given in μg X/gU; and

 $\frac{K_x}{K_y}$ is the slope, expressed as the relative sensitivity factor (RSF) [18, 31] of an element X, relative to the internal reference standard, Y.

The concentration of the internal standard, Y, is taken as 20 μ g Y/gU when analysing unknown U₃O₈ samples and 132 μ g Y/gU when analysing unknown UF₄ samples. The choice of these concentrations of the internal standard is comprehensively described on pages 29, 103 and 122.



The concentration of an element X varies according to the range of graphite standards prepared. The choice of these ranges is comprehensively described on page 103 for a U_3O_8 /graphite matrix and on page 122 for a UF₄/graphite matrix.

The instrument signal, Q_x/Q_y^- , is obtained when doing data interpretation and is taken as the intercept at a 50% transmission of the Hull function plot. This is described on page 36.

The origin (0;0), of the calibration graph is also incorporated in the calibration line. This is shown as follows: When C_x tends to infinity, then the expression C_y/C_x tends to zero when C_y is taken as constant. From equation (2), when C_x tends to infinity, then Q_x tends to zero. Likewise, the expression Q_x/Q_y^- tends to zero when Q_y^- is taken as constant because C_y is constant. Thus both expressions tend to the origin (0;0) when C_x tends to infinity. This verifies the use of the origin as a data point when compiling calibration graphs.

Linear regression formulae [29] (see Appendix A on page 174) are used to determine the standard error, s_m , in the slope of the regression line. The confidence limits of the slope, expressed as a, is given by the following formula [32]:

where:

 s_m is the standard error of the slope, and t is the Student's t-value [33] at a 95% confidence level (CL) with (n-2) degrees of freedom where n is the number of data points (x;y) used to draw up the calibration graph.

The parameters RSF, α , c, r and n obtained from the regression line are given in Table 5.2 (see page 111).



6.1.2 Propagation-of-errors approach [30, 34]

This method is used when determining the concentration C_{χ} , of an element X, in an unknown U_3O_8 sample. Equation (4) can be rewritten as follows:

$$C_{x} = \frac{(RSF \pm \alpha) . (C_{y} \pm c_{y})}{\frac{Q_{x}}{\frac{Q_{y}}{Q_{y}}}} (95\% CL) \dots (6)$$

The confidence limits a, of the slope or relative sensitivity factor is obtained from Table 5.2 on page 111. Likewise, the applicable relative sensitivity factor RSF, is given in Table 5.3 (see page 120). The concentration of the internal standard, Y, given by C_{v} , is taken as 20 μ g Y/gU where graphite powder has been spiked with 80 μ g Y/gC. This graphite powder, called UFY80, is used as electrode material when analysing unknown U₃O₈ sam-The error in C_v , given by c_v , is taken as 0,5% which is ples. the maximum imprecision of a 1 000 μ 1 varipette used to dispense the Y ICP standard solution. The precision of the Mettler H10T mass balance used to weigh out the required mass of graphite powder is 0,1 mg which gives an error of 0,002% when 5 grams of graphite is used. The Y ICP standard solution is certified to <0,01% and the error is not significant. These errors can be ignored statistically and only the error in the varipette, 0,5%, is taken as c_v [38].

The precision of the method is also known and is given in Table 6.1 (see page 147). For a single analysis of an unknown U_3O_8 sample, the error coupled to the instrument signal, Q_X/Q_y^- , for element X is taken as twice the standard deviation, 2s [35, 38]. This is based on the assumption of a normal distribution of results where an analysis result has a 95% chance of lying within two standard deviations of the mean.



When considering the general error formulae used in composite errors, the following applies [36, 37]: For a number of quantities, n, with means \bar{x}_1 , \bar{x}_2 ,, \bar{x}_n , with standard errors a_1 , a_2 , ..., a_n , the standard error of

any function of $\bar{x}_1, \bar{x}_2, \dots, \bar{x}_n$, namely, $f(\bar{x}_1, \bar{x}_2, \dots, \bar{x}_n)$ is

given by
$$\alpha$$
, where $\alpha^2 = (\frac{\partial f}{\partial \bar{x}_1})^2 \alpha_1^2 + (\frac{\partial f}{\partial \bar{x}_2})^2 \alpha_2^2 + \dots + (\frac{\partial f}{\partial \bar{x}_n})^2 \alpha_n^2$

The quotient of two mean values is given by:

$$f(\bar{x}_{1}, \bar{x}_{2}) = \frac{\bar{x}_{1}}{\bar{x}_{2}}$$

$$thus \quad \frac{\partial f}{\partial \bar{x}_{1}} = \frac{1}{\bar{x}_{2}} \quad and \quad \frac{\partial f}{\partial \bar{x}_{2}} = -\frac{\bar{x}_{1}}{\bar{x}_{2}}$$

$$This \ gives \ \alpha^{2} = (\frac{1}{\bar{x}_{2}})^{2} \quad \alpha_{1}^{2} + (-\frac{\bar{x}_{1}}{\bar{x}_{2}})^{2} \quad \alpha_{2}^{2}$$

$$= \frac{1}{\bar{x}_{2}^{4}} \quad (\bar{x}_{2}^{2}\alpha_{1}^{2} + \bar{x}_{1}^{2}\alpha_{2}^{2})$$

$$Therefore \quad \alpha = \frac{1}{\bar{x}_{2}^{2}} \quad \sqrt{\bar{x}_{2}^{2}\alpha_{1}^{2} + \bar{x}_{1}^{2}\alpha_{2}^{2}} \quad \dots \dots \dots \dots \dots (7)$$



The product of two mean values is given by:

 $f(\overline{x}_1, \overline{x}_2) = \overline{x}_1 \cdot \overline{x}_2$

thus $\frac{\partial f}{\partial \bar{x}_1} = \bar{x}_2$ and $\frac{\partial f}{\partial \bar{x}_2} = \bar{x}_1$

This gives $\alpha^2 = \overline{x}_2^2 \alpha_1^2 + \overline{x}_1^2 \alpha_2^2$

Applying the above equations (7) and (8) to equation (6), the standard error, s_C, of the concentration of element X in the x unknown sample is derived.

Thus
$$s_{C_{X}} = \frac{1}{Q_{X}} \cdot \sqrt{\frac{Q_{X}}{(Q_{Y}^{-})^{2}} \cdot (C_{Y}^{2}\alpha^{2} + RSF^{2}c_{Y}^{2}) + (RSF \cdot C_{Y})^{2} \cdot (2s)^{2}} \cdot \dots \cdot (9)$$

The final result of element X is reported as:

$$C_{\mathbf{x}} \pm s_{C_{\mathbf{x}}}$$
 (95 % CL)

This gives the confidence interval derived using the propagationof-errors method at a 95 % confidence level.



6.1.3 Precision

In order to determine the precision coupled to the analysis of U_3O_8 /graphite matrix samples using spark-source mass spectrometry, three of the prepared graphite standards with concentrations of 1,0; 10,0 and 50,0 µg X /gU were each analysed six times (i.e. n = 6) mixed with the base U_3O_8 (see page 103). The results obtained are tabulated in Table 6.1 on page 147. The precision that is obtained is for both the instrument and the analyst.

The standard error at a 95% confidence level (CL) was determined using the following formula [37]:

where:

 \bar{x} is the mean of the six analyses of one standard; s is the standard deviation of the six analyses; and t is the Student's t-value taken at a 95% confidence level using (n - 1) degrees of freedom (v).

Before the above formula could be used, the data obtained had to be subjected to the Dixon outlier test [38, 39, 40, 41] in order to ascertain whether there were any "mavericks". The Dixon outlier test assumes that the parent population from which the measurements are obtained is normally distributed.

One way of assessing a suspect measurement is to compare the difference between it and the measurement nearest to it in size with the difference between the highest and lowest measurements. The ratio of the differences is known as Dixon's Q and is given as Q_{calc} in the following basic formula:

| suspect value - nearest value |

 Q_{calc}

(largest value - smallest value) © University of Pretoria (2)



The critical values of Q, given as Q_{tab} , are taken from the table of critical values for Q at a 95% confidence level (CL).

The following reasoning is applied in the Dixon test: If $Q_{tab} \ge Q_{calc}$, then the suspect value is retained; if $Q_{calc} > Q_{tab}$, then the suspect value is rejected. From the table of critical values of Q, the sample size in this case is taken as six.

It is important to note that at a 95% CL there is still a 5% chance of incorrectly rejecting the suspect value. When measurements are repeated only a few times rejection of one value makes a great difference to the mean and standard error. This has a considerable effect on the estimation of the precision. The importance of caution in rejecting outliers cannot be over-emphasised. There is also the possibility of two suspect values which leads to masking in the application of the Dixon Q-test.

Using the above approach, suspect values were rejected for a number of elements from each of the standards. This is shown in Table 6.1 where n = 5. For Mo^{1+} (n = 4) and Sm^{1+} (n = 3), the experimental data obtained was limited as the spectral lines on the photographic plate could not be measured in all the cases.

An assessment of the results tabulated in Table 6.1 reveals that most of the standard errors at a 95% CL are below 20% with the exception of a few cases which will be explained below. This is in accordance with values reported by many other authors [31] who have used electrical detection, radio frequency (RF), glow discharge (GD) and other types of spark-source mass spectrometers for analysing U samples.



The first few elements in Table 6.1, namely B, Mg and A1, have high standard errors at all the concentration levels. This is ascribed to interference of their spectral lines at masses 10 and 11 for B, 12,5 for Mg and 13,5 for A1, due to the spectral lines of the matrix component C at masses 12 and 13. The C spectral lines, being from the major constituent of the sample, are intense and dispersed in the region surrounding them, thus affecting the adjacent spectral lines and their precision, irrespective of concentration.

The standard errors for most of the elements at a concentration level of 1 μ g X /gU are relatively high. This is a result of unreliable data obtained from the transmission curves. Only a few points could be utilised in the Hull function plot as most of these were light points. This could also be ascribed to the fact that at this concentration level, the detection limit for some of the elements is reached. Typical examples affected in this manner are Mn¹⁺, Zn¹⁺, Zr¹⁺ and the heavier elements such as the rare earths Sm, Eu and Dy.

The high standard errors at a 95% CL for the heavier elements, such as the rare earths at a concentration level of $1 \mu g X / gU$, is ascribed to the fact that these elements provide small ion yields of the various charge states resulting in poor transmission curves. The atomic size of these elements affects the number of ions entering the ion source due to collisions. These ions also have a smaller velocity down the flight tube of the mass spectrometer. All these factors have a decisive impact on the nett total of ions yielded at the photographic plate.

The very high standard error for Mo^{1+} at a 95% CL, namely 84,1%, can be ascribed to the previous reasons (poor ion yield, near the



low concentration detection limit, as well as the small number of useful data points). When applying the formula to determine the standard error at a 95% CL, the degrees of freedom (v) is given as (n - 1), i.e. 3 where n = 4, which is relatively small. This means that the standard deviation, s, is multiplied by a factor 1,59 (3,182/2) giving a higher standard error. As n gets larger, the factor of t/\sqrt{n} gets smaller, thus reducing the standard error in a significant way.

The standard errors for Ca²⁺ and Si¹⁺ are relatively high as the Ca²⁺ spectral line was measured as a doublet and the Si¹⁺ spectral line was measured as a triplet. The analyst has to set windows around these lines and this affects the background surrounding the spectral lines which are under scrutiny. This leads to a weaker precision at all concentration levels.

The high standard error for Ni¹⁺ at 95% CL at a concentration of 50 μ g Ni /gU, namely 34,2%, is verified as follows. From the raw data obtained, there is one data point out of the set of six (n = 6) that appears to differ from the remainder. However. when applying the Dixon outlier test to this data point, the test shows that this data point cannot be taken as an outlier and must thus be retained. This leads to the high standard error. If the Dixon outlier test had shown that this point could be rejected, the precision would have been 15,9% for the remainder of the This could be interpreted as a possible data points (n = 5). limitation of the Dixon outlier test.

The precision values obtained are used together with the relative sensitivity factors (RSF's) when analysing the unknown U_3O_8 samples where the error in the instrument signal is taken as twice the standard deviation.

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<u>TABLE 6.1</u>: Precision for U_3O_8

1				T			
Element	Charge	$C_{\rm X} = 1\mu g \ X \ /gU$		$C_{X} = 10\mu g X / gU$		$C_{\mathbf{X}} = 50 \mu g \mathbf{X}$	/gU
	State	Std Error at 95% CL (%)	n	Std Error at 95% CL (%)	n	Std Error at 95% CL (%)	n
В	1	27,6	6	24,8	6	36,1	6
Mg	2			10,3	5	40,4	6
A1	2			24,7	6	22,6	6
Si Si	2 1	38,6	6	11,1 25,3	6 6	16,6 35,5	6 6
Ca	2	12,0	6	24,8	6	29,5	6
Ti Ti	2 1	21,2	6	6,1	5	13,2	6
V V	2 1	7,6	6	13,9 10,5	6 6	15,9 8,8	6 6
Cr Cr	2 1	17,7	6	10,8 14,0	6 6	10,7 18,6	6 6
Mn Mn	2 1	29,7	6	16,3 19,1	6 6	22,0 19,1	6 6
Fe Fe	2 1	18,9	6	19,0 15,5	6 6	12,8 15,4	6 6
Co Co	2 1	6,6	6	11,2 5,0	6 6	17,2 17,7	6 6
Ni	1	19,3	6	2,6	6	34,2	6
Cu Cu	2 1	15,3	6	7,1 15,3	6 6	17,0 19,3	6 6
Zn	1	32,5	6	8,8	6	21,6	6
Sr Sr	2 1	18,1	6	10,2 9,4	6 6	17,2 15,7	6 6
Zr Zr	2 1	36,1	6	8,4 6,2	6 6	15,8 11,2	6 6
Nb Nb	2 1	18,2	6	10,6 10,9	6 6	15,6 5,8	6 5



Table 6.1: Continued

	Charge	$C_{\mathbf{X}} = 1 \mu g \mathbf{X} / g U$		$C_{\mathbf{X}} = 10 \mu g X$	/gU	$C_{\mathbf{x}} = 50 \mu g X$	/gU
Element	State	Std Error at 95% CL (%)	n	Std Error at 95% CL (%)	n	Std Error at 95% CL (%)	n
Mo Mo	2 1	84,1	4	8,6 7,1	6 6	16,2 11,2	6 6
Ru Ru	2 1			13,9 7,7	6 5	12,2 5,0	6 5
Cd	1			10,4	б	15,3	6
In	1	23,9	6	11,7	6	21,9	6
Sb Sb	2 1	34,1	6	7,6 12,2	6 6	8,6 16,3	6 6
Ba Ba	2 1	27,5	6	8,6 15,9	6 6	8,9 17,1	6 6
Sm Sm	2 1	48,3	5	9,4 18,8	6 3	10,7 17,0	6 6
Eu Eu	2 1	33,3	6	7,3 5,8	6 6	14,2 8,8	6 5
Gd Gd	2 1			6,8 8,4	5 5	9,3 5,0	6 5
Dy Dy	2 1	32,0	5	14,9 7,3	6 5	9,8 12,4	6 6
Bi	2			25,2	6	15,0	6
Th	2	25,8	6	12,9	6	20,2	6

6.1.4 Confidence Intervals - U₃O₈

Confidence limits of the slope, expressed as α , have a significant influence on the relative sensitivity factor (RSF) derived



as the slope of the calibration curve. Large a values mean large uncertainties in the RSF's. These uncertainties must be included in the overall errors calculated for the final analysis results. Values of a greater than 20% in Table 5.2 (see page 111) can be ascribed to a number of reasons, of which the important ones are given below.

The value of n has a significant influence on the value of α . This can be demonstrated using equation (5) on page 139 where the t-value is obtained using (n - 2) degrees of freedom at a 95% confidence level (CL). For n = 7, the t-value from the Students t-Distribution Table is 2,571. The standard error in the slope, s_m , must be multiplied by this number in order to obtain the α value and leads to large confidence limits of the slope.

When determining the calibration curve parameters, each analysis of a graphite standard sample was treated as an individual analysis. Thus, when a graphite standard was analysed in triplicate, the value of n was taken as three. This was typically done using the check graphite standards where some elements were analysed for the first time, e.g. Na, P, K and W. Using two such check graphite standards together with the origin (0;0) gives a t-value of 2,571, where n = 7. This means that a standard error in the slope of 20% becomes a confidence limit of 51,4%. A number of elements in Table 5.2 fall into this category, namely Na¹⁺ (11%), P¹⁺ (8,1%), P²⁺ (13,6%), K²⁺ (7,8%) and W²⁺ (14,5%), where the standard error is given in brackets after each element.



The ion yields of certain elements with specific charge states at their lowest concentration levels are not very good, with the result that poor transmission curves are obtained. Only a few long exposure values are used in the Hull function plot and the rest of the data points are discarded as light points. The charge state differs from element to element depending on the atomisation and ionisation of the particular element. This can be illustrated when plotting characteristic curves of number of ions yielded against charge state. A number of cases in Table 5.2 where a is near or greater that 20 % can be placed into this category, namely K^{2+} , Ru^{2+} , Ba^{1+} , W^{1+} , Sm^{1+} , Mo^{1+} and Sb^{1+} .

Elements with large atomic radii are more prone to collisions and also have a slower velocity down the flight tube. This leads to fewer ions reaching the photoplate. From Table 5.2, elements falling into this category are Sm^{1+} , W^{2+} , Ba^{1+} , Mo^{1+} , Sb^{1+} and Ru^{2+} .

The correlation coefficient, r, in Table 5.2 can also be coupled to a larger a value. Ideally r should be unity, thus values of r < 0,90 show that the fit of calibration data to the regression line is seriously affected by a few bad data points. The inclusion of these bad data points is confirmed by applying the Dixon outlier test which shows that these values have to be retained. However, great caution should be exercised in drawing conclusions from the result of repeated applications of the Dixon's test. If a few statistical outliers are found at a certain particular concentration level this is not very serious, but if several outliers occur at different concentration levels, this may be considered as indicating that the regression line and thus the RSF is This would lead to a large spread of data points inaccurate. resulting in a large standard error in the slope, s_m.



Correspondingly, a larger a value is obtained. Elements in Table 5.2 having poor correlations where r < 0,90 are Fe^{1+} (r = 0,853) and Ba^{1+} (r = 0,897). This is in spite of n being large for Fe^{1+} (n = 30) and Ba^{1+} (n = 22). Elements in Table 5.2 having correlation coefficients of r < 0,95 are the following: Mg^{2+} , Si^{2+} , Ca^{2+} , Mo^{1+} , Sb^{1+} and Sm^{1+} .

For Mg²⁺, Si²⁺, Fe¹⁺ and Na¹⁺ it is significant to note that these elements all have high background concentrations in the blank base U₃O₈ sample. The influence of this high blank concentration on the calibration line is discussed on page 105. This effectively reduces the range on the x-axis of the calibration plot. Typically, for Fe¹⁺ the range on the x-axis is from zero to 0,2844. The spread of data points in this case is larger than over a greater range on the x-axis and results in a poor fit of the data points on the regression line. Another reason for Mg^{2+} having an α of 19,3% is the fact that it is measured at m/e 12,5 which lies inbetween the two spectral lines of the major component of the U₃O₈/graphite mixture, namely ¹²C and ¹³C at m/e 12 and 13, respectively. Intense fogging on the surrounding background makes the measurements of Mg²⁺ difficult and inaccurate.

When using a values to determine the error coupled to an element's concentration in an unknown U_3O_8 sample, the analyst must exercise great care. In the case of Ba^{1+} (23,0%) and Sm^{1+} (45,0%), the analyst should avoid using these charge states, and should rather use the other charge states where the a values are more acceptable. The same argument applies for W^{2+} (40,3%).

The α value for the impurity elements in a U₃O₈/graphite matrix are tabulated in Table 5.2. However, these have also been given as a visual presentation in the form of two periodic tables, the



first for the singly charged species, Figure 6.1, and the other for the doubly charged species, Figure 6.2. It is demonstrated that the appropriate application of the guidelines for quantification enables the acquisition of analytical data within very acceptable confidence intervals for most of the selected elements.

6.1.5 Confidence Intervals - UF4

The confidence limits of the slope, expressed as a and as a percentage in Table 5.5 on page 127, is a direct measure of the uncertainty coupled to the RSF. The a value for S is the only one which is relatively high (26,9%) for impurities in a UF₄ matrix. This could be attributed to a number of factors of which the most important is the fact that sulphur is measured at mass 32 as a doublet with the main interference being ${}^{64}Zn^{2+}$. This could influence the data and result in a bigger spread of data points for the calibration curve. This bigger spread implies a larger standard error in the slope, resulting in a large a value. This fact is also supported by the relatively poor correlation coefficient obtained (r = 0,9575) for the regression line.

The α value for S could also be influenced by the relatively high background concentration in the blank UF₄ ($C_x = 385, 4 \ \mu gS/gU$). This value is used together with the concentration of the standard to define the x-value in a data point (x;y) when applying linear regression. The higher the blank concentration, the more influence it has on the C_y/C_x value on the x-axis. The standard error for S in the blank UF₄ at a 95% confidence level (38,74%) is also an indication of the difficulty experienced to obtain reliable data for sulphur in a UF₄ matrix.





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Figure 6.2: Confidence intervals (a) at 95% CL for X^{2+} in U₃O,

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The other α values in Table 5.5 are all acceptable in the sense that they fall within the precision of the instrument and the analyst. The exceptionally good α values obtained for A1 = 0,84% and Zn = 0,87% where n = 10 for both elements is an indication of the accuracy of the method over a wide concentration range. The reproducibility of the results and the homogeneity of the standards are illustrated by these α values. It should also be noted that A1 and Zn both have the lowest concentrations in the blank UF, as shown in Table 5.4 on page 123.

6.2 <u>Comparative</u> analyses

6.2.1 International standard U₃O₈ No IAEA/SR-54

The analysis results are tabulated in Table 6.2. For the certified reference material (CRM) SR-54 the concentration values and their confidence intervals at 95% CL for impurity elements in U_3O_8 were obtained from the certificate of analysis. Various analytical methods were used to obtain these concentration values. The results obtained using spark-source mass spectrometry are the mean of four analyses, where equation (4) on page 136 was used to calculate the concentration $C_{_{\mathbf{Y}}}$ of impurity element X The standard error values at 95% CL in Table 6.2 in the CRM. were obtained using equation (9) on page 142. The SSMS concentration values compare favourably to those certified for the CRM SR-54, especially if the confidence interval is also taken into account. Where differences do occur, notibly for V, it must be borne in mind that the concentration value for the CRM SR-54 was presented as non-certified information.

6.2.2 Internal U₃O₈ certified standards

As a result of the non-availability of suitable standards at trace levels of elements in a U matrix, the Atomic Energy Corporation prepared a series of standards according to guidelines as



<u>TABLE 6.2</u> :	Comparison	of	U ₃ 0,	CRM	SR-54	with	SSMS
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Element	Certified conc. value (µg X /gU)	Confidence interval at 95% CL	SSMS conc. value (µg X /gU)	Std error at 95% CL
Al	71,3	54,8 - 82,0	70,4	15,9
Со	4,2	4,0 - 4,3	5,2	1,3
Cr	3,6	3,1 - 4,3	2,9	0,8
Cu	5,0	4,2 - 6,7	5,7	0,5
Fe	64,7	46,0 - 77,5	66,2	10,2
K	1,7*	-	3,3	0,7
Mg	0,99*	0,81 - 1,1	1,9	0,8
Mn	15,6	14,3 - 16,9	18,4	3,7
Mo	13,0	9,5 - 17,5	12,7	1,1
Na	2,8*	-	3,9	0,8
Ni	11,4	8,4 - 13,9	10,8	2,0
Si	34,3*	18,0 - 53,5	29,8	7,5
Ti	0,98*		1,74	0,37
V	3,7*		0,12	0,01
Zn	2,4*	0,89 - 3,2	2,2	0,2
* The: non-	se values are n certified info	not certified, but are primation values.	presented as	

laid down by the New Brunswick Laboratory[#]. These standards covered a wide concentration range and were prepared in a U_3O_8

U.S. Department of Energy, New Brunswick Laboratory, 9800 S. Cass Avenue, Building 350, Argonne, Illinois, 60439, U.S.A.



matrix. The standard with the highest concentration level of impurity elements is called ES 1 and the comparison between the certified value and the concentration value obtained with the spark-source mass spectrometer is given in Table 6.3. The standard with the lowest concentration of impurity elements is called ES 5 and the comparison of results obtained is given in Table 6.7. Standards with concentrations falling inbetween ES 1 and ES 5, named ES 2, ES 3 and ES 4, are given in Tables 6.4, 6.5 and 6.6 respectively.

Of every standard in the ES series of standards, three samplings were each analysed in triplicate. This resulted in each ES series of standards being analysed nine times by a specific analytical technique. The spark-source mass spectrometer (SSMS) concentration values given in Table 6.3 to Table 6.7, are the mean concentrations over nine analyses. These concentration values within an ES standard were also subjected to the Dixon outlier test to ascertain whether there were any outliers before each final mean value was reported.

The formula used to calculate the concentration, $C_{_X}$, of an impurity element X in each of the ES series of standards is given by equation (4) on page 136. However, this concentration value also contains the contribution from that impurity element also found in the graphite which was used to mix with the U_3O_8 ES series of standards. This has been described on page 108. The concentration levels of impurity elements in the graphite were quantified and deducted from the mean concentration values reported for each of the ES series of standards.



Various analytical methods were used by different laboratories in order to certify these internal U_3O_8 standards, amongst others:

- Inductively coupled plasma (ICP) optical emission spectroscopy (OES),
- Ion chromatography (IC),
- Carrier distillation emission spectroscopy (CDES),
- Atomic absorption spectroscopy (AAS), and
- UV spectroscopy.

It is beyond the scope of this investigation to go into any detail of how the data obtained for the ES series of standards analysed with the above methods, was evaluated. The certified concentration values and confidence intervals at a 95% CL for the various impurity elements across the ES series of standards given in Tables 6.3 to 6.7 were obtained after the evaluation. These certified values were calculated from the experimental data.

The standard error values at a 95% CL in Tables 6.3 to 6.7 were obtained using equation (9) on page 142. However, the term 2s in this equation was replaced by the term $s.t/\sqrt{n'}$ as denoted by equation (1) on page 143. This is in accordance with the fact that the Q_x/Q_v^- value used in equation (9) is the mean of several (nine) analyses as previously mentioned in this section. The standard error coupled to this mean Q_x/Q_v^- value at a 95% CL is thus derived using equation (1) where n is taken as nine and s is the standard deviation over the nine analyses. The other terms used in equation (9) are identical to those used in equation (6) on page 142 and which were comprehensively described. The use of equation (6) was not warranted as multiple analyses were performed and not just a single analysis.



When comparing the results in Tables 6.3 to 6.7, a number of facts should be kept in mind. The certified values must not be accepted as being the absolute values for particular impurity elements in the series of ES standards. A better representation of the results obtained is given in Appendix C on page 191 where graphs have been compiled for all the impurity elements across the concentration range for each of the analytical methods in comparison to the expected concentration values. In this way anomalies can be detected and comparisons drawn between the spark-source mass spectrometry results and the expected concentration values.

Another interesting fact to consider is whether there is a meaningful difference between a certified value of, for example, 0,1 μ g Cd/gU and a SSMS value of 0,64 μ g Cd/gU, as reported in Table 6.7. Both these values are less than 1 μ g Cd/gU and at these trace levels the detection limits of certain analytical instruments have to be considered. The same could be true for Fe in Table 6.4 where the certified value is given as 208 μ g Fe/gU and the SSMS value is given as 264 μ g Fe/gU. In view of the various confidence intervals for these two values, it is clear that the analyst should not compare exact values with each other but also take cognicance of the confidence limits coupled to a result when assessing such data.

The SSMS concentration value obtained for Ca across the ES series of standards is higher than the certified concentration values. The higher value could possibly be coupled to an incorrect relative sensitivity factor (RSF) for Ca. This can be seen in the graph for Ca in Appendix C where the graph for SSMS (method B) lies above the dotted line which represents the true concentration values. The very high value for Ca obtained for the ES 1 standard with SSMS was also obtained by three other analytical techniques, namely A, C and D. It has not been possible to



confirm the reasons for this difference. Ca is a difficult element to determine with spark-source mass spectrometry and the investigation has not been persued for this element.

The SSMS concentration value obtained for Th across the ES series of standards is higher than the certified concentration values reported for ES 1, ES 2 and ES 3, although no confidence intervals were reported for these values. However, the SSMS results compare favourably to the expected values as shown in the graph in Appendix C.

It should be noted from the graphs in Appendix C that the mass spectrometry results in general, compare remarkably well with the expected standard values.



<u>Table</u>	<u>6.3</u> :	Comparison	of	U ₃ O ₈ -Standard	ES	1	with	SSMS	
					~~~	-		DDIID	

ſ		I		
Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error at 95% CL
A1	234	189 - 279	242	43
В	5,7	5,0 - 6,4	4,9	1,0
Bi	14,3	11,6 - 17,0	13,1	3,0
Ca	272	245 - 299	416	110
Cd	· 5,5	5,0 - 6,1	6,0	1,3
Со	26,6	23,7 - 29,5	28,8	3,5
Cr	125	77 - 174	154	27
Cu	104	84,4 - 124	120	21
Dy	0,56	0,43 - 0,69	0,71	0,24
Eu	0,56	0,44 - 0,68	0,69	0,16
Fe	827	663 - 990	972	191
Gd	0,64	0,41 - 0,87	0,85	0,34
In	6,2	4,4 - 7,9	8,9	1,6
K	536	481 - 591	379	112
Li	11,5	9,31 - 13,7	13,2	3,8
Mg	. 56,2	48,5 - 63,9	49,8	14,6
Мл	55,3	47,5 - 63,2	65,1	15,5
Мо	54,6	46,1 - 63,1	59,4	7,3
Ni	233	209 - 259	243	47
Sb	11,2	9,2 - 13,1	13,8	2,8
Si	206	169 - 244	221	65
Sm	0,60	0,51 - 0,69	0,62	0,17
Th	3,4	-	11,0	1,7
Ti	52,5	39,9 - 65,1	56,4	12,5
v	5,08	3,97 - 6,19	5,40	0,38
W	13,3	11,4 - 15,2	12,7	5,0
Zn	. 247	207 - 287	261	41
Zr	59	© University of Pr	etoria 55	6,6



Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error at 95% CL
A1	115	93 - 137	120	24
В	3,8	3,3 - 4,3	3,5	0,7
Bi	5,3	4,2 - 6,3	5,6	1,5
Ca	108	97 - 119	163	32
Cd	. 2,7	2,4 - 3,0	3,0	0,7
Со	13,5	12,0 - 14,9	13,9	1,1
Cr	59	36 - 82	65	11
Cu	54,1	43,7 - 64,4	58,3	5,7
Dy	0,56	0,43 - 0,69	0,69	0,16
Eu	0,39	0,30 - 0,48	0,49	0,14
Fe	208	165 - 251	264	53
Gd	0,47	0,29 - 0,65	0,64	0,42
In	5,3	3,8 - 6,8	6,4	1,1
K	180	162 - 199	171	35
Li	9,51	7,70 - 11,3	10,8	3,1
Mg	21,8	18,7 - 24,8	22,9	6,2
Mn	25,1	21,6 - 28,7	29,0	4,5
Мо	2,0	1,7 - 2,4	2,4	0,6
Ni	97,4	87,3 - 107	92,0	11,1
Sb	8,0	6,6 - 9,4	10,0	1,9
Si	75	59 - 90	77	17
Sm	0,59	0,50 - 0,68	0,66	0,32
Th	0,6		5,5	0,58
Ti	25,2	19,1 - 31,2	26,7	4,4
V	2,03	1,55 - 2,51	2,18	0,25
W	5,7	5,0 - 6,4	5,3	2,37
Zn	98,4	82,2 - 115	95,9	14,1

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Zr

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<u>Table 6.4</u> :	Comparison	of	$U_{3}O_{a}$ -Standard	ES	2	with	SSMS
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<i>Table 6.5</i> :	Comparison	of	U ₃ O ₈ -Standard	ES	3	with	SSMS

	I	Y		
Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error at 95% CL
A1	68	54 - 81	68	18
В	1,4	1,2 - 1,6	1,3	0,3
Bi	3,8	3,0 - 4,6	4,9	1,7
Ca	72	65 - 79	99	20
Cd	1,0	0,9 - 1,2	1,3	0,3
Со	5,1	4,5 - 5,7	5,8	0,6
Cr	28	17 - 40	29	7
Cu	34,0	27,4 - 40,5	38,3	5,6
Dy	0,48	0,36 - 0,60	0,54	0,21
Eu	0,39	0,30 - 0,48	0,50	0,11
Fe	72	56 - 89	65	16
Gd	0,22	0,12 - 0,32	0,74	0,20
In	4,3	3,0 - 5,5	5,7	1,0
K	87	78 - 96	79	22
Li	7,12	5,75 - 8,49	7,86	2,1
Mg	11,4	9,8 - 13,0	15,9	4,9
Mn	12,1	10,4 - 13,8	13,3	2,1
Mo	1,2	1,0 - 1,4	1,3	0,3
Ni	53,9	48,3 - 59,6	52,2	8,2
Sb	3,9	3,1 - 4,7	5,2	1,2
Si	44	33 - 54	63	21
Sm	0,43	0,36 - 0,50	0,56	0,20
Th	0,3	-	3,0	0,5
Ti	10,9	8,3 - 13,6	10,1	2,0
V	1,01	0,74 - 1,28	1,22	0,12
W	4,2	3,6 - 4,7	3,7	1,6
Zn	54,8	45,6 - 63,9	62,7	7,6
Zr	49	© University of Preto	46 vria	6



<u>Table 6.6</u> : 0	Comparison	of	U308	-Standard	ES	4	with	SSMS
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Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error at 95% CL
A1	23	19 - 28	27	5
В	0,6	0,5 - 0,7	0,8	0,1
Bi	2,5	1,9 - 3,0	3,1	0,8
Ca	23,8	21,2 - 26,4	34,1	5,7
Cd	0,5	-	1,5	0,4
Со	2,7	2,4 - 3,0	3,5	0,3
Cr	16	9 - 23	19	3
Cu	11,4	9,1 - 13,6	14,2	1,8
Dy	0,40	0,30 - 0,50	0,59	0,16
Eu	0,37	0,28 - 0,46	0,51	0,13
Fe	29	21 - 37	40	8
Gd	0,24	0,13 - 0,35	0,90	0,38
In	2,5	1,7 - 3,3	4,7	0,7
K	48	43 - 53	46	12
Li	3,25	2,60 - 3,90	3,73	0,44
Mg	5,4	4,6 - 6,2	8,8	2,2
Mn	5,73	4,9 - 6,6	7,24	1,32
Мо	5,3	4,5 - 6,2	6,7	0,9
Ni	23,2	20,7 - 25,7	25,0	2,5
Sb	1,6	1,2 - 2,0	4,2	0,7
Si	13	8 - 19	31	8
Sm	0,41	0,35 - 0,47	0,59	0,10
Th	_		1,1	0,2
Ti	5,5	4,2 - 6,9	6,3	1,1
V	0,44	0,29 - 0,59	0,79	0,17
W	2,8	2,4 - 3,2	3,3	1,5
Zn	22,9	18,9 - 26,8	29,0	4,0
Zr	40	© University of Pret	oria 37	3,4



<u> Table 6.7</u> : Comparison	of	U ₃ O ₈ -Standard	ES	5	with	SSMS	
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	· · · · · · · · · · · · · · · · · · ·	T		
Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error of 95% CL
A1	12	0 - 15	14	3,4
В	0,4	0,30 - 0,40	0,9	0,2
Bi	0,6	0,5 - 0,8	1,6	0,6
Ca	11	9,7 - 12,3	29	6,7
Cd	0,1		0,64	0,2
Со	2,6	2,3 - 2,9	3,8	0,5
Cr	12	7 - 17	12	2
Cu	6,2	5,0 - 7,5	8,5	0,8
Dy	0,23	0,16 - 0,30	0,50	0,38
Eu	0,22	0,16 - 0,28	0,36	0,08
Fe	19	13 - 25	24	5
Gd	0,16	0,08 - 0,20	0,39	0,02
In	1,8	1,2 - 2,4	3,1	0,5
K	20	17 - 22	22	7
Li	1,86	1,47 - 2,25	2,37	0,86
Mg	2,4	2,0 - 2,8	5,9	1,7
Мл	3,09	2,6 - 3,6	4,8	0,9
Мо	20,9	17,6 - 24,2	24,4	2,6
Ni	12,8	11,4 - 14,2	15,4	2,0
Sb	0,5	0,3 - 0,8	2,6	0,6
Si	_		85	33
Sm	0,18	0,14 - 0,22	0,30	0,26
Th	_	-	0,71	0,2
Ti	3,1	2,3 - 3,9	4,5	0,8
v	0,14	0,05 - 0,23	0,39	0,1
W	0,9	0,8 - 1,1	1,2	1,0
Zn	13,2	10,8 - 15,6	18,1	3,3
Zr	27	© University of Pret	oria 23	2



### CHAPTER SEVEN

### GENERAL COMMENTS AND CONCLUSIONS

The success of the project for the development of analytical and data interpretation methods for the qualitative and quantitative analysis of trace impurities in uranium compounds with sparksource mass spectrometry has been adequately demonstrated.

Not only did the mass spectrometry results contribute to the characterisation of the internal  $U_3O_8$  impurity standards, but the analytical data was in many cases closer to the expected values than those of any of the other analytical techniques.

Furthermore, the ability to analyse  $UF_4$  materials provided analytical results which could not be obtained with any other technique available at the time.

The use of the ratio between singly and doubly charged exposure values as well as the use of the mean exposure value for the internal standard to determine whether a photoplate is acceptable or not, is a new approach to data interpretation in spark-source mass spectrometry. In this way possible misleading results can be directly avoided. Other quality assurance data interpretation methods have also been introduced. This thesis is now being used as a reference document for the mass spectrometry laboratory.

Contamination is an ever present threat to elemental trace level analysis. An effective but expensive solution would be a laboratory conforming to class 100 requirements. A relatively inexpensive alternative has been implemented in this laboratory. A laminar flow cabinet, where a curtain of HEPA filtered air is induced at the opening, is used for all sample preparation steps. Due to the positive pressure of air within the cabinet no contamination in the form of dushiverity of Peroria


The apparent disadvantages of the spark-source mass spectrometric technique are:

- 1 Successful use requires wide experience, both in the operation of equipment and in the reading and interpretation of spectra.
- 2 The instrument is essentially a comparator; for quantitative analyses, standards of composition similar to the material under analysis are required. Unknown samples therefore present a problem when quantitative results are required.
- 3 The accuracy and precision are not as high as for some spectroscopic methods, notably inductively coupled plasma mass spectrometry (ICP-MS). It should be realised that these techniques have their own unique limitations, for example, laser ablation has a big problem with point inhomogeneity.

The use of spark-source mass spectrometry to analyse trace impurities in uranium compounds is still one of the most powerful techniques available. This is confirmed by the following advantages:

- 1 The procedure is specific for the element being determined. Sources of interference can be unequivocally identified and in many cases eliminated.
- 2 Quantitative determination of traces of the elements in a powder sample can be achieved without any preliminary chemical treatment. All solid materials may be determined.
- 3 A permanent record is obtained on a photographic plate.



- 4 The technique may be applied to the determination of small quantities of added constituents or of traces of impurities to solidstate matrices where conventional methods of analysis are difficult, fail, or give less accurate results.
- 5 The information content of analytical data which can be utilised is vast. This compensates for the relatively high operation costs of the technique. A direct complete picture can be obtained for all major and minor elements with the analysis of a single sample. This is especially useful when characterising unknown samples as well as for semi-quantitative analyses. Quantitative analysis with alternative methods for the identified impurities can then be executed cost effectively.
- 6 All isotopes of an element are recorded on a photoplate with intensities according to their isotopic abundances which leads to undisputed confirmation that a particular element is present in the sample as an impurity.
- 7 The up-time and reliability of the instrument is a proven fact, making this technique comparable if not better than any other analytical technique in this field.

Spark-source mass spectrometry today has wider applications than just for the analysis of uranium compounds. Fields in which this technique is actively used include biomedical [42], geological [43] and horticultural science [44], as well as agricultural and environmental sciences [45]. It continues to play a prominent role in the contemporary nuclear technology laboratory [46, 47].



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# LINEAR REGRESSION FORMULAE [29]

•

y = mx + c

$$s_{xy} = \frac{\binom{n}{j=1} (\frac{x}{j}) - \binom{n}{j=1} (\frac{x}{j}) (\frac{x}{j})}{\binom{n}{j=1} (\frac{x}{j})^{2}} - \frac{\binom{n}{j=1} (\frac{x}{j})^{2}}{\binom{n}{j=1} (\frac{x}{j})^{2}}$$

$$s_{yy} = \frac{\binom{n}{(z - y)}}{\binom{n}{j=1} (\frac{y}{j})} - \frac{\frac{j=1}{j-1} (\frac{x}{j})}{\binom{n}{n}}$$

$$s_{xx} = \binom{n}{(z - y)} - \frac{\binom{n}{(z - y)^{2}}}{\binom{n}{n}}$$

$$s_{xy} = \binom{n}{(z - y)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}}$$

$$s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}}$$

$$s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}}$$

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$$s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}}$$

$$s_{xy} = \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}}$$



### APPENDIX B

TABLE OF ATOMIC AND MOLECULAR LINES FOR SPARK SOURCE MASS SPECTROMETRY OF

COMPLEX SAMPLE-GRAPHITE MIXES

R. A. BURDO AND G. H. MORRISON Department of Chemistry Cornell University, Ithaca, N.Y.

# ABSTRACT

A detailed table of atomic and molecular mass spectral lines has been prepared to aid in the interpretation of interferences and assignment of spectral lines in complex spectra arising from the spark source analysis of natural insulating powders blended with graphite to sustain the RF spark. The compilation consisting of 3000 listings is particularly useful for multielement trace analysis of geological and biological solids. Included are carbides, oxides, polymers, multiply-charged ions, and other molecular species of several or more major and minor elements as well as a large number of trace elements.



#### INTRODUCTION

Spark source mass spectrometry is a useful technique for multielemental trace analysis Spark source mass spectrometry is a useful technique for multielemental trace analysis of geological and biological solids. Such insulating materials are usually powdered and mixed with graphite to produce strong and conducting electrodes. However, the sparking of complex graphite mixes yields complicated spectra containing the carbides, oxides, polymers, multiply-charged ions, and other molecular species of several or more major and minor ele-ments as well as a large number of trace elements. The primary purpose of the following table is to aid in the interpretation of inter-ferences and assignment of spectral lines in complex spectra arising from the spark source analysis of natural insulating nowders in a graphite matrix. In a secondary sense, the table

analysis of natural insulating powders in a graphite matrix. In a secondary sense, the table may also be applied to other sample types or even to other fields of mass spectrometry such

may also be applied to other sample types or even to other fields of mass spectrometry such as ion probe analysis where molecular species become relatively more important. There are indeed other excellent mass tables available for general use, but they are limited for application to the specific problem as stated. More explicitly, the table of Owens and Sherman (1) is arranged by individual element with comprehensive coverage for certain kinds of species excluding carbides, oxides, and many molecular species. The table of Guthrie and Heath (2), albeit arranged by mass, excludes carbides, most oxides, charge-exchange species, and other species of interest. The aim herein is to include those species omitted in preceding tables but of possible interest in complex graphite systems, to arrange the table in order of ascending mass values, to include the relative abundance of each species listed, to indicate the theoretical resolution required to sepa-rate a listed species from a line of analytical value, and finally to be concise in format but comprehensive in scope. The latter requirement, has resulted in approximately 3000 listings each containing four data words and producing a text of approximately 12,000 words on a physical format of only thirteen pages.

Istings each containing four data words and producing a text of approximately 12,000 word on a physical format of only thirteen pages. The entire table was manually calculated, compiled, and typed and is therefore not meant as a manual of supercritical mass and abundance data, but merely as an interpretive and useful guide. The user must assume any liability of any kind incurred in the employ-ment of this table. Further, no claim is made as to the existence or nonexistence of any species listed herein, nor to that of any species accidentally or purposely omitted.

#### EXPLANATION OF TABLE

Each listing consists of a row of four words starting with the name of the species and followed by the mass, abundance, and resolutional requirement of the named species respectively.

### I. NOMENCLATURE OF SPECIES

The usual chemical notation is used to identify the elemental constuents of the species. A leading superscript refers to the nominal mass of the species and a trailing superscript refers to the positive charge of the species. The plus signs of the charge superscripts are omitted since all species are ions of positive charge. The charge superscripts omitted since all species are ions of positive charge. The charge superscript is omitted entirely for species having a single positive charge. A special two-digit charge superscript indicates a charge-exchange species where the first digit is the initial charge of the species before a charge-reducing collision and the second digit gives the resulting or final charge after collision. The general nomenclature and the special meaning of the nominal mass superscript are best illustrated by example.

#### Elementally Homogeneous Species I.A.

- 12C a singly-charged ion of carbon 12 a triply-charged ion of carbon 12 (a) :
- 12Č3 (ъ)

(c)	12 C2	:	a homo-isotopic dimer of carbon and the only combination of carbon
	_		isotopes having a nominal mass of 24. (Absence of superscript = +1).
(d)	²⁵ C2	:	a hetero-isotopic dimer of carbon having a +2 positive charge and
			containing all combinations of carbon isotopes having a nominal mass
			of 25. (Only one combination in this case).

- of 25. (Only one combination in this case). a trimer of silicon containing all combinations of silicon isotopes giving a nominal mass of 86, ie,  8  Si₃ = ( 28 Si₂ +  30 Si) + ( 28 Si +  29 Si₂), where the parentheses indicate the combinations having the same nominal eeSis (e) • mass.
- 12C35 : (f)a charge-exchange species of carbon 12 where the initial charge is +3 and the final charge is +2.

I.B. Elementally Heterogeneous Species

²⁸SiC : (a)

- ⁴¹SiC : (b)
- a monocarbide of silicon 28 and the only significant* combination of carbon and silicon isotopes having a nominal mass of 40. all the combinations** of silicon and carbon isotopes having a nominal mass of 41, ie,  $\binom{29}{51} + \frac{12}{2}$  and  $\binom{29}{51} + \frac{13}{2}$ . the only significant* combination of silicon and carbon isotopes having a nominal mass of 108, ie, there is only one silicon trimer of nominal mass 84 and only one carbon dimer of nominal mass 24. all the combinations** of silicon trimer and carbon dimer having a nominal mass of 109, ie,  $\binom{85}{513} + \frac{12}{2}C_2$  and  $\binom{28}{513} + \frac{25}{2}C_2$ . ²⁸Si3C2: (c)
- ¹⁰⁹S1₃C₂: (d)

The word 'significant' means that if a single combination of isotopes is cited, then it is either the only possible combination or a combination which accounts for 99.0% or more of

- of the abundance of all possible combinations. The phrase 'all the combinations' means that the combinations included are either the only possible ones or that they cumulatively account for 99.0% or more of the abundance of all combinations.
  - The starred definitions have meaning in relation to the mass and abundance data following a cited species (see parts II and III).
- II. MASS (second word)

The masses of singly-charged species are taken from the table of Guthrie and Heath (2) and are rounded to five decimal places. Some elements are known to less than five places while others are only approximated vas producted by a (/) following the last digit in the mass value. Polymeric and heterogeneous species have masses equal to the sum of



the individual contributing masses. Charge-exchange masses are obtained by multiplying the singly-charged mass by a factor  $(m/n^2)$  where (m) is the initial and (n) the final charge of the ion. Multiply-charged ions have masses equal to the singly-charged mass divided by the

the ion. Multiply-charged ions have masses equal to the singly-charged mass divided by the integral number of positive charges. For species containing more than one combination of isotopes (eg., I.A.e, I.E.b, and I.B.d), the mass is that of the combination of isotopes which is the most abundant, as opposed to masses of single combinations which are unequivocal. The grouping of combinations of isotopes of the same elements to produce a species of the same chemical formula was performed to reduce the number of listings and is based on the fact that the combinations in a group are not resolvable with present commercial apparatus which have resolutions of 10,000 maximum and 5,000 or less practical.

#### <u>ABUNDANCE</u> (third word)

Isotopic abundances are based on Guthrie and Heath (2). Abundances apply only to species of the same kind (same chemical formula, same charge, but possibly different exact masses). For example, ²⁹SiC at mass 39.97693 comprises 31.19% of the total amount of silicon carbide formed from all combinations of silicon and carbon isotopes, ⁴¹SiC at mass 40.97649 accounts for 5.67%, etc. The abundance of ²⁹SiC is that of a single combination while that of ⁴¹SiC is the sum of the abundances of more than one combination. The abundances of molecular species which are elementally homogeneous are calculated using the binomial expansion according to Hill (3) or the equivalent probability formula given by Owens and Sherman (1) for polyatomic clusters:

 $RA = (A^{a}B^{b}C^{c}...N^{n})(M!)/(a!b!c!..n!)$ 

1.

where RA is the relative abundance of a given polyatomic cluster (a specified combination of isotopes) containing M total atoms of an element which has isotopes A', B', C',...N' with isotopic abundances A, B, C, ...N respectively and where the number of atoms of each isotope contained in the cluster is a, b, c, ...n respectively. The summation (a+b+c+...n) is equal to M. This formula is applied to each specific combination of isotopes until all possible combinations are exhausted.

For clusters containing different elements, the above formula is applied to each ele-ment individually and the abundance of the heterogeneous cluster is taken as the product of the indivual RA's for each element in the cluster.

The tabled abundances are given in percent. The appearance of an (E) in the tabled abundance indicates a negative exponential form so that 1.2E3, for example, means 00.0012%. For species containing more than one combination (seeI), the abundance is the sum of all combinations considered, whereas the mass is that of the most abundant combination.

#### IV. RESOLUTIONAL REQUIREMENT (fourth word)

Resolution is defined as  $R = M_0/4M$ .  $M_0$  is indicated in the table by a series of five dashes for a line of interest at each nominal mass unit and at some half-mass units where appropriate. A negative value for R indicates that the listed species occurs at a lower mass than  $M_0$ , the latter being indicated by the next dashed line. A positive value of R indicates a higher mass than  $M_0$  which is defined as the first previous dashed line. The appearance of an (E) in the resolution value indicates a positive exponential form so that 15E3, for example, means a resolution of 15,000. There are no exponential forms for resolutions less than 10,000 (= 10E3).

### V. SCOPE

The number and kinds of species included for each element depends on its definition as a major, minor, or trace constituent in geological and biological samples. Carbon, being the matrix considered, is defined as a major element. Other defined majors are oxygen, sodium, silicon, phosphorous, sulfur, potassium, calcium, titanium, and iron. Minors are given as chromium, nickel, zinc, strontium, zirconium, and barium. Most other elements are defined as trace.

defined as trace. For trace elements the species considered are: singly-and-multiply charged ions up to +3, polymerization up to the dimer only, mono-and-dicartides, and mono-and-di-oxides. For minor elements the species are: singly-and-multiply charged ions up to +4, polymer-ization up to the trimer, formation of cxide up to the trioxide and cartide to the tricartide, and charge-exchange species with initial charges of +4 or less. Major elements have more extensive coverage: singly-and-multiply charged ion up to +6, polymerization up to four atoms, formation of tetra-oxide and tetra-cartide, charge-exchange species with initial charge of 7 or less, and some complex species having two atoms of the major species and one to three atoms or carbon or oxygen. Polymer formers such as carbon, aluminum, and silicon are considered to form even more complex species and some combinations of these elements with other major elements are included. Appropriate higher degrees of polymerization and carbide and oxide formation are listed for these three elements. Only the lower-charged species of rare gases are considered.

polymerization and carbide and oxide formation are fisted for these three elements. Only the lower-charged species of rare gases are considered. Hydrocarbons up to mass 100 are included. The first hydrides(MH) of all elements from lithium to molybdenum plus barium, lan-thanum, and cerium are also listed. The mass range covered is from 1 to 270 with reductions in the number of entries from mass 210 to 270 where only two elements, thorium and uranium, are of interest.

#### REFERNCES

1. E.B. Owens and A.M. Sherman, Mass Spectrographic Lines of the Elements, MIT Tech. E.B. Owens and A.M. Sherman, Mass Spectrographic Lines of the Elements, Mill Tech. Rep. No. 265, 1962
 J.W. Guthrie and R.L. Heath, Table of Atomic Masses, Sandia Corporation Monograph SCR-245, 16th Ed., 1961
 H.C. Hill, Introduction to Mass Spectrometry, Heydon and Son, London, 1966

1 _H 3402	1.00782	99.985		3656 3616	5.99451	00.014	- 292	43Ca5	8.59176	00.146	
1206	2.00000	98,893	- 143	³⁰ S1 ⁵	5.99459	00.337	- 293 - 295	26 _{Mg} 3	8.65675	83.76 11.17	-2107
⁴ He ²	2.00130	99.999	- 157	24 Mg4 25 Mg 65	5.99626	78.70	- 319	35C14	8.74221	75.529	
°Li ^j 2D	2.00500	07.42	- 221	1803	5.99972	00.204	- 391	44Ca5	8.79110	02.06	+ 026
1 H2	2.01565	99.970	+1300	12 C2 87 4	6.00000	98.893	- 398	53 Cr ⁶	8.82344	09.55	
¹³ C ⁶	2.16723	01.107		515	6.01512 6.10/76	100.000		54~ 6	8.88606	99.759	107
120'0 7143	2.33328	99.893		14N43	6,22358	99.63 ⁴	- 273	54Fe ⁶	8.98993	02.30	- 405
13C76	2.52837	01.107		²⁶ Mg ⁶⁵ 25Mg ⁴	6.23582	11.17	- 587	45 Sc ⁵	8.99118	100.000	- 429
1909 1909	2.60067	01.107		19 F3	6.33280	100.000		36A4	8.99189	00.337	- 441 - 444
14N5	2.80051	99.634		3255 27 1 85	6.39441	95.0	303	27A13	8.99384	100.000	- 491
1708 12085	2.83319	00.037		зэКе	6.49395	93.10	- 3820	15 ^C 35	9.00000	98.893	- 739
1806	2.99986	00.204	- 186	26Mg4 1302	6.49565	11.17		₽Be	9.01219	100.000	
12 ⁷⁴	3.00000	98.893	- 187	33 <u>5</u> 5	6.59429	00.76	+1011	29 S154 55Mp 6	9.05515	04.70	+ 210
°Be ³ °L†2	3.00407 ]	100.000 07.42	- 252	40 A 6 40 Ca 6	6.66040	99.6 96.97	-22E4	4 ⁶ T1 ⁵	9.19053	08.00	
3 He	3.01603	01.4E4		40Ke	6.66067	00.012	+27E3	46Ca ⁵ 37 C1 4	9.19074	00.003	+44E3
SH2	3.01605	00.030	+15E4 + 512	²⁰ Ne ³ 12053	6.66415	90.92	+1790	5°Fe ⁶	9.32249	91.66	-2961
16078	3,11051	99.759		28 S1 65	6.71446	92.21	+100+	28513 39865	9.32564	92.21	- 604
13 Ce5	3.12080	ói.ió7		27A14 34c5	6.74538 6.79358	100.000		30 S154	9.36680	03.09	
13C4	3.19898 3.25084	99.759		41K6	6.82697	06.88		⁴⁷ T1 ⁵ 17053	9.39075 9.44396	07.29	
17076	3.30531	00.037		²⁹ S1 ⁶⁵	6.95436	04.70		57 Fe 6	9.48923	02.19	- 953
1705	3.33765	19.61 00.037		⁴² Ca ⁵ 35C15	6.99310 6.99377	00.64 75.529	- 306	38Å4	9.49068	00.063	-1115
18076	3.49976	00.204	- 437	28S14	6.99423	92.21	- 322	19 _F ≥ 48m-∤5	9.49920	100.000	
- * N * 7 L i ²	3.50800	99.634	- 485 	²¹ Ne ³ 14 _N 2	6.99795 7.00154	00.257 99.638	- 389 - 485	48 Ca 5	9.59051	00.185	+10E3
1805	3.59983	00.204		7Li	7.01600	92.58		**Ca **	9,59102	02.06	+6706
12 054	3.66977	80.39 98.893		°LiH	7.02282	07.42	+1029	58 Fe8	9.65555	00.33 69.18	-2945
15 _N 4	3.75003	00.366		43 _{Ca} 6	7.10885	99.759 00.146		29 S13	9.65883	04.70	
16065	3.83163 J 3.83878	99.759		23Na54	7.18431	100.000		39 _K 4	9.67930	93.10	+ 472
24 _{Mg} 6	3.99751	78.70	- 786	365105 3655	7.19370	03.09	+ 765	13032	9.75252	01.107	+ 840
1604	3.99873	99.759	-1034	36Å5	7.19351	00.337	+ 781	⁴⁹ Ti ⁵ 597.8	9.78957	05.51	
4He	4.00000	99.999	-1540	29 Si ⁴	7.22409	04.70		41Kes	9.83084	93.10	+1138
² H ₂	4.02820	02.0E4	+ 156	44 Ca 8	7.32592	02.06		^{so} Ni ^s	9.98846	26.23	- 409
13054 17085	4.06355	01.107		37 C15	7.39318	24.471	+T0T4	50 T15	9.98896	05.34	- 410
25 _{Mg} 6	4.07979 4.16431	10.13		31p85 45co8	7.43370	100.000	-0100	50V5	9.98943	00.24	- 426
170 ⁴ 18065	4.24978	00.037		³⁰ Si ⁴	7.49344	03.09		20 _{Ne} 2	9.99127	90.92	- 599
2 6 _{Mg} 6	4.33043	11.17	- 829	24Mg ⁵⁴ 15M ²	7.49533	78.70	+3965 ±1134	18053 105	9.99953	00.204	- 747
1303 14154	4.33445	01.107		17043	7.55170	00.037		¹⁰ Be	10.01294	19.61	+17E3
27Å] 6	4.49692 ]	100.000	-1570	32565 3104	7.67330	95.0		⁹ BeH	10.02001	99.985	+1416
1804 9265	4.49979	00.204	<b></b> <b>-</b> 713	39K5	7.79274	93.10		^{e1} Ni ^e 51,75	10.15518	01.19	
2 ³ Na ⁵	4.59796	100.000	1 1 22	2⊃Mg э∓ 47 m 1 8	7.80807	10.13	+ 508 + 240	23Na43	10.21767	100.000	
^{c o} Si ⁶ 14 N ³	4.66282 4.66769	92.21 99.634	- 960 	48 _{T1} 6	7.99132	73.98	-1303	41K4 82 N4 8	10.24046	06.88	-3006
19 _F 4	4.74960 1	100.000		48 Ca 6	7.99209	00.185	-1489	31P3	10.32459	100.00	
29 S16	4.79717	78,70		40 Ca 5	7.99240	99.6 96.97	-1619	63 Cu 6	10.38810	83.76	-7547
30 _{S1} 6	4.99563	03.09		40K5	7.99280	00,012	-1717	42 Ca 4	10.48966	00.64	
25 Mg 5	4.99717	10.13	+3240	24 _{Mg} 3	7.99502	92.0 78.70	-3264	²¹ Ne ² 14 _N 32	10,49692	00.257	+1445 + 829
15N3	4.99841 5.00004	99•759 00.366	+1797 +1130	180 ² 18043	7.99746	99.759		44 Ca. 65	10.54932	02.06	,
10 ^{B2}	5.00647	19.61	+ 461	7LiH	8.02382	92.57	+ 303	34g54	10.58813	09.55	
31p8	5.16229	100.000		2 6 _{Mg} 54	8.11956	11.17		64N18	10.65466	01.08	-3947
170 ⁵⁴	5.31223	00.037	- 275	34 <u>5</u> 85	8.15229	04.22	-1434	32 _S 3	10.65486	48.89 95.0	-4262
3256 1603	5.32868	95.0	-1801	41K2	8.19237	06.88		24 Mg 43	10.66002	78.70	+1702
12 643	5.33333	98.893	+3149	3354 50m,8	8.24287	00.76	-1847	54Cr5	10.78777	02.38	- 224 -72E3
3356 1152	5.49524	00.76	- 585	50 Cr ⁶	8.32434	04.31	-1950	54Fe ⁵	10.78792	05.82	
28 S15	5.59539	92.21	•	50 ₀ 8 25 _{М~} 3	8.32453	00.24	-2040	55 Mr 5	10.08741	100 00	- 507
18054 3456	5.62474 5.66131	00.204	-1120	42 Ca 5	8.39173	00.64	+ 132	eezne	10.98768	27.81	- 509
17 03	5.66638	00.037		27A154 19F43	8.43173	100.00	+ 703	44Ca4 33c3	10.98887	02.06	- 539
^{- 3} Na ⁴ 24 _{Mo} 85	5.74745 1 5.75641	78.70	+ 642	51 _V 8	8.49066	99.76	- 954	²² Ne ²	10.99569	08.82	- 808
13 c 43	5.77926	01.107	+ 181	3454	8.49197	ó4.22	-1118	В 10 вн	11.02076	80.39 19.61	+ 962
²°Si⁵	5.79530	04.70		170 ²	8.49957	00.037		40T1 05	11.02863	08.00	+ 570

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25 ₅₂ 43	11.10482	10.13		⁶⁸ Zn ⁵	13.53497	18.57		58Fe54	17.47967	91.66	-3680
37 Zn 3	11.15452	04.11	- 344	^{4 1} K ³	13.65394	03.38		⁷ ^o Zn ⁴	17.48134	00.62	-5677
56 <u>-e</u> 5	11.18699	51.66		57 Fe ⁶⁵	13.66450	02.19	+1293	35012	17.48442	75.529	
45 Sc 4	11.23898	100.00		⁵⁵ Mn ⁴	13.73451	100.00		53Cr3	17.64688	09.55	
47 Ti 65	11.26842	07.29		⁴⁴ Ca ⁵⁴	13.73609	02.06	+8693	40 Ca 43	17.76115	96.97	
^{se} Zn ^s	11.32081	18.57	-6256	31P43	13.76612	100.00	+ 434	3253	17.76226	95.0	+1923
3453	11.52262	04.22		⁶⁹ Ga ⁵	13.78514	60.4	+ 271	∍′Ee⊐"	17.79251	02.19	+ 510
57 - 5	11.58703	02.19		58 Fe ⁶⁵	13.90400	00.33		54 Cr ³	17,97962	02.38	- 921
െപ്പ്പ	11.48762	60.4	-1581	560.4	17 08274	01 00	ROL	54 - 3	17 97987	05.32	- 933
4 ôr i 4	11.48816	08.00	-1708	707.5	17.90074	91.55	- 724	3 egž	17.98354	00.014	-1152
4 8 Ca 4	11.48842	00.003	-1777	70755	17.35460	20.52	- / 55	3682	17.98377	00.337	-1170
23 _{Na} 2	11.49489	100.000		43 003	13 08601		- //0	241032	17,98878	78.70	-1734
48 7 4 65	11.50751	73.98	+ 911	28012	17 098/17	00.64	- 021	180	17,99916	00.204	
26 43		, , , , , , , , , , , , , , , , , , , ,		14N	10.90047	92.21	- 959	12 02	18.00000	96.71	+21E3
Mg	11.54782	11.17		140	14.0000	99.624	.2017	ษะถ้	18.01056	99.747	+1579
Seres	11.58666	00.33	-28E3	1364	14.00524	LT.UI	+0252	SLIC	18.01500	07.34	+1136
³³ Ni ³	11.58707	69.18		12 01	14.01115		+1/26	9 8eo	18.02439	100.00	+713
Gee	11.65400	20.52	-5112	7 T CH2	14.01565	98.863	+1113	14 _{NH}	18.03437	99.584	+ 511
Zno	11,65422	00.62	-5658	Ll2	14.05200	85+71	+ 484		-0 -0 -0	00 77	
35013	11.65628	75.529		32 ₅ 43	14.20981	95.0	- 593	11:43	15.10415		
7′T17	11.73794	07.29		⁵⁷ Fe ⁴	14.23385	02.19		41K-3	18.20526	106.00	
2°Co2	11.78664	100.00		19 _F 35	14.24880	100.00	+ 952	37 m	18.91269		
('Ga°	11.32080	39.6		46T154	14.36020	08.00		3, C1-	18.45295	24.4/1	- 087
60 N 1 5	11.98615	26.23	- 866	⁴³ Ca ³	14.31959	00.146		3 / C5	12.20100	2.25	<b>-</b> >07
50 m 1 35	11.98675	05 45	- 906	2 6 _{Mg} 5 3	14.43477	11.17		58 _{Fe} 3	18.64498	91.66	
7225	11 08:03	27 43	- 018	59-4			0010	25 _{Mg} 32	18.73938	10.13	
49714	11 09200	73.08	- 910	50 Fe	14.40222	00.22	-2945	з4 ₅ 5э	18.87103	04.22	
50 7, 35	11 08705	04 31	- 027	29 212	14.40,004	69.10	- 2226	=7 = 3	-0.07017	00.10	053
48754	11 08813	00 186	-1011	44 2 3	14.40025	04.70		o re	18.9/04/	02.19	- 900
3623	11 08003		-100#	••℃a 47	14.65103	02.06		JGAE	10.90101		-1773
3613	11 08012	00.014	-1110	* 1712	14.67242	07.29	+ イエク	192	18.99840	100.00	
271143	11.90910	100.550	-1110	Sa Co.	14.73330	100.00	2.47	38 C S	19.00336	00.036	+3830
2411-2	11.99100	100.00	-1462	NI NI	14.98269	26.23	- 861	13OH	19.00698	00.204	+2214
1 4 4 3 2	11.99252	(3.70	-1604	*°T12*	14.98373	73.98	- 916	H ₂ O	19.01477	00.037	+1161
120	11.99619	99.759	-2150	#PSc2	14.98531	100.00	-1014	¹⁹ LiC	19.01600	91.64	+1079
	12.00000	90.092		Si	14.98688	03.09	-1134	HaO	19.01837	99.714	+ 951
-BH	12.01713	30.33	+ 701	2/A193	14.98974	100.00	-1446				- 0 <b></b>
⁵ Li ₂	12.03000	00.551	+ 400	TPN	15.00011	00.366		seres	19.31110	00.33	-2050
73 ~ 6				12 CH3	15.02347	98.523	+ 642	- NT-	19.31178	69.18	
Geo	12.15389	07.78	- 547	14NH	15.01090	99.509	+1390	39K5	19.48186	93.10	
SU KUT	12.17616	93.10		34043	15 09683	04.22		2 Mg32	19.48695	11.17	+3827
11	12.18622	01.13	+1510	51N+4	15 23277	01 13		44Ca43	19.53577	02.06	+ 361
7426	12.23697	05.51	-01	4 5 - 3	15 31754		_L3F3	50 m 3	10 07602	26.23	-1288
<u>f</u> geg	T5°250T/	26•2 <u>4</u>	-6845	467.3	15 31700	00.003		40 12	10 08110		-1777
'Se'	12.52042	00.87	-7950	62 N - 4	15 18200			40 00 2	10 08120	99.00	-1793
CT CT	15.25181	24.471		3152	15 18688	100.00	- ) 2 ) )	40 <del>,,</del> 2	10 28200		1015
SzN15	12.38567	03.66		35 - 33	19.40000	100.00	1 (* 17 7	20 10	10.00200		-1910
28Si43	12.43418	92.21		28 21 53	15.541/1	(5.549	-1262	- NG	19.99244	90,92	11/151
52 Cr 65	12.46752	33.76	- 459	507.54	15.54274	92.21			20.00022	00 200	
50Ti4	12.48620	05.45	-1859	5011154	15.50775	05.24		120	20.01400	00.204	- + 094
50Cr4	12.48651	04.31	-1949	o Croi	15.60814	04. <u>91</u>	+40セン	1002	20.02565	UD.35	+ 590
50 _V 4	12.48679	00.24	-2038	³³ Cu [*]	15.73240	69.09		27 1 32	20.23616	100.00	
⁷⁵ As ³	12.49695	100.00	-2093	TITI	15.65059	01.21		e1ਜ਼ੋੜੇ3	20.31036	01.19	
4° Ca54	12.48831	96.97	-2710	64N14	15.98199	01.08	-1238	4 3 4 3	20.42330		
²⁵ Mg ²	12.49292	10.13		64Zn4	15.93229	48,35	-1267	4122	20.48002	06.33	
63 7.,5	10 53500	so co		49743	15.98265	73.93	-1305	-32 <del>. 1</del> 3	20.84273	03.66	
3813	12 000094 10 85/0/	00.083		48 Ca 3	15.98413	00.135	-1401	47 - 43	20.86745	07.29	
53 ~ , 65	10 00578		- 448	3252	15.98604	95.0	-1303		20.001.7	0,020	
51.4	12 73500			1 eO	15,09491	- 99. T59		<u> </u>	20.97653	69.09	-1212
17 632	10 74035	00 037	+ 053	15NH	16.00793	00.366	+1229	34574	20.97831	00.56	-1351
23 1 53	12 77200	100.00	- 231	14NH2	16.01872	99.955	+ 671	- Tacar	20.37931	00.54	-1444
64 11 - 5	10 79650	100.00	-5353	12 CH4	16.03130	<u>98.341</u>	+ 400	205102	20.98270	92.21	-1383
6475	12.73583	42.80	// 	29 ~ . 5 7	10.00005			~_Se	20.99385	00.257	
41254	12,80057	06.88	+ 867		16.09805	04.70	2072	ĭ∃eC	21.01219	98.89	+1144
29 . 43	12.87843	04.70		- Cr - 4	10.20141		- 20122	2 - E2	51.05552	¢1.52	+ 739
540,65	10 04633	02.38	- 224	Cu- 49m+3	TP.52TAD	20.91		95 _{2b} 4	21.22801	72.15	
54 - 65	12 24551	03 32	- 225		16.01096	02.51	7007	54 11 3	21.30932	01.03	-5553
		0,		33 <i>c</i> 2	10.40171	27.01		34 Zn3	21.30971	E3 89	
>2Cr4	12.93513	83.76	- 713	532 54	16.40575	00./5		48 43	21.31020	<u>ร</u> รุ วล์	+4353
55 Cu ⁵	12,98556	30.91	- 731	50013	10.54545	V7•22		36~ 1			• •
зөКз	12.98790	93.10	- 841	50212	16.64026	05.24	1057		21.47754	07.86	-11E3
^{2 6} Vg ²	12.99130	11.17	-1078	Cr ⁻	10.54050		++02フ よう1 マネ	- Caf	21.47939	-00.146	
13C	13.00336	01.107		30 0+53	16.64905	00.24	キビエニン	39.0 <b>U</b> 3	21.64259	20.91	
12 CH	13.00782	98,378	+2916	$-51^{-4}$	10.05209		4-4 J.4	87 ~ 4	21.64650	75.10	+2235
¹³ Li ₂	13.03112	13.74	+ 468	~'Zn*	TP.()T(Q	04.11		Sr	21.72725	09.36	-27 E4
- 55M-65	13 18613	100 00	- 265		10.000000	02.00			=1.72733	2(.35	
867 <u>~</u> 5	13 18501	27 81	- 265	-7₹e9 <b>*</b>	15.35613	05.32	キィラニク	- SI32	21.73237	04.70	+4311
5304	13 03610	00 EE		⁶⁸ Zn ⁴	16,98122	18.57	- 949	⁶⁶ 7n ³	21.97575	27-81	-0157
4013	13 30080	22.22	-22 FL	sı _V 3	16,98133	99.75	- 955	39574	21.97650	82.56	-1847
40 0 3	13 30080	77.50	- a a s = = =	34 _S 2	16.98393	ó4.22	-1118	447,22	21.97775	02.06	
- ∪a 40-⁄-3	13 30133	20.97	10823	170	16,99913	00.037		22110	21,99138	08.82	+1612
30 C + 43	17.76122	00.012	+202J 1753	1 SOH	17,00274	99.747	+4709	[€] 1.10	22.00001	07.40	+ 683
244-53	17.30500	78 70	+3202	14NH2	17.02655	99.593	+ 320	1020	22.01294	19.39	+ 625
Mig	12.2505	10.10	TJEVE			100 000		118	22.01861	64.63	+ 574
⁶⁷ Zn ⁵	13.38543	04.11		^{&gt;} Mn ^{&gt;}	17.16814	T00.000		=			
5 6 ₇ e 65	13.42439	91.66		31p53	17.20765	100.000		>0T143	22.19768	05.34	- 773
54(Jr4	13.48472	02.38	-2230	23 Na32	17.24234	100.000		SC Cr43	22.19824	04.31	- 738
547e4	13.48490	05.82	-2298	52Cr ³	17.31350	83.75		Ca_53	22.20143	_96.97	- 339
27 A12	13.49077	100.00		39K43	17.31720	93.10	+4579	8974	22.22643	100.00	
18032	13.49937	00.204	+1569	-				°′Zn ³	22.30905	04.11	



90Zr4	22.47608	51.48	-12E3	⁵⁰ Ti ⁵³ 500753	27.74710	05.34	-39E3	³⁸ Zn ²	32.96302	27.81	-3907
45 Sc ² 30 St 32	22.47796	100.00		567 <u>6</u> 2	27 267/17	04.51 01.88		99 Ru3	32.96868	12.72	-6812 -12E3
68 Zn3	22.64162	18.57	79524	63 Cu43	27.96871	91.00 69.09	-3404	335 13284	32.97146	00.76	
⁹¹ Zr ⁴ 41 _K 53	22.72633	11.22		845r3	27.97050	56.90	-4351	32 SH	32.97989	95.0	+3911
з9 _{Са} з	22,97524	60.4	-1581	2851	27.97693	92.21		³³⁰ 2	32.99405	00.075	+1460
92Zr4	22.97617	17.11	-1689	²⁷ AlH ¹² CO	27.98936	99.985	+2251	100 Ru ³ 100 Mo ³	33.302/	12.62	-20E4
*°T1 ² 45Ca ²	22.97632	08.00	-1708	14N2	28,00615	90.66 99.269	+1556 + 957	87 Zn2	33.46357	04.11	
23 Na	22.98978	100.00		¹² C ₂ H ₄	28.03130	97.75	+ 524	¹³ *Ba* 101 _{Bu} 3	33.47606	02.42	+2679
23BC 7L10	23.00931	79.72	+1177	⁹⁵ Rb ³ ⁵⁴ 7n ⁴³	28.30401	72.15		135 Ba 4	33.72639	06.59	
52Cr43	23.08467	83.76	12009	57 Fe ²	28.46770	02.19		⁶⁸ Zn ²	33.96243	18.57	-6256
93Nb4	23.22642	100.00		esgr3	28.63645	09.86		102 Ru3	33.96786 33.96791	04.22 31.61	+68E4
⁷⁰ Ge ³	23.30800	20.52	+5955	52 Cr 53	28.35584	83.76	+50E)	102 Pd3	33.96829	óo.96	+79E3
⁷⁰ Zn ³ 47m42	23.30845	00.62	+52E3	590u*5	28.35679	30.91	+30E3	33SH	33.97928	07.81	$+412^{\circ}$ +2974
94Zr4	23.47691	17.40	+23E3	58 Ni2	28.96666	00.33 69.18	-2948 -3289	³⁴ 0 ₂ 10PC	33.99408	00.407	+1295
53Cr43 7163	23.52918	09.55		⁸⁷ Sr ³	23.96966	07.02	-4242	DU2	34.01294	19.10	+ 10-
54 Cr 43	23.97283	02 38	-1064	29 S1	28.97649	04.70	-4312	103 Rh3	34.30152	100.00	
54 Fe ⁴³	23.97316	05.82	-2019	²⁸ SiH	28.98475	92.20	+3508	⁶⁹ Ga ² 4 6 ₇₁ 32	34.46286 34.46447	60.4 08.00	
′~Ge³ 48∏12	23.97386	27.43	-2145	12C170	28.99910	00.037	+1282	138 Ba4	34.47622	71.66	+2580
48 Ca2	23.97626	00.185	-2731	12 CHO 29N	29.00274	98.64	+1104	104Pd ³ 104 _{P1} 3	34.63443 34.63474	10.97 18.58	+11E4
°Zr⁼ 32 _S 32	23.97733	02.80 95.0	-3111	12 C2 H5	29.03912	97.74	+ 463	139 La 4	34.72651	99.911	
² ⁴ Mg	23.98504	78.70		зэкза	29.22278	93.10		⁷⁰ Ge ²	34.96200	20.52	-5105
²³ NaH ¹² Ca	23.99760	99.985	+1910 +1603	385r ³ 536553	29.30200	82.56		105 Pd3	34.96267 34.96827	22.23	-5650 -60E3
73 _{Ge} 3	24.30778	07.76		59 Co2	29.46659	100.00		35Cl	34.96885	75.529	
55 Mn 43	24.41691	100.00	-8690	89 Y3	29.63524	100.00		¹⁴⁰ Ce ⁴	34.97560 34.97632	88.48	+468]
**Ca>3 +9T12	24.41972	02.06		⁶⁰ N1 ² 54Cr ⁵³	29.96538	26.23	-3577	23NaC	34.98978	98.89	+1669
74 Ge3	24.64033	36.54		54Fe ⁵³	29.96645	05.82	-4100	3502	34.99829	99.75 1.4E4	+1188
567e43	24.64085	00.87 91.66	+47E3	$^{90}Zr^{3}$ $^{40}Ca^{32}$	29.96881	51.48 96.97	-5305 -16E3	35BC2	35.00931	79.05	+ 861
^{so} Ti ²	24.97239	05.34	-1858	30Si	29.97376	03.09		47 T1 ³² 108043	35.21382	07.29 27.33	
50Cr ² 50772	24.97302	04.31	-1949	²⁰ S1H ¹⁴ NO	29.98451 29.99799	04.70 39.39	+2841 +1237	10 8 Cd 3	35.30198	01.215	+35E3
⁷⁵ As ³	24.97390	100.00	-2038	120180	29.99916	00.202	+1180	⁷¹ Ga ² 142 _{Ce} 4	35.46241	39.6 11.07	+2377
25Mg	24.98584	10.13		15 N2	30.00000	94.57	+1133	107 Ag3	35.63495	51.35	
25 C2	25.00336	02.189	+2559 +1426	12CH2O	30.01056	99.63	+ 315	⁷² Ge ² 48m432	35.96080	27.43	-5718
⁹ BeŌ	25.00711	99.759	+1175	°L1C2 ¹² C2He	30.01500	97.73	+ 727	38 <u>5</u>	35.96709	00.014	
57⊐-43	25.00/02	91.100		91 _{Zr} 3	30.30177	11.22		зед 108 рдз	35.96755	00.337 26.71	+79E: +49E3
^{7 a} Se ³	25.30643	02.19	-38E3	81 _{N1} 2 551-53	30.46554	01.19		1H35C1	35.97568	75.52	+3750
⁷⁶ Ge ³ 51172	25.30710	07.76		69 Ga 4 3	30.63365	60.4	-25E3	23Na13C	35 <b>.</b> 90504	01.107	+1378
34532	25.47590	04.22	+6515	92Zr ³ 92Mo ³	30.63489	17.11 15.84	 12483	3 # C3	36.00000	96.71	+1097
51 _{C4} 4377;53	25.50502	5.4E4	+ 771 + 445	41K32	30.72137	06.88	14,47	109 _A -3	36 30154	48.65	+ ) <b>)</b> -
77 Se ³	25.64000	07.58		62 11 ²	30.96417	03.66	-7230	⁷³ Ge ²	36.46167	07.76	
58Fe43	25.74814	00.33		31p	30.96855	100.00	-5945	110 Cd 3 110 Pd 3	36.63443 36.63482	12.39 11.81	+94E
52Cr ² 78583	25.97026	83.76	-2107	30 SiH	30.98158	03.09	+3961	74762	36,96050	36.54	-6846
⁷⁸ Kr ³	25.97340	00.354	-2927	15CE	30.99840	98.893	+1457	74 Se ²	36.96127	60.87	-7981
^{с 5} Мд 25 Мдн	25.98259	11.17	+2347	1300	31.00251	00.002	+1077	1117da	36.96809	12.75	+17 E
12 CN	26.00307	98.54	+1269	³¹ L1C2	31.01600	90.70	+ 733	^{а а} зн 37 н С	36.97491	00.014	+5120
10 BO	26.00571	19.56	+1029	¹² CH ₃ O	31.01839	98.62 01.66	+ 694	773	37.00336	03.25	+ 987
12C2H2	26.01565	97.77	+ 786	94 _{M0} 3	31.30198	09.04	-55E3	12 Co H	37.00782	96.70	+ 882
⁴⁷ T1 ⁵³ 597-43	26.08431	07.29	- 760	94Zr ³	31.30255	17.40		112Cd ³	37.30102	24.07	
35C132	26.22664	75.529		ea Ca	31.50502	00.0013	3	50T132	37.45859	05.34	-17E
⁷⁹ Br ³ 53Cr ²	26.30613	50.537		57 Fe53	31.63078	02.19	-7849	50Cr ³² 7542	37.45954	04.31	-28E3
60 Ni 43	26.63590	26.23	-9123	64 M 4 2	31.06308	01.08	-3952	¹¹³ In ³	37.63477	04.28	
^{so} Se ³ so _K ,3	26.63882	49.82	+67E4	⁸⁴ Zn ²	31.96457	<u>48.89</u>	-4263	113Cd3 85Pb43	37.63482	12.26 72.15	+75E4
48T153	26.63775	73.98	-25E3	^{9 6} Мо ³ 9 6 _{В11} 3	31.96832 31.9696	16.53	-8526 -13£3	78 _{Se} 2	37.95964	09.02	-12E3
54Cr ²	26.96944	02.38	-2230	9 SZr ³	31.96977	02.30	-14E3	^{7 6} Ge ²	37.96065	07.76	-18E
STFe [∠] 81 _{Br} 3	26.96980 26.97214	05.82 49.463	-2870	зеS зірн	31.97207 31.98158	99.985	+3362	114Cd ³	27.96273 37.96785	28.86	+7415
27Ă1	26.98154	100.00		1802	31.98983	99.52	+1800	114 Sn ³ 1 r ³⁷ cn	37.9680	00.66	+720
- ~ MgH 12 (15 N	26.99041	11.11 00.362	+1453	12 _{CH4} 0	32.00176 32.02613	01.11 99.60	+1077 + 591	³⁸ MgC	37.98269	11.16	+1910
11B0	27.00422	80.20	+1190 +1084	58 _{Fe} 53	32.18517	00.33		²⁵ Mg ¹³ C 197_	37.98920	00.112	+1434
12 C2 Ha	27.00643	97.762	+ 643	97 MO3	32.30207	09.46		3873	38,00670	00.036	+ 863
⁸² Kr ³	27.30448	11.56	-26E3	130 Ba4	32.47656	00.101	+2562	$^{12}C_{2}$ ¹⁴ N	38.00307	97.43	+ 943
82 Se ³	27.30554	09.19		⁹⁸ Мо ³ 98 р., 3 (С)	<b>University</b>	of Pretor	1 <u>2</u> 2083	03 M2	JU-U1905	20.09	<i>⊤ (</i> ⊥(
⁸³ Kr ³	27.63802	11.55		74Ge43	32.85378	36.54	.2007				



115 Sn ³ 115 In ³ 77 Se ² 118 Sn ³ 118 Cd ³ 52 Cr ³² 78 Se ² 78 Kr ² 39 K 117 Sn ³ 27 ALC 23 NaO 26 Mg ¹³ C	38.30112 38.30120 38.45999 38.63406 38.63500 38.95530 38.95530 38.95810 38.96371 38.96371 38.96371 38.98154 38.988605 38.988605	00.35 95.530 14.55 07.530 07.55 03.55 03.62 97.68 97.68 90.12 90.28 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.12 90.1	-48E4  +41E3 -4678 -7777 -11E3  +9765 +2190 +1856 +1748	43 Ca 42 CaH 129 Xe ³ 31 PC 27 AlO 30 S112 C 25 Mg180 12 C2 19 F 11 BO ₂ C 2H ₃ H ₇ 130 Ba	42.95373 42.96645 42.96825 42.97376 42.97711 42.997911 42.99884 42.999913 43.005477 43.30117 43.30208	00.146 00.64 26.44 93.76 00.021 97.50 97.50 97.53 00.101	+5601 +42860 +2332 +1065 +1450 +1450 +1065 + 748 -4853	3 6 SC 144 Nd3 24 Mg23 144 Sm3 35 Cl13 C 30 St13 26 O3 24 MgC2 12 C4 145 Nd3 97 Mo2 37 C3	47.96709 47.967093 47.97055 47.972202 47.972202 47.972292 47.973200 47.973200 47.973200 47.973200 47.973200 47.938500 47.938500 48.0000 43.345311 48.50168	00.013 23.85 61.34 03.09 00.34 09.006 93.28 76.97 95.63 03.30 03.46 07.25	+2505 +2167 +2122 +1977 +1914 +1294 +1294 + 921
¹² C ₂ ¹⁵ N ⁷ LiO ₂ ¹³ C ₃ ¹² C ₃ H ₃ ³⁸ Sr ⁴³	39.00011 39.00581 39.01005 39.02347 39.06934	00.362 92.13 01.4E4 96.70 82.56	+1070 + 926 + 841 + 652	130 Te3 58 Fe32 87 Sr2 87 Rb2 131 Xe3 88 cm2	43.30232 43.44999 43.45450 43.45465 43.63503	34.48 00.33 07.02 27.85 21.18	+18E4 -9635  +29E4	49Ti 98M02 48TiH 37C1C	48.63756 48.69584 48.94787 48.95299 48.95577 48.95577	17.22 30.91 05.51 23.78 73.97 24 20	+ 834 +9560 +6196 +2715
¹¹⁸ Sn ³ ⁷⁹ Br ² ⁸⁹ Y ⁴³ ¹¹⁹ Sn ³ ⁵³ Cr ³² ⁹⁰ 7 x ⁴³	39.30068 39.45920 39.51365 39.63438 39.70549	24.03 50.537 100.00 08.58 09.55	7800	44Ca 43CaH 132Ba3 132Xe3 28S10 3222	43.95550 43.95550 43.966837 43.96837 43.96837 43.96835 43.97184	52.56 02.06 00.146 00.097 26.89 91.99	-1885 +3960 +3415 +3502 +2690	49 SO 49 Mg2 147 Sm3 98 Ru ² 49 MgC ₂ 49 O ₂	48.96540 48.97088 48.97150 48.9777 48.98584 48.98584	00.80 15.95 14.97 01.87 11.63	+2641 +2127 +2071 +1680 +1290
soSe2 soKr2 40A 40Ca 40K 120Sn ³ 120Te ³	39.95824 39.95824 39.95830 39.96239 39.96259 39.96250 39.96740 39.96740	49.82 02.27 99.60 96.97 00.012 320	-7320 -9187 -9315 -20E4  +28E3 +8308 +7175	52 SC 31 p13 C 26 Mg13 O CO2 C2 H4 O C3 H8 59 C0 32	43.97207 43.97711 43.98175 43.98983 44.02621 44.06260 44.19989	94.0 01.107 00.023 97.8 97.51 96.62 100.00	+2653 +2026 +1674 +1280 + 622 + 410	49 C4 12 C4 H 148 Sm ³ 148 Nd ³ 99 Ru ² 149 Sm ³	49.00336 49.00782 49.30481 49.30549 49.45303 49.63893	04.29 95.62 11.24 05.73 12.72 13.83	+ 382 + 316 +73E3
39 KH 29 S1C 24 MgO 27 Al 13 C 12 C2 O 12 C3 H4	39.97153           39.97693           39.97693           39.97996           39.98489           39.99491           40.03130	93.09 91.19 78.60 98.89 97.56 95.60	+4470 +2993 +2301 +1791 +1236 + 582	1330s ³ a9 y ² 134 Ba ³ 134 Xe ³ a0 Xi ³² 90 Zr ²	44.30171 44.45286 44.63475 44.63514 44.94808 44.95217	100.00 100.00 02.42 10.44 26.23 51.46	+1124 -5734 -1223	50 Ti 50 Cr 50 V 100 Ru ² 100 M0 ² 49 TiH 34 SO	49.94479 49.944605 49.94716 49.953 49.95326 49.955269 49.955269 49.955269	05.34 04.31 00.22 02.63 03.63 05.51	+40E3 +21E3 +6083 +5897 +4582 +2776
121503 54Cr32 54Fe2 31Br2 122Te3 122Sn3 52Kr2 32Sr43 52Kr2 41K	40.30124 40.45415 40.45471 40.45820 40.63449 40.634652 40.95832 40.95832 40.95833	57.25 02.38 05.82 49.46 04.72 17.11 11.56 09.88	-9965 -12E3 -21E4 -8032 -12E3	44 CaH 135 Ba3 29 SiO 45 SC 27 AlO \$5 CO2 12 C2 HsO 136 Ba3 136 Ce3	44.99675142 444.99675142 444.9967750 444.9969710 444.9969710 444.9969710 445.9997 445.9997 445.445 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.45 455.4545.45 455.45 455.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.4545.45 455.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45 455.4545.45	02.06 06.59 04.69 01.80 00.204 01.175 97.50 07.81 00.193	+6075 +3568 +2902 +2305 +1314 +1207 + 575 	50 Mg2 37 ClC 23 NaAl 130 Sm ³ 150 Nd ³ 50 MgC2 50 O ₃ 12 CF2 50 C4 12 C Ha	49.9672301 49.977301 49.977301 49.977301 49.9988880 49.9988880 49.9988880 49.9988880 49.9988880 50.0055	18.61 00.27 100.00 07.44 05.62 11.16 00.61 98.89 00.61	+2187 +2041 +1883 +1815 +1733 +1321 +1320 +9806 +806
123 Sb ³ 123 Te ³ 40 CaH 40 KH 41 SiC 23 Na ¹⁸	40.96806 40.9681 40.97041 40.97182 40.97649	42.75 00.37 96.96 00.012 05.67	+6575 +6533 +4774 +4100 +2792 +1508	136Xe ³ 91Zr ² 137Ba ³ 92Zr ² 43Ti	45.30240 45.45286 45.63519 45.95234 45.95234	08.87 11.22 11.32 17.11 03.00	+48E3	151 Eu3 101 Ru2 152 Sm3 152 Sd3	50.30651 50.453 50.63979 50.63981	47.32 17.07 26.72 00.20	F . CJ
12 C2 17 0 12 C2 HO 9 BeO2 12 C3 H5 55 Mp 32	40.99910 41.00274 41.0020 41.0391	00.037 97.55 99.52 96.66	+1099 +1001 +1020 + 530	4 5 C 4 9 2 Mo 2 4 5 S C H 3 4 S C 1 3 5 E a 3		03.7E3 15.84 99.935 04.17 71.66	+43625 +426360 +430625 +30625 +30655	102 542 102 542 50 774 50 774 50 774 50 774 102 542 50 774 102 542 50 774 102 542 50 774 102 542 50 774 102 542 50 774 102 542 102 544 102 544 100 544 1000 1000 10000000000000000000000000	50.45957 50.45957 50.455267 50.455267 50.45571	99.78 71.61 00.76 05.74 05.74 05.74	+6457 +6029 +5903 +5151 +2582
124Te3 124Sn3 124Sn3 124Xe3 33Kr2 125Te3 94Zr43	41.30104 41.30175 41.30204 41.45703 41.63487 41.73673	04.61 05.94 00.096 11.55 06.99 17.40	-58E3  +14E4	50 S10 135 Ce3 135 L18 25 S1 23 Na2 14 NO2 C2 H 60	45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.56800 45.568000 45.568000 45.568000 45.568000 45.5680000 45.56800000000000000000000000000000000000	03.08 00.25 00.089 00.138 100.00 99.15 97.49	+2365 +2863 +2863 +1956 +1706 +1741 + 515	³³ ClO ²⁴ MgAl ²⁸ SiNa ⁵¹ Mg2 ¹⁵³ Eu ³ ²⁷ AlC2 ¹⁹ FO2	50.96376 50.96651 50.96674 50.96674 50.9664 50.9735 50.9664 50.9662 50.9662 50.9662	- 70 - 70 - 20 - 20 - 20 - 20 - 20 - 20 - 20 - 2	+2576 +2254 +2241 +2034 +1726 +1358 +1152
537632 34Kr ² 84Sr ² 42Ca 128Te ³ 128Xe ³ 41mu	41.95120 41.95576 41.95663 41.95863 41.968363 41.968363	91.66 56.90 00.56 00.64 18.71	-5647 -15E3 -20E3 -4497 +4497	139 La ³ 93 Nb ² 140 Ce ³ 47 Ti 94 Zr ² 94 Vo ²	46.30201 46.45283 46.53509 46.95176 46.95582	99.911 100.000 33.48 07.29 17.40	+2323	13 CF2 51 C4 C4H3 154 Gd3 154 Sm3 103 5%2	51.00016 51.01005 51.02346 51.30698 51.30731	01.11 05.4E4 95.61 02.15 22.71	+ 207 + 771 + 641 -16E4
⁴² SiC ²⁶ Mg0 ²⁴ Mg ¹⁸ 0 ¹² C ₂ 180 ⁸⁴ C ⁷	41.96965 41.97649 41.97751 41.98420 41.99916 42.00000	06.00 03.11 11.11 00.16 97.56 92.48	+2766 +2222 +1641 +1035 +1014	4°TiH 31P0 35ClC 141Pr3 29Sii80	46.96045 46.96872 46.96885 46.96916 46.97565	09.04 08.00 99.76 74.69 100.00 00.01	+5403 +2763 +2763 +2747 +26981 +1961	208004 155043 89322 207 Fb4 5207	51.49361 51.6409 51.69428 51.74397 51.94051	23.6 14.73 60.4 22.6 83.76	+1245 + 967
12 BO2 12 C2H2O 12 C3H6 127 I3 85 Rb2 85 C2	42.00274 42.01056 42.04695 42.30155 42.45601 42.50168	19.52 97.54 96.64 100.00 72.15 07.25	+ 951 + 808 \ + 475	- NaC2 15NO2 - 3Cu ³² 142Nd ³ 142Ce ³ 95M0 ²	46.98978 46.98991 47.19720 47.30249 47.30310 47.45222	97.80 00.36 69.09 27.11 11.07 15.72	+1234 +1231 -78E3	104Pd ² 51VH 104Ru ² 28SiMg 36SO 40CaC	51.95180 51.95180 51.95211 51.96197 51.96200 51.96259	10.97 99.935 13.53 72.57 00.014 95.90	+4667 +4601 +4478 +2420 +2417 +2352
128 Xe ³ 128 Te ³ 57 Fe ³² 88 Sr ² 86 Kr ²	42.63450 42.63518 42.70155 42.95468	01.919 31.79 02.19 09.86	-63E3 	14313 64Zn ³² 48Ti 96Mo2 48Ca	47.94686 47.94686 47.94795 47.95248 47.95253	12.17 48.89 73.98 16.53 00.185	-44E3  +11E3 +10E3	² ⁶ Mg ₂ ² ⁵ MgAl ⁵ ² KC ¹⁵ ⁶ Dy ³ ¹⁵ ⁶ Gd ³	51.96518 51.96738 51.96706 51.971/ 51.97409	01.25 10.13 01.04 00.052 20.47	+2105 +1933 +1956 +1704 +1547
43 Ca	42.95878	00.146		⁹⁶ Ru ² ⁹⁵ Zr ² 47TiH 32SO	47.9544 <b>Univer:</b> 47.95959 47.96699	05.51 of Prefor 94.8	+7434 147156 44123 +2518	²⁰⁸ Pb ⁴ ¹² C ₃ O ¹² C ₄ H ₄	51.99416 51.99416 51.99492 52.03128	90.18 52.3 96.48 95.60	+1427 + 968 + 955 + 572





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SOVO	65.94207	00.24	+4115	70	60 02700	20 52		57 5 61			
³³ S ₂	65.94293	00.006	+3906	70Zn	69.92534	00.82	+5283	50 CmC	71.95814	02.19	+4323
Jacris C	65.94401	00.106	+3673	⁷⁰ FeC	69.23331	00.35	+7503	74040	77.04065	04.22	+3762
43m+180	65.94525	93.10	+3434	69 GaH	69.93353	60.4	+7330	5851-0	73 34560	05.04	+3107
1221 2	65.94711	00.151	+3132	⁵⁴ CrO	69.93379	02.38	+7135	42 CaO-	73 01813	00.21	+2005
132p-2	65.95205	26.89	+2533	54FeO	69.93452	05.31	+6540	74Mg	73 06268	37.18	+2077
34co	02·95256	00.097	+2487	70 S2	69.93495	05.001	+6380	148 m2	73.95721	11 24	+20/11
50102	02.95/69	104.20	+2024	53NiC	69.93535	68.41	+6155	148 _{Nd} 2	73.95823	05 77	+1086
M320	07.96254	15.50	+1809	35 CT_	69.93771	56.05	+5097	2 6MgOs	73.96732	11.00	+1507
27 Mg20	65.96659	01.03	+1626	57 Fe ¹³ C	89.93 <u>976</u>	00.024	+4734	74 Møn Ch	73.96763	18.54	+1585
AL2C	65.96308	98.90	+1780	52 Cr180	69.93967	00.171	+4451	74 MgC	73.93259	11.11	+1200
138 243	65.97576	03.14	+1381	7051-0	69.95069	05.95	+2619	74Ce	74.00670	00.176	+ 863
1981-3	65.97.58	0.4.51	+1381	46080	63 95%69		+035Å	12 CaHa	74.01564	93.50	+781
12 A2	65.90592	10.02	+1049	4 6T1C2	69.95263	07.82	+2442	149 0-2		17 07	
U11 C U	66.00000	85.45	+ 891	27 Å ] 2	69.95799	99.75	+2053	Sm	74.45840	13.83	
CSH6	66.04692	94.50	+ 545	70 SC	69.96786	04.10	+1592	⁷⁵ As	74.92171 :	100.00	
199 _{Hg} 3	66.32274	16.84		CaHio	70.0782	94 45	+ 453	⁵⁹ CoO	74.92809	99.76	+12E3
133Cs ²	66.45257	100.00		NapCp	69.97976	97.80	+1254	7⁴GeH	74.92882	36.53	+11E3
133 3211	66.50168	10.90	+1353	947.32			,	⁴⁸ TiAl	74.92949	73.98	+9630
200 _{Hg} 3	66.65611	23.13		141p.2	70.40070	1/.40		^{es} CuC	74.92959	68.33	+9506
ອອ _ບ ເຊ	66.67929	105.05	+2876	- Pr	10.45274	T00.00	+9062	SeH	74.93036	00.87	+8661
67 7		01 77		⁷¹ Ga	70.92482	39.6		57Fe ¹⁸ O	74.93457	00.004	+5812
- 211 667рН	65.92714 66.03387	04.11		⁷⁰ GeH	70.93181	20.52	+10E3	2 TAC ⁵	74.94398	97.56	+3364
551000	66 07805	27.01	+9945	⁵⁵ MnO	70.93297	99.76	+8702	(PMgg	74.95347	05.34	+2359
5100	66.97005	93.09	+6124	59 CoC	70.93318	98.89	+8484	²⁵ Mg3	74.95752	00.01	+2092
57 5-	66 03033	99.52	+5596	44CaAl	70.93654	02.06	+6052	150 Sm ²	74.95845	07.44	+2039
28 a + 39 v		00.054	+5490	58Fe ¹³ C	70.93666	03.7E3	+5990	⁴³ CaO ₂	74.95858	00.145	+2032
54 cm 13 c	66.94064	05.05	+4950	SeNi ¹³ C	70.93370	00.766	+5110	150Nd2	74.96041	05.63	+1936
54 m 13 c	66.94222	00.026	++++>0	530r130	70.93981	00.019	+4735	35 KCa	74.96371	90.04	+1784
40002711	66.94296	00.064	+4251	°*FeOH	70.94231	05.81	+4055	27A103	74.96627	99.25	+1681
49 ma 18 0	66.94440	90.97	+2070	TiC ₂	70.95176	07.31	+2633	2'AlC4	74.98154	95.65	+1253
1342,2	66 05013	00.011	+>>/0	KO2	70.95351	92.65	+2472	С _в Нз	75.02346	93.48	+ 736
134 _{Vo} 2	66 05217	102.42	+25(0		70.95374	27.11	+2452	^{isi} Eu ²	75.45977	47.32	
35010	50.952/1 66 05865	75 17	+2010	11°Cer	70.95465	11.07	+2378	760			
67 CaCa	66 05878	12.11	+2124	23 NaO3	70.97451	36.72	+1427	'SSe	75.91925	09.02	0
31p7_	66 97376	06 72	+2110	- NaC4	70.98978	92.62	+1091	four o	15.92019	07.76	+2082
201473	65 92010	70.12	+1063	C5H11	11.02605	94.44	+ 440	54 N10	(5.92560	26.1/	+1252
134 ~2	67.00336		+ 879	143Nd ²	71.15479	12.17		647mC	75.92190	18 25	+0745
$C = H_{\pi}^{\cup 11}$	67.05474	00.011 04.40	+ 525	7200	71 00150	07 113		75 A GU	75.92914	00.086	+7107
202- 2				56500	71 00085		11/27	76701	75.92952	27 08	+7300
135502	67.52354	29.30		60 N 4 C	71 03077	91.77 05 04	+7935	63 0, 13 0	75 03202	00 765	+5566
307.32	67.45278	06.59		720100	71 92071	4J•77 01 93	+6956	52 CrC2	75 94051	81.92	+3576
203m-3	67.42025	51.46		71Gou	71 0306h	30 6	+6500	32 S.C	75.94414	39.25	+3054
- <u>-</u> -	01.0010	29.50		360_	71 03418	29.0 3 0 FG	+5713	44CaOa	75.94529	02.05	+2919
⁸⁸ Zn	67.92486	13.57		7201	71 37478	36.97	+5461	7 SMZa	75.95023	03.29	+2453
5°FeC	67.93194	90.64	+9594	590,130	71 03953		1,1817	152 Sm ²	75.95968	26.72	+1879
⁸⁷ ZnH	67.93496	Q4.11	+6725	540,130	71 07303	01.107	-++OI4	152 Jd2	75.95971	00.20	+1878
⁵² CrO	67.93543	33.56	+6426	54 - 180	71 05377			28 S10a	75.96166	91.54	+1~91
58 S2	67.93573	00.204	+6249	72040-	71 04705	72 50	T0405	⁴⁰ CaCa	75.96259	93.79	+1753
SiÇa	67.93979	39.42	+4550	2951002	71 24977	74.33	+2646	28SiC4	75.97693	38.19	+1318
^{oo} Mn ¹ ^o C	67.94140	01.107	+4107	4º CaOo	71.25230	36.5 <u>0</u>	+2335	¹² CO4	75.97964	97.94	+1259
* KAI	67.94337	C6.88	+\$670	43 Ca.Ca	71.95253	00.181	+2325	12CgH4	76.03123	33+47	+ 378
50 T1 50	57.94/95	00.011	+2553	144 Nd ²	71.35490	23.35	+2154	1532	78 - 203	52 13	
	67.94521	00.009	+3339	24.23	71.05513	13.71	+2144			JC•10	
1350-2	01.40219		+2405	144 Šm2	71. 5533	03.02	+2101	Se	<u>78.91998</u>	07.55	
136v.2	01.92224	00.195	+2000	^{2 4} MgO ₃	71.03977	78.13	+1407	<u>3</u> 1110	73.92600	01.13	++;;;;;;
2804 0	01.90000 07.05780	31 00	+2262	^{2 4} Mg ₂ C ₂	71,97003	30 <b>.</b> 53	+1+35	~~tet	10.15/10		+1122
44000	27 0 = = 00	02.015	+22=2	24 MgC ₄	71.93504	75.27	+113-	7 êdayî	70.141.0	10.9. 17. Te	+9062
3290	67 07207	02.01	+1430	⁷² Ca	72.00000	93.52	+ 717	85 77	79.92001	30.27	17260
204 Dh3	67 00103	91.95	+1027	145 NJ2	70 15203	08 30	_	647513 r	70.22110	00 54	+9062
204 _{Ur} 3	67 30116	06 35	+1025	14502_	72 50188	11 78	±1637	53777	76 34065	00.34	+3709
Ca Ha	63.06256	<u>34</u> 44	+ 403	~12		ر. •مد - مع	· ( ·	520,250	76.04387	01.37	+-220
205		70 70		- 3 Ge	72.92334	07.73		45 Sc0,	73.94752	99.52	+2793
137 D-2	55.5246	/0.50		JeH 570	72.92941	27.47	+12E3	77.53	76.95102	66. <u>3</u> 8	+2475
20 6 m 3	67.492/9	11.52		7 3 X 4 9	72.05052	02.19	+1022	1547,12	76.26047	02.15	+1900
	00.00010	27.5		5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5	72.72107 70.52107	01.4/ 01.5/	オジャワト	154 5 2 2	73.98097	22.71	+1877
⁶⁹ Ga	63.92571	60.4		551180	/2.35464 70 02701	00 00 h	+0400 15001	29 SiOa	76.96122	04.87	+1865
92Zr ³²	68.92850	17.11	+25E3	73T*A	12.30121 70 01707	00.204	〒フビロ上 エンハママ	41%Ca	73.36183	36.65	+1333
⁶⁸ ZnH	68.93268	18.57	+9889	1102 7301_0	16.74/7/ 70 14833	03.57	+2019	77 SiC4	76.27649	08.45	+1361
5°Fe ¹³ C	68.93529	01.015	<b>+</b> 7194	41K0-	72 05163	16.35	+2573	13C04	76.)3300	01 <b>.1</b> 0	+1221
FeC	68.93541	02.166	+7106	73 _{Mar}	72.05502	18-32	+22=3	12C6H5	77.03910	97.45	+ 643
⁵³ CrO	68.93556	09.53	+6998	146142	72,35635	17.22	+2209	232mh3	77 3480	100 00	
69S2	65.93855	02.E4	+5368	37 C1Ca	72.23590	23.67	+1713	1557,32	77.4614	14.73	
¹³⁸ Ba ²	69.95244	71.66	+2579	25 _{M2} 02	72.97057	10.06	+1544		it• ∘≎π⇒	ш • , ^с	
rae Ces	68.95302	00.25	+2524	73 Mg Co	72.57088	16.96	+1534	/ªSe	77.91739	27.52	
- ³⁵ La ^e	65.95337	00.089	+2487 `	73 MgCa	72.23584	13.07	+1167	/ [°] Kr	77.92019	00.35-	+2353
Si2C	68.95342	09.50	+2487	730 -	73.00336	06.29	+ 911	N10	17.92325	05.84	+13 E3
3′C102	68,95570	24.35	+2298	12CeH	73.00782	93.51	+ 363	~~ZnC 397	11.92605	21.50	+0999
45 ScC2	69.•95592	97 <b>.</b> 80	+2282	147 -2	73 12705	1/1 017	-	41x37 ~7	77.92742	36.68	+//60
SCa	68.97542	03.83	+1387	5m-	12.70120	⊥+•≯{		77 Satt	11.927()	01.60 01.60	+1500
eu'Pb'	68.99196	22.6	+1040	74Ge	73.92100	36.54		000 65 0,13 0	11.42/30		+1405
CsHə	69.0704	94.46	+ 476	′_⁴Se	73.92254	00.87	+4853	780m0	11.49110 77 5207	00.54	+25/1
208 _{Pb} 3	69.32555	52.3		⊃¤FeO	73.92822	00.33	+10E3	54 240	77 03041	05 50	+3027 13507
¹³⁹ La ²	69.45302	<u>99.911</u>		' NiC	73.92834	03.63	+1053	785.0	77 03003	07 05	+2007 17160
209 _{Bi} 3	69.65978 :	100.00		2°NiQ	73.93026	69.01	+7983	4 °T10~	ィイ・ブノブブフ 77、ロムクルド	07 98	+/*/ +3110
70 ₀₀	69.02300	20 53		737 Fe ¹⁸ 0	73.93110	00.137	+7319	78 _{Møs}	77.04777	00 14	+2266
50	~~~ <i>~~~</i> /77	20.72		GeH	73.93116	07.76	+7276	15 6 Dv2	77.957/	00.052	+1967
				39 v 21 🔞 🚺	versityedf	Pretoria	+6838	y	11.02217	00.092	F7201
				VCT	12.7256	10.52	+0295				



³⁰ SiO3 ⁴² CaC3 15 ⁶ Gd ² ³¹ P ₂ O ²⁷ Al ₂ C2 ²³ Na ₂ O2	77.95849 77.95863 77.96113 77.96244 77.96308 77.96938	03.07 00.62 20.47 99.76 97.80 97.52	+1895 +1889 +1781 +1730 +1705 +1499	³⁴ SO ₃ ⁴ ⁶ TiC ₃ ⁵⁰ Mg ₂ O ₂ 164Dy ² 164Er ²	81.95261 81.95263 81.95745 81.9643 81.9649	04.19 07.74 18.53 28.18 01.56	+2277 +2275 +2007 +1718 +1697	¹⁷⁵ Lu ² 56Fe ³² S 88Sr 40Ca ⁴⁸ Ti 72Ge0	87.471/ 87.90401 87.90601 87.91081 87.91650	97.41 87.08 82.56 71.74 27.37	-44E3  +18E3 +8372
78 SiC4 14NO4 12C23 12C6H6 235U3	77.97376 77.98271 78.00000 78.04692 78.3476	03.16 98.67 86.49 93.45 00.72	+1382 +1193 + 943 + 602	165 _{H0} 2 56FeA1 83Kr 26S155Mn	81.96786 82.46455 82.91348 82.91405 82.91405	04.04 100.00 91.66 11.55 92.21	+1599 -15E4 	88Ca2 87SrH 87RbH 76SeC 76GeC	87.91653 87.91681 87.91712 87.91928 87.92129	00.40 07.02 27.85 08.92 07.67	+8348 +8139 +7912 +6624 +5753
157 _{Gd} 2 157 _{C13} 79 _{Br}	78.4621 78.50168 78.91839	15.68 12.60 50.537	+1982	⁶⁷ ZnO ⁸³ Ca ₂ ⁸² SeH 71 GaC	82.92205 82.92278 82.92445 82.92445	04.10 00.28 09.19	+092) +1023 +9498 +7973	^{5 6} FeO2 ⁸⁸ Si3 ⁶⁴ ZnC2 ⁶⁴ NiC2	87.92174 87.92445 87.92914 87.92796	91.22 00.28 47.81 01.06	+5505 +4767 +3801 +4003
⁵² CrAl ³³ CuO 78SeH 79ZnC 79K-	78.92205 78.92451 78.92521 78.92714	83.76 68.92 23.52 04.42	+22E3 +13E3 +12E3 +9019	⁵⁹ CoC2 ⁵¹ VO2 ⁸³ TiC3 ³⁵ ClO3	82.93318 82.93378 82.95176 82.95355	97.80 99.28 97.31 74.98	+4334 +4202 +2199 +2099	52 CrC3 28 S1202 32 S2C2 40 Ca03	87.94051 87.94368 87.94414 87.94414	81.01 84.62 88.26 96.27	+2547 +2333 +2305 +2114
⁶⁸ Zn ¹³ C ⁵⁵ MnC2 ⁴⁷ T102 ³¹ P03	78.92941 78.93805 78.94156 78.95849	00.31 97.80 07.25 99.28	+7168 +4014 +3406 +1968	¹⁸⁸ Er ² ³⁵ ClC ₄ 167 _{Er²} 280456Ec	82.9644 82.96885 83.4653	33.41 72.24 22.94	+1647 +1513	² ⁴ MgO ₄ ¹⁷ ⁸ Hf ² ¹⁷ ⁸ Lu ² ¹⁷ ⁸ Lu ²	87.96468 87.9704 87.9710 87.97136	92.75 77.94 05.20 02.59 12.73	+1365 +1365 +1352 +1345
79 CaC3 158 Dy2 158 Gd2 31 PC4	78.95878 78.96200 78.9622 78.97376	00.161 00.09 24.87 95.65	+1954 +1810 +1801 +1425	84Kr 84Sr 57FeAl	83.91325 83.91325 83.91695	56.90 00.56 02.19	-48E3 +23E3	¹² C7H4 177Hf ² 897	88.03128 88.4713 88.90572	92.46 18.50 100.00	+ 702
158 _C 2 C ₆ H <del>7</del> 239 _U 3	79.00335 79.05474 79.3495	00.847 93.44 99.274	+ 929 + 579	⁶⁸ ZnO 72GeC 52CrO2	83.91808 83.91977 83.92159 83.93031	18.53 27.13 83.36	+1785 +1383 +1083 +4919	57 Fe ³² S 88 SrH 73 GeO 89 SeC	88.90748 88.91383 88.91825 88.91998	02.08 82.55 07.73 07.60	+51E3 +11E3 +7095 +6235
^{ao} Se ^{so} Kr ²⁸ Si ⁵² Cr	79.46244 79.91647 79.91659 79.91744	100.000 49.82 02.27 77.24	+ 703  +67E4 +82E3	⁶⁰ NiC ₂ ⁸⁴ TiC ₃ ⁴⁸ CaC ₃ 168 Tr	83.93079 83.93078 83.94795 83.95253 83.95253	78.40 25.65 71.79 00.18	+4784 +4787 +2418 +2136 +1609	89 S13 57 FeO2 65 CuC2 89 CrC3	88.92401 88.92521 88.92778 88.94065	00.013 02.18 30.23 11.96	+4861 +4562 +4030 +2545
⁸⁴ N10 ⁸⁴ Zn0 ⁸⁰ ZnC ⁴⁰ Ca ₂	79.92287 79.92405 79.92486 79.925517	01.08 48.77 18.41 93.45	+13E3 +11E3 +9525 +9186	168 <u>7</u> 62 12 _{C7} 169 _{Tm} 2	83.96695 84.00000 84.46717	00.135 92.48 100.00	+1563 + 967	³ Si ₂ O ₂ ⁴ KO ₃ ⁴ KC ₄ ²⁵ MgO ₄ 178 Hf ²	88.94324 88.94563 88.96183 88.96548 88.9715	08.62 06.83 06.58 10.03 27.14	+2370 +2228 +1584 +1488 +1352
H ⁷⁹ Br ⁵⁵ FeC2 55Mn ²⁵ C2	79.9252 79.92622 79.93194 79.94141	50.52 89.64 02.19	+8197 +5166 +3204	85S1Fe 85Rb 58TeAl	84.90843 34.91202	06.33 72.15	-24E3	¹² C ₇ H ₅ ¹⁷⁹ Hf ² ⁹⁰ 7r	89.03910 89.4726 89.90433	92.45 13.75 51.46	+ 667
³² S ₂ O ⁴⁸ CaO ₂ ²⁸ Si ₂ C ₂ ⁴⁴ CaC ₃ ³² SO ₃	79.93775 79.93905 79.94233 79.95386 79.95500 79.95602	90.03 90.184 83.16 01.99 94.32	+3735 +3539 +3090 +2137 +2074 +1981	⁸⁴ SrH ⁸⁵ GeC ⁸⁵ Si ₃ ⁵³ CrO ₂ ⁸⁵ N1C2	84.92107 84.92334 84.93035 84.93045 84.93109	00.39 00.56 07.97 11.99 09.50 01.73	+9383 +9383 +7501 +4632 +4607 -± ⁴⁴ 53	45 SC2 89 YH 7 4 GeO 90 SeC 7 4 SeO 59 <b>B</b> 00	89.91184 89.91354 89.91591 89.91591 89.91739 89.91745 89.92311	100.00 99.985 36.38 23.32 00.87	+12E3 +9762 +7764 +6884 +6852 +4787
²⁴ Mg2O2 150Dy2 160Jd ² 32SC4 12CgHa	79.95990 79.9620 79.96361 79.97207 80.06256	61.64 02.294 21.90 92.77 93.43	+1840 +1755 +1695 +1437 + 547	³⁷ ClC ₃ ³⁷ ClC ₄ 170Yb2 170Er ² ⁸⁵ C7 12C7	84.94787 84.96590 84.967/ 84.9678 85.00336	07.73 02.40 03.03 14.38 07.25	+2369 +1576 +1544 +1522 + 930	58 NiO2 532nC2 39 K2C 90 CrC3 54 FeC3	89.92515 89.92605 89.92742 89.93887 89.93961	68.85 27.20 85.72 02.61 05.63	+4318 +4139 +3894 +2602 +2548
¹⁶¹ Dy ²	80.4629	18.88		171Yb ²	85.468/	92.49 14.31	+ 505	⁹⁰ Si202 ²⁸ Mg04	89.94051 39.96223	05.89 11.06	+2485 +1553
54FeAl 65CuO 80SeH 69GaC 81FeC2	80.92115 80.92269 80.92269 80.92429 80.92571 80.93541	05.82 30.84 49.81 59.73 04.15	+17 E3 +13E3 +10E3 +8710 +4261	⁸ ⁶ Sr ⁸ ⁶ Kr 54 Fe ³² S 70 GeO 85 RbH 79 70	85.90935 85.91079 85.91168 85.91390 85.91984	09.86 17.37 05.53 60.3 72.14	+60E3 +37E3 +8996 +3190	²⁷ Al ₂ C ₃ 180 W2 180 Ta ² 180 Hf ² 12 C ² 5 12 C - H	59.96308 59.9723 59.973/ 59.9731 90.00000 90.04692	96.72 00.135 00.012 35.24 84.58 92.43	+1530 +1323 +1309 +1307 + 940 + 631
²⁷ Al ₃ ⁸¹ S1 ₂ C ₂ ⁴⁹ Mg ₂ O ₂	80.93767 80.94462 80.95342 80.96070	05.48 100.00 12.12 15.87	+3808 +2869 +2187 +1827	8 * GeC 7 * SeC 8 * Si3	85.92100 85.92254 85.92762	36.23 00.87 08.49	+7374 +6513 +4702	$181Ta^{2}$ $181C^{2}_{15}$	90.4729 90.50168	99.988 14.22	+3144
162 Dy ² 162 Er ² 12 C ₆ H9 163 Dy ²	80.9628 80.96436 81.07038 81.4639	25.53 00.136 93.41 24.97	+1745 +1688 + 526	54 CrO2 54 CrO2 54 FeO2 8 STIC3 50 CrC3 27 AloO2	55.92594 85.92867 85.92941 85.94479 85.94065 85.95289	02.37 05.79 05.34 04.17 99.52	+4924 +4446 +4283 +2424 +2341 +1973	90ZrH 75As0 79BrC 59CoC2 .91ZpCa	90.90592 90.91215 90.91662 90.91839 90.92298 90.922714	51.45 99.76 49.98 97.80 04.63	+13E3 +8045 +6955 +5148 +4166
²⁸ Si ⁵⁴ Fe ⁸² Se ⁵⁵ MnAl ⁸² ZnO ⁸² Caa	81.91345 81.91654 81.91663 81.91959 81.92096	11.56 05.37 09.19 100.00 27.74	-26E3 -91E4 +28E3 +19E3	172 YD2 $31 P_2 C_2$ $8 C_7$ $12 C_7 H_2$ 173 YD2	85.9626 85.96753 86.00670 86.01564	21.32 97.80 00.244 92.48	+1612 +1477 + 382 + 808	55MnC3 54Fe ³⁷ C3 27AlO4 192W2 182C15	90.93805 90.94297 90.96114 90.9730 91.00335	96.72 00.189 99.04 26.41 01.115	+2777 +2414 +1629 +1343 + 927
⁴ 1K ₂ ⁷ °GeC H ⁸ 1Br ⁷ °ZnC	81.92366 81.92399 81.92425 81.92534	00.47 20.29 49.44 00.63	+12E3 +11E3 +11E3 +9405	87 Sr 87 Rb 88 SrH 71 GaO	86.90899 86.90930 86.91717 86.91973	07.02 27.85 09.86 39.50	+28E4 +11E3 +8092	183 _W 2 40Ca ⁵² Cr ⁹² Zr ⁴⁶ T12	91.4741 91.90337 91.90467 91.90526	14.40 81.22 17.11 00.64	-71E3  +16E4
Ga+3C 82 FeC2 50 TiO2 58 NiC2 88 S2O 50 CrO2 82 SisCo	01.92906 81.93331 81.93459 81.93535 81.93585 81.93585 81.95069	00.669 00.368 05.31 67.66 08.00 04.29 05.98	+6590 +4911 +4561 +4376 +4498 +4262 +2405	75ASC 74Ge13C 55MnO2 87S13 39KO3 174Yb2 38VC	86.92171 86.92436 86.92785 86.92718 86.94841 86.96287	98.89 00.40 99.52 00.81 92.43 31.84	+6832 +5654 +4608 +4773 +2205 +1615	92 Mo 91 ZrH 78 SeO 76 GeO 80 SeC 80 SeC 80 N102 92 75 C	91.90855 91.91314 91.91419 91.91620 91.91620 91.92057 91.92057	15.84 11.22 09.01 07.75 49.27 26.10 18.25	+24E3 +11E3 +9654 +7971 +7789 +5780 +4552
			/	^{17 4} Hf ² ¹² C ₇ H ₃	87.02346	92.47	+1425 + 759	21102	J =+ J = + 00		

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4°Ca ₂ C	91.92517	92.42	+4483	967 rH	26 21712	02 80	18882	539.0	100 005-0		
44CaO3	91.94023	02.05	+2584	es CuOs	96.91758	30.76	+8523	es curda	100.92538	09.48	+4951
² Si ₂ C ₃	91.95386	32.24	+1868	97GeC2	96,92334	ó8.19	+5657	101020	100.92775	29.09	+4450
2°CaC4	91.95550	01,97	+1908	<u>97</u> Si3Č	96.93035	12.73	+4014	202 Hg2	100.98531	29.80	+1256
184002	91.95657	91.35	+1771	, NiCs	96.93109	02.00	+3895	C _B H ₅	101.03910	91.42	+ 752
184 _{W2}	91.9745	30.84	+1245	271103	96.93257	05.47	+3676	135 _{Ba} 32	101.17216	06.59	
185 0 2		20.84	+1010	97 T1 C.	96.99952	99.76	+2908	203 m	101.4360	29,50	
Re-	92.474	37.07		194p+2	96.94/0/ 96.9817/	32 3	+2526 ±1284	1020	101 99050	27.00	
93Nb	92.90566	100.00		194 ČŽ	97.00335	01.26	+ 398	51m	101.00695	07.22	-0920
772rH	92.91249	17.11	+14E3	97 Cs -	97.00335	08.20	+ 998	1025	101.00795	39.54	-0+50
albrC	92.91489	07.57	+10E3	¹² C ₈ H	97.00782	91.45	+ 954	3 5 C O	101.90575		
61NtO	92.91642	40.92	+5634	195 _{Pt} 2	97,4831/	33.8		907rC	101.90425	0 <b>9.</b> 04	+1954
⁶⁹ GaC2	92.92571	59.07	+6100	98m.		22.00	7790	102 pd	101 20486	00.96	+1, L,
93FeC3	92.93530	05.10	+3134	98M0	97.09273	05.20	-7.589	89v13r			+19F3
27AlgC	92.94462	98.89	+2385	9 55rC	97.90990	00 75	±29.53	⁷⁰ Ge02	101.91379	20.42	+10E3
³ P3	92.95129	100.00	+2036	⁹² SeO	97.91154	09.18	+18E3	102 SeCa	101.91739	23.15	+7460
29 CI2C3	92.95342	11.14	+1945	⁹⁷ MoH	97.91403	09.46	+12E3	¹⁰² Si30	101.92253	08.47	+5420
18602	92.95613	04.65	+1841	98S3.	97.91201	11.43	+16E3	54CrQ ₃	101.92360	02.36	+5129
1850-2	92.9124	20.41	+1352	^{BS} Rb ¹³ C	97.91545	00.80	+10E3	°⁴FeO3	101.92434	05.78	+4944
187- 2	92.910/	01.59	+1721	³³ ZnO ₂	97.91585	27.68	+9920	^{CC} ZnC ₃	101.92605	26.90	+4566
1870-2	93.477/	62.93		745eC-	97.92100 97.92100	25•91 00 85	+6510	102 CrC4	101.92025	07.51	++1)1
08-	92.4(0/	01.64	+94 83	98SiaC	37.92762	08.53	+4524	54FeC4	101.93961	05.57	+2840
40 Ti2	93.90058	12.37	-1353	98 NiCa	97.92834	03.58	+4379	27A1203	101.94781	99 <b>.</b> 28	+2312
T ^o CaFe	93.90247	05.64	-13E3	⁵⁰ TiO3	97.92952	05.30	+4159	204 Pb2	101.98654	01.48	+1231
94/7m	93.90594	09.04	-55E3	50 CrO3	97.93078	04.28	+3948	204 Hg ²	101.98674	Q6.85	+1228
785e0	92.90764	17.40	100 53	SOCIC4	97.94479	05.35	+2523	12C17	102.00000	32.72	+1059
93NbH	93.91348	- <u>6</u> 0 - 97	+2023	34co	97.94605	04.12	+2445	Caris	102.04692	91.41	+ 712
82 SeC	93.91663	09.09	+10E3	98 ₂₁ ,	27 954/02	01 87	+2039	205T12	102.4869_	70.50	
⁶² N102	93.91814	03.64	+8944	31 P2Ca	97.96753	96.72	+1591	205C17	102.50168	15.75	+6934
³⁹ K ₂ O	93.92233	86.47	+6393	196Hg2	97.98291	00.146	+1273	13'Ba32	102.67918	11.32	
GeC2	93.92399	20.07	+5744	19 SPt2	97.9836	25.3	+1261	103Cr2	102.88670	00,82	-5765
58 N# C	93.93331	00.39	+3658	95Ca.	98.00670	00.321	+ 972	87 SrO	102.90390	07.00	-16E4
	92.92222	07 04	+2209	- Ce Hz	98.01564	91.44	+ 893	a7 RDO	102.90421	27.78	<b>-</b> 30 E4
94SiaCa	93,950.69	06.01	+2181	¹⁹⁷ Au ²	98.4836	100.00		103Rh	102.90455	100.00	
46T1C4	93.95263	07.65	+2087	⁹⁹ Tia	38.89266	00.59	-7387	¹⁰³ Zr <b>C</b>	102.90532	11.67	+13E4
³⁰ SiO4	93.95340	03.06	+2052	99 Ru	28.90605	12.72		$\frac{71}{2}$ GaO ₂	102.91462	39.41	+10E3
31P202	93.95735	99.52	+1890	99SrC	98.90899	07.05	+34 E3	[BrC ₂	102.91839	49.42	+7435
-000s2	93.9785/	13.3	+1325	87 RbC	98.90930	27.54	+30 E3	103 grad	102.92278	99.28	+5645
¹⁸⁹ 0s ²	94.4793/	16.1		⁹ ³ MoH	98.91380	23.78	+13E3	55Mm C	102.92714	04,00	++>>>>
95 min	a4 80070	11 67	-2073	~' <u>1</u> n02	98.91694	04.09	+9082	3970.	102.90000	92.21	+2652
40 CaMn	94,90091	96.97	-27 53	63 Cu C-	38 32350	97.00	+6216	20 6ph2	102,98722	23.6	+1245
95 _{Mo}	94.90444	15.72		35C104	98,94849	74.80	+2330	CaH ₇	103.05474	91.40	+ 685
⁷⁹ BrC	94.91330	50.42	+11E3	198 Pt2	96.9823	07.21	+1297	207 Dh2	103 48704	22.6	
MoH	94.91376	09.04	+10E3	¹⁹⁸ Hg ²	98.98337	10.02	+1279	138 Ra 32	103.42866	71.66	1746
ZrH	94.91546	17.40	+8615	CsH3	99.02346	91.43	+ 842	1040	107 20100	70 37	hees
40 ca Fa	25 80480	88 88	-661)	¹⁹⁹ Hg ²	99.48411	16.34		38 G MO	103.00102	30.36	-4623
9eria	95.39539	56.38	-7152	50m4.	00 88058	00.00	= =	104 DA	107 20328	10 07	
9 ^e Mo	95.90496	16.53	-2223	50 Cr2	99.39210	00.19	-4233	104 Pm	107,90422	13.58	+1124
⁹ [€] Ru	95.9087	05.51	-16E4	100 _{R11}	99,905/	12.52	-87 53	1047rC	103, 20467	17.04	+75Ë3
9 ⁶ Zr	95.90930	02.30		100570	99.90610	31.7×	-25E4	[∋] 2MoC	103.90355	15.66	+20E3
SeO	95.91138	49.71	+46E3	100 _{Mo}	99,90651	09.63		72 GeO2	103.91139	27.30	+13E3
B4gnC	95.91226	15.72	+ ラビビラ	⁸⁴ SrO	39.30816	00.56	+60 E3	30 SeC2	103.91647	48.72	+7877
325	95.91622	85.74	+1453	a7 Rb13C	99.91265	27.54	+16E3	Jereos	103.91664	91.00	+/////
64 NiO2	95 <b>.</b> 91776	01.07	+1123	^{co} ZnO ₂	99.91266	18.43	+1253	40 Ca - C-	103.32517	21.30	44747
64Zn02	95.91896	48.65	+9928	Tage C2	99.91928	08.52 .	+7324	567eC/	103.93194	37.67	+3625
$^{40}Ca_{2}O$	95.92008	93.22	+8397	52 CrO-	29.92129	83 16	+5/50 16340	28 Siz03	103.93859	34.42	+2943
GeC ₂	95.92159	26.83	+7804	23 Sta0	39.92521	78.21	+5203	⁴⁰ Ca04	103.94250	96.04	+2649
28 Ci C	95.93077	25.40	+4467	39 K2 C2	99.92742	84.77	+4778	208 Pb2	103.93333	52.3	+1222
48mi0-	95.95079	((・)) フェール5	++++02	⁶⁴ NIC3	<u>99</u> .92796	01.04	+4655	CsHa	104.06256	91.39	+ 652
³² SaOa	95.93396	89.82	+3889	³⁴ ZnC ₃	99.92914	47.28	+4415	¹³⁹ La ³²	104.17952	99.911	
∂°TiC4	95.94795	71.07	+2481	SecrC4	99.94051	20.11	+2938	²⁰⁹ 3i ²	104.43967	100.000	
³² S04	95.95173	94.09	+2260	200 <u>1 -</u> 2	99.94414 00 08/12	01.29	+2504	105 ₀₋₀	104.38159	16.00	-4516
+340s ²	95.9811/	41.0	+1336	C-H-	100-03128	2/•1/ 91.42	+ 801	səyo.	104.90063	99.76	-25E3
Pt ^e 12 <i>0</i>	95.9824/	00.78	+1312	201 2		, <u> </u>		105 Pd	104.90492	22.23	
U8 193- 2	96.00000	91.46 	+1057	Hgf	100.48515	T2•55		⁹³ NbC	104.90566	93.39	+13E4
 19362	96.4834/	62.7		101 Ru	100.905/	17.07		⁷³ Ge02	104.91314	07.72	+13E3
∪īe	96.50168	⊥4•99	+5278	39YC	100.90572	<u>9</u> 8.89	+1424	³¹ BrC ₂	104.916-2	48.37	+9044
Tia	96.89581	08.93	-9318	⇒ RbO	100.90693	71.98	+5253	P FeO3	104.92011	02.17	+6861
CaFe	96.89827	02.12	-12E3	100	100.90945	00.914	+とうどう	105 mg/	104.92896	30.40 0 = 02	++246
MO Blb-0	96.90621	09.46		69COO	100.91433	09.00 60 11	+1772)	57 St - 0	104.03815	08.60	+7147
-bru 35 brc	70.71133	49.54	+1983 ±1753		100,01008	07 - 61	+6736	27 41 - 0-	104 044460	37.80	+2636
● ^M OH	96.91278	16-53	+15E3	101Sia0	100.92526	11.96	+4981	AT305	<u></u>	-1 -	,20,0
97 Sa	96.91561	02.06	+10E3		2 . 2	-	-	10 °Cr2	105.37938	04.90	-4501
								² ZrO	105.59924	51.34 27 33	-29E3
								Pa	100.90591	e(•22	



10 8 Pd	105,90291	27.33		113-				10 -			0
10602		- 01 - 01 F		Fe ₂	112.86735	04.02	-3056	* Ca ₃	119.88776	90.34	-8303
	102.90292	01.217	+25522	⁹⁷ MoO	112.90112	00 46	3653	88 Sr0a	119.89592	82.16	-19F3
⁹ "MoC	105.90594	08.94	+35E3	113 -	110 00 120		- 7027	104 740			30 53
947rC	105,90764	17.21	+2253	2 2 2 ¹¹¹	112.90450	04:28		Pau	113.03013	10.94	- 30 E 3
93 130				113Cd	112.90446	12.26	+71E4	¹⁰ *RuO	119.89914	18.53	-39E3
NDC	102.90901	01.10/	+17 ビラ	119 _{Ru}	112 005	17 00	1.000	120 cm	110 00000	30 85	
¹⁰⁶ FeC₄	105.93331	00.41	+3484	89	112.905	11.02	+T0F4	Sn	119.90220	22.02	
58 NIC	105 03525	66 17	12005	YC ₂	112.90572	97.80	+80E3	¹⁰⁰ PdC	119.90347	26.41	+94E3
	105.92525	00.11	+2265	⁸¹ BrOa	112 00622	10 22	LEO EZ	108 040	110 00407	00 865	LELES
°°Si203	105.93542	05.88	+3258	65 2. 2	112.90022	77.22	モンタニノ	120-000	119.90.01		+0+57
			. / _ / 0	CuOs	112.91251	30.69	+14E3	Te	119.90449	00.089	+52E3
107 Cr ₂	106.87592	00.46	-4224	49 T104	112,92751	05.46	14867	120 MoCa	119.90496	16.41	14383
917.0	106 00003	11 00	0777	65 m. m			++007	960.0			
10410	108.90025	TT. 20	-2555	27.0404	116.96110	29.56	+4809	- RuC2	119.9007	05.29	+10ピン
10' MoC	106.90444	10.68	-27 E4	~'Alg02	112.93444	99.52	+3746	⁹ ⁶ ZrC ₂	119.90930	02.74	+17E3
107 4	100 00007					,,,, <u>,</u> _		5600	110 01168	00 78	11353
Ag	106.90403	51.35		114Fea	113.86525	00.66	-2974	37	119.91150	90.70	
947 n130	106.01000	00 103	±17 🖬 3	57		00000		≤′Al₄C	119.92616	98,89	+5004
75 1 2	100091099			rez	112.01002	00.05	-3481	28 StaCa	119.93079	75.83	+4104
' ASO2	106.91151	99.52	+16E5	9°MoQ	113.90089	23.72	-43E3	120-303			1.1.0.0
54				11401	117 00755			010	150.00000	09.44	+T556
J ^T Cr ₂	107.87774	00.06	-4194	Ca	113.90355	28.86		1 3 1			0000
5400	107 87000	00 74		¹¹⁴ RuC	113,90373	31.45	+63E4	¹²¹ Ni2	120.86186	00.62	-2889
CL65	101.01922	00.54	-4450	114	113 0030			1217	100 99777	07 70	7700
J2Zr0	107.89958	17.07	-28E3	ao_ ^{on}	112.90.59	00.66	+シンピ4	K3	120.00/2/	01.52	-1,299
92 _{M00}	107.00346	15.80	-10 86	³ [°] ZrC ₂	113.90433	50.33	+15E4	eg XO2	120.89552	99.52	-15E3
108-1	1010/10	1).00	- 10 10	102 PAC	113,00486		18753	105 040	120 80073	55 18	_ ਤੁਹੇਸ਼ਤੇ
- Pd	107.90347	26.71		82 - 2				ruo	120.09917	~~• <u>1</u> 0	
108 CA	107 00407	00 875	18 FL	Se02	113.90645	09.17	+39E3	121Sb	120.90371	57.25	
108.00	101.30401	00.079	-TO P-	5°T104	113,92443	05.29	+5455	109 100	IZO OOLEI	18 11	エコスアは
+ O o MoC	107.90496	16.47	+72E3	50000	113 005 00			121.000	120.90401		
96 _{Bu} C	107 9087	05 45	101 83		117.92009	04.21	+2142	MCC2	120.90621	09.61	+40ビン
782.0	107.9001		+2107	<u> </u>	113.92605	26.60	+5062	⁵⁷ Fe0₄	120.91505	02.17	+11E3
_ SeO₂	107.90910	08.98	+19E3	98 Ru0	113.040/	01.87	12452	12104 0	120 03035	1 1 1 1 1	11538
96ZrC	107.90930	02.77	+19E3	12 2				1212130	3120.97075	14.14	77970
78000		07 70	11/177	019	114.00000	00.09	+TTOT	15_1C10	121.00335	10.02	+1512
deu2	101.91111	01.12	+1+0)	99	111 00000	10.00	1	122		07 1.2	000
°°SrC⊳	107.91325	00.55	+11E3	Ruo	114.90096	12.69	-43E3	122 Ni2	121.85911	03.41	-2784
27 41.	107 02613	100 00	14762	115 Sn	114,90335	00.35	-4464	110 FeaC	121.87155	10.55	-3888
60 x x 4	107.92017	100.00	++/02	115 -				551 2			jug ho
~~N1C₄	107.93077	25.09	+2953	10°° TU	T14.2020T	22. (2		Mn2C	TST.0( 010	70.09	-4549
28 Sta Ca	107.93079	76.67	+3050	¹⁰³ RhC	114.90455	98.89	+12E4	122 Caa	121,88435	01.79	-6572
440.0				1157 n.C.	174 00530	1210	6753	907.0			1/1777
-∵ca0₄	107.93514	02.04	+2411	90-2102	117.900022	12.10	+0(1)	2702	121.09412	51.21	-1462
¹² Ca	108.00000	90.44	+1118	ZrfSC	2114.90769	01.13	+28E3	^{10 e} PdO	121.89782	27.26	-24E3
09	100.00000			<b>F</b> 0			-	108040			- 50 83
217 C2	108.50168	16.50		°°Ni2	115.87070	47.86	-3681	- Cuu	121.90004	UI•EI	- 79-27
018	100. 00100	10.00		58 80-	116 86662	00 001	3258	¹²² Te	121,90290	02.46	
93 mbo	108 00057	00 76	07 E3	P 4 5 5 5	119.00002	00.001	- 72.50	110		10.05	
108.00	100.90097	22.10	-2127	°⁻Sr0₂	115.90305	00.56	-14E4	++ CaC	121.90329	15.52	+ウエビ4
10° Ag	108.90461	48.65		100 Bu	115,900	12.50	-5383	110 PdC	121,90447	11.68	+78E3
109 100	108 00621	00 51	16853	100100				122120		07 17	1002
77	100.90021	09.07	+001	MOO	115.90142	09.61	-1554	- MOC2	121.90590	27.41	+40 57
( SeO ₂	108,90980	07.54	+21E3	118 _{Sn}	115,90219	14.30		^{e e} SrC ₃	121,90935	09.54	+19E3
85 RbCa	108.91202	70.56	+1583	104 010		10.02		58 TAN.	121 01205	00 33	+12E3
967	100.01000			Pac	TT2+20,250	T0.02	+1154	58.04			
- Zrisc	100.91265	00.051	+1462	104 RuC	115.90422	18.37	+57E3	³⁰ N104	121.91499	60.52	+10E2
- ^{IUS} SiaC	<pre>&gt;108.93035</pre>	13.50	+4231	1167.0	115 00467	16 66	ルファス	12251-0	-121.92762	08.60	+4931
109 ~	100 00336	00 10	1103	110000	119.90407	10.90		980.730		01.83	10386
⊂a	109.000000	09.12	+110)	Cd	115.90499	07.58	+41E3	, Ruce	121.95-7	01.07	+2,000
110	100 97155	10 67	7107	92MoCa	115,90855	15.49	+18E3	144C10	122.00670	00,505	+1174
re2	109.07100	10.01	-2462	522.0		Số cố		123	122 88678	<u></u> Ω	-7063
^{J J} Mn ₂	109.87611	100.00	-4044	-Cr04	115.92015	02.90	+0+22	91	122.00010		1 1 1 7 7
94Ma0	100 00085	00 02	1653	28 Sta0a	115.92061	78.02	+6298	² ZrO ₂	122.89512	11•1 <i>(</i>	-14E2
MOU	109.90005	09.02	-4262	1167-0	115 02/86	17 04	16113	107 AgO	122.89974	51.23	-28E3
¶ 4Zr0	109,90255	17.36	-15E4	ZnC4	112.92400	11.94	モンエン	100			/
110 04	100 00300		-	* CapCa	115.92517	90.38	+5044	±≤ Sb	122.90418	42.75	
ca	103.30253	16.22		232mh2	116 0100	100.00	+1185	123 CAC	122.00428	12.75	+1255
¹¹⁰ Pd	109.90447	11.81	+93E3	111	110.0190	100.00		1230	122.90420		+12 10
110MoC	100 00508	23 62	⊥น้ำ ธ่3	397	116 80113	80 70	-9766	Te	122.9043	00.07	+T0E2
78 2.0	109.90790			1013			70.07	¹²³ RuC ₂	122.90605	12.48	+66E3
SeO2	109.90721	22.42	+20E2	101 RuO	116.9000	17.022	-2052	123 cmC-	122 20802	07 11	+26F3
^{ae} SrC ₂	109.90935	09.64	+18E3	85 BDO2	116.90182	71.80	-91E3	2 DI 03	122.90099	01.11	
397		86.26	17878		110190100			^e RbCa	122.90930	26.94	+24E3
_ <u>r</u> 505	109.91/24	00.20	+1010	¹¹⁷ Sn	116.90310	07.61		1230	ີ 27 ຄຳຄໍຄິ	0515	+1161
¹¹⁰ SiaC	- 109 <b>.</b> 92763	08.55	+4515	117010	110 00190	20 10	10953	<b>V10</b>	12/01000	00.01)	1 7 7 9 7
4 6 T 1 0	100 03227	07.02	±3702	Pac	116.90462	22.10	+6052	124.	103 35873	00 57	-2664
31-04	109.97221			⁹³ NbCa	116,90566	97.80	+46E3	- N12	12/0000	00.57	-2004
- P203	T03.92555	99.20	+2244	8501 0	116 02017	11 03	<u>re848</u>	⁵⁶ FeaC	123.86388	83.09	-3000
98 RuC	109.954/	01.85	+2167	01302	110.92011		10000	12400	103 88070	05 70	-5053
1100	110 00670		1063	⁵³ CrO₄	116.92029	09.46	+600T	a_3	122.000/2	02.19	- 10 - 10
C9	TT0.00010	00.409	+106)	27 41-0-	116,94462	96.72	+2816	⁹² ZrO ₂	123.39447	17.03	-12E3
1117	110 97500	00 26	3700	23410		05 653	008	92M00-	123.89835	15.76	-18E3
Fe2	TTO 01205	00.20	-2790		111.0202	05.057	÷ 330	108-10			1957
95MoO	110.89935	10.73	-23E3	2352	117 6014	00 70		PdO	T55.02020	<0.30	-1053
11100		10 76		<b>-</b> u-	111 • 7414	00.12		TOB COO	123.89898	00.871	-20E3
<b>-</b> ua	TTO-20458	14.(5		118	117 96010	36 00	-3081	124 CAC	123.00306	23.04	-57 E3
99 Run	110.00605	12.58	+6353	°Ni2	TT(*00015	J0.29	- <i>Je</i> 01	124~		51.37	25.22
79				59 Co-	117.86636	100.00	-3304	''e	TSD•A09T5	04.6L	- ウダ やう
Br02	TTO . 20013	20.29	+2017	102 5.0	117 8096	31 63	- 35 57	124 RuCo	123.905	12.32	-50 E4
¹¹¹ SrC-	110.90899	07.09	+24E3	HuO	111.02004	21.22	-2222	1240	107 0000	OF OF	
87 02 7	110 00030	27 34	エククデネ	^{ee} Sr0,	117.89915	09.81	-4⊥E5	· Sn	122.90524	UD•94	
63	TTO . 202.20	- I •		102 040	117 80077	00.96	-52E3	1240-0	123 00010	80 08	<u> ተ</u> ገ և ም ሥ
°° CuOa	110.91432	68 <b>.</b> 59	+11E3	Fau	TT1 . 02211			- SrUg	T57.700T0		
63 0 1 0	110 62050	86.08	+4382	118 Sn	117.90205	24.03		⁺≃⁴Xe	123.90612	00.01	+14E4
47			11202	118	117 00001	07 00	11200	100MAC-	123.00651	09.42	+98E3
T104	110.93140	06.97	+4089	PdC	117.90291	21.28	+1+54	80			
111 _{Ca}	111.01008	00.011	+1048	10 0 CAC	117.90593	01.20	+30 E3	°∼NiO₄	123.91041	25.90	+2453
~ <b>9</b>			· · -	841-0	117 00601	08 84	+30 83	27A1.0	123.92107	99.76	+7827
112 Po-	111.86388	84.0e	-2856	- MOU2	111.20274					,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	
112-22			27717	∃*ZrC>	117.90764	17.02	+とエビク	113 For C	124.86735	03.97	-3351
Fez	TTT.0(595	00.04	-2(12	8801-0-	117,01744	08.45	+7661	93			ייים ול ר
9 6MOO	111 80087	16.40	-35 83	542 2		~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	17163	I NDO2	124.09546	72.25	-14E3
1100	102201		رشار ر	_⁼Cr0₄	117.91851	02.00	<b>*(</b> <u>+</u> <u>2</u> 2	109 AgÕ	124.89952	48.53	-25E3
TTE Cd	111.90306	24.07		54Fe0.	117.91925	05.76	+6855	113720	104 00412	04 52	- 30 11
9 6 R110	111 00361	05.50	+2014					128			
967 -				119 Ni-	118.86644	01.65	-3239	⁺f°CdC	124.90446	15.09	-70E4
^o ^o ZrO	111.90421	02.19	+91E2	110			QEE II	125 To	124 004A2	06.99	
112 RuC	111.905	12.62	+58E3	®Ka	118.88925	17.09	-0224	125 - ~			12250
112		00.00	16553	87 Sm0-	118.80870	06.99	-27E3	RuC2	124.905	10.97	キククビ4
sn	TTT•202T	20.30	T2252	87			-3053	an -	10F 0F0	1	<u> </u>
112 SrCa	111.9061	80.89	+37E3	- RbO2	TT0.02775	< 1 • 1 Z		os Cu2	125.85918	47.73	-2017
80	111 00000	40 36	+3552	103 RhŌ	118.89946	99.76	-32E3	1235 0	125 86525	00.65	-3260
100002	TTT. 20052	77.20		110-		00 -0		re20			
+00MoC	111.90651	09.52	+2253	÷∸° Sn	110.90315	00.50		° [™] MoO>	125.89574	09.00	-16E3
28 4	111 00770	72-30	+24E3	1194-0	118 00111	10.72	+9283	947-0	125 80711	17.32	-20 83
40		72.52	10000	MOU2		±2.15		110102		きん・イラ	
~~Ca202	111.91554	92 <b>.5</b> 0	+0901	+0" AgC	118.90483	50.78	+(155	++°CdO	125.59820	12.36	-2253
48 11 1 1	111.92759	73.27	+4562	55Mnn	118.01760	99.04	+8178	110 PAO	125.89938	11.78	-28E3
*64 7 ~ ~		16 70	Lunn	238		66°	- dei	128			- 20-2
~~ZnC4	TTT•75(26	40.0		~ J O U2	LLY.0245	770214	- 70I	÷€°CdC	125.90355	20.60	- 29 54
³² S=0a	111.92887	89.60	+4336	120		11 01	2010	128R1C-	125.90373	31.28	-90E4
				- Niz	119.06154	11.94	-2777	12 8m-	125 00287	18 71	
				-				T.e	10/05+70/01		

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12 600	125 00397	18 71		1 4 -	177 25001	10 00	0510	14104	10 85031	02 63	-2555
114900	125 20320	00 65	14025	87 m	122.35091	10.50	-2510	9311-0	140.09274	20.22	-2250
907-0	125.90 00	10.77	+0750	~j_n₂	137.35423	00.17	-2680		140.59059	19.20	1153
12 Arts	125.90435	49.11	+27 5.4	110 7-2C2	133.87155	10.43	-4094	125 AgU2	140.09441	40.42	1957
102 DIG	125.90445	00.09	+2224	⁵⁵ Mn ₂ C ₂	133.87610	97.80	-4757	141	140.59952	05.70	-1062
PdC2	125.90406	00.94	+1254	102 Ru02	133.89353	31.46	-13E3	f SnC2	140.9051	07.19	-2422
- J- C2 1	125.00000	(9•⊥4	+1010	³⁶ SrO ₃	133.89410	09.79	-13E3	12 TeC	140.90555	21.44	
⁹⁵ MoO2	126.89424	10.71	-12EB	118 SnO	133.39696	23.97	-18E3	SSN6C4	140.,0555	90.00	-(10)
111CdO	126.80919	12.72	-23EF	¹²² TeC	133.9029	02.43	-99E3	141 Pr	140.90743	100.00	
115 SnC	126,90335	00.35	- 27 मई	110 CdCa	133.90329	12.12	-14E4	140CeH	140.91310	38.47	+25E3
115 TnC	126.00361	94.66	-1274	122 SnC	133,00346	04.67	$-17 \pm 4$	142 7	141 34558	11 23	-2227
103 BhCa	126.90455	57. Sõ	-7295	134 _{B2}	133 00425	02 12		xe2	141.JC	-1	-2227
127 7	126 00466	100.00		110 010	177 00427	11		144Tis	141.54853	14.51	-2335
127720	126 00532	12 52	10F4	Bee e	100.90447	11.55	+6124	' ¹ Ga ₂	141.84964	15.68	-2379
63 0.00	126 00023	68 <u>1</u> 3	12853	sec. o	122.90925	09.42	+2613	110 Fee0a	141.86137	10.62	-2961
254 22	127 00335	02 085	1296	1340	172.91275	00.45	+1(E)	⁵⁵ Mn ₂ 0 ₂	141.86592	99.52	-3271
647n	127 85502	23 21	-2527	011	194.006/0	00.611	+1207	107 AgCl	141.87368	38.78	-3984
128 0.	107 85737	20.91	0855	135~02	134.85200	01.53	-2519	⁹⁴ ZrÕ3	141.89237	17.27	-8382
	127.05727	42.11	-2000	87 SrO-	134 80372	06.07	_1153	110 Cd02	141.89309	12.33	-8754
⁵⁶ Fe ₂ O	127.35879	83.81	-2735	87 800-	134 80403	27 65	-1283	¹¹⁰ Pd0 ₂	141.39427	11.75	-9442
¹²⁸ Ca ₃	127.33053	00.64	-5112	103 500-	134 80435		-1253	^{12 a} TeO	141.89878	13.65	-14E3
52 Cr2 C2	127.88102	68.61	-5214	119 0-0		27•J2	1007	142 SnC2	141.00205	23.67	-20E3
^{9 6} MoO ₂	127.89476	16.45	-12E3	123010	174.09006	00.56	-1057	130 BaC	141,90623	00.100	-46E3
9 °Ru02	127.8985	05.48	-18E3	135616	124.90410	42.20	-90E2	130 TeC	141,90695	34.10	-60E3
112Cd0	127.89797	23.95	-17E3	LOO CAC2	194.90420	T5.90	-1124	142 _{Nd}	141.90748	27.11	-78E3
⁹ €ZrC₂	127.89910	02.79	-20E3	135 Ea	134.90555	06.59		947rC4	141.90764	16.64	-86E3
112 Sn0	127.9000	00.95	-23E3	27A15	134.90770	100.00	+63E3	142 0	141.00030	11.07	
116SnC	127,90219	14 14	-38E3	68 7	175 84070	oz he	01.87		1 1. 0		- 1
104 PdCa	127,90329	10.73	-56E3	1127. 0	155.04912	02.45	-2407	IZ IO	142.89957	99.76	-14E3
128 Xe	127.90351	01.917	-6323	40 0 - 0	2122.06500	02.20	-2226	5 SnC2	142.90315	02.92	-22E3
104 R110-	127,90422	18.17	-GÁES	T CagO	1000267	90.12	-0203	143Nd	142.90958	12.17	
128 ZrCa	127.00467	16.91	-1554	Se SrOg	125.39082	ST.96	-1083	142NdH	142.91530	27.11	+25E3
116 ₀₄₀	127 00400	07.50	-2354	10 FPdO2	135.89308	10.92	-12E2	¹⁴² CeH	142.91712	11.07	+19E3
1280-	107 00555	31 70		$104 \text{RuO}_2$	135.89402	18.49	-1353	7200	1/12 8/1218	07 50	-2160
40 a - 0	127.90000	21.19	100 23	120 Sn0	135.89711	32.77	-19E <u>3</u>	144m2	147.04710	11.17	2182
10 Ca203	T51.90330	92.10	+2950	¹²⁰ TeO	135.89940	00.089	-27 E3	1447.	142.04200	22 51	-5105
97100	108 80201		1077	124TeJ	135.89898	04.56	-25E3	Je2	142.04499	22·91	-2220
113700	128 90001	00.07		136CdC2	135.90306	23.82	-10E4	3°Fe202	143.555/0	32.6L	-2565
113240	108 90027	10 07	-2020	¹³⁶ Ba	135.90437	07.81		Agci	143.57346	12.57	-2682
129 0. 0	120.09997	12.20	-2452	ll2SnC2	135.9051	00.94	+19 E4	to Ca3C2	147.88776	38.35	-6522
129	120.9051	07.69	-(942	124SnC	135.90524	05.87	+16E4	112CdO2	143.39286	23.95	-8495
129 D 10	125.904/4	25.44		¹³⁶ SrC ₄	135.90610	79.26	+79E3	12°TeO	143.90046	31.70	-15E3
PaC2	128.90482	51.98	+1655	¹³⁶ Ce	135.90707	00.193	+50E7	111 SnC2	143.9022	32.32	-19E3
NbCa	128,90764	96.72	+4523	¹³⁶ Xe	135,90721	08.87	+48E3	13Z BaC	143.90512	00.096	-31E3
~′Al ₃ O ₃	128,92935	99.23	+5233	137	170 00075		7 7 7 0	144Nd	143.90980	23.35	
130-	100 Pellon	07 00	01 50	101 Hez Ca	2106.06735	05.77	-2532	<u>1</u> 4 4 Sm	143.91185	03.09	+78E3
EE.	129.35401	27.20	-2452	ag Yog	136.39042	99.28	-9037	27A14C3	143.92616	26.72	+8800
Jug	129.35556	09.55	-2228	105 Pd02	136.89462	22.12	-13E3	C15	100000	57.46	+1595
³ MoO ₂	129.39578	23.67	-12E3	121SbO	136.89862	57.11	-20E3	145710	144.24377	10.78	-2122
114CdO	129.39846	28.79	-15E3	¹¹³ InC ₂	136.90430	04 <b>.1</b> 9	-11E ⁴	145 200	144,84403	04.15	-2159
114Sn0	129.3983	00.66	-18E3	137 CdC2	136.90446	12.52	-1254	113 700-	122 83210	04 26	-80.60
¹³⁰ SnC	129.90205	23.92	-27 E3	137 TeC	156.90462	06.96	-14E4	113040-	100 37036	12 20	-8141
130 Pd C2	129.90291	27.22	-32 E3	137 Ba	136.90557	11.32		121ch/2	122.0 220	55 00	-1753
¹³⁰ Хе	129.90350	04.08	-37E3					133720	144 00513	22.22	-2123
10 °CdC2	129,90593	01.19	-13E ¹	59 Ga2	137.35142	36.48	-2530	- 45		90.09	
¹³⁰ Ba -	129.90823	00.1Ĉ1	-13E4	ZrOg	137.33906	51.09	-3717	= 10 IId	144.91208	05.30	
¹³⁰ Te	129.90695	34.43		- PdO ₂	137.59271	27.20	-1233	145 712	145.00335	11.78	+1587
94ZrCa	120.90764	13.83	+19E4	ty 20d0a	137.39573	01.21	-15E3	148-1	a 1 = 21 0 00		2007
131~	170 37710		0.000	tffTeO	137.99781	02.45	-20E3	1480-	1 2 . 2 . 0	07.04	-2027
10 1	100.00010	JUZ	-2519	tffSn0	137.39837	04.71	-21E3	1021227	+-2· *-27	22.32	-2001
Z RuO2	130.39505	12.66	-14E3	130CdC2	137.90355	23.49	-10E4	114040	- Teb. 105T		-2-22
115 SnO	130.39326	00.35	-19E5	137TeC	137.90387	13.55	-14E4	132 - 0202		20. 2	-,2-2
113 InO	170.39852	22.40	-20E3	-14SnC2	137.9039	00.65	-14E4	1307-0	1-2.50130 1-2.50130		-1222
131SnC	130.90315	03.73	-68E2	$g_0 ZrC_4$	137.90433	49.22	-25E4	122-00	142.90100	24.20	-1422
131 AgC2	130.90485	20.25	-25252	¹³⁸ Ba	137.90488	71.66		122000	1 = 50352	02.41	-1922
Xe	130.90508	21.13		¹³⁸ Ce	137.90603	00.25	+1254	1345.0	1-7.10.40	04.02	-1020
1327n-	131,35080	25 80	-2522	138 La	137.90674	00.039	+7+E3	==================================	1,5 01045	02+29 17 00	-エ(コン
40 00 0	131 92776	20.27	-7508	317 0	170 20000		0.05.0	d	1-2.41269	T1.55	
100 p	171 8010	J7•)4 10 = 0	-1000 -1722	ĭ †∠rOg	T22.20005	11.14	- : : : : : : : : : : : : : : : : : : :	17512	1-8.00670	00.725	+1552
100100	121 80071	12.50		123 AU02	158.89463	51.10	-1422	147742	148.94081	01.30	-1989
116002	171 90710		-1027 1077	123500	138.89909	42.02	-56.57	147 200	748, 2447E	05.57	-2094
116040	171 20000	14.21		12°TeO	135.8992	00.87	-20E2	115 Tr.O.	148.30741	25.26	- 69 69
1320-0	171.099990	20 23	16722	1 SnC2	138.90335	00.25	-52=2	123576	148.00419	41.B1	-1423
108 040	171 00220	22.50		113 InCa	138.90361	93.61	-57 E2	147 BaC	148.00555	06.55	-1653
108 040	131 20107	20.12	-00 ±5	139 IC	138.90466	98.89	-1024	134 ta 13	d 46.20760	00.026	-21E3
132V2	131 00016	26.30	-1/24 1//24	139 TC4	158.90532	12.94	-20 E4	2741=C	146.00770	28.39	-2253
120mar	131 00000	20.09	ーエッジャ - フィント	139 La	120.90603	99.911		147 cm	146 01440	14 07	/
132-	1)1.90449	00.037		тгг∋ан	138.91540	71.65	+20E3	147 0	1 7 01002	20.007	. 1677
Ba	191.90512	00.097		⁷⁰ Gep	139.34798	04.21	-2442	C12	T+1:0T003	00.027	+100%
- S1303	121.91552	77.33	+15E3	140 345	139.35053	47.84	-2555	148Tia	147.33752	00.68	-1874
- Al ₄ C ₂	191.92616	97.80	+6269	140	139 85321	01 40	-2697	148 Geo	147.34200	17.81	-1987
C ₁₁	795.00000	80 <b>.</b> 45	+1390	28312	139.88465	66 66	-6733	5 6 7 6 2 Ca	147.86388	31.26	-2317
1337n-	132.85318	02.29	-2558	923r0a	179,33040	16.00	-8810	118Sn0a	1-7.39199	14.23	-6045
1010.0	130 8018	16.00	 _1 3 5 3	103 240-	139, 99327	26 68	-1253	1130405	147.39479	07.54	-6826
85phA	130 2069	10.77 71 67	-1683	124TeO	139,89803	04 É8		124TeC-	147.39898	00.139	-8462
117 0003	132 80801	$1 \pm 0 = 0 = 0$	-1057	1245n0	139,90015	05.03	-1959 -2753	132Ba0	147.90003	00.097	-9000
13300	132 00513	100 00	-1767	11eSnC-	139,90219	13.00	-45 23	148 EaC	147.00437	07.79	-12E3
109/ -7	130 00/21	100.00 17 28	-26Fh	1407-0				135 _{Ba} ĭ3	c 47.90891	00.07	-20E3
B5 pr a	130 01000	-1.50 60 01		116020	170 00467	16.34	-23E4	124 SnC-	147.90524	05.81	-13E3
85 0 4	130 01608	11 00		14000	130 00E0P	07.41 gg 10	-4024	138CeC	147.90707	00.191	-16E3
1337	172 · 7100		+1353	128 Ter	130 00555	31 11	15050	¹⁴⁸ Sm	147.01442	11.24	-73E3
611		10.90	1-10-1	139 _{1.2} H		00 00	T7254	148Nd	147.91646	05.73	
				27 41.00	Louvaroite	DProtori	TLOL)			-	
				···⊥4∪29	MIN MULDHY U	110001	いーエフトレフ				



149Ge2	148.84463	01.20	-2063								
^{as} Rb0₄	148.89170	71.46	-5933	12.0	0.			144 cmC	167 01165	03.00	87.00
117 SnO2	148.89290	07.57	-6230	TeO2	157.89367	18.62	-5139	156D.C	167.91105	09.02	-0169
¹³³ CsO	148.90004	99.76	-8885	NdO	157.90239	27.04	-7175	152 Sm()	167 01427	26 66	-9990
149 TeC2	148.90462	06.94	-12E3	134 CeO	157.90421	11.04	-7822	152040	167.01434		-1057
¹ ³ BaC	148.90557	11.28	-13E3	158N4C	157.90425	02.37	-7837	168GdC	167.92226	20.40	-21E3
149 BaC	148.90772	00.086	-16E3		157.91269	17.12	-14E3	168 Er	167.9308	27.07	
149 Sm	148.91680	13.83		158 CH	157.92401	00.09	-4124	168 Yh	167.93390	00.135	+54E3
150 Geo	149.84229	05.67	-1909	158 g	157.9244	24.87		12 C14	168.00000	85.55	+2427
75A50	149.84342	100.00	-1937	13	150.000005	00.847	+2000	1 49 -			
865r04	149.38899	09.77	-4712	158 Cr3	158.82003	01.23	-1516	137 Fea	168.79929	05.52	-1251
134 BaO	149.89916	02.35	-6921	¹⁵⁹ Se ₂	158.83661	01.39	-1800	169 BaO2	168,89537	11.27	-4225
150 TeCa	149,90387	18.45	-8845	143 NdO	158.90449	12.14	-7794	NdC2	168.91206	08.64	-7582
150 BaC	149.90488	71.00	-0405	159 BaC2	158.90555	06.50	-8221	¹⁵⁵ EuO	168.91551	52.05	-8972
138 CeC	149,90603	00.25	-1053	147 SmC	158.91449	14.80	-15E3	+ °° GdC	168.9241	15.74	-17 E3
138 TaC	149,90674	00.088	-1153	159Tb	158.92488	100.00		105 Tm	168.93434	100.00	
150 Sm	149.91690	07.44	-3883	¹⁵⁹ C13	159.01008	00.038	+1865	189C14	169.00335	13.42	+2448
150 Nd	149.92082	05.62		160 0 -	150 9700%		1 40 4	170 Fee	169.80319	00.96	-1287
87	1,9,9,2002	0.02		160 0	159.02294	29.14	-1696	170 Sra	169.82260	00.11	-1504
Sr04	150.88863	06.95	-4883	5 6 T 0		49.99	-1751	85 Rh2	169.82404	52.06	-1527
° RbO4	150.88894	27.58	-4932	1280-0	150 8575	02.41	-2025	138 BaOa	169.89468	71.32	-4157
115 Sn02	150.89295	08.54	-5676	160 2002	159.0595	07 79	~21(0	138 CeO2	169.89585	00.25	-4275
135Ba0	150.90046	06.57	-7909	144 140	150 00/77	07.70	-7000	138 La02	169.89654	00.089	-4351
<td>150.90261</td> <td>99.76</td> <td>-8914</td> <td>1440-0</td> <td>159.904//</td> <td>22.19</td> <td></td> <td>134 BaCa</td> <td>169.90425</td> <td>02.34</td> <td>-5421</td>	150.90261	99.76	-8914	1440-0	159.904//	22.19		134 BaCa	169.90425	02.34	-5421
$I_2^{IC_2}$	150.90466	97.80	-10E3	1380-0	150 00707	09.00		146NdCa	169.91269	16.84	-7418
191BaC	150.90824	00.79	-13E3	160 0-0	150 01/00	11 00	-/941	154Gd0	169.91585	02.14	-8604
- ⁻ Eu	150.91954	47.82		148 Mag	150 016/6	11.29	-1252	154 SmO	169.91684	22.66	-9058
152 Cra	151.83261	00.47	-1751	160	150 0030	02.00	-1353	158 DVC	169.924	00.089	-15E3
15256	151.83856	01.22	-1880	160 04	150 00701	21 00		170 GdC	169.9244	24.76	-15E3
40 Can	151.87758	89.91	-3636	da	109.96761	21.90		170 Yb	169.934/	03.03	-11E4
885r0.	151.88574	81.77	-4519	161 BaC2	160.90557	11.36	-7994	170 Er	169.9356	14.88	
120 Sn0-	151.89200	32.60	-5553	145NdO	160.90697	08.28	-8592	170 C14	170.00670	00.977	+2390
136Ba0	151.89928	07.79	-7566	1 SmC	160 <b>.916</b> 8	13.80	-18E3	171	170 8000	00 070	_1=07
140 CeC	151.90528	87.50	-11E3	181Dy	160.9257	18.88		1397.0	170 80587	00.019	-1000
128 TeC-	151.90555	31.09	-11E3	81pr-	161 8308h	24 47	-1746	171B-0	170 00555	71.47 06 15	-+205
152 Jac	151.90938	01.106	-15E3	16250-	161 83310	00 15	-1751	147 cmC	170.90555	11 61	
152 Sm	151.91936	26.72		130 800-	161 80603	00 101	-5476	155040	170.91449	14.04	-1941
152 GA	151,91943	00.20	+20 E5	130 ToO2	161 80675	34 31	-5613	159 mb C	170.91/01	14.09	-9293
		00.20		27 1 1 27	161 88024	100.00	-1453	17117	170.92400	90.09	-1262
153Se2	152.83926	01.37	-1880	162800-	161 00488	70.33	-7815	1710	171 01008		10307
SSY04	152.88536	99.04	-4339	138000	161.90400	00.245	-8274	014	1/1.01000	00.044	+2301
121Sb02	152.89351	56.97	-5645	162 SmC	161.9169	07.51	-1983	172 Sr2	171.81935	01.90	-1621
- BaO	152.90048	11.29	-7600	150 NdC	161.92082	05.56	-34E3	172 Rb2	171.82132	40.19	-1655
153 PrC	152.90748	98.89	-12E3	162 DV	161.9256	25.53		140 CeO2	171.89508	88.05	-5705
153	152.90065	00.979	-1969	162 Er	161.92873	00.136	+52E3	170 DyC	171.9239	02.27	-1354
ш	192.9200	92.10		1637.0	1 (0, 0080)	01 67	9770	156D o	171.90437	07.76	-8254
$^{154}Cr_3$	153.82707	09.07	-1623	1387.0	162.90024	01.5/		130Dy0	171.909	00.052	-1123
156Se2	153.83667	05.68	-1805	147 cup	162.90605	99.71	-7004	1/2 SmC2	171.91442	11.31	-16E3
⁹⁰ ZrO ₄	153.88397	50.97	-4055	151 m.g	162.90940	14.92	-0075	1 NdC2	171.91646	05.60	-20E3
¹²² TeO ₂	153.8927	02.45	-5266	163p.	162.91924	41.29	-2069		171.91717	20.42	-21E
¹²² SnO ₂	153.8933	04.70	-5376	Dy	102.9210	27.91			171.92721	21.66	-86E)
138 BaO	153.89979	71.49	-6952	164Fe3	163.81415	00.93	-1434	TY TYD	171.9252/	51.95	
138 LaO	153.90165	00.089	-7590	164Se2	163.83326	00.84	-1721	173 Sr2	172.81834	01.38	-1445
130 D 0	153.90094	00.25	-(222)	132 BaO2	163.89492	00.097	-4882	141 Pr02	172.89728	99.52	-4247
130 BaC2	153.90625	00.099	-9004	140 CeC2	163.90528	86.53	-7060	¹⁷³ BaC ₃	172.90557	11.20	-5333
142 TeC2	153.90695	22.62	-10E3	148 SmO	163.90933	11.21	-8551	173SmC2	172.9168	13.78	-8157
142 NdC	153.90748	56.9T	-1153	148NdO	163.91138	05.72	-9575	157 Gd0	172.91901	15.64	-9107
15401	153.9095	10.95	-12E)	152 SmC	163.91936	26.42	-18E3	173DyC	172.9257	18.70	-14E3
1540	153.92094	02.15	-1014	152GdC	163.91943	00.198	-18E3	173 Yb	172.938/	16.13	
10 Sm	122.95132	55.(1		164Dy	163.9285	28.18		58 M.	173 80605	77 11	nligg
155Cr3	154.82721	02.07	-1622	¹ ⁶ ⁴ Er	163.9298	01.56	<b>+</b> 13E3	174920	173 81545	16.77	-1570
155Se2	154.83737	03.56	-1816	55 _{Mna}	164.81415	100.00	-1435	174 Rh-	173.81860	07.76	-1625
⁹¹ Zr04	154.88496	11.11	-4105	133C602	164.89493	99.52	-4827	142 NdO-	173.89728	26.98	-6141
123Sb02	154.39398	42.54	-5394	141 PrC-	164.90748	97.80	-7629	142 CeO-	173.8991	11.02	-6567
¹³⁹ La0	154.90094	99.67	-7120	1 49 SmO	164.91171	13.80	-9484	17 4 Ba C-	173.90488	69.68	-8301
-Jong NgC	154.90958	12.30	-12 <u>E3</u>	153 EuC	164.9206	51.60	-19E3	174 SmC-	173.9169	07.58	-20E3
122CeC	154.91265	00.123	-15E3	1850-0	161 00861	01 04	-8061	158Dv0	173.919	00.09	-26E
TP2 GG	154.9227	14.73		- CeC2	104.90004	01.94	-000 ¹	158 <u>Gd</u> 0	173.91931	24.8í	-28E
158 Cr-	155,82153	59.40	-1548	- Of Ho	164.9291	TOO.00		150 NdC-	173.92082	05.50	-36E
15856	155,83575	14.68	-1802	166FPA	165-80340	14.67	-1325	174DyC	173.9256	25. ⁴ 6	INF.
927r0.	155,88431	16.05	-4108	134 Ran-	165.80405	02.41	-4780	17 4 YĎ	173.9256	3 <b>1.</b> 84	
40 Ca-C-	155,88776	87.37	-4510	142 NAC-	165.90748	26.51	-7819	¹⁶² ErC	173.92873	00.134	+56E3
124TeOr	155.88878	04 59	-4657	142 CeC-	165.90930	10.83	-8553	174Hf	173.939	00.18	+13E3
124 Sn0-	155.89504	05.91	-5728	150 SmO	165.91181	07.42	-9824	1750-	174 81500	11 50	-1 270
132 Ba.C-	155.90512	00.095	-9097	150 NdO	165.91573	05.61	-13E3	143NAA	174 80038	12 11	-12/0
15 eNdC	155.9098	23.72	-13E3	154GdC	165.92094	02.13	-21E3	1397.002	174 20603	75.77	-78en
144SmC	155.91165	03.06	-15E3	154SmC	165.92193	22.46	-44E3	151 E. C-	174,01054	46.77	-7780
15 eGd	155.92226	20.47		leeEr	165.9287	33.41		159 mh0	174,01070	99.76	-7877
156C13	156.00000	86.49	+2006	187 -	166 80005	00.70	-1385	175DvC	174.9278	24.97	-1283
157	156 80107	20 10	_1530	135 Ran-	166.80535	06.56	-4740	175 Lu	174.942/	97.41	
0r3	156 8301C	20.10	-1700	1 67 NAC-	166.00059	12 40	-7979	17 8		77 00	
93NTLO	156 98570		-1077	167 CaC-	166-01265	00.242	-9352	1760	175.50147	2(.66	-1246
125004	156 800000	77.04	-5287	1515.0	166 Q144F	47.70	-1053	144	T(2.01505	PO.TE	-1346
1330-0	156 00517	00.90	-9207	1 87 240	166-0227	14 50	-2183		1/5.0996	22.14	-4080
1410-0	156,00230	99.76	-7228	1 67 Er	166.9305	22.04	/	140 C-C	175 00500	07.00 85 57	-4263
145 NAC	156.91206	08.47	-15E3	1 68 -				160 770	175 01881	00.01	-+099
157 Gd	156.9241	15.68		28 CFe3	Tel. 19265	11.12	-1244	152 cm C	175 01036	26 13	-7530
157 Či 3	157.00335	12.60	+1980	4000	167 87200	20.00	-2420	152GdC~	175.91943	20.10	-7554
1587-	157 81080	07 31	_1517	1360.0	167 90117	07.77	_1686	1 80 Gd 0	175.92212	21.85	-8541
158c	157 8338C	02 20	-1711 -1711	136000	167 80687	00.102	-4040	17 SDVC	175.9285	28.15	-12E3
79 Br-	157,83678	25 54	-1802	168 N.M.J	There and a start	f Profileri	2-700A	164 ErC	175.9298	01.54	-14E3
942.r0.	157.88728	17.23	-4257	11 W 2	$\mathcal{O}$ and $\mathcal{O}$ $\mathcal{O}$ $\mathcal{O}$ $\mathcal{O}$ $\mathcal{O}$					-	-
			・ニント								



	17 SHf 17 SLu 17 SYb	175.92212 175.9419 175.94272	05.20 02.59 12.73	-8541 -2223	173 EuO2 185 BaC4 185 DyCa	184.9140 184.90557 184.9257	51.93 11.17 18.52	-4919 -4359 -8294	193 _{CU3} 193 _{MO2} 181 _{DVO2}	192.78515 192.81042 19 <b>2.</b> 9155	19.80 10.60 18.79	-1063 -1235 -3769
	⁵⁹ CO3 177Ni3 145NdO2	175.79954 176.90179 176.90186	100.00 01.71 08.26	-1238 -1257 -4354	1 89 TmO 185 YbC 185 Re	184.9292 184.938 184.948	99.76 16.37 37.07	-9843 -19E3	169 TmC2 177 HfO 181 TaC 193 Ir	192.9343 192.9374 192.9458 192.9667/	97.80 18.46 98.88 62.7	-5956 -6586 -9233
	161Dy0 165HoC 177Hf	176.9206 176.92061 176.9291 176.9425	18.83 98.89 18.50	-5080 -8083 -13E3	¹⁸⁵ Ni ₃ ⁹³ Nb ₂ ¹⁸⁶ Zr ₂ ¹⁸⁶ Mo2	185.78501 185.81132 185.81231 185.81449	00.09 100.00 08.83 02.86	-1122 -1334 -1344 -1365	193C18 194Zn3 194M02	193.00335 193.78197 193.81094	14.99 19.95 10.49	+5265 -1070 -1273
	¹⁷⁸ N13 89Y2 146NdO2 162DYO 1542dC	177.79689 177.81144 177.90249 177.92051	19.53 100.00 17.14 25.47	-1218 -1353 -4393 -7912	138 BaO3 188 BaC4 154 GdO2 154 SmO2 188 YbC	185.88961 185.90488 185.91074 185.91173 185.9256	71.14 70.03 02.14 22.60 31.67	-3044 -4058 -4653 -4772 -7408	194 Ruz 162 DyOz 170 YbCz 170 ErCz 178 HfO	193.86270 193.9154 193.934 193.9356 193.9379	00.21 25.41 02.96 14.55 27.07	-1928 -4049 -6620 -7002 -7636
	154SmC2 162ErO 166ErC 175U6	177.92193 177.92364 177.9287	22.21 00.136 33.04	-8445 -9191 -12E3	186DyC2 162ErC2 170YD0 170Er0	185.9256 185.92873 185.9290 185.9356	25.38 00.133 03.02 14.84	-7408 -8464 -8569 -12E3	182WC 194Pt 194C16	193.9460 193.9633/ 194.00670	26.12 32.9 01.26	-11E3 +4469
	179 _{Ni3} 147 _{SmO2} 179 _{3dCa}	178.79720 178.90429 178.9227	27.14 01.30 14.90 14.73	-1209 -4374 -7953	174HfC 186W 186OS	185.939 185.9507 185.952	00.18 28.41 01.59	-16E3 +14E4	195 MO2 195 Ru2 183 DyO2 195 Yb C-	194.73506 194.81219 194.81475 194.91760	02.95 07.53 01.40 24.85	-1067 -1266 -1237 -4012
	163 DyO 179 ErC 179 Hf	178.92271 178.9305 178.9452	24.86 23.05 13.75	-7957 -12E3	187 M02 187 Zr2 139 LaO3 155 GdOa	186.78738 186.81299 186.81462 186.89076	00.003 04.98 00.63 99.19	-1129 -1335 -1351 -3004 -4516	179HfO 195WC 195Pt 195C18	194.9401 194.9401 194.9481 194.9662/ 195.01008	14.08 13.72 14.53 33.8 00.066	-9490 -7470 -11E3 
	100 N13 90 Zr2 148 SmO2 148 NdO2 180 GdC2	179.79446 179.80866 179.90422 179.9065 179.92226	07.37 26.48 26.48 05.70 20.34	-1187 -1309 -4297 -4544 -7548	187 DyC2 171 Yb0 175 LuC 187 Re	186.9278 186.9310 186.942 186.953/	24.98 14.28 96.33 62.93	-7419 -8498 -17E3	198Zn3 198M02 198Ru2 28S17	195.78078 195.81196 195.31370	24.65 08.84 01.43	-1052 -1263 -1277 -1524
	164 DyO 164 ErO 180 ErC 168 YbC 180 W	179.92341 179.92471 179.9308 179.9339	28.11 01.56 27.02 00.134	-7931 -8413 -12E3 -15E3	188Nis 188Nis 188Zr2 188Mo2	186.956/ 187.78463 187.81528 187.81188	01.64 00.014 03.99 06.05	+62E3 -1091 -1327 -1311	164 ErO2 164 DyO2 196 YbC2 180 WO	195.91960 195.92340 195.9252 195.9394	01.55 23.04 21.35 00.135	-4126 -4484 -4677 -7075
	180 Ta 180 Hf 12 C15	179.945/ 179.945/ 179.9461 180.00000	00.012 35.24 84.58	-16E4 -13339	140 CeC4 156GdO2 172YbO 188 DyCa	187.90528 187.91206 187.9201 187.9285	84.63 20.37 21.76 28.11	-2010 -3641 -4192 -5108 -6618	180 TaO 1840sC 196WC 196Hg	195.9410 195.9399 195.946/ 195.9489 195.96583	00.012 00.018 30.46 00.146	-7205 -9288 -1123 -1524
	1812r2 149SmO2 165H00 1813dC2	130.79262 130.30965 130.9066 180.9241 180.9241	00.43 11.56 13.76 99.76 15.78	-1181 -1329 -4616 -8339 -8339	164 ErC2 176HfC 188 LuC 176YbC	187.9298 187.9408 187.9419 187.94272	01.53 05.14 03.64 12.59	-6936 -12E3 -13E3 -13E3	19 SPt 197 Zn3 197 MO2 197 Ru2	195.9671/ 196.78115 196.81272 196.81370	25.3 03.35 01.82 02.36	-1059 -1275 -1283
	169 TmC 181 Ta 181 C15 182 N4	180.9343 180.9458 181.00335	98.89 98.988 14.22	-16E3 +3144	⁶³ Cu ₃ ¹⁸⁹ MO ₂ ²⁷ Alz	187.9569 188.78877 188.81476 188.87078	02.59 32.98 05.84	-1113 -1315 -2154	¹⁹⁷ Si7 185H002 197 YbC2 181Ta0	196.83806 196.9189 196.938/ 196.9407	20.22 99.52 15.24 99.747	-1525 -4078 -6745 -7432
	182Zr2 134BaO3 134BaC4 150SmO2	191.90907 191.90900 181.88898 191.90425 191.90670	13.87 02.40 02.31 07.40	-1328 -3191 -4358 -4630	157 GdO2 185 HOC2 173 YbO 189 HfC	188.91390 188.9291 188.9330 188.9425	15.60 97.30 16.09 18.36	-4237 -6427 -7410 -1223	198 Zn3 198 Ru2	196.9672 196.9672 197.77814 197.81243	100.00 17.99 05.57	-1062 -1298
	150 NdO2 165ErO 182 GdC2 170 YbC	131.91062 181.92361 181.924 181.934/	05.59 33.33 24.66 03.00	-5143 -8126 -8270 -15E3	¹⁹⁰ Nis 190Mo2 1907ra	188.9585 189.78425 189.31453 189.81694	16.1 00.001 12.99	-1057 -1271 -1291	198517 198517 134BaO4 185ErO2 199VbC-	197.81249 197.83533 197.88390 197.9185	04.00 16.39 02.40 33.25	-1301 -1531 -2453 -4294
	182 ₀ 182 ₀ 183 ₂ 272	191.9356 191.9460 182.00670 182.80999	14.72 26.41 1.115 03.84	-18E3  +2997 -1325	158Gd02 174Yb0 188ErC2 174Hf0	189.9142 189.9205 189.9287 189.9339	24.75 31.76 32.67 00.18	-3815 -4367 -5381 -6311	174HfC2 182WO 186WC 186OSC	197.939/ 197.9409 197.9507 197.952/	00.75 26.65 28.10 01.57	-7735 -8353 -1453 -1653
	183 Nis 135 BaO3 182 BaC4 159 TbC2	132.79019 182.89028 182.90555 182.92488	00.12 06.54 06.40 97.80	-1159 -3164 -4300 -7879	190 HfC 190 Pt 191 Cu3	189.9430 189.964 190.78696	27.04 00.013 44.26	-9046 	198 Pt 198 Hg 199 Zng 199 Pul-	197.9646 197.96675 198.77996	07.21 10.02 03.19	+9223
	187 ErO 183 YbC 183 W 183 C ₁₅	182.92541 182.9360 182.9481 183.01008	22.88 14.18 14.40 00.054	-8063 -15E3  +2952	159 TbO2 191 ErC2 175 LuO 191 HfC	190.80940 190.91468 190.9305 190.9369	06.91 99.52 23.16 97.18 13.90	-1240 -3920 -5804 -7206 -1153	199 S17 135 BaO4 167 ErO2 175 LuC2	198.83489 198.88519 198.9203 198.942/	04.33 06.53 22.83 95.27	-1492 -2397 -4152 -7588
	¹⁸⁴ Ni ₃ ¹⁸⁴ Zr ₂ ¹⁸⁴ MO ₂ ¹³⁶ BaO ₃	183.78744 183.80934 183.31710 183.88910	00.49 20.83 02.51 07.75	-1139 -1318 -1396 -3076	⁶⁴ Zn ₃ ¹⁹² MO2	190.9634 191.78388 191.81192	37.3 11.69 13.05	-1077 -1277	193W0 187 ReC 187 OsC 199 Hg	198.9430 198.953/ 198.956/ 198.96822	14.33 62.23 01.62 16.84	-7889 -13E3 -16E3
•	160 BaC4 160 DyC2 152 SmO2 184 YbC 168 FrO	183.90437 183.9239 183.90916 183.9252 183.9257	07.73 02.24 26.59 21.74 27.00	-4131 -7358 -4629 -7762 -7932	¹⁹² Ru2 ¹⁶⁰ DyO2 ¹⁶⁰ GdO2 ¹⁹² ErC2	191.81860 191.81740 191.9137 191.91703 191.9308	00.078 00.31 02.28 21.30 26.97	-1337 -1326 -3958 -4250 -6113	200Zn3 200Ru2 200M02 200S17	199.77696 199.81110 199.81302 199.83216	10.01 09.16 00.93 01.37	-1045 -1263 -1288 -1469
	160 GdC2 168 Yb0 1840s 184W	183.92721 183.9288 183.946 183.9489	21.41 00.135 00.018 30.64	-8481 -9156 -63E3	168YbC2 176Hf0 176Lu0 176Yb0	191.9339 191.9357 191.9368 191.9376	00.132 05.19 02.58 12.70	-6783 -7244 -7558 -7803	¹³⁶ BaO4 168 ErO2 176 HfC2 200 LuC2 176 VLC	199.88401 199.92060 199.9408 199.9419	07.73 26.94 05.09 04.56	-2371 -4190 -7264 -7317
	185Ni3 185Zr2 137BaO3	184.78776 184.81296 184.89030	00.03 03.91 11.24	-1154 -1370 -3205	180WC 180TaC 192HfC 192Os 192P <del>+</del>	191.9445 191.945 191.9461 191.9622	00.134 00.012 35.00 41.0	-11E3 -11E3 -12E3 -12E3	-1002 1840s0 184W0 1880sC 200Hg	199.9409 199.9409 199.9438 199.9569 199.96833	12.45 00.018 30.57 13.2 22.13	-7290 -7290 -8152 -1823
					¹² C ₁₈	117561218 Ot	Riefdus	+5078	<b>-</b> -		-	



201Zn3 201Ru2 137Ba0 169Tm0 201HfC	200.77805 200.80978 4 200.88521 2 200.9241 2 200.9425	01.36 12.35 11.21 99.52 18.20	-1045 -1252 -2362 -4351 -7232	1880sCz 194Pt0 198PtC 211HgC	209.952 209.9582 209.9646 209.96675	01.55 32.8 07.13 16.76	-34E3  +33E3 +25E3	232 Sn2 232 Cd2 232 PbC2 232 Th	231.80638 231.80998 231.97665 232.0380	03.05 00.57 51.6 100.00	-1002 -1018 -3782
2010sC 201Hg	200.943/ 200.9585 200.97209	36.98 16.0 13.22	-7364 -17E3	187 ReC2 195 PtO 199 HgC	210.80773 210.953 210.9611 210.96822	12.15 61.54 33.7	-1376 -27E3	²³³ Sn ₂ ²⁰⁹ B1C ₂ ²³⁴ Sn ₂	232.80529 232.97934 233.80424	02.46 97.80 08.04	+1338 - 991
²⁰² Zn ₃ 202 Ru ₂ 138 BaO4	201.77577 201.8087 201.88452	03.45 11.58 70.97	-1037 -1247 -2346	212 Pd2 180 HfO2 196 P+0	211.80582 211.9359	13.55 35.07	-1357 -8121	234U 235 Sn2 23511	234.0403 234.80515 235.0428	00.0056	; - <u>-</u> - - 989
170 Yb02 170 Er05	201.9238	03.03	-4313	212HgC	211.96833	23.06	+34E3	238Sn2	235.80439	16.65	
202 HfC2	201.9430	26.95	-7311	213Pd2	212.80829	11.88	-1385	237 Sn2	236,80530	09.16	-1497
²⁰² 0sC	201.9456	28.35 26.3	-8071 -13E3	197 Au0	212.9 <i>3</i> 56 212.9621	99•51 99•76	-8036	²⁰⁸ T10 ₂	236.9636	70.20	
≥°≃Hg	201.97063	29.80		²¹³ HgC 214D4	212.97029	13.33	+26E3	^{20 6} Pb02	237.96424	23.5	-2822
203 Zn3 203 Ru2	202.77685 202.8087/	00.47 15.52	-1041 -1244	214Ag2	213,80966	26.37	-1978	238U	238.0486	99.2739	)
¹⁷¹ Yb0 ₂ ²⁰³ HfC ₂	202.9258	14.24	-4403	¹⁸⁷ WO2 ¹⁹⁸ Pt0	213.9358 213.9595	26.28 02.19	-8274 -99E3	²³⁹ Sn ₂ ²⁰⁷ Pb0a	238.80535	06.40 22.5	-1490
187 ReO	202.948/	62.78	-8493	¹⁹⁸ HgO 214HgC	213.96166	10.00	+24 E3	240 Sn2	239.80440	14.76	-1227
¹⁹¹ IrC	202.9510	37.3	-9712 -24E3	215 Pd2	214.80695	05.25	-1397	²⁰⁸ Pb0 ₂ ²⁴⁰ C ₂₀	239.96645	52.0 79.99	-7154
2047.	202.9719	29.50		183WO2 199 _{H2} 0	214.9379 214.96313	14.33 16.80	-8520	241 Sn2	240.80661	01.71	-1225
204 Ru2	203.80746	14.68	-1027 -1232	203T1C	214.9719	29.17	+25E3	²⁴² C20	241.00335	17.93	
¹⁷² Yb0 ₂	203.88492 203.9150	87.63 21.71	-2314 -3512	218Pd2 218Ag2	215.80694 215.80944	13.58 49.96	-1119 -1134	242C20	241.00566 242.0067 <b>0</b>	05.98 01.91	
180WC2 180TaCa	203.9445	00.132	-7137	184W02 200Hg0	215,9387	30.49	-3524	^{2 43} Sn ₂ 2 43 C	242.80839	01.02	-1205
204HfC2	203.9461	34.76	-7560	204 PbC	215.97308	01.46	-8024	244 Sna	243.80692	04.13	
192 PtC	203.9648	40.55	-19E3 -25E3	12C18	215.97947	81.80	-0142	232 ThC	244.0380	98.89	
204 Hg	203.97308	01.48 06.85	 +52E4	217 Cd2 186WO	216.81021	00.31	-1124	232ThO 238UC	248.0329 250.0486	99.76 98.175	
¹² C ₁₇	204.00000	82.72	+7577	205T1C	216.9738	69.72	-7344	252C21 253C	252.00000	79.14	
205 Zng 205 Ru2	204.77505 204.8092	00.067 06.34	-1031 -1245	218 Cdo	217.00555	16,50		²⁵⁴ C ₂₁	254.00670	02.09	
¹⁷³ YbO ₂ ¹⁸¹ TaCa	204.9278	16.05	-4456	218 Pd2 218 A 7	217.80794	06.31	-1097	238 _{U0} - 232mb 0	254.0435	99.035	+5930
1890s0 1937.00	204.9534	16.1	-10E3	202 HgO	217.96553	29.73	-5295	238UC2	256.0300	97.00	
205T1	204.9738	70.50	-2965	^{20 8} PbC ²¹⁸ C18	217.97444 218.00670	23.3 01.571	-6758	232ThO2	264.0278	99 <b>.</b> 52	9496
20.67	205.00335	15.75	+6937	219 Cd2	218.80835	00.52	-1086	285 285 C22	265.00335	19.29	
20 6 Ru2	205.80795	11.75	-1033 -1237	203T10 219PbC	218.9668 218.97588	29.43 22.7	-5060 -6404	288C22	266.00670	02.27	
²⁰⁶ Pd2 206Rh2	205.80814 205.80910	00.21	-1239 -1246	²¹⁹ C ₁₈	219.01008	00.094		238U02	270.0384	98.796	
¹⁷⁴ YbO ₂ ¹⁸² WC ₂	205.9154	31.69 25.83	-3489 -7242	220 Pd2	219.80658	02.66 01.39	-1383 -1383				
1900s0 1940+0	205.9497	26.3	-8326	²⁰⁴ Pb0 ²⁰⁴ Hg0	219.96799 219.96838	01.48 06.83	+57 E4				
20 6 pb	205.97444	26.4	-1069	²²⁰ PbC	219.97665	52.0	+25E3				
207 D4	206.00670	01,41	+6385	205T10	220.80757	03.37 70.3	-1371				
175LuO2	206.9318	96.94	-4695	²⁰⁹ B1C	220.97934	98.89	+21E3				
191 IrO	206.9481 206.9583	14.66 37.2	-7451 -12E3	so ebo	221.00635	23.5	-1962				
²⁰⁷ PtC 207 Pb	206.9662 206.97588	33.8 22.6	-21E3	223Cd2 207 Ph0	222.80734	08.27	-1364				
207 C ₁₇	207.01008	00.079	+6052	224Cd2	223.80684	16.20	-1360				
²⁰⁸ Zn3 208Pd2	207.77554	00.002 01.73	-1034 -1223	224S18 208 ph0	223.81544	52.27	-1435				
208 Ru2 176Hf0	207.80844	03.45	-1236	75Asa	224.76513	100.00	-1076				
^{17 6} LuO ₂	207.9317	02.58	-4627	225 Cd2 20° B10	224,80783	13.26	-1352				
208WC2	207.9489	30.29	-7495	228Cd2	225.80661	17.27					
1920s0 192Pt0	207.9571	40.9	-11E3 -13E3	227 Cd2	226.80801	09.01					
²⁰⁸ PtC ²⁰⁸ Pb	207.9671 207.97665	25.37 52.3	-22E3	228 Cd2 228 In2	227.80710	08.19	-1188				
209 Pd2	208.80810	04.88	-1220	²⁰⁴ PbC2 228 _{C19}	227.97308 228.00000	01.45 80.89	-8470				
¹⁷⁷ HfO ₂ ¹⁸⁵ ReC ₂	208.9323 208.948	18.41 36.25	-4443 -6668	229 Cd2	228.80945	01.86	-1181				
193 IrO 197 Auc	208.9616	62.5	-12E3	230 To -	229.00335	01 62 17.22					
209B1	208.97934	100.00		230 Cd2	229.80854	04.38	-1161				
²¹⁰ Pd2 178Hf0-	209.80619 209.80964	11.45	-1381 -8266	231 _{PbCa}	230.00670	22.6					
18 6WC2	209.9507	27.78	-28E3	~~~ <u>~</u>	University c		ia				





# APPENDIX C

# COMPARISON OF EXPERIMENTAL ANALYTICAL DATA TO EXPECTED VALUES FOR SELECTED ELEMENTS USING VARIOUS ANALYTICAL TECHNIQUES

# Laboratory

Analytical Method

Α	Inductively	coupled	plasma	(ICP)	optical
	emission sp	ectroscop	oy (OES)	)	

- B Spark-source mass spectrometry (SSMS)
- C Inductively coupled plasma (ICP) optical emission spectroscopy (OES)
- D Atomic absorption spectroscopy (AAS)
- E Arc emission spectroscopy (AES) (AgC1 buffer)
- F Arc emission spectroscopy (AES) (NaC1 buffer)
- G Direct current emission spectroscopy

Experimental and expected values are given in the units  $\mu$ gX/gU. The dotted lines depict expected concentrations.



































# CHAPTER FIVE

# QUANTITATIVE ANALYSIS

## 5.1 Calculation Methods

The calculation method used to derive the formula for determination of relative sensitivity factors (RSF's) for impurity elements in different matrices relative to an internal standard is discussed in detail on page 138.

For clarity, the essential formulae are also given here:



where:

 $K_{x}/K_{y}$  is the RSF for element X relative to the internal standard, X (see page 28).

Equation (1) can be rewritten as follows:



where:

 $C_x$  is the unknown concentration of an element X,  $C_y$  is the known concentration of the internal standard,



 $Q_x/Q_y^-$  is the ratio between the exposure values of an element X and the internal standard at 50% transmission, and  $K_x/K_y$  is the relative sensitivity factor for element X relative to the internal standard, which is derived from calibration plots as the slope of the regression line.

Equation (1) can be used to determine the RSF of any element X relative to any internal standard (IS) in any matrix Z. Rewriting equation (1) into the above notation gives:

$$(RSF_{IS}^{X})_{Z} = \begin{bmatrix} \frac{Q_{X}}{Q_{IS}} \\ \frac{Q_{IS}}{C_{X}} \\ \frac{C_{IS}}{C_{X}} \end{bmatrix}_{Z}$$
 .....(3)

This formula is directly related to the general formula for a RSF, namely:

### where:

 $C_{ms}$  is the concentration of an element X relative to an internal standard determined experimentally with the mass spectrometer, and

 $C_{true}$  is the true concentration of an element X relative to an internal standard where both concentrations are known.

The calculation method used to derive the formula which is used to determine the unknown background concentration of an element X in different matrices, Z, using different standards is given below. The general spark-source mass spectrometry equation applies:



where:

 $\begin{pmatrix} C_{X} \end{pmatrix}_{Z}$  is the unknown concentration of element X in matrix Z, K_X is a constant for element X, and  $\begin{pmatrix} Q_{X} \end{pmatrix}_{Z}$  is the instrument signal for element X in matrix Z.

Equation (5) also applies when a known standard (STD) is added to the matrix Z:

where:

 $(C_{x})_{z+std}$  is the unknown concentration of element X in the matrix Z plus the known concentration of element X in the standard,  $K_{x}$  is a constant (see equation (5)), and  $(Q_{x})_{z+std}$  is the combined instrument signal for element X and the standard in the matrix Z.

In order to determine the unknown background concentration  $\binom{C}{x'z}$  of element X in matrix Z, equations (5) and (6) are combined as follows:

$$(C_{\mathbf{x}})_{z+std} - (C_{\mathbf{x}})_{z} = K_{\mathbf{x}} \left[ \frac{1}{(Q_{\mathbf{x}})_{z+std}} - \frac{1}{(Q_{\mathbf{x}})_{z}} \right]$$

This difference is equal to the concentration of the added standard, expressed as  $\binom{C}{x}_{std}$ :



 $\binom{(Q_x)_z}{z}$  and  $\binom{(Q_x)_z}{z+std}$  values can be determined as outlined on page 105 below.

 $\binom{C}{x}_{std}$  values are known and  $K_x$  can be calculated. Inserting the  $K_x$  value for element X in equation (5) enables the determination of  $\binom{C}{x}_z$ . This leads to the following equation:

$$(C_{x})_{z} = (C_{x})_{std} \cdot \frac{(Q_{x})_{z+std}}{(Q_{x})_{z} - (Q_{x})_{z+std}} \dots \dots \dots (8)$$

Equation (8) is the fundamental formula used to determine the background concentration of an element X in a matrix Z, using known prepared graphite standards. This formula will be used to determine background concentrations of impurity elements in  $U_3O_8$  and  $UF_4$  matrices in the following sections. The instrument signals of element X in both the matrix Z and the combination of matrix plus standard can be expressed relative to an internal reference standard (IS) (see page 28).  $Q_{\rm IS}$  values are the same in the Z and Z+STD matrices for a particular choice of Y concentration.

Equation (8) then converts to:

$$(C_x)_z = (C_x)_{std} \cdot \frac{(Q_x/Q_{IS})_{z+std}}{(Q_x/Q_{IS})_z - (Q_x/Q_{IS})_{z+std}} \dots \dots (9)$$


This formula only holds true when  $(Q_x/Q_{IS})_z$  is larger than  $(Q_x/Q_{IS})_{z+std}$ . The opposite can never happen in spark-source mass spectrometry because the concentration is inversely proportional to the instrument signal. Thus, the higher the concentration, i.e. when the standard is added to the matrix Z, the resultant instrument signal will be smaller than that for only the matrix Z.

## 5.2 <u>U₃O₈/graphite matrix quantitation</u>

#### 5.2.1 Blank correction

In order to determine relative sensitivity factors (RSF's) for impurity elements in a U₃O₈/graphite matrix, the blank U₃O₈ sample must first be quantified. Considerable effort was initiated to obtain a blank  $U_3O_8$  sample with few impurity elements to ensure a background spectrum relatively free from spectral lines. This blank base  $U_3O_8$  sample (ES 0) was then mixed with a graphite powder, spiked with Y as an internal reference standard, in the ratio of five parts  $U_3O_8$  to one part graphite by mass. The choice of this ratio has been discussed on page 30. The sample was then analysed several times to obtain an instrument signal,  $(Q_x / Q_y)_{U_1 O_4}$  for element X relative to the internal standard, Y, in a  $U_3O_8$ /graphite matrix. The exposure value for Y,  $Q_v^-$ , is the mean of the singly and doubly charged species. The blank base U₃O₈ sample used for this purpose is stoichiometric i.e. 100 per cent  $U_3O_8$ .

To be able to quantify the impurity elements present in the blank base  $U_3O_8$  sample, a range of graphite standards were prepared



which contained the impurity elements under investigation in different concentrations, together with Y as internal reference standard. The method followed to prepare these graphite standards has been described on page 26. UCAR SP1 graphite powder was used for these standards. The concentration range of the standards is as follows:

U₃O₈ used: stoichiometric i.e. 84,8 per cent U. Concentrations: 4 μg X /gC 20 μg X /gC 40 μg X /gC 100 μg X /gC 200 μg X /gC

Expressed relative to U, the concentrations  $(C_x)_{x \text{ std}}$  for each impurity element X, become:

1 μg X /gU 5 μg X /gU 10 μg X /gU 25 μg X /gU 50 μg X /gU

The concentration of Y added to each of the above graphite standards as internal standard is 20  $\mu$ g Y/gC or 5  $\mu$ g Y/gU.

In addition to the above range of graphite standards using UCAR SP1 graphite, a range of check standards were also prepared using Ultra 'F' graphite. The main reason for preparing these check standards was to see whether results obtained for certain elements using UCAR SP1 graphite could not be improved by using Ultra 'F' graphite. The difference between these two graphite powders' background spectra for certain elements was used to



check the results obtained from the UCAR SP1 range of graphite standards. This was especially useful for Fe, which has a high background concentration in UCAR SP1 compared to Ultra 'F'. Additional impurity elements not incorporated in the UCAR SPI graphite standards were now added to these check standards using Ultra 'F' graphite. These elements could not be added to the UCAR SP1 graphite because of spectral line interferences from elements already added. However due to the absence of these interfering elements in Ultra 'F' graphite these additional impurity elements could be added and analysed without any interference. Elements falling into this category were Li, W, P, Na, K and S. This fact also accounts for the low value for the number of analyses in Table 5.2 (see page 111) where the calibration curve parameters are listed.

The concentration range of these check graphite standards is as follows:

Concentrations: 20 μg X /gC 40 μg X /gC 80 μg X /gC 200 μg X /gC

Expressed relative to U, the concentration,  $(C_x)_{std}$ , becomes:

5 μg X /gU 10 μg X /gU 20 μg X /gU 50 μg X /gU



The concentration of Y added to each of the above graphite check standards as internal standard is 80 µgY/gC or 20 µgY/gU.

Using standard addition methods, each of the above graphite standards are mixed with the blank base  $U_3O_8$  sample in the ratio of five parts  $U_3O_8$  to one part graphite by mass. Similarly, as for the blank base  $U_3O_8$ /graphite matrix sample, each sample is analysed several times to obtain an instrument signal,  $(Q_x/Q_y^-)_{U_3O_8+std}$ , for element X relative to the internal standard in the blank base  $U_3O_8$  plus the graphite standard. These instrument signals are used in equation (9) to calculate the concentration of element X in the blank base  $U_3O_8$ ,  $(C_x)_{U_3O_8}$ .

$$(C_{x})_{U_{3}O_{8}} = (C_{x})_{std} \qquad \frac{(Q_{x}/Q_{y}^{-})_{U_{3}O_{8}} + std}{(Q_{x}/Q_{y}^{-})_{U_{3}O_{8}} - (Q_{x}/Q_{y}^{-})_{U_{3}O_{8}} + std}$$

The results obtained to quantify the impurity elements in the blank base  $U_3O_8$  sample are given in Table 5.1 as  $C_{\chi}(SSMS)$  in  $\mu g \chi / g U$ .

The concentration values for Na (20,9), Mg (26,0), Si (18,3) and Fe (20,3) are all very high in comparison to the concentrations of the graphite standards e.g. the 1, 5, 10 and 25  $\mu$ gX/gU standards. This fact greatly influences the gradient of the calibration line. This is shown as follows:

On the x-axis of the calibration curve, the ratio  $C_y/C_x$  is plotted where  $C_x = (C_x)_{std} + (C_x)_{30}$ . Thus when  $(C_x)_{030}$  is large, the ratio  $C_y/C_x$  becomes smaller where  $C_y$  is taken as constant. This makes the gradient, m, of the regression line



<u>Table 5.1</u>: Blank Base  $U_3O_8$  (ES 0) quantification

Element	Charge State(+)	n	Std Error at 95 % CL (%)	C _x (SSMS) (µg X /gU)	Certified conc (µg X /gU)
В	1	18	10,4	9,8	0,07
Na	1	5	42,1	20,9	5
Mg	2	12	31,2	26,0	0,5
A1	2	18	13,3	9,6	1
Si	2	16	33,6	18,3	17
Р	1&2	12	18,4	3,5	-
Ca	2	35	16,1	6,0	2,2
K	1&2	6	25,2	5,6	4
Ti	1&2	14	12,6	0,42	0,3
V	1&2	38	18,0	0,38	0,31
Cr	1&2	45	10,0	5,3	2
Mn	1&2	34	12,6	0,35	0,14
Fe	1&2	22	9,7	20,3	13
Со	1&2	26	8,1	0,30	0,1
Ni	1	28	10,5	2,4	0,8
Cu	1&2	26	12,3	0,5	0,3
Zn	1	31	7,3	1,78	1,66
Zr	1&2	36	12,9	3,5	0,5
Мо	2	12	18,7	2,5	0,3
Sb	1	25	14,1	1,22	1,2
Li	1	3	19,3	0,19	0,21



inaccurate and limits the calibration range. In this way the RSF is influenced directly by a high background concentration. Even elements with lower background concentrations e.g. B (9,8) and A1 (9,6) influence the Q-values of the lower graphite standards with concentrations of 1, 5 and 10  $\mu$ gX/gU. The same can be said for Ca (6,0), K (5,6) and Cr (5,3) which influence the two lowest graphite standards with concentrations of 1 and 5  $\mu$ gX/gU. The rest of the elements in Table 5.1 have background concentrations which do not influence the calculation of relative sensitivity factors significantly.

The  $C_{_X}$  values in Table 5.1 determined for impurity elements in the blank base  $U_3O_8$  are only for the elements in their elemental state. The hydrogenated and oxygenated species of the elements have not been considered. When analysing unknown  $U_3O_8$  samples with the spark-source mass spectrometer, it is assumed that the same degree of hydrogenation and oxygenation of elements in the sample takes place as with the  $U_3O_8$  calibration standard samples. This assumption is reasonable if the unknown sample is also stoichiometric  $U_3O_8$  and the sparking parameters used to generate ions are identical for the  $U_3O_8$  sample as for the  $U_3O_8$  calibration standard samples.

The chemical composition of the impurity elements within the  $U_3O_8$ samples are also assumed to be similar to those in the  $U_3O_8$  calibration standard samples. The plasma generated between the two electrodes in the ion source provides the equalising locality for such differences. In this plasma the chemical structures are atomised and ionised and recombination of species takes place.

The high standard errors at 95% confidence level (CL) for Na (42,1%) and K (25,2%) can be ascribed to the small number of data



points (n = 5 for Na and n = 6 for K). The fact that the concentration of Na in the blank base  $U_3O_8$  sample is quite high ( $C_x = 20,9 \ \mu g \ Na/gU$ ) also plays a direct role in the relatively high uncertainty.

Similarly, the high standard errors at 95% CL for Mg (31,2%) and Si (33,6%) can also be ascribed to the high concentrations of these two elements in the blank base  $U_3O_8$  sample ( $C_x = 26,0$  for Mg and  $C_x = 18,3$  for Si). This explains why the  $(C_x)_{U_3O_8}$  values for these two elements fluctuated over the concentration range of the graphite standards. This fluctuation can further be enhanced by the position on the photoplate where the spectral lines of Mg at m/e 12,5 and of Si at m/e 14,5 are influenced by background emulsion fogging due to the strong spectral line of the major component, ¹²C at m/e 12. This interference directly affects the results obtained for Mg and Si and can lead to large standard errors.

For the remainder of the impurity elements in the blank base  $U_3O_8$  sample, the standard errors at a 95% CL show typical values comparable to the precision of the method, namely approximately 20%. The large values of n for these elements also ensures the reliability of the lower ( $C_X$ )  $U_3O_8$  values over the concentration range of the graphite standards.

In Table 5.1 concentration values of impurities in the base  $U_3O_8$  material obtained with the spark-source mass spectrometer are compared with values obtained using different analytical techniques (see certified concentration column). These techniques are described on page 158. The main reason for some of the differences is the fact that the  $C_{_{\rm X}}$  (SSMS) values include the concent



tration of that particular element present in the graphite powder used. In other words, the  $C_x$  (SSMS) value reported is a combination of the concentration of that particular element in the blank base  $U_3O_8$  sample as well as the concentration of that particular element in the UCAR SP1 graphite or Ultra 'F' graphite used. In this way, the impurities in the graphite powder have been quantified and should be kept in mind when using these graphite powders for future analyses.

Differences can also be due to contamination picked up from a variety of sources. An important source of contamination, especially at trace level concentrations, is from ordinary dust in the laboratory environment [24]. Typical elements found in dust samples collected in the laboratory and analysed for impurities included such elements as B, Mg, Al, Si and Ca. It has also been shown that the Na from NaCl in human perspiration is a significant source of Na contamination. Another source of contamination is from the stainless steel tools which are used in the preparation of the electrodes. Possible impurity elements include Al, Cr, Fe, Ni, Zr and Mo. It is thus difficult at this stage to identify the exact sources of contamination and to quantify these impurities. Proposals to prevent or minimise such contamination are discussed in Chapter 7 on page 166.

## 5.2.2 Calibration Curves

Calibration curves are constructed according to equation (1) on page 98.  $Q_x/Q_y^-$  is plotted on the y-axis. The value of  $C_x$  in  $C_y/C_x$  is taken as the sum of the concentrations of an element X in the prepared graphite standard plus the value in the blank base  $U_3O_8$ . Expressed as symbols,  $C_x = C_{std} + C_{U_3O_8}$  where  $C_{U_3O_8}$ is obtained from Table 5.1 on page 106.



The slope,  $K_{\chi}/K_{\gamma}$ , of the calibration curve is the relative sensitivity factor (RSF) of that particular impurity element X present in the matrix  $U_{3}O_{8}$  relative to an internal standard, Y. Calibration curve parameters are listed in Table 5.2. The parameters c, r and n are discussed below. The standard error,  $s_{m}$ , in the slope is expressed in the form of the confidence limits of the slope,  $\alpha$ , at a 95% confidence level (CL). These two parameters are discussed on pages 115 and 148 in terms of the statistical significance of the results.

The values of the intercept on the y-axis (c) are, with only a few exceptions, relatively close to the origin (0;0). The value of c must be evaluated in perspective with the magnitude of the scale of the y-axis. Elements with high RSF's have large absolute values for c. Examples of such elements are K²⁺ (c = -0,6448) and  $Bi^{2+}$  (c = -1,0788). Furthermore, elements with large a's also tend to have large values for c. This follows from the uncertainty in the slope of the regression line. Elements classified into this category are Mo¹⁺ and W²⁺. The intercept on the y-axis is reflected in the correlation coefficient of the fit of data to a regression line. A bad fit suggests that there are unreliable data points which, when included, would affect the intercept on the y-axis. Elements falling into this category are Mo¹⁺ and Ba¹⁺. The value of c is not of importance as it is not incorporated directly into any calculations regarding concentration or RSF's.

However, the value obtained for r is an indication of the fit of the data to the regression line. Ideally, r should be unity. The values of r obtained in Table 5.2 are generally quite good. The rather poor fits of data for  $Fe^{1+}$  (r = 0,8529),  $Ba^{1+}$ (r = 0,8972) and  $Mg^{2+}$  (r = 0,9278) are also apparent from the



# Table 5.2: U₃O₈ Calibration curve parameters

	T		•			
Element	Charge State(+)	m (RSF)	a (%)	с	r	п
В	1	1,1468	4,6	-0,0122	0,9961	19
Na	1	0,2483	28,2	0,0016	0,9716	7
Mg	2	1,7725	19,3	-0,0898	0,9278	21
A1	2	1,2399	10,9	0,0083	0,9740	22
Si	2	1,2836	15,1	-0,0197	0,9273	32
P	1	0,2178	20,8	0,0121	0,9839	7
P	2	1,3978	37,8	0,0511	0,9649	6
Ca	2	0,3035	12,2	-0,0216	0,9317	44
K	1	0,1073	15,7	-0,0014	0,9883	8
K	2	18,3676	24,2	-0,6448	0,9910	5
Ti	1	0,2598	16,0	0,0004	0,9660	15
Ti	2	0,4684	5,3	-0,0061	0,9969	12
V	1	0,3025	2,4	0,0248	0,9955	24
V	2	0,5004	19,9	0,0489	0,9580	13
Cr	1	0,2408	9,9	0,0087	0,9622	36
Cr	2	0,7199	9,4	-0,0082	0,9847	18
Mn	1	0,1529	10,3	0,0357	0,9753	23
Mn	2	1,0094	17,8	0,0324	0,9660	13
Fe	1	0,2301	23,6	0,0041	0,8529	30
Fe	2	1,1867	13,1	-0,0039	0,9809	13
Co	1	0,2697	4,0	-0,0049	0,9957	25
Co	2	1,2153	12,9	0,0362	0,9836	12
Ni	1	0,2397	5,7	0,0099	0,9898	29
Cu	1	0,2987	7,3	0,0215	0,9840	28
Cu	2	3,9934	8,2	0,0669	0,9924	13
Zn	1	0,6078	7,4	0,0074	0,9857	25
Sr	1	0,4877	10,0	0,1405	0,9767	23
Sr	2	0,3316	11,7	0,0109	0,9848	13

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## Table 5.2: Continued

	Y					
Element	Charge State(+)	m (RSF)	α (%)	с	r	n
Zr	1	1,3375	7,8	0,0501	0,9839	25
Zr	2	0,6769	8,9	-0,0154	0,9911	13
Nb	1	1,3581	8,5	0,0273	0,9814	25
Nb	2	0,9780	10,1	-0,0180	0,9886	13
Мо	1	2,8176	19,2	-0,3758	0,9249	22
Мо	2	1,4294	9,1	-0,0468	0,9907	13
Ru	1	2,8572	6,0	-0,0171	0,9927	20
Rů	2	5,1368	19,2	0,0095	0,9609	13
Cd	1	1,1031	13,2	0,1175	0,9702	25
In	1	0,5853	12,5	0,1331	0,9607	25
In	2	7,7360	11,9	0,0027	0,9842	13
Sb	1	1,7565	16,9	0,0113	0,9342	24
Sb	2	7,0408	7,5	-0,1386	0,9937	13
Ba	1	0,5416	23,0	0,6769	0,8972	22
Ba	2	0,4784	10,5	0,0230	0,9879	13
Sm	1	4,2008	45,0	0,0000	0,9310	7
Sm	2	0,6019	4,9	0,0437	0,9945	26
Eu	1	4,6455	6,2	0,0082	0,9962	12
Eu	2	0,6633	9,7	0,0179	0,9743	26
Gd	1	3,6455	7,4	-0,0127	0,9960	12
Gd	2	0,9391	5,5	-0,0087	0,9939	20
Dy	1	7,2053	6,3	-0,1353	0,9960	12
Dy	2	0,6998	5,5	0,0883	0,9922	24
W	2	2,1239	40,3	0,5395	0,9604	6
Bi	2	20,1841	14,8	-1,0788	0,9681	16
Th	2	2,0486	7,7	-0,0852	0,9889	19
Li	1	0,0243	7,1	0,0002	1,0000	5



large errors in the slopes where a for  $Fe^{1+} = 23,6\%$ , a for  $Ba^+ = 23,0\%$  and a for  $Mg^{2+} = 19,3\%$ . Another explanation for the poor calibration lines for  $Fe^{1+}$  and  $Mg^{2+}$  is the high values of these elements in the blank base  $U_3O_8$ , where  $C_{U_3O_8} = 20,3 \ \mu g \ Fe/gU$  for  $Fe^{1+}$  and  $C_{U_3O_8} = 26,0 \ \mu g \ Mg/gU$  for  $Mg^{2+}$ . This is in spite of the large number of data points (n) used to draw the calibration curves for these elements. The calibration graph for  $Fe^{1+}$  in a  $U_3O_8$  matrix is given in Figure 5.1 as an example of a poor calibration curve.

Good calibration curves were obtained for Co1+ and V1+ as indicated by the correlation coefficients obtained for these elements where r = 0,9957 and r = 0,9955, respectively. Factors contributing to the good fit of data points for these elements is the fact that they both have very small a values where a = 4,0% for  $Co^{1+}$  and  $\alpha = 2,4\%$  for V¹⁺. Another reason is the fact that they both have small concentrations in the blank base  $U_3O_8$  where  $C_{U_3O_8} = 0,3 \ \mu gCo/gU$  for  $Co^{1+}$  and  $C_{U_3O_8} = 0,38 \ \mu gV/gU$  for  $V^{1+}$ . In both cases the value of n is large where n = 25 for  $Co^{1+}$  and n = 24 for  $V^{1+}$ . A typical example of a good calibration curve is given in Figure 5.2 for  $Co^{1+}$  in a  $U_3O_8$  matrix. Another good calibration curve is obtained for B1+ where the concentration obtained in the blank base  $U_3O_8$  is fairly high where  $C_{U_3O_8} = 9,8$  $\mu gB/gU$  for  $B^{1+}$ . The other parameters coupled to this calibration curve are: r = 0,9961; n = 19 and  $\alpha = 4,6\%$ . This calibration line is also given in Figure 5.3 as a good line where a large background concentration is present.

The value of n in Table 5.2 is the number of data points where each analysis was taken as a separate data point. The value for the blank is also incorporated in n as a data point.







<u>Figure 5.2</u>: Calibration curve for  $Co^{1+}$  in  $U_3O_8$ /graphite matrix







## 5.2.3 Relative sensitivity factors (RSF's) - U₃O₈

The instrument sensitivity for a particular element is totally unique for a specific spark-source mass spectrometer and detection system. Different RSF's will be obtained for an element using a radio frequency (RF) spark compared to a triggered lowvoltage discharge spark as was used in this investigation.

Another important factor to be considered is that a RSF for a particular element X will differ from matrix to matrix [25]. This is illustrated when comparing RSF's obtained for mutual elements (e.g. A1, P, Ca, Si and Zn) for both a UF₄ and a  $U_3O_8$  matrix. Differences in this case could be ascribed, among other reasons, to the fact that in a UF₄ matrix, fluorination occurs within the plasma resulting in less elemental species of ions. © University of Pretoria



A RSF is also unique with regard to a particular internal reference standard.

It was beyond the scope of this investigation to determine whether a RSF for an element in a  $U_3O_8$  matrix will differ from that for another uranium oxide matrix, for example  $UO_2$  or  $UO_3$ . It is the author's opinion that there would not be a significant difference because the combinations of uranium and oxygen would create very similar plasma conditions [11]. In all uranium oxide matrices, there is an over-abundance of oxygen species generated within the plasma.

Correlations between physico-chemical properties of various elements as impurities and relative sensitivity factors have been published [23, 26]. Instead of using standards to determine RSF's, some authors have determined theoretical RSF's from making use of various combinations of physico-chemical properies of the elements. For the purpose of this investigation, an attempt will only be made to explain certain of the anomalies observed in the experimentally determined RSF's.

Physico-chemical properties such as heats of vaporisation, electrical resistivity, thermal conductivity, ionisation potentials, atomic radii and melting points were studied and some correlations drawn. These correlations are qualitative at their best. Due to the complexity of plasmas in relation to the physico-chemical properties, anomalies cannot be adequately explained in this qualitative fashion. It would require computer simulations involving chemical and physical studies in order to relate the properties to RSF's. This is a very complex task which has not been described in the literature and is beyond the scope of this



thesis. Qualitative comments will nevertheless be offered for some of the observations.

The high relative sensitivity factors (RSF's) obtained for a few of the impurity elements in a  $U_3O_8$ /graphite matrix can be related to their physico-chemical properties with some degree of confidence. Elements which do not readily form ions of a particular species tend to have high RSF's for this species. A prime example is K²⁺ which has a very low ion yield for doubly charged species. A factor in this regard is the fact that potassium has only one valence electron in its outermost shell (4s orbital). This valence electron is readily lost to form the singly charged state having the noble gas structure of argon. Thereafter, it would require far more energy to remove a second electron to form the doubly charged species. This fact could be related to the second ionisation potential  $(I_p^{II})$  for K which, together with the other alkali-earth metals, has the highest  $I_P^{II}$  of all the ele-The RSF of 18,3676 obtained for K²⁺ differs consideraments. bly from that obtained for  $K^+$  (RSF = 0,1073). It is evident that K⁺ ions are formed in great abundance in the mass spectrometer. Another element which has a small RSF is Li (RSF = 0,0243). Both Li and K are alkali-earth metals of group IA which readily lose an electron to have a noble gas structure. In the case of Li, this would be helium. Na also has a relatively small RSF namely All the group IA elements have of the lowest melting 0.2483. points which would contribute to the high yield of ions for these elements and the subsequent low RSF's. These elements also have of the lowest electrical resistivity of all the elements present. This fact could also contribute to these elements being atomised and ionised more easily.



Bismuth has a high electrical resistance which could account for the very poor ion yield for the Bi²⁺ ion and the subsequent high RSF value. Only the doubly charged Bi²⁺ was recorded (see page 71). Bismuth is also the most diamagnetic of all the metals and the thermal conductivity is lower than any metal, except for Hg. Both the electrical resistivity and the thermal conductivity are physico-chemical properties which play a role in the generation of the plasma between the two electrodes in the ion-source.

Another group of elements having relatively high RSF's are the singly charged species of the rare-earth metals e.g. Sm, Eu, Gd and Dy. These all have relatively high electrical resistivities and large atomic radii. It was found that the ion yield for doubly charged species was greater than for the singly charged species. This can be demonstrated by plotting the number of ions yielded against the charge state [27].

It would seem that the larger the atom becomes, the fewer ions reach the photoplate, probably due to their momentum and collisions in the flight tube. Elements falling into this category are  $W^{2+}$ ,  $Th^{2+}$ ,  $Sb^{2+}$ ,  $In^{2+}$ ,  $Ru^{2+}$ ,  $Ru^{1+}$  and  $Mo^{1+}$ , and high RSF's could be expected. However, it should be taken into account that the number of ions generated in the ion source also plays a determining role.

The relatively high RSF for  $Cu^{2+}$  (RSF = 3,9934) is of interest as it is the highest of the 3d transition elements. Cu and Ag



have of the lowest electrical resistance as well as the highest thermal conductivity. They both are group IB elements having electron configurations such that their d-orbitals are filled and having one electron in the outermost s-orbital. The filled dorbitals lead to stability and an electron is readily lost from the half filled s-orbital. In order to lose another electron to form Cu²⁺ species, more energy is required to remove an electron from a paired 3d orbital resulting in a high RSF for Cu²⁺.

Only a few of the physico-chemical properties of the elements have been referred to in order to explain some of the anomalies obtained with RSF's for impurities in a  $U_3O_8/graphite$  matrix. Properties such as bond strengths in diatomic molecules and heats of formation of gaseous atoms from elements in their standard states should also be included when attempting to explain these anomalies.

The RSF's obtained from calibration curves can be checked by making use of the instrument signals obtained. The ratio between the instrument signal for the singly charged state of an element and the instrument signal for the doubly charged state of the same element at a concentration level should be the same as the ratio between the RSF of the singly charged state of the particular element and the RSF for the doubly charged state of that ele-The ratio  $X^{1+}/X^{2+}$  is independent of the concentration of ment. element X. A number of elements were measured both in the singly and doubly charged states at two different concentration The means of the ratio  $X^{1+}/X^{2+}$  between these two concenlevels. trations were compared and good correlation was obtained. This ratio was used to test the ratio RSF X1+/RSF X2+ for the same element using the RSF's obtained in Table 5.3. Good agreement was obtained for most of the elements, which confirmed that outliers did not seriously influence the determination of RSF's. The ratio  $X^{1+}/X^{2+}$  can be used with a RSF for  $X^{1+}$  to get an estimate of the RSF for  $X^{2+}$  and vice versa.



Table 5.3: Relative Sensitivity Factors: U₃O₈/Graphite Matrix

RSF Singly	Element	RSF Doubly	RSF X1+	X1+/X2+	X1+/X2+
charged Species		charged Species	$\frac{RST}{RSF}$ X ²⁺	C _x =10µgX/gU	C _x =50µgX/gU
0,0243	Li				
1,1468	В				
0,2483	Na				
	Mg	1,7725			
	A1	1,2399			
	Si	1,2836			
0,2178	Р	1,3978			
	Ca	0,3035			
0,1073	K	18,3676			
0,2598	Ti	0,4684			
0,3025	v	0,5004	0,60	0,60	0,58
0,2408	Cr	0,7199	0,33	0,34	0,37
ò,1529	Mn	1,0094	0,15	0,15	0,15
0,2301	Fe	1,1867	0,19	0,20	0,20
0,2697	Со	1,2153	0,22	0,22	0,21
0,2397	Ni				
0,2987	Cu	3,9934	0,07	0,08	0,09
0,6078	Zn				
0,4877	Sr	0,3316	1,47	1,55	1,85
1,3375	Zr	0,6769	1,98	2,03	2,06
1,3581	Nb	0,9780	1,39	1,42	1,27
2,8176	Мо	1,4294	1,97	2,02	2,02
2,8572	Ru	5,1368	0,56	1,37	0,67



## Table 5.3: Continued

RSF Singly charged Species	Element	RSF Doubly charged Species	RSF X ¹⁺ RSF X ²⁺	X ¹⁺ /X ²⁺ C _x =10μgX/gU	X ¹⁺ /X ²⁺ C _x =50µgX/gU
1,1031	Cd				
0,5853	In	7,7360	0,08	0,08	0,09
1,7565	Sb	7,0408	0,25	0,25	0,24
0,5416	Ba	0,4784	1,13	1,08	1,19
4,2008	Sm	0,6019	6,98	6,63	6,55
4,6455	Eu	0,6633	7,00	7,05	7,58
3;6455	Gd	0,9391	3,88	3,97	3,89
7,2053	Dy	0,6998	10,30	10,64	9,76
	W	2,1239			
	Bi	20,1841			
	Th	2,0486			

## 5.3 UF₄-graphite matrix quantitation

## 5.3.1 Blank correction

In order to determine relative sensitivity factors (RSF's) for impurity elements in a UF₄/graphite matrix, the blank UF₄ sample which was to be used to simulate the matrix material first had to be quantified. Considerable effort was initiated to obtain a blank UF₄ sample with the least impurity elements to ensure a background spectrum relatively free from spectral lines. This blank UF₄ sample was mixed with graphite powder, spiked with Y as an internal reference standard, in the ratio of one to one by



mass. The sample was then analysed several times to obtain an instrument signal  $(Q_x/Q_y^-)_{UF_4}$  for element X relative to the internal standard, Y. The exposure value for Y,  $Q_y^-$ , is the mean for the singly and doubly charged species. The blank UF₄ sample used for this purpose is stoichiometric i.e. 100 per cent UF₄.

A range of graphite standards were prepared with the impurity elements of interest at different concentrations, together with Y as internal reference standard. The method followed to prepare these graphite standards is given on page 26. The concentration range of these graphite standards is as follows:

UF₄ used: stoichiometric i.e. 75,8% per cent U. Concentrations: 100 µg X /g UF₄ 200 µg X /g UF₄ 500 µg X /g UF₄ 700 µg X /g UF₄ 1 000 µg X /g UF₄

Expressed relative to U, the concentrations  $\begin{pmatrix} C \\ x \end{pmatrix}$  for each impurity element X, become:

132 μg X /gU 264 μg X /gU 660 μg X /gU 924 μg X /gU 1 319 μg X /gU

The concentration of Y added to each of the above graphite standards as internal standard is 132 µgY/gU.



These standards were used to quantify the impurity elements in the blank UF₄. Using standard addition methods, each of the above graphite standards was mixed with the blank UF₄ sample in the ratio of one to one by mass. Similar to the blank UF₄ graphite matrix sample, each spiked sample is analysed several times to obtain an instrument signal,  $(Q_x/Q_y^-)_{UF_4}$ , for element X relative to the internal standard, Y. The concentration of each element X can be determined on the basis of equation (9) discussed on page 101:

$$(C_x)_{UF_4} = (C_x)_{std} \cdot \frac{(Q_x/Q_y)_{UF_4+std}}{(Q_x/Q_y)_{UF_4} - (Q_x/Q_y)_{UF_4+std}}$$

Results are given in Table 5.4 as  $C_{x}$  in  $\mu gX/gU$ .

Table 5.4: Blank UF₄ quantification

Element	Isotope	Isotopic Abundance(%)	Charge State	n	Std Error at 95% CL (%)	C _x (µg X/gU)
A1	27	100	2	8	21,36	5,6
Р	31	100	2	5	34,85	76,7
Ca	40 42	96,94 0,65	2 2	9	12,48	25,2
Si	30	3,09	1	5	13,59	77,4
S	32	95,0	1	5	38,74	385,4
C1	35 37	75,72 24,28	1 1	10	21,35	52,5
Zn	64 67	48,89 27,77	1 1	8	23,78	4,0



The concentration value for S is quite high (385,4  $\mu$ gS/gU). This greatly influences the calibration line. On the x-axis of the calibration curve, the ratio  $C_y/C_x$  is plotted where  $C_x = (C_x)_{std}$ +  $(C_x)_{UF_4}$ . When the background concentration of an element X in the blank UF₄,  $(C_x)_{UF_4}$ , is large, the ratio  $C_y/C_x$  becomes smaller, where  $C_y$  is taken as constant. This makes the gradient of the regression line inaccurate and limits the calibration range. The other impurity elements have background concentrations which do not influence the calibration.

The  $C_{_X}$  values in Table 5.4 determined for impurity elements in the blank UF₄ are only for the elemental states. The fluorinated species of the elements have not been considered. When analysing UF₄ samples with the spark-source mass spectrometer, it can be assumed that the same degree of fluorination of the elements takes place in the sample as with the UF₄ calibration samples. This assumption is valid if the unknown sample is also stoichiometric UF₄ and the sparking parameters used to generate ions are identical for the UF₄ sample as for the UF₄ calibration samples.

The chemical structures of the impurity elements in the UF₄ sample are assumed to be similar to those in the UF₄ calibration samples. The plasma generated between the two electrodes in the ion source provides the equalising locality for such differences. In this plasma the chemical structures are broken in the process of atomisation and ionisation and recombination of species can take place.

The preparation and characterisation of graphite standards to obtain relative sensitivity factors (RSF's) for impurity elements



in a UF₄ sample were done under serious production pressures due to the study of reactions in the uranium fuel production process and time was not allowed to analyse the blank UF₄ sample more comprehensively. It was nevertheless decided to include the results in this thesis as they were reasonable in terms of the precision of the method and made a major contribution to the solving of the production problems at the time. The fact that the UF₄ work was done as an additional project under severe time constraints must be kept in mind when accessing the small number of data points on which the principles have been demonstrated.

The high standard errors at 95 % confidence level (CL) for P (34,85%) and S (38,74%) can be ascribed to the small number of data points which were statistically acceptable. This shows how the  $(C_x)_{UF_4}$  values for these two elements fluctuated over the concentration range of the standards resulting in the  $C_x$  values at higher concentrations being rejected leaving n = 5 with still a larger error in the remaining  $(C_x)_{UF_4}$  values. The standard error at 95 % CL obtained for Si (13,59%) with n = 5 seems to be the exception where the remaining  $(C_x)_{UF_4}$  values show a better standard error at lower concentration levels of the graphite standards. For the above three elements, namely P, Si and S, their concentrations present in the UF₄ sample are the highest, which has a direct influence in the standard errors at 95 % CL.

For the remainder of the impurity elements in the blank UF₄ sample, the standard errors at a 95 % CL show typical values comparable to the precision of the method, namely ~ 20 %. The larger value of n for these elements also shows the reliability of the lower  $(C_x)_{UF_4}$  values over the concentration range of the graphite standards.



## 5.3.2 Calibration curves

The procedure used to construct calibration curves is given in detail on page 137. A few interesting observations are high-lighted below.

Similar to procedures followed for the  $U_3O_8$  matrix (see page 109), the instrument signal,  $Q_x/Q_y^-$ , is plotted on the y-axis and the ratio between the concentrations,  $C_y/C_x$ , is plotted on the x-axis. The value of  $C_x$  in  $C_y/C_x$  is taken as the sum of the concentrations of an element X in the prepared graphite standard plus the value of the blank UF₄, expressed as,  $C_x = C_{std} + C_{UF_4}$ , where  $C_{UF_4}$  is obtained from Table 5.4.

The slope of the resultant curve is the relative sensitivity factor (RSF) of that particular impurity element X present in the matrix  $UF_4$  relative to an internal reference standard, Y.

Theoretically, the calibration curve should pass through the origin (see page 139). The values of the intercept on the y-axis, c, listed in Table 5.5 are in accordance with this fact for most of the elements. The values obtained for P and Cl must be kept in perspective as the values of m for these two elements are also large in magnitude compared to the rest. Negative values for c on the y-axis could indicate a minimum detection value for  $C_{x}$  on the x-axis. Below this minimum detection value, non-linearity is evident. For the purpose of this investigation, the highest concentration measured was 1319  $\mu$ g X/gU. A1 and Zn display good linearity over the entire concentration range.



## Table 5.5: UF, Calibration curve parameters

Element	Isotope	Isotopic Abundance(%)	Charge State	m (RSF)	α (%)	с	r	n
A1	27	100	2	2,0059	0,84	0,0008	0,9999	10
Р	31	100	2	25,7454	10,6	-0,9496	0,9917	10
Ca	40 42	96,94 0,65	2 2	0,6104	3,64	-0,0169	0,9980	16
Si	30	3,09	1	0,9438	8,38	-0,0490	0,9948	10
S	32	95,0	1	0,6891	26,9	-0,0123	0,9575	9
C1	35 37	75,72 24,28	1 1	20,0095	4,82	-0,9232	0,9965	16
Zn	64 67	48,89 27,77	1 1	0,4946	0,87	0,0279	0,9999	10

The calibration graph for Zn in the  $UF_4$  matrix is given in Figure 5.4 as an example of a good calibration curve.

The calibration graph for S in a  $UF_4$  matrix is given in Figure 5.5 as an example of a poor calibration curve.



Figure 5.4: Calibration curve for  $Zn^{1+}$  in a UF₄/graphite matrix



Figure 5.5: Calibration curve for  $S^{1+}$  in UF₄/graphite matrix



The poor fit of data for S is manifested through the relatively large error in the slope ( $\alpha = 26,9\%$ ) and the high value obtained for S in the blank UF₄. Where blank values are reasonably high, uncertainties in these values are reflected in all other data points. This also happens when standards are added to a quantity which is not known in absolute terms.

The value of n in Table 5.5 is an indication of the number of data points used to construct the calibration curves, where each data point is taken as a single analysis. The value for the blank is also incorporated as a data point.

## 5.3.3 <u>Relative Sensitivity Factors (RSF's) - UF</u>4

For the impurity elements investigated in a UF₄ matrix, various physico-chemical properties were studied in order to find a qualitative solution for the very high RSF's obtained for P (25,7454) and C1 (20,0095) listed in Table 5.5. Properties such as first and second ionisation potentials  $(I_p)$ , bond strength  $(B_s)$  of the F-X species, heats of formation  $(H_f^{\circ})$  of gaseous atoms from elements in their standard states, heat of vaporisation  $({\rm H}^{\circ}_{vap}),$  electronegativity (E  $_{\rm neg}),$  melting points (M  $_{\rm p})$  and boiling points (B_p) were studied [28]. No specific physico-chemical property can be singled out to explain anomalies in RSF's as each property plays a role within the plasma. When the melting points and heats of vaporisation are compared between the various elements, it is apparent that P and Cl have the lowest values. However, these elements also have of the highest E and ionisation potentials.



## 5.4 <u>Semi-quantitative</u> analysis

## 5.4.1 50% Transmission intercept method

This method is more time consuming than the appearance level method (see page 132) but is still quicker than setting up the MD100 microdensitometer to obtain analytical data. Instruments required to perform this method are a Hilger & Watts^{*} microphotometer Model L-500-2 equipped with a carriage to hold a photographic plate and a Fluk[#] multimeter. Many of the principles and preliminary procedures discussed in detail for the appearance level method also apply to this method. However, only the operational procedure will be discussed below.

The marked photographic plate is positioned and the lens focused, once the light of the photocell has been switched on. A clear plate region of at least 5mm in diameter is made on the photographic plate where there are no spectral lines of interest, by scraping away the emulsion on the photographic plate. This spot will serve as the 100% transmission region in order to calibrate the multimeter.

The intensity of the light is adjusted by means of the photocell amperage so that when the beam of light is mechanically shut off

- * Hilger & Watts Ltd, 98 St Pancras Way, Camden Road, London NW1.
- # John Fluke MFG. Co. INC, P.O. Box 43210, Mountlake Terrace, Everett, Washington, 98043, U.S.A.



there is 0% transmission of light and when the beam of light passes through the clear plate region there is a 100% transmission of light through the photoplate. The Fluke digital multimeter is coupled to the photocell output using its 1 volt scale so that 0% transmission is zero volt on the multimeter and 100% transmission is 1,0 volt on the multimeter. The second decimal scale is sufficient for this method as a reading of 0,65 volt on the multimeter gives a reading of 65% transmission of light through the spectral line. Dark spectral lines on the photoplate will have lower percentage transmission of light through them than lighter spectral lines. The 50 % transmission intercept method can now be implemented.

An element of known concentration is used to obtain a k-factor The ²³⁴U²⁺ spectral line at m/e 117 is used as e.g. U or Y. internal standard or the ⁸'Y¹⁺ or ⁸'Y²⁺ spectral lines at m/e 89 and 44,5, respectively, can be used as internal standard if Y is present in the sample. A transmission curve is obtained by plotting on the y-axis, using ordinary graph paper, the multimeter reading multiplied by 100 to obtain a percentage transmission for each spectral line on the photographic plate. This is plotted against the natural logarithm on the x-axis of the applicable exposure value of each spectral line on the photographic plate i.e. % T on the y-axis and In Q on the x-axis. From this transmission curve, the exposure value at 50 % transmission is read off the graph paper and is used in the general formula to obtain a k-factor.

The same procedure is followed as above to obtain a transmission curve for an element X of interest. The exposure value at 50 % transmission is used, together with the k-factor obtained from



the internal reference to obtain the concentration value,  $C_x$ , of element X. However, this concentration is only for that particular isotope of element X. In order to obtain the total concentration  $C_x$  of element in the sample, the isotopic abundance of the applicable isotope measured must be incorporated.

This method is suitable to obtain concentration values for impurity elements in a sample where no relative sensitivity factors are available. In this case the RSF is taken as unity and the final result obtained differs from the true value by about a factor of two or three. The fact that no background correction has been incorporated must be borne in mind. This method can be utilised with high and low concentrations of impurity elements as long as there is a spectral line that can produce a workable transmission curve. Both the semi-quantitative methods are extremely useful for analysing uranium samples where no standard is available. In this case the uranium is taken as the internal standard and used to quantify impurity elements.

## 5.4.2 Appearance level method

This method is the more reliable method of the two used for semiquantitative analysis. However, its interpretation differs from analyst to analyst as will be illustrated below. The only instrument required to perform this method is a microscope which is equipped with a carriage to hold a photographic plate. Whilst looking through the eye-piece of the microscope, the analyst must be able to move the carriage holding the photographic plate, along both the x- and y-axes. The x-direction gives the analyst the opportunity to view the spectrum on the photographic plate in its entirety whereas movement in the y-direction focuses on a specific area of the photoplate and the number of different exposures in the form of spectral lines can be counted. This last step is the essence of the method.



If an uranium oxide sample, for example  $U_3O_8$ , has been mixed with graphite powder spiked with the internal reference standard, Y, of known concentration, then the U and/or Y are used as the elements of known concentration. A prerequisite for using the U line as reference, is that the isotopic composition is known. If the U is natural, then the concentrations of the various isotopes are known and can be used as reference concentrations. This is shown below as an example.

Uranium used: natural isotopic abundance (converted to mass percent): 238 = 99,286 235 = 0,710 234 = 0,0055 thus concentration of: ²³⁸U = 992 860 µg ²³⁸U/g U₃O₈ ²³⁵U = 7 100 µg ²³⁵U/g U₃O₈ ²³⁴U = 55 µg ²³⁴U/g U₃O₈

The concentration of the  $^{234}U$  isotope of uranium is normally used as it has a value similar to impurity levels in the  $U_3O_8$ .

The above concentrations can be expressed in general ppm terms as  $\mu g$  of the U isotope per total mass of U (in grams). For natural uranium in U₃O₈ the concentrations are:

² ³ ⁸ U = 882 425 ppm ² ³ ⁵ U = 6 167 ppm ² ³ ⁴ U = 47,8 ppm

When graphite powder spiked with a known concentration of Y is mixed with the  $U_3O_8$ , it is done in the ratio of five parts  $U_3O_8$ to one part graphite by mass. This was shown on page 30. The concentration of the Y in the graphite is typically 80 µg Y/gC. When mixed with  $U_3O_8$ , the concentration of Y relative to uranium is approximately 20 µg Y/gU. These two concentrations are used when applying the appearance level method.



When a set of spectral lines belonging to a specific element on the photographic plate is investigated under the microscope, dark lines at longer exposures up to light lines at shorter exposures, are observed. At very short exposures, no spectral lines are detected depending on the concentration level of that element in the sample.

The faintest detectable spectral line is called the appearance line. According to the exposure pattern used, this appearance line thus has a specific appearance exposure. The appearance exposure can thus be defined as that exposure necessary for a specific impurity element present at a certain concentration level to become visible to the analyst. This is where the difference in interpretation of the appearance level method varies from analyst to analyst. What might be the appearance exposure for one analyst is not necessarily that for the other analyst.

When performing semi-quantitative analyses with this method, both the  $Y^{1+}$  and  $Y^{2+}$  lines at masses 89 and 44,5, respectively, are scrutinized to obtain appearance exposures. Similar to quantitative analysis procedures, the mean of these two values is obtained:

$$Q_{\overline{y}} = \frac{Q_{y^{1+}} + Q_{y^{2+}}}{2}$$

When applying the general formula for spark-source mass spectrometry,

k-factor  $concentration (C) = -------, \qquad \dots \dots \dots \dots \dots \dots (1)$  exposure (Q)the k-factor for Y , K_y, can be obtained:  $K_y = C_y \cdot Q_y^- \qquad \dots \dots \dots \dots \dots (2)$ 



where:

C is the concentration of the internal standard Y, relative to the U content, i.e. typically 20  $\mu$ g Y/gU in the above example, and

 $Q_{_{m V}}^-$  is the mean appearance exposure of the internal standard.

For an unknown impurity element X present in the  $U_3O_8$  sample, the appearance exposure,  $Q_X$ , is determined using the same method as described above.

Using the above  $Q_x$  and  $K_y$  from equation (2) in equation (1), the concentration  $C_x$  of element X relative to the internal standard is determined:

$$C_{\mathbf{X}} = \frac{K_{\mathbf{Y}}}{Q_{\mathbf{X}}}$$
(3)

If the internal standard is not present, the U spectral lines are used in exactly the same way. However, only the  23   $^{4}U^{2+}$  spectral line at m/e 117 is suitable for use. The concentration of an element X is then expressed relative to the  23   $^{4}U$  isotope.

This method is a quick way to obtain a concentration for an element without using relative sensitivity factors. The result can differ by a factor of two or three compared to the use of relative sensitivity factors (RSF's). In the above case, the sensitivity of an element X relative to an internal standard is taken as unity. If a RSF does exist for an element X relative to Y in a specific matrix, then it can be used together with the usual formula given below which was derived on page 98:



$$C_{\mathbf{x}} = \frac{RSF \cdot C_{\mathbf{y}}}{\frac{Q_{\mathbf{x}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}{\frac{Q_{\mathbf{y}}}$$

The appearance exposure of element X,  $Q_x$ , is expressed as a ratio together with the mean appearance exposure of the internal standard,  $Q_y^-$ . The concentration  $C_x$  obtained for element X is only the concentration of that particular isotope of element X. In order to obtain the total concentration of the element, the concentration obtained for that particular isotope measured, is divided by its isotopic abundance and multiplied by 100 to cancel the percentage.



## CHAPTER SIX

#### **EVALUATION OF THE METHOD**

## 6.1 <u>Statistical significance of results</u>

## 6.1.1 Statistical approach

Data interpretation is based on the graphic method [29, 30]. This incorporates the use of calibration lines which are obtained from plotting the instrument signal, y, against the concentration, x, of an element. The relationship between x and y can be derived by linear regression using the standard formula:

where:

*m* is the slope of the calibration line, and c is the intercept of the y-axis.

The general spark-source mass spectrometry formula [8] can be interpreted on this basis:

where:

 $C_x$  is the concentration of element X,  $K_x$  is a constant and  $Q_x$  is the exposure value at 50% transmission of element X.

Equation (2) can be rewritten in the form of equation (1) as follows:

$$\frac{1}{Q_x} = K_x \cdot C_x$$

The intercept c, on the y-axis of equation (1) is taken as zero and is explained later on in this section (see page 139). © University of Pretoria


The same general formula applies for the internal standard Y, namely:

$$C_{y} = \frac{K_{y}}{Q_{-}}$$
(3)

 $Q_y^-$  is the mean exposure value of Y for the charge states 1+ and 2+ (see page 29).

Combining equations (2) and (3) gives:

$$\frac{Q_{\mathbf{x}}}{Q_{\mathbf{y}}^{-}} = \frac{K_{\mathbf{x}}}{K_{\mathbf{y}}} \cdot \frac{C_{\mathbf{y}}}{C_{\mathbf{x}}} \qquad \dots \dots \dots \dots (4)$$

where:

 $\frac{Q_x}{Q_y^-}$  is the instrument signal, expressed as the ratio between the exposure value,  $Q_x$ , of element X at 50% transmission and the exposure value  $Q_y^-$ , of the internal reference standard, Y, at 50% transmission;  $\frac{C_y}{C}$  is the ratio between the concentration of the internal

reference standard, Y, and the concentration of element X which is given in  $\mu g$  X/gU; and

 $\frac{K_x}{K_y}$  is the slope, expressed as the relative sensitivity factor (RSF) [18, 31] of an element X, relative to the internal reference standard, Y.

The concentration of the internal standard, Y, is taken as 20  $\mu$ g Y/gU when analysing unknown U₃O₈ samples and 132  $\mu$ g Y/gU when analysing unknown UF₄ samples. The choice of these concentrations of the internal standard is comprehensively described on pages 29, 103 and 122.



The concentration of an element X varies according to the range of graphite standards prepared. The choice of these ranges is comprehensively described on page 103 for a  $U_3O_8$ /graphite matrix and on page 122 for a UF₄/graphite matrix.

The instrument signal,  $Q_x/Q_y^-$ , is obtained when doing data interpretation and is taken as the intercept at a 50% transmission of the Hull function plot. This is described on page 36.

The origin (0;0), of the calibration graph is also incorporated in the calibration line. This is shown as follows: When  $C_x$  tends to infinity, then the expression  $C_y/C_x$  tends to zero when  $C_y$  is taken as constant. From equation (2), when  $C_x$ tends to infinity, then  $Q_x$  tends to zero. Likewise, the expression  $Q_x/Q_y^-$  tends to zero when  $Q_y^-$  is taken as constant because  $C_y$ is constant. Thus both expressions tend to the origin (0;0) when  $C_x$  tends to infinity. This verifies the use of the origin as a data point when compiling calibration graphs.

Linear regression formulae [29] (see Appendix A on page 174) are used to determine the standard error,  $s_m$ , in the slope of the regression line. The confidence limits of the slope, expressed as a, is given by the following formula [32]:

where:

 $s_m$  is the standard error of the slope, and t is the Student's t-value [33] at a 95% confidence level (CL) with (n-2) degrees of freedom where n is the number of data points (x;y) used to draw up the calibration graph.

The parameters RSF,  $\alpha$ , c, r and n obtained from the regression line are given in Table 5.2 (see page 111).



# 6.1.2 Propagation-of-errors approach [30, 34]

This method is used when determining the concentration  $C_{\chi}$ , of an element X, in an unknown  $U_3O_8$  sample. Equation (4) can be rewritten as follows:

$$C_{x} = \frac{(RSF \pm \alpha) . (C_{y} \pm c_{y})}{\frac{Q_{x}}{\frac{Q_{y}}{Q_{y}}}} (95\% CL) \dots (6)$$

The confidence limits a, of the slope or relative sensitivity factor is obtained from Table 5.2 on page 111. Likewise, the applicable relative sensitivity factor RSF, is given in Table 5.3 (see page 120). The concentration of the internal standard, Y, given by  $C_{v}$ , is taken as 20  $\mu$ g Y/gU where graphite powder has been spiked with 80  $\mu$ g Y/gC. This graphite powder, called UFY80, is used as electrode material when analysing unknown U₃O₈ sam-The error in  $C_v$ , given by  $c_v$ , is taken as 0,5% which is ples. the maximum imprecision of a 1 000  $\mu$ 1 varipette used to dispense the Y ICP standard solution. The precision of the Mettler H10T mass balance used to weigh out the required mass of graphite powder is 0,1 mg which gives an error of 0,002% when 5 grams of graphite is used. The Y ICP standard solution is certified to <0,01% and the error is not significant. These errors can be ignored statistically and only the error in the varipette, 0,5%, is taken as  $c_v$  [38].

The precision of the method is also known and is given in Table 6.1 (see page 147). For a single analysis of an unknown  $U_3O_8$  sample, the error coupled to the instrument signal,  $Q_X/Q_y^-$ , for element X is taken as twice the standard deviation, 2s [35, 38]. This is based on the assumption of a normal distribution of results where an analysis result has a 95% chance of lying within two standard deviations of the mean.



When considering the general error formulae used in composite errors, the following applies [36, 37]: For a number of quantities, n, with means  $\bar{x}_1$ ,  $\bar{x}_2$ , ....,  $\bar{x}_n$ , with standard errors  $a_1$ ,  $a_2$ , ...,  $a_n$ , the standard error of

any function of  $\bar{x}_1, \bar{x}_2, \dots, \bar{x}_n$ , namely,  $f(\bar{x}_1, \bar{x}_2, \dots, \bar{x}_n)$  is

given by 
$$\alpha$$
, where  $\alpha^2 = (\frac{\partial f}{\partial \bar{x}_1})^2 \alpha_1^2 + (\frac{\partial f}{\partial \bar{x}_2})^2 \alpha_2^2 + \dots + (\frac{\partial f}{\partial \bar{x}_n})^2 \alpha_n^2$ 

The quotient of two mean values is given by:



The product of two mean values is given by:

 $f(\overline{x}_1, \overline{x}_2) = \overline{x}_1 \cdot \overline{x}_2$ 

thus  $\frac{\partial f}{\partial \bar{x}_1} = \bar{x}_2$  and  $\frac{\partial f}{\partial \bar{x}_2} = \bar{x}_1$ 

This gives  $\alpha^2 = \overline{x}_2^2 \alpha_1^2 + \overline{x}_1^2 \alpha_2^2$ 

Applying the above equations (7) and (8) to equation (6), the standard error, s_C, of the concentration of element X in the x unknown sample is derived.

Thus 
$$s_{C_{X}} = \frac{1}{Q_{X}} \cdot \sqrt{\frac{Q_{X}}{(Q_{Y}^{-})^{2}} \cdot (C_{Y}^{2}\alpha^{2} + RSF^{2}c_{Y}^{2}) + (RSF \cdot C_{Y})^{2} \cdot (2s)^{2}} \cdot \dots \cdot (9)$$

The final result of element X is reported as:

$$C_{\mathbf{x}} \pm s_{C_{\mathbf{x}}}$$
 (95 % CL)

This gives the confidence interval derived using the propagationof-errors method at a 95 % confidence level.



#### 6.1.3 Precision

In order to determine the precision coupled to the analysis of  $U_3O_8$ /graphite matrix samples using spark-source mass spectrometry, three of the prepared graphite standards with concentrations of 1,0; 10,0 and 50,0 µg X /gU were each analysed six times (i.e. n = 6) mixed with the base  $U_3O_8$  (see page 103). The results obtained are tabulated in Table 6.1 on page 147. The precision that is obtained is for both the instrument and the analyst.

The standard error at a 95% confidence level (CL) was determined using the following formula [37]:

where:

 $\bar{x}$  is the mean of the six analyses of one standard; s is the standard deviation of the six analyses; and t is the Student's t-value taken at a 95% confidence level using (n - 1) degrees of freedom (v).

Before the above formula could be used, the data obtained had to be subjected to the Dixon outlier test [38, 39, 40, 41] in order to ascertain whether there were any "mavericks". The Dixon outlier test assumes that the parent population from which the measurements are obtained is normally distributed.

One way of assessing a suspect measurement is to compare the difference between it and the measurement nearest to it in size with the difference between the highest and lowest measurements. The ratio of the differences is known as Dixon's Q and is given as  $Q_{calc}$  in the following basic formula:

| suspect value - nearest value |

 $Q_{calc}$ 

(largest value - smallest value) © University of Pretoria .... (2)



The critical values of Q, given as  $Q_{tab}$ , are taken from the table of critical values for Q at a 95% confidence level (CL).

The following reasoning is applied in the Dixon test: If  $Q_{tab} \ge Q_{calc}$ , then the suspect value is retained; if  $Q_{calc} > Q_{tab}$ , then the suspect value is rejected. From the table of critical values of Q, the sample size in this case is taken as six.

It is important to note that at a 95% CL there is still a 5% chance of incorrectly rejecting the suspect value. When measurements are repeated only a few times rejection of one value makes a great difference to the mean and standard error. This has a considerable effect on the estimation of the precision. The importance of caution in rejecting outliers cannot be over-emphasised. There is also the possibility of two suspect values which leads to masking in the application of the Dixon Q-test.

Using the above approach, suspect values were rejected for a number of elements from each of the standards. This is shown in Table 6.1 where n = 5. For  $Mo^{1+}$  (n = 4) and  $Sm^{1+}$  (n = 3), the experimental data obtained was limited as the spectral lines on the photographic plate could not be measured in all the cases.

An assessment of the results tabulated in Table 6.1 reveals that most of the standard errors at a 95% CL are below 20% with the exception of a few cases which will be explained below. This is in accordance with values reported by many other authors [31] who have used electrical detection, radio frequency (RF), glow discharge (GD) and other types of spark-source mass spectrometers for analysing U samples.



The first few elements in Table 6.1, namely B, Mg and A1, have high standard errors at all the concentration levels. This is ascribed to interference of their spectral lines at masses 10 and 11 for B, 12,5 for Mg and 13,5 for A1, due to the spectral lines of the matrix component C at masses 12 and 13. The C spectral lines, being from the major constituent of the sample, are intense and dispersed in the region surrounding them, thus affecting the adjacent spectral lines and their precision, irrespective of concentration.

The standard errors for most of the elements at a concentration level of 1  $\mu$ g X /gU are relatively high. This is a result of unreliable data obtained from the transmission curves. Only a few points could be utilised in the Hull function plot as most of these were light points. This could also be ascribed to the fact that at this concentration level, the detection limit for some of the elements is reached. Typical examples affected in this manner are Mn¹⁺, Zn¹⁺, Zr¹⁺ and the heavier elements such as the rare earths Sm, Eu and Dy.

The high standard errors at a 95% CL for the heavier elements, such as the rare earths at a concentration level of  $1 \mu g X / gU$ , is ascribed to the fact that these elements provide small ion yields of the various charge states resulting in poor transmission curves. The atomic size of these elements affects the number of ions entering the ion source due to collisions. These ions also have a smaller velocity down the flight tube of the mass spectrometer. All these factors have a decisive impact on the nett total of ions yielded at the photographic plate.

The very high standard error for  $Mo^{1+}$  at a 95% CL, namely 84,1%, can be ascribed to the previous reasons (poor ion yield, near the



low concentration detection limit, as well as the small number of useful data points). When applying the formula to determine the standard error at a 95% CL, the degrees of freedom (v) is given as (n - 1), i.e. 3 where n = 4, which is relatively small. This means that the standard deviation, s, is multiplied by a factor 1,59 (3,182/2) giving a higher standard error. As n gets larger, the factor of  $t/\sqrt{n}$  gets smaller, thus reducing the standard error in a significant way.

The standard errors for Ca²⁺ and Si¹⁺ are relatively high as the Ca²⁺ spectral line was measured as a doublet and the Si¹⁺ spectral line was measured as a triplet. The analyst has to set windows around these lines and this affects the background surrounding the spectral lines which are under scrutiny. This leads to a weaker precision at all concentration levels.

The high standard error for Ni¹⁺ at 95% CL at a concentration of 50  $\mu$ g Ni /gU, namely 34,2%, is verified as follows. From the raw data obtained, there is one data point out of the set of six (n = 6) that appears to differ from the remainder. However. when applying the Dixon outlier test to this data point, the test shows that this data point cannot be taken as an outlier and must thus be retained. This leads to the high standard error. If the Dixon outlier test had shown that this point could be rejected, the precision would have been 15,9% for the remainder of the This could be interpreted as a possible data points (n = 5). limitation of the Dixon outlier test.

The precision values obtained are used together with the relative sensitivity factors (RSF's) when analysing the unknown  $U_3O_8$  samples where the error in the instrument signal is taken as twice the standard deviation.

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<u>TABLE 6.1</u>: Precision for  $U_3O_8$ 

1				T			
Element	Charge	$C_{\rm X} = 1\mu g \ X \ /gU$		$C_{X} = 10\mu g X / gU$		$C_{\mathbf{X}} = 50 \mu g \mathbf{X}$	/gU
	State	Std Error at 95% CL (%)	n	Std Error at 95% CL (%)	n	Std Error at 95% CL (%)	n
В	1	27,6	6	24,8	6	36,1	6
Mg	2			10,3	5	40,4	6
A1	2			24,7	6	22,6	6
Si Si	2 1	38,6	6	11,1 25,3	6 6	16,6 35,5	6 6
Ca	2	12,0	6	24,8	6	29,5	6
Ti Ti	2 1	21,2	6	6,1	5	13,2	6
V V	2 1	7,6	6	13,9 10,5	6 6	15,9 8,8	6 6
Cr Cr	2 1	17,7	6	10,8 14,0	6 6	10,7 18,6	6 6
Mn Mn	2 1	29,7	6	16,3 19,1	6 6	22,0 19,1	6 6
Fe Fe	2 1	18,9	6	19,0 15,5	6 6	12,8 15,4	6 6
Co Co	2 1	6,6	6	11,2 5,0	6 6	17,2 17,7	6 6
Ni	1	19,3	6	2,6	6	34,2	6
Cu Cu	2 1	15,3	6	7,1 15,3	6 6	17,0 19,3	6 6
Zn	1	32,5	6	8,8	6	21,6	6
Sr Sr	2 1	18,1	6	10,2 9,4	6 6	17,2 15,7	6 6
Zr Zr	2 1	36,1	6	8,4 6,2	6 6	15,8 11,2	6 6
Nb Nb	2 1	18,2	6	10,6 10,9	6 6	15,6 5,8	6 5



## Table 6.1: Continued

	Charge	$C_{\mathbf{X}} = 1 \mu g \mathbf{X} / g U$		$C_{\mathbf{X}} = 10 \mu g X$	/gU	$C_{\mathbf{x}} = 50 \mu g X$	/gU
Element	State	Std Error at 95% CL (%)	n	Std Error at 95% CL (%)	n	Std Error at 95% CL (%)	n
Mo Mo	2 1	84,1	4	8,6 7,1	6 6	16,2 11,2	6 6
Ru Ru	2 1			13,9 7,7	6 5	12,2 5,0	6 5
Cd	1			10,4	б	15,3	6
In	1	23,9	6	11,7	6	21,9	6
Sb Sb	2 1	34,1	6	7,6 12,2	6 6	8,6 16,3	6 6
Ba Ba	2 1	27,5	6	8,6 15,9	6 6	8,9 17,1	6 6
Sm Sm	2 1	48,3	5	9,4 18,8	6 3	10,7 17,0	6 6
Eu Eu	2 1	33,3	6	7,3 5,8	6 6	14,2 8,8	6 5
Gd Gd	2 1			6,8 8,4	5 5	9,3 5,0	6 5
Dy Dy	2 1	32,0	5	14,9 7,3	6 5	9,8 12,4	6 6
Bi	2			25,2	6	15,0	6
Th	2	25,8	6	12,9	6	20,2	6

# 6.1.4 Confidence Intervals - U₃O₈

Confidence limits of the slope, expressed as  $\alpha$ , have a significant influence on the relative sensitivity factor (RSF) derived



as the slope of the calibration curve. Large a values mean large uncertainties in the RSF's. These uncertainties must be included in the overall errors calculated for the final analysis results. Values of a greater than 20% in Table 5.2 (see page 111) can be ascribed to a number of reasons, of which the important ones are given below.

The value of n has a significant influence on the value of  $\alpha$ . This can be demonstrated using equation (5) on page 139 where the t-value is obtained using (n - 2) degrees of freedom at a 95% confidence level (CL). For n = 7, the t-value from the Students t-Distribution Table is 2,571. The standard error in the slope,  $s_m$ , must be multiplied by this number in order to obtain the  $\alpha$ value and leads to large confidence limits of the slope.

When determining the calibration curve parameters, each analysis of a graphite standard sample was treated as an individual analysis. Thus, when a graphite standard was analysed in triplicate, the value of n was taken as three. This was typically done using the check graphite standards where some elements were analysed for the first time, e.g. Na, P, K and W. Using two such check graphite standards together with the origin (0;0) gives a t-value of 2,571, where n = 7. This means that a standard error in the slope of 20% becomes a confidence limit of 51,4%. A number of elements in Table 5.2 fall into this category, namely Na¹⁺ (11%), P¹⁺ (8,1%), P²⁺ (13,6%), K²⁺ (7,8%) and W²⁺ (14,5%), where the standard error is given in brackets after each element.



The ion yields of certain elements with specific charge states at their lowest concentration levels are not very good, with the result that poor transmission curves are obtained. Only a few long exposure values are used in the Hull function plot and the rest of the data points are discarded as light points. The charge state differs from element to element depending on the atomisation and ionisation of the particular element. This can be illustrated when plotting characteristic curves of number of ions yielded against charge state. A number of cases in Table 5.2 where a is near or greater that 20 % can be placed into this category, namely  $K^{2+}$ ,  $Ru^{2+}$ ,  $Ba^{1+}$ ,  $W^{1+}$ ,  $Sm^{1+}$ ,  $Mo^{1+}$  and  $Sb^{1+}$ .

Elements with large atomic radii are more prone to collisions and also have a slower velocity down the flight tube. This leads to fewer ions reaching the photoplate. From Table 5.2, elements falling into this category are  $Sm^{1+}$ ,  $W^{2+}$ ,  $Ba^{1+}$ ,  $Mo^{1+}$ ,  $Sb^{1+}$  and  $Ru^{2+}$ .

The correlation coefficient, r, in Table 5.2 can also be coupled to a larger a value. Ideally r should be unity, thus values of r < 0,90 show that the fit of calibration data to the regression line is seriously affected by a few bad data points. The inclusion of these bad data points is confirmed by applying the Dixon outlier test which shows that these values have to be retained. However, great caution should be exercised in drawing conclusions from the result of repeated applications of the Dixon's test. If a few statistical outliers are found at a certain particular concentration level this is not very serious, but if several outliers occur at different concentration levels, this may be considered as indicating that the regression line and thus the RSF is This would lead to a large spread of data points inaccurate. resulting in a large standard error in the slope, s_m.



Correspondingly, a larger a value is obtained. Elements in Table 5.2 having poor correlations where r < 0,90 are  $Fe^{1+}$ (r = 0,853) and  $Ba^{1+}$  (r = 0,897). This is in spite of n being large for  $Fe^{1+}$  (n = 30) and  $Ba^{1+}$  (n = 22). Elements in Table 5.2 having correlation coefficients of r < 0,95 are the following:  $Mg^{2+}$ ,  $Si^{2+}$ ,  $Ca^{2+}$ ,  $Mo^{1+}$ ,  $Sb^{1+}$  and  $Sm^{1+}$ .

For Mg²⁺, Si²⁺, Fe¹⁺ and Na¹⁺ it is significant to note that these elements all have high background concentrations in the blank base U₃O₈ sample. The influence of this high blank concentration on the calibration line is discussed on page 105. This effectively reduces the range on the x-axis of the calibration plot. Typically, for Fe¹⁺ the range on the x-axis is from zero to 0,2844. The spread of data points in this case is larger than over a greater range on the x-axis and results in a poor fit of the data points on the regression line. Another reason for  $Mg^{2+}$  having an  $\alpha$  of 19,3% is the fact that it is measured at m/e 12,5 which lies inbetween the two spectral lines of the major component of the U₃O₈/graphite mixture, namely ¹²C and ¹³C at m/e 12 and 13, respectively. Intense fogging on the surrounding background makes the measurements of Mg²⁺ difficult and inaccurate.

When using a values to determine the error coupled to an element's concentration in an unknown  $U_3O_8$  sample, the analyst must exercise great care. In the case of  $Ba^{1+}$  (23,0%) and  $Sm^{1+}$ (45,0%), the analyst should avoid using these charge states, and should rather use the other charge states where the a values are more acceptable. The same argument applies for  $W^{2+}$  (40,3%).

The  $\alpha$  value for the impurity elements in a U₃O₈/graphite matrix are tabulated in Table 5.2. However, these have also been given as a visual presentation in the form of two periodic tables, the



first for the singly charged species, Figure 6.1, and the other for the doubly charged species, Figure 6.2. It is demonstrated that the appropriate application of the guidelines for quantification enables the acquisition of analytical data within very acceptable confidence intervals for most of the selected elements.

# 6.1.5 Confidence Intervals - UF4

The confidence limits of the slope, expressed as a and as a percentage in Table 5.5 on page 127, is a direct measure of the uncertainty coupled to the RSF. The a value for S is the only one which is relatively high (26,9%) for impurities in a UF₄ matrix. This could be attributed to a number of factors of which the most important is the fact that sulphur is measured at mass 32 as a doublet with the main interference being  ${}^{64}Zn^{2+}$ . This could influence the data and result in a bigger spread of data points for the calibration curve. This bigger spread implies a larger standard error in the slope, resulting in a large a value. This fact is also supported by the relatively poor correlation coefficient obtained (r = 0,9575) for the regression line.

The  $\alpha$  value for S could also be influenced by the relatively high background concentration in the blank UF₄ ( $C_x = 385, 4 \ \mu gS/gU$ ). This value is used together with the concentration of the standard to define the x-value in a data point (x;y) when applying linear regression. The higher the blank concentration, the more influence it has on the  $C_y/C_x$  value on the x-axis. The standard error for S in the blank UF₄ at a 95% confidence level (38,74%) is also an indication of the difficulty experienced to obtain reliable data for sulphur in a UF₄ matrix.





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Figure 6.2: Confidence intervals (a) at 95% CL for  $X^{2+}$ in U₃O,

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The other  $\alpha$  values in Table 5.5 are all acceptable in the sense that they fall within the precision of the instrument and the analyst. The exceptionally good  $\alpha$  values obtained for A1 = 0,84% and Zn = 0,87% where n = 10 for both elements is an indication of the accuracy of the method over a wide concentration range. The reproducibility of the results and the homogeneity of the standards are illustrated by these  $\alpha$  values. It should also be noted that A1 and Zn both have the lowest concentrations in the blank UF, as shown in Table 5.4 on page 123.

#### 6.2 <u>Comparative</u> analyses

#### 6.2.1 International standard U₃O₈ No IAEA/SR-54

The analysis results are tabulated in Table 6.2. For the certified reference material (CRM) SR-54 the concentration values and their confidence intervals at 95% CL for impurity elements in  $U_3O_8$  were obtained from the certificate of analysis. Various analytical methods were used to obtain these concentration values. The results obtained using spark-source mass spectrometry are the mean of four analyses, where equation (4) on page 136 was used to calculate the concentration  $C_{_{\mathbf{Y}}}$  of impurity element X The standard error values at 95% CL in Table 6.2 in the CRM. were obtained using equation (9) on page 142. The SSMS concentration values compare favourably to those certified for the CRM SR-54, especially if the confidence interval is also taken into account. Where differences do occur, notibly for V, it must be borne in mind that the concentration value for the CRM SR-54 was presented as non-certified information.

#### 6.2.2 Internal U₃O₈ certified standards

As a result of the non-availability of suitable standards at trace levels of elements in a U matrix, the Atomic Energy Corporation prepared a series of standards according to guidelines as



<u>TABLE 6.2</u> :	Comparison	of	U ₃ 0,	CRM	SR-54	with	SSMS
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Element	Certified conc. value (µg X /gU)	Confidence interval at 95% CL	SSMS conc. value (µg X /gU)	Std error at 95% CL
Al	71,3	54,8 - 82,0	70,4	15,9
Со	4,2	4,0 - 4,3	5,2	1,3
Cr	3,6	3,1 - 4,3	2,9	0,8
Cu	5,0	4,2 - 6,7	5,7	0,5
Fe	64,7	46,0 - 77,5	66,2	10,2
K	1,7*	-	3,3	0,7
Mg	0,99*	0,81 - 1,1	1,9	0,8
Mn	15,6	14,3 - 16,9	18,4	3,7
Мо	13,0	9,5 - 17,5	12,7	1,1
Na	2,8*	-	3,9	0,8
Ni	11,4	8,4 - 13,9	10,8	2,0
Si	34,3*	18,0 - 53,5	29,8	7,5
Ti	0,98*		1,74	0,37
V	3,7*		0,12	0,01
Zn	2,4*	0,89 - 3,2	2,2	0,2
* The: non-	se values are n certified info	not certified, but are primation values.	presented as	

laid down by the New Brunswick Laboratory[#]. These standards covered a wide concentration range and were prepared in a  $U_3O_8$ 

# U.S. Department of Energy, New Brunswick Laboratory, 9800 S. Cass Avenue, Building 350, Argonne, Illinois, 60439, U.S.A.



matrix. The standard with the highest concentration level of impurity elements is called ES 1 and the comparison between the certified value and the concentration value obtained with the spark-source mass spectrometer is given in Table 6.3. The standard with the lowest concentration of impurity elements is called ES 5 and the comparison of results obtained is given in Table 6.7. Standards with concentrations falling inbetween ES 1 and ES 5, named ES 2, ES 3 and ES 4, are given in Tables 6.4, 6.5 and 6.6 respectively.

Of every standard in the ES series of standards, three samplings were each analysed in triplicate. This resulted in each ES series of standards being analysed nine times by a specific analytical technique. The spark-source mass spectrometer (SSMS) concentration values given in Table 6.3 to Table 6.7, are the mean concentrations over nine analyses. These concentration values within an ES standard were also subjected to the Dixon outlier test to ascertain whether there were any outliers before each final mean value was reported.

The formula used to calculate the concentration,  $C_{_X}$ , of an impurity element X in each of the ES series of standards is given by equation (4) on page 136. However, this concentration value also contains the contribution from that impurity element also found in the graphite which was used to mix with the  $U_3O_8$  ES series of standards. This has been described on page 108. The concentration levels of impurity elements in the graphite were quantified and deducted from the mean concentration values reported for each of the ES series of standards.



Various analytical methods were used by different laboratories in order to certify these internal  $U_3O_8$  standards, amongst others:

- Inductively coupled plasma (ICP) optical emission spectroscopy (OES),
- Ion chromatography (IC),
- Carrier distillation emission spectroscopy (CDES),
- Atomic absorption spectroscopy (AAS), and
- UV spectroscopy.

It is beyond the scope of this investigation to go into any detail of how the data obtained for the ES series of standards analysed with the above methods, was evaluated. The certified concentration values and confidence intervals at a 95% CL for the various impurity elements across the ES series of standards given in Tables 6.3 to 6.7 were obtained after the evaluation. These certified values were calculated from the experimental data.

The standard error values at a 95% CL in Tables 6.3 to 6.7 were obtained using equation (9) on page 142. However, the term 2s in this equation was replaced by the term  $s.t/\sqrt{n'}$  as denoted by equation (1) on page 143. This is in accordance with the fact that the  $Q_x/Q_v^-$  value used in equation (9) is the mean of several (nine) analyses as previously mentioned in this section. The standard error coupled to this mean  $Q_x/Q_v^-$  value at a 95% CL is thus derived using equation (1) where n is taken as nine and s is the standard deviation over the nine analyses. The other terms used in equation (9) are identical to those used in equation (6) on page 142 and which were comprehensively described. The use of equation (6) was not warranted as multiple analyses were performed and not just a single analysis.



When comparing the results in Tables 6.3 to 6.7, a number of facts should be kept in mind. The certified values must not be accepted as being the absolute values for particular impurity elements in the series of ES standards. A better representation of the results obtained is given in Appendix C on page 191 where graphs have been compiled for all the impurity elements across the concentration range for each of the analytical methods in comparison to the expected concentration values. In this way anomalies can be detected and comparisons drawn between the spark-source mass spectrometry results and the expected concentration values.

Another interesting fact to consider is whether there is a meaningful difference between a certified value of, for example, 0,1  $\mu$ g Cd/gU and a SSMS value of 0,64  $\mu$ g Cd/gU, as reported in Table 6.7. Both these values are less than 1  $\mu$ g Cd/gU and at these trace levels the detection limits of certain analytical instruments have to be considered. The same could be true for Fe in Table 6.4 where the certified value is given as 208  $\mu$ g Fe/gU and the SSMS value is given as 264  $\mu$ g Fe/gU. In view of the various confidence intervals for these two values, it is clear that the analyst should not compare exact values with each other but also take cognicance of the confidence limits coupled to a result when assessing such data.

The SSMS concentration value obtained for Ca across the ES series of standards is higher than the certified concentration values. The higher value could possibly be coupled to an incorrect relative sensitivity factor (RSF) for Ca. This can be seen in the graph for Ca in Appendix C where the graph for SSMS (method B) lies above the dotted line which represents the true concentration values. The very high value for Ca obtained for the ES 1 standard with SSMS was also obtained by three other analytical techniques, namely A, C and D. It has not been possible to



confirm the reasons for this difference. Ca is a difficult element to determine with spark-source mass spectrometry and the investigation has not been persued for this element.

The SSMS concentration value obtained for Th across the ES series of standards is higher than the certified concentration values reported for ES 1, ES 2 and ES 3, although no confidence intervals were reported for these values. However, the SSMS results compare favourably to the expected values as shown in the graph in Appendix C.

It should be noted from the graphs in Appendix C that the mass spectrometry results in general, compare remarkably well with the expected standard values.



<u>Table</u>	<u>6.3</u> :	Comparison	of	U ₃ O ₈ -Standard	ES	1	with	SSMS	
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Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error at 95% CL
A1	234	189 - 279	242	43
В	5,7	5,0 - 6,4	4,9	1,0
Bi	14,3	11,6 - 17,0	13,1	3,0
Ca	272	245 - 299	416	110
Cd	· 5,5	5,0 - 6,1	6,0	1,3
Со	26,6	23,7 - 29,5	28,8	3,5
Cr	125	77 - 174	154	27
Cu	104	84,4 - 124	120	21
Dy	0,56	0,43 - 0,69	0,71	0,24
Eu	0,56	0,44 - 0,68	0,69	0,16
Fe	827	663 - 990	972	191
Gd	0,64	0,41 - 0,87	0,85	0,34
In	6,2	4,4 - 7,9	8,9	1,6
K	536	481 - 591	379	112
Li	11,5	9,31 - 13,7	13,2	3,8
Mg	. 56,2	48,5 - 63,9	49,8	14,6
Мл	55,3	47,5 - 63,2	65,1	15,5
Мо	54,6	46,1 - 63,1	59,4	7,3
Ni	233	209 - 259	243	47
Sb	11,2	9,2 - 13,1	13,8	2,8
Si	206	169 - 244	221	65
Sm	0,60	0,51 - 0,69	0,62	0,17
Th	3,4	-	11,0	1,7
Ti	52,5	39,9 - 65,1	56,4	12,5
v	5,08	3,97 - 6,19	5,40	0,38
W	13,3	11,4 - 15,2	12,7	5,0
Zn	. 247	207 - 287	261	41
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Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error at 95% CL
A1	115	93 - 137	120	24
В	3,8	3,3 - 4,3	3,5	0,7
Bi	5,3	4,2 - 6,3	5,6	1,5
Ca	108	97 - 119	163	32
Cd	. 2,7	2,4 - 3,0	3,0	0,7
Со	13,5	12,0 - 14,9	13,9	1,1
Cr	59	36 - 82	65	11
Cu	54,1	43,7 - 64,4	58,3	5,7
Dy	0,56	0,43 - 0,69	0,69	0,16
Eu	0,39	0,30 - 0,48	0,49	0,14
Fe	208	165 - 251	264	53
Gd	0,47	0,29 - 0,65	0,64	0,42
In	5,3	3,8 - 6,8	6,4	1,1
K	180	162 - 199	171	35
Li	9,51	7,70 - 11,3	10,8	3,1
Mg	21,8	18,7 - 24,8	22,9	6,2
Mn	25,1	21,6 - 28,7	29,0	4,5
Мо	2,0	1,7 - 2,4	2,4	0,6
Ni	97,4	87,3 - 107	92,0	11,1
Sb	8,0	6,6 - 9,4	10,0	1,9
Si	75	59 - 90	77	17
Sm	0,59	0,50 - 0,68	0,66	0,32
Th	0,6		5,5	0,58
Ti	25,2	19,1 - 31,2	26,7	4,4
V	2,03	1,55 - 2,51	2,18	0,25
W	5,7	5,0 - 6,4	5,3	2,37
Zn	98,4	82,2 - 115	95,9	14,1

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<u>Table 6.4</u> :	Comparison	of	$U_{3}O_{a}$ -Standard	ES	2	with	SSMS
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<i>Table 6.5</i> :	Comparison	of	U ₃ O ₈ -Standard	ES	3	with	SSMS

	I	Y		
Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error at 95% CL
A1	68	54 - 81	68	18
В	1,4	1,2 - 1,6	1,3	0,3
Bi	3,8	3,0 - 4,6	4,9	1,7
Ca	72	65 - 79	99	20
Cd	1,0	0,9 - 1,2	1,3	0,3
Со	5,1	4,5 - 5,7	5,8	0,6
Cr	28	17 - 40	29	7
Cu	34,0	27,4 - 40,5	38,3	5,6
Dy	0,48	0,36 - 0,60	0,54	0,21
Eu	0,39	0,30 - 0,48	0,50	0,11
Fe	72	56 - 89	65	16
Gd	0,22	0,12 - 0,32	0,74	0,20
In	4,3	3,0 - 5,5	5,7	1,0
K	87	78 - 96	79	22
Li	7,12	5,75 - 8,49	7,86	2,1
Mg	11,4	9,8 - 13,0	15,9	4,9
Mn	12,1	10,4 - 13,8	13,3	2,1
Мо	1,2	1,0 - 1,4	1,3	0,3
Ni	53,9	48,3 - 59,6	52,2	8,2
Sb	3,9	3,1 - 4,7	5,2	1,2
Si	44	33 - 54	63	21
Sm	0,43	0,36 - 0,50	0,56	0,20
Th	0,3	-	3,0	0,5
Ti	10,9	8,3 - 13,6	10,1	2,0
V	1,01	0,74 - 1,28	1,22	0,12
W	4,2	3,6 - 4,7	3,7	1,6
Zn	54,8	45,6 - 63,9	62,7	7,6
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<u>Table 6.6</u> : 0	Comparison	of	U308	-Standard	ES	4	with	SSMS
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Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error at 95% CL
A1	23	19 - 28	27	5
В	0,6	0,5 - 0,7	0,8	0,1
Bi	2,5	1,9 - 3,0	3,1	0,8
Ca	23,8	21,2 - 26,4	34,1	5,7
Cd	0,5	-	1,5	0,4
Со	2,7	2,4 - 3,0	3,5	0,3
Cr	16	9 - 23	19	3
Cu	11,4	9,1 - 13,6	14,2	1,8
Dy	0,40	0,30 - 0,50	0,59	0,16
Eu	0,37	0,28 - 0,46	0,51	0,13
Fe	29	21 - 37	40	8
Gd	0,24	0,13 - 0,35	0,90	0,38
In	2,5	1,7 - 3,3	4,7	0,7
K	48	43 - 53	46	12
Li	3,25	2,60 - 3,90	3,73	0,44
Mg	5,4	4,6 - 6,2	8,8	2,2
Mn	5,73	4,9 - 6,6	7,24	1,32
Мо	5,3	4,5 - 6,2	6,7	0,9
Ni	23,2	20,7 - 25,7	25,0	2,5
Sb	1,6	1,2 - 2,0	4,2	0,7
Si	13	8 - 19	31	8
Sm	0,41	0,35 - 0,47	0,59	0,10
Th	_		1,1	0,2
Ti	5,5	4,2 - 6,9	6,3	1,1
V	0,44	0,29 - 0,59	0,79	0,17
W	2,8	2,4 - 3,2	3,3	1,5
Zn	22,9	18,9 - 26,8	29,0	4,0
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<u> Table 6.7</u> : Comparison	of	U ₃ O ₈ -Standard	ES	5	with	SSMS	
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Element	Certified conc value (µg X /gU)	Confidence in- terval 95 % CL	SSMS conc value (µg X /gU)	Std Error of 95% CL
A1	12	0 - 15	14	3,4
В	0,4	0,30 - 0,40	0,9	0,2
Bi	0,6	0,5 - 0,8	1,6	0,6
Ca	11	9,7 - 12,3	29	6,7
Cd	0,1		0,64	0,2
Со	2,6	2,3 - 2,9	3,8	0,5
Cr	12	7 - 17	12	2
Cu	6,2	5,0 - 7,5	8,5	0,8
Dy	0,23	0,16 - 0,30	0,50	0,38
Eu	0,22	0,16 - 0,28	0,36	0,08
Fe	19	13 - 25	24	5
Gd	0,16	0,08 - 0,20	0,39	0,02
In	1,8	1,2 - 2,4	3,1	0,5
K	20	17 - 22	22	7
Li	1,86	1,47 - 2,25	2,37	0,86
Mg	2,4	2,0 - 2,8	5,9	1,7
Мл	3,09	2,6 - 3,6	4,8	0,9
Мо	20,9	17,6 - 24,2	24,4	2,6
Ni	12,8	11,4 - 14,2	15,4	2,0
Sb	0,5	0,3 - 0,8	2,6	0,6
Si	_		85	33
Sm	0,18	0,14 - 0,22	0,30	0,26
Th	_	-	0,71	0,2
Ti	3,1	2,3 - 3,9	4,5	0,8
v	0,14	0,05 - 0,23	0,39	0,1
W	0,9	0,8 - 1,1	1,2	1,0
Zn	13,2	10,8 - 15,6	18,1	3,3
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CHAPTER SEVEN

GENERAL COMMENTS AND CONCLUSIONS

The success of the project for the development of analytical and data interpretation methods for the qualitative and quantitative analysis of trace impurities in uranium compounds with sparksource mass spectrometry has been adequately demonstrated.

Not only did the mass spectrometry results contribute to the characterisation of the internal U_3O_8 impurity standards, but the analytical data was in many cases closer to the expected values than those of any of the other analytical techniques.

Furthermore, the ability to analyse UF_4 materials provided analytical results which could not be obtained with any other technique available at the time.

The use of the ratio between singly and doubly charged exposure values as well as the use of the mean exposure value for the internal standard to determine whether a photoplate is acceptable or not, is a new approach to data interpretation in spark-source mass spectrometry. In this way possible misleading results can be directly avoided. Other quality assurance data interpretation methods have also been introduced. This thesis is now being used as a reference document for the mass spectrometry laboratory.

Contamination is an ever present threat to elemental trace level analysis. An effective but expensive solution would be a laboratory conforming to class 100 requirements. A relatively inexpensive alternative has been implemented in this laboratory. A laminar flow cabinet, where a curtain of HEPA filtered air is induced at the opening, is used for all sample preparation steps. Due to the positive pressure of air within the cabinet no contamination in the form of dushiverity of Peroria



The apparent disadvantages of the spark-source mass spectrometric technique are:

- 1 Successful use requires wide experience, both in the operation of equipment and in the reading and interpretation of spectra.
- 2 The instrument is essentially a comparator; for quantitative analyses, standards of composition similar to the material under analysis are required. Unknown samples therefore present a problem when quantitative results are required.
- 3 The accuracy and precision are not as high as for some spectroscopic methods, notably inductively coupled plasma mass spectrometry (ICP-MS). It should be realised that these techniques have their own unique limitations, for example, laser ablation has a big problem with point inhomogeneity.

The use of spark-source mass spectrometry to analyse trace impurities in uranium compounds is still one of the most powerful techniques available. This is confirmed by the following advantages:

- 1 The procedure is specific for the element being determined. Sources of interference can be unequivocally identified and in many cases eliminated.
- 2 Quantitative determination of traces of the elements in a powder sample can be achieved without any preliminary chemical treatment. All solid materials may be determined.
- 3 A permanent record is obtained on a photographic plate.



- 4 The technique may be applied to the determination of small quantities of added constituents or of traces of impurities to solidstate matrices where conventional methods of analysis are difficult, fail, or give less accurate results.
- 5 The information content of analytical data which can be utilised is vast. This compensates for the relatively high operation costs of the technique. A direct complete picture can be obtained for all major and minor elements with the analysis of a single sample. This is especially useful when characterising unknown samples as well as for semi-quantitative analyses. Quantitative analysis with alternative methods for the identified impurities can then be executed cost effectively.
- 6 All isotopes of an element are recorded on a photoplate with intensities according to their isotopic abundances which leads to undisputed confirmation that a particular element is present in the sample as an impurity.
- 7 The up-time and reliability of the instrument is a proven fact, making this technique comparable if not better than any other analytical technique in this field.

Spark-source mass spectrometry today has wider applications than just for the analysis of uranium compounds. Fields in which this technique is actively used include biomedical [42], geological [43] and horticultural science [44], as well as agricultural and environmental sciences [45]. It continues to play a prominent role in the contemporary nuclear technology laboratory [46, 47].



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LINEAR REGRESSION FORMULAE [29]

•

y = mx + c

$$s_{xy} = \frac{\binom{n}{j=1} (\frac{x}{j}) - \binom{n}{j=1} (\frac{x}{j}) (\frac{x}{j})}{\binom{n}{j=1} (\frac{x}{j})^{2}} - \frac{\binom{n}{j=1} (\frac{x}{j})^{2}}{\binom{n}{j=1} (\frac{x}{j})^{2}} \\ s_{yy} = \frac{\binom{n}{(z - y)}}{\binom{n}{j=1} (\frac{y}{j})} - \frac{\frac{j=1}{j-1} (\frac{x}{j})}{\binom{n}{n}} \\ s_{xx} = \binom{n}{(z - y)} - \frac{\binom{n}{(z - y)^{2}}}{\binom{n}{n}} \\ s_{xx} = \binom{n}{(z - y)} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{n}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{(z - x)^{2}}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{(z - x)^{2}}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{(z - x)^{2}}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{(z - x)^{2}}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{(z - x)^{2}}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{(z - x)^{2}}} \\ s_{xy} = \binom{n}{(z - x)^{2}} - \frac{\binom{n}{(z - x)^{2}}}{\binom{n}{(z - x)^{2}}} \\ s_{xy} = \binom{n}{(z - x)^{2}}} \\ s_{xy} = \binom{n}{$$



APPENDIX B

TABLE OF ATOMIC AND MOLECULAR LINES FOR SPARK SOURCE MASS SPECTROMETRY OF

COMPLEX SAMPLE-GRAPHITE MIXES

R. A. BURDO AND G. H. MORRISON Department of Chemistry Cornell University, Ithaca, N.Y.

ABSTRACT

A detailed table of atomic and molecular mass spectral lines has been prepared to aid in the interpretation of interferences and assignment of spectral lines in complex spectra arising from the spark source analysis of natural insulating powders blended with graphite to sustain the RF spark. The compilation consisting of 3000 listings is particularly useful for multielement trace analysis of geological and biological solids. Included are carbides, oxides, polymers, multiply-charged ions, and other molecular species of several or more major and minor elements as well as a large number of trace elements.



INTRODUCTION

Spark source mass spectrometry is a useful technique for multielemental trace analysis Spark source mass spectrometry is a useful technique for multielemental trace analysis of geological and biological solids. Such insulating materials are usually powdered and mixed with graphite to produce strong and conducting electrodes. However, the sparking of complex graphite mixes yields complicated spectra containing the carbides, oxides, polymers, multiply-charged ions, and other molecular species of several or more major and minor ele-ments as well as a large number of trace elements. The primary purpose of the following table is to aid in the interpretation of inter-ferences and assignment of spectral lines in complex spectra arising from the spark source analysis of natural insulating nowders in a graphite matrix. In a secondary sense, the table

analysis of natural insulating powders in a graphite matrix. In a secondary sense, the table may also be applied to other sample types or even to other fields of mass spectrometry such

may also be applied to other sample types or even to other fields of mass spectrometry such as ion probe analysis where molecular species become relatively more important. There are indeed other excellent mass tables available for general use, but they are limited for application to the specific problem as stated. More explicitly, the table of Owens and Sherman (1) is arranged by individual element with comprehensive coverage for certain kinds of species excluding carbides, oxides, and many molecular species. The table of Guthrie and Heath (2), albeit arranged by mass, excludes carbides, most oxides, charge-exchange species, and other species of interest. The aim herein is to include those species omitted in preceding tables but of possible interest in complex graphite systems, to arrange the table in order of ascending mass values, to include the relative abundance of each species listed, to indicate the theoretical resolution required to sepa-rate a listed species from a line of analytical value, and finally to be concise in format but comprehensive in scope. The latter requirement, has resulted in approximately 3000 listings each containing four data words and producing a text of approximately 12,000 words on a physical format of only thirteen pages.

Istings each containing four data words and producing a text of approximately 12,000 word on a physical format of only thirteen pages. The entire table was manually calculated, compiled, and typed and is therefore not meant as a manual of supercritical mass and abundance data, but merely as an interpretive and useful guide. The user must assume any liability of any kind incurred in the employ-ment of this table. Further, no claim is made as to the existence or nonexistence of any species listed herein, nor to that of any species accidentally or purposely omitted.

EXPLANATION OF TABLE

Each listing consists of a row of four words starting with the name of the species and followed by the mass, abundance, and resolutional requirement of the named species respectively.

I. NOMENCLATURE OF SPECIES

The usual chemical notation is used to identify the elemental constuents of the species. A leading superscript refers to the nominal mass of the species and a trailing superscript refers to the positive charge of the species. The plus signs of the charge superscripts are omitted since all species are ions of positive charge. The charge superscripts omitted since all species are ions of positive charge. The charge superscript is omitted entirely for species having a single positive charge. A special two-digit charge superscript indicates a charge-exchange species where the first digit is the initial charge of the species before a charge-reducing collision and the second digit gives the resulting or final charge after collision. The general nomenclature and the special meaning of the nominal mass superscript are best illustrated by example.

Elementally Homogeneous Species I.A.

- 12C a singly-charged ion of carbon 12 a triply-charged ion of carbon 12 (a) :
- 12Č3 (ъ)

(c)	12 C2	:	a homo-isotopic dimer of carbon and the only combination of carbon
	_		isotopes having a nominal mass of 24. (Absence of superscript = +1).
(d)	²⁵ C2	:	a hetero-isotopic dimer of carbon having a +2 positive charge and
			containing all combinations of carbon isotopes having a nominal mass
			of 25. (Only one combination in this case).

- of 25. (Only one combination in this case). a trimer of silicon containing all combinations of silicon isotopes giving a nominal mass of 86, ie, 8 Si₃ = (28 Si₂ + 30 Si) + (28 Si + 29 Si₂), where the parentheses indicate the combinations having the same nominal eeSis (e) • mass.
- 12C35 : (f)a charge-exchange species of carbon 12 where the initial charge is +3 and the final charge is +2.

I.B. Elementally Heterogeneous Species

²⁸SiC : (a)

- ⁴¹SiC : (b)
- a monocarbide of silicon 28 and the only significant* combination of carbon and silicon isotopes having a nominal mass of 40. all the combinations** of silicon and carbon isotopes having a nominal mass of 41, ie, $\binom{29}{51} + \frac{12}{2}$ and $\binom{29}{51} + \frac{13}{2}$. the only significant* combination of silicon and carbon isotopes having a nominal mass of 108, ie, there is only one silicon trimer of nominal mass 84 and only one carbon dimer of nominal mass 24. all the combinations** of silicon trimer and carbon dimer having a nominal mass of 109, ie, $\binom{85}{513} + \frac{12}{2}C_2$ and $\binom{28}{513} + \frac{25}{2}C_2$. ²⁸Si3C2: (c)
- ¹⁰⁹S1₃C₂: (d)

The word 'significant' means that if a single combination of isotopes is cited, then it is either the only possible combination or a combination which accounts for 99.0% or more of

- of the abundance of all possible combinations. The phrase 'all the combinations' means that the combinations included are either the only possible ones or that they cumulatively account for 99.0% or more of the abundance of all combinations.
 - The starred definitions have meaning in relation to the mass and abundance data following a cited species (see parts II and III).
- II. MASS (second word)

The masses of singly-charged species are taken from the table of Guthrie and Heath (2) and are rounded to five decimal places. Some elements are known to less than five places while others are only approximated vas producted by a (/) following the last digit in the mass value. Polymeric and heterogeneous species have masses equal to the sum of



the individual contributing masses. Charge-exchange masses are obtained by multiplying the singly-charged mass by a factor (m/n^2) where (m) is the initial and (n) the final charge of the ion. Multiply-charged ions have masses equal to the singly-charged mass divided by the

the ion. Multiply-charged ions have masses equal to the singly-charged mass divided by the integral number of positive charges. For species containing more than one combination of isotopes (eg., I.A.e, I.E.b, and I.B.d), the mass is that of the combination of isotopes which is the most abundant, as opposed to masses of single combinations which are unequivocal. The grouping of combinations of isotopes of the same elements to produce a species of the same chemical formula was performed to reduce the number of listings and is based on the fact that the combinations in a group are not resolvable with present commercial apparatus which have resolutions of 10,000 maximum and 5,000 or less practical.

<u>ABUNDANCE</u> (third word)

Isotopic abundances are based on Guthrie and Heath (2). Abundances apply only to species of the same kind (same chemical formula, same charge, but possibly different exact masses). For example, ²⁹SiC at mass 39.97693 comprises 31.19% of the total amount of silicon carbide formed from all combinations of silicon and carbon isotopes, ⁴¹SiC at mass 40.97649 accounts for 5.67%, etc. The abundance of ²⁹SiC is that of a single combination while that of ⁴¹SiC is the sum of the abundances of more than one combination. The abundances of molecular species which are elementally homogeneous are calculated using the binomial expansion according to Hill (3) or the equivalent probability formula given by Owens and Sherman (1) for polyatomic clusters:

 $RA = (A^{a}B^{b}C^{c}...N^{n})(M!)/(a!b!c!..n!)$

1.

where RA is the relative abundance of a given polyatomic cluster (a specified combination of isotopes) containing M total atoms of an element which has isotopes A', B', C',...N' with isotopic abundances A, B, C, ...N respectively and where the number of atoms of each isotope contained in the cluster is a, b, c, ...n respectively. The summation (a+b+c+...n) is equal to M. This formula is applied to each specific combination of isotopes until all possible combinations are exhausted.

For clusters containing different elements, the above formula is applied to each ele-ment individually and the abundance of the heterogeneous cluster is taken as the product of the indivual RA's for each element in the cluster.

The tabled abundances are given in percent. The appearance of an (E) in the tabled abundance indicates a negative exponential form so that 1.2E3, for example, means 00.0012%. For species containing more than one combination (seeI), the abundance is the sum of all combinations considered, whereas the mass is that of the most abundant combination.

IV. RESOLUTIONAL REQUIREMENT (fourth word)

Resolution is defined as $R = M_0/4M$. M_0 is indicated in the table by a series of five dashes for a line of interest at each nominal mass unit and at some half-mass units where appropriate. A negative value for R indicates that the listed species occurs at a lower mass than M_0 , the latter being indicated by the next dashed line. A positive value of R indicates a higher mass than M_0 which is defined as the first previous dashed line. The appearance of an (E) in the resolution value indicates a positive exponential form so that 15E3, for example, means a resolution of 15,000. There are no exponential forms for resolutions less than 10,000 (= 10E3).

V. SCOPE

The number and kinds of species included for each element depends on its definition as a major, minor, or trace constituent in geological and biological samples. Carbon, being the matrix considered, is defined as a major element. Other defined majors are oxygen, sodium, silicon, phosphorous, sulfur, potassium, calcium, titanium, and iron. Minors are given as chromium, nickel, zinc, strontium, zirconium, and barium. Most other elements are defined as trace.

defined as trace. For trace elements the species considered are: singly-and-multiply charged ions up to +3, polymerization up to the dimer only, mono-and-dicartides, and mono-and-di-oxides. For minor elements the species are: singly-and-multiply charged ions up to +4, polymer-ization up to the trimer, formation of cxide up to the trioxide and cartide to the tricartide, and charge-exchange species with initial charges of +4 or less. Major elements have more extensive coverage: singly-and-multiply charged ion up to +6, polymerization up to four atoms, formation of tetra-oxide and tetra-cartide, charge-exchange species with initial charge of 7 or less, and some complex species having two atoms of the major species and one to three atoms or carbon or oxygen. Polymer formers such as carbon, aluminum, and silicon are considered to form even more complex species and some combinations of these elements with other major elements are included. Appropriate higher degrees of polymerization and carbide and oxide formation are listed for these three elements. Only the lower-charged species of rare gases are considered.

polymerization and carbide and oxide formation are fisted for these three elements. Only the lower-charged species of rare gases are considered. Hydrocarbons up to mass 100 are included. The first hydrides(MH) of all elements from lithium to molybdenum plus barium, lan-thanum, and cerium are also listed. The mass range covered is from 1 to 270 with reductions in the number of entries from mass 210 to 270 where only two elements, thorium and uranium, are of interest.

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1 _H 3402	1.00782	99.985		3656 3616	5.99451	00.014	- 292	43Ca5	8.59176	00.146	
1206	2.00000	98,893	- 143	³⁰ S1 ⁵	5•99459 5•99475	00.337	- 293 - 295	26 _{Mg} 3	8.65675	83.76 11.17	-2107
⁴ He ²	2.00130	99.999	- 157	24 Mg4 25 Mg 65	5.99626	78.70	- 319	35C14	8.74221	75.529	
°Li ^j 2D	2.00500	07.42	- 221	1803	5.99972	00.204	- 391	44Ca5	8.79110	02.06	+ 026
1 H2	2.01565	99.970	+1300	12 C2 87 4	6.00000	98.893	- 398	53 Cr ⁶	8.82344	09.55	
¹³ C ⁶	2.16723	01.107		515	6.01512 6.10/76	100.000		54~ 6	8.88606	99.759	107
120'0 7143	2.33328	99.893		14N43	6,22358	99.63 ⁴	- 273	54Fe ⁶	8.98993	02.30	- 405
13C76	2.52837	01.107		²⁶ Mg ⁶⁵ 25Mg ⁴	6.23582	11.17	- 587	45 Sc ⁵	8.99118	100.000	- 429
1909 1909	2.60067	01.107		19 F3	6.33280	100.000		36A4	8.99189	00.337	- 441 - 444
14N5	2.80051	99.634		3255 27 1 85	6.39441	95.0	303	27A13	8.99384	100.000	- 491
1708 12085	2.83319	00.037		зэКе	6.49395	93.10	- 3820	15 ^C 35	9.00000	98.893	- 739
1806	2.99986	00.204	- 186	26Mg4 1302	6.49565	11.17		₽Be	9.01219	100.000	
12 ⁷⁴	3.00000	98.893	- 187	33 <u>5</u> 5	6.59429	00.76	+1011	29 S154 55Mp6	9.05515	04.70	+ 210
°Be ³ °L†2	3.00407]	100.000 07.42	- 252	40 A 6 40 Ca 6	6.66040	99.6 96.97	-22E4	4 ⁶ T1 ⁵	9.19053	08.00	
3 He	3.01603	01.4E4		40Ke	6.66067	00.012	+27E3	46Ca ⁵ 37 C1 4	9.19074	00.003	+44E3
SH2	3.01605	00.030	+15E4 + 512	²⁰ Ne ³ 12053	6.66415	90.92	+1790	5°Fe ⁶	9.32249	91.66	-2961
16078	3,11051	99.759		28 S1 65	6.71446	92.21	+100+	28513 39865	9.32564	92.21	- 604
13 Ce5	3.12080	ói.ió7		27A14 34c5	6.74538 6.79358	100.000		30 S154	9.36680	03.09	
13C4	3.19898 3.25084	99.759		41K6	6.82697	06.88		⁴⁷ T1 ⁵ 17053	9.39075 9.44396	07.29	
17076	3.30531	00.037		²⁹ S1 ⁶⁵	6.95436	04.70		57 Fe 6	9.48923	02.19	- 953
1705	3.33765	19.61 00.037		⁴² Ca ⁵ 35C15	6.99310 6.99377	00.64 75.529	- 306	38Å4	9.49068	00.063	-1115
18076	3.49976	00.204	- 437	28S14	6.99423	92.21	- 322	19 _F ≥ 48m-∤5	9.49920	100.000	
- * N * 7 L i ²	3.50800	99.634	- 485 	²¹ Ne ³ 14 _N 2	6.99795 7.00154	00.257 99.638	- 389 - 485	48 Ca 5	9.59051	00.185	+10E3
1805	3.59983	00.204		7Li	7.01600	92.58		**Ca **	9,59102	02.06	+6706
12 054	3.66977	80.39 98.893		°LiH	7.02282	07.42	+1029	58 Fe8	9.65555	00.33 69.18	-2945
15 _N 4	3.75003	00.366		43 _{Ca} 6	7.10885	99.759 00.146		29 S13	9.65883	04.70	
16065	3.83163 J 3.83878	99.759		23Na54	7.18431	100.000		39 _K 4	9.67930	93.10	+ 472
24 _{Mg} 6	3.99751	78.70	- 786	365105 3655	7.19370	03.09	+ 765	13032	9.75252	01.107	+ 840
1604	3.99873	99.759	-1034	36Å5	7.19351	00.337	+ 781	⁴⁹ Ti ⁵ 597.8	9.78957	05.51	
4He	4.00000	99.999	-1540	29 Si ⁴	7.22409	04.70		41Kes	9.83084	93.10	+1138
² H ₂	4.02820	02.0E4	+ 156	44 Ca 8	7.32592	02.06		^{so} Ni ^s	9.98846	26.23	- 409
13054 17085	4.06355	01.107		37 C15	7.39318	24.471	+T0T4	50 T15	9.98896	05.34	- 410
25 _{Mg} 6	4.07979 4.16431	10.13		31p85 45co8	7.43370	100.000	-0100	50V5	9.98943	00.24	- 426
170 ⁴ 18065	4.24978	00.037		³⁰ Si ⁴	7.49344	03.09		20 _{Ne} 2	9.99127	90.92	- 599
2 6 _{Mg} 6	4.33043	11.17	- 829	24Mg ⁵⁴ 15N2	7.49533	78.70	+3965 ±1134	18053 105	9.99953	00.204	- 747
1303 14154	4.33445	01.107		17043	7.55170	00.037		¹⁰ Be	10.01294	19.61	+17E3
27Å] 6	4.49692]	100.000	-1570	32565 3104	7.67330	95.0		⁹ BeH	10.02001	99.985	+1416
1804 9265	4.49979	00.204	 - 713	39K5	7.79274	93.10		^{e1} Ni ^e 51,75	10.15518	01.19	
2 ³ Na ⁵	4.59796	100.000	1 1 22	2⊃Mg э∓ 47 m 1 8	7.80807	10.13	+ 508 + 240	23Na43	10.21767	100.000	
^{c o} Si ⁶ 14 N ³	4.66282 4.66769	92.21 99.634	- 960 	48 _{Ti} 8	7.99132	73.98	-1303	41K4 82 N4 8	10.24046	06.88	-3006
19 _F 4	4.74960 1	100.000		48 Ca 6	7.99209	00.185	-1489	31P3	10.32459	100.00	
29516	4.79717	78.70		40 Ca 5	7.99240	99.6 96.97	-1619	63 Cu 6	10.38810	83.76	-7547
30 _{S1} 6	4.99563	03.09		40K5	7.99280	00,012	-1717	42 Ca 4	10.48966	00.64	
25 Mg 5	4.99717	10.13	+3240	24 _{Mg} 3	7.99502	92.0 78.70	-3264	²¹ Ne ² 14 _N 32	10,49692	00.257	+1445 + 829
15N3	4.99841 5.00004	99•759 00.366	+1797 +1130	180 ² 18043	7.99746	99.759		44 Ca. 65	10.54932	02.06	,
10 ^{B2}	5.00647	19.61	+ 461	7LiH	8.02382	92.57	+ 303	34g54	10.58813	09.55	
31p8 281.5	5.16229	100.000		2 6 _{Mg} 54	8.11956	11.17		64N18	10.65466	01.08	-3947
170 ⁵⁴	5.31223	00.037	- 275	34 <u>5</u> 85	8.15229	04.22	-1434	32 _S 3	10.65486	48.89 95.0	-4262
3256 1603	5.32868	95.0	-1801	41K2	8.19237	06.88		24 Mg 43	10.66002	78.70	+1702
12 643	5.33333	98.893	+3149	3354 50m,8	8.24287	00.76	-1847	54Cr5	10.78777	02.38	- 224 -72E3
3356 1152	5.49524	00.76	- 585	50 Cr ⁶	8.32434	04.31	-1950	54Fe ⁵	10.78792	05.82	
28 S15	5.59539	92.21	•	50 ₀ 8 25 _{М~} 3	8.32453	00.24	-2040	55 Mr 5	10.08741	100 00	- 507
18054 3456	5.62474 5.66131	00.204	-1120	42 Ca 5	8.39173	00.64	+ 132	eezne	10.98768	27.81	- 509
17 03	5.66638	00.037		27A154 19F43	8.43173	100.00	+ 703	44Ca4 33c3	10.98887	02.06	- 539
^{- 3} Na ⁴ 24 _{Mo} 85	5.74745 1 5.75641	78.70	+ 642	51 _V 8	8.49066	99.76	- 954	²² Ne ²	10.99569	08.82	- 808
13C ⁴ 3	5.77926	01.107	+ 181	3454	8.49197	ó4.22	-1118	В 10 вн	11.02076	80.39 19.61	+ 962
²°Si⁵	5.79530	04.70		170 ²	8.49957	00.037		40T1 05	11.02863	08.00	+ 570

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25 43	11.10482	10.13		⁶⁸ Zn ⁵	13.53497	18.57		58Fe54	17.47967	91.66	-3680
37 Zn 3	11.15452	04.11	- 344	^{4 1} K ³	13.65394	05.38		⁷ ^o Zn ⁴	17.48134	00.62	-5677
56 <u>-e</u> 5	11.18699	51.66		57 Fe ⁶⁵	13.66450	02.19	+1293	35012	17.48442	75.529	
45 Sc 4	11.23898	100.00		⁵⁵ Mn ⁴	13.73451	100.00		53Cr3	17.64688	09.55	
47 Ti 65	11.26842	07.29		⁴⁴ Ca ⁵⁴	13.73609	02.06	+8693	40 Ca 43	17.76115	96.97	
^{se} Zn ^s	11.32081	18.57	-6256	31P43	13.76612	100.00	+ 434	3253	17.76226	95.0	+1923
3453	11.52262	04.22		⁶⁹ Ga ⁵	13.78514	60.4	+ 271	∍′Ee⊐"	17.79251	02.19	+ 510
57 - 5	11.58703	02.19		58 Fe ⁶⁵	13.90400	00.33		54 Cr ³	17,97962	02.38	- 921
െപ്പ്പ	11.48762	60.4	-1581	560.4	17 08271	01 00	ROL	54 - 3	17 97987	05.32	- 933
4 ôr i 4	11.48816	08.00	-1708	707.5	12 09/90	91.55	- 724	3 egž	17.98354	00.014	-1152
4 8 Ca 4	11.48842	00.003	-1777	70755	17.35460	20.52	- / 55	3682	17.98377	00.337	-1170
23 _{Na} 2	11.49489	100.000		43 003	13 08601		- //0	241032	17,98878	78.70	-1734
48 7 4 65	11.50751	73.98	+ 911	28012	17 098/17	00.64	- 021	180	17.99916	00.204	
26 43		, , , , , , , , , , , , , , , , , , , ,		14N	10.90047	92.21	- 959	12 02	18.00000	96.71	+21E3
	11.54782	11.17		140	14.0000	99.624	.2017	ษะถ้	18.01056	99.747	+1579
Seres	11.58666	00.33	-28E3	1364	14.00524	LT.UI	+0252	SLIC	18.01500	07.34	+1136
³³ Ni ³	11.58707	69.18		12 01	14.01115		+1/26	9 8eo	18.02439	100.00	+713
Gee	11.65400	20.52	-5112	7 T CH2	14.01565	98.863	+1113	14 _{NH}	18.03437	99.584	+ 511
Zno	11,65422	00.62	-5658	L12	14.05200	85+71	+ 484		-0 -0 -0	00 77	
35013	11.65628	75.529		32 ₅ 43	14.20981	95.0	- 593	11:43	15.10415		
7′T17	11.73794	07.29		⁵⁷ Fe ⁴	14.23385	02.19		41K-3	18.20526	106.00	
2°Co2	11.78664	100.00		19 _F 35	14.24880	100.00	+ 952	37 m	18.91269		
('Ga°	11.32080	39.6		46T154	14.36020	08.00		3, C1-	18.45295	24.4/1	- 087
60 N 1 5	11.98615	26.23	- 866	⁴³ Ca ³	14.31959	00.146		3 / C5	12.20100	2.25	- >07
50 m 1 35	11.98675	05 45	- 906	2 6 _{Mg} 5 3	14.43477	11.17		58Fe3	18.64498	91.66	
7225	11 08:03	27 hz	- 018	59-4			0010	25 _{Mg} 32	18.73938	10.13	
49714	11 09200	73 08	- 910	50 Fe	14.40222	00.22	-2945	з4 ₅ 5э	18.87103	04.22	
50 7, 35	11 08705	04 31	- 027	29 212	14.40,004	69.10	- 2226	=7 = 3	-0.07017	00.10	053
48754	11 08813	00 186	-1011	44 2 3	14.40025	04.70		o re	18.9/04/	02.19	- 900
3623	11 08003		-100#	••℃a 47	14.65103	02.06		JGAE	10.90101		-1773
3613	11 08012	00.014	-1110	* 1712	14.67242	07.29	+ イエク	192	18.99840	100.00	
271143	11.90910	100.550	-1110	Sa Co.	14.73330	100.00	2.47	38 C S	19.00336	00.036	+3830
2411-2	11.99100	100.00	-1462	NI NI	14.98269	26.23	- 861	13OH	19.00698	00.204	+2214
1 4 4 3 2	11.99252	(5.70	-1604	*°T12*	14.98373	73.98	- 916	H ₂ O	19.01477	00.037	+1161
120	11.99619	99.759	-2150	#PSc2	14.98531	100.00	-1014	¹⁹ LiC	19.01600	91.64	+1079
	12.00000	90.092		SI	14.98688	03.09	-1134	HaO	19.01837	99.714	+ 951
-BH	12.01713	30.33	+ 701	2/A193	14.98974	100.00	-1446				- 0
⁵ Li ₂	12.03000	00.551	+ 400	TPN	15.00011	00.366		seres	19.31110	00.33	-2010
73 ~ 6				12 CH3	15.02347	98.523	+ 642	- NT-	19.31178	69.18	
Geo	12.15389	07.78	- 547	14NH	15.01090	99.509	+1390	39K5	19.48186	93.10	
SU KUT	12.17616	93.10		34043	15 09683	04.22		2 Mg32	19.48695	11.17	+3827
11	12.18622	01.13	+1510	51N+4	15 23277	01 13		44Ca43	19.53577	02.06	+ 361
7426	12.23697	05.51	-01	4 5 - 3	15 31754		_L3F3	50 m 3	10 07602	26.23	-1288
<u>f</u> geg	T5°250T/	26•2 <u>4</u>	-6845	467.3	15 31700	00.003		40 12	10 08110		-1777
'Se'	12.52042	00.87	-7950	62 N - 4	15 18200			40 00 2	10 08120	99.00	-1793
CT CT	15.25181	24.471		3152	15 18688	100.00	-) 2))	40 ,, 2	10 28200		1015
SzN15	12.38567	03.66		35 - 33	19.40000	100.00	1 (* 17 7	20 10	10.00200		-1910
28Si43	12.43418	92.21		28 21 53	15.541/1	(5.549	-1262	- NG	19.99244	90,92	11/151
52 Cr 65	12.46752	33.76	- 459	507.54	15.54274	92.21			20.00022	00 200	
50Ti4	12.48620	05.45	-1859	5011154	15.50775	05.24		120	20.01400	00.204	- + 094
50Cr4	12.48651	04.31	-1949	o Croi	15.60814	04. <u>21</u>	+40セン	1002	20.02565	UD.35	+ 590
50 _V 4	12.48679	00.24	-2038	³³ Cu [*]	15.73240	69.09		27 1 32	20.23616	100.00	
⁷⁵ As ³	12.49695	100.00	-2093	TITI	15.65059	01.21		e1ਜ਼ੋੜੇ3	20.31036	01.19	
4° Ca54	12.48831	96.97	-2710	64N14	15.98199	01.08	-1238	4 3 4 3	20.42330		
²⁵ Mg ²	12.49292	10.13		647n4	15.93229	48,35	-1267	4122	20.48002	06.33	
63 7.,5	10 53500	so co		49743	15.98265	73.93	-1305	-32 . 1 3	20.84273	03.66	
3813	12 000094 10 85/0/	00.083		48 ca 3	15.98413	00.135	-1401	47 - 43	20.86745	07.29	
53 ~ , 65	10 00578		- 448	3252	15.98604	95.0	-1303		20.001.9	0,020	
51.4	12 73500			1 eO	15,09491	- 99. T59		<u> </u>	20.97653	69.09	-1212
17 632	10 74035	00 037	+ 053	15NH	16.00793	00.366	+1229	34524	20.97831	00.56	-1351
23 1 53	12 77200	100.00	- 231	14NH2	16.01872	99.955	+ 671	- TECAE	20.37931	00.54	-1444
64 11 - 5	10 79650	100.00	-5353	12 CH4	16.03130	<u>98.341</u>	+ 400	205102	20.98270	92.21	-1383
6475	12 73583	42.80	// 	29 ~ . 5 9	10.00005			~_Se	20.99385	00.257	
41254	12,80057	06.88	+ 867		16.09805	04.70	2072	ĭ∃eC	21.01219	98.89	+1144
29 . 43	12.87843	04.70		- Cr - 4	10.20141		- 20122	2 - E2	51.05552	¢1.52	+ 739
540,65	10 04633	02.38	- 224	Cu- 49m+3	TP.52TAD	20.91		95 _{2b} 4	21.22801	72.15	
54-65	12 24551	03 32	- 225		16.01096	02.51	7007	54 11 3	21.30932	01.03	-5553
		0,		33 <i>c</i> 2	10.40191	27.01		34 Zn3	21.30971	E3 89	
>2Cr4	12.93513	83.76	- 713	532 54	16.40575	00./5		48 43	21.31020	<u>ร</u> รุ วล์	+4353
55 Cu ⁵	12,98556	30.91	- 731	50013	10.54545	V7•22		36~ 1			• •
зөКз	12.98790	93.10	- 841	50212	16.64026	05.24	1057		21.47754	07.86	-11E3
^{2 6} Vg ²	12.99130	11.17	-1078	Cr ⁻	10.54050		++02フ よう1 マネ	- Caf	21.47939	-00.146	
13C	13.00336	01.107		30 0+53	16.64905	00.24	キビエニン	39.0 U 3	21.64259	20.91	
12 CH	13.00782	98,378	+2916	-51^{-4}	10.05209		4-4 J.4	87 ~ 4	21.64650	75.10	+2235
¹³ Li ₂	13.03112	13.74	+ 468	~'Zn*	TP.()T(Q	04.11		Sr	21.72725	09.36	-27 E4
- 55M-65	13 18613	100 00	- 265		10.000000	02.00			=1.72733	2(.35	
867 <u>~</u> 5	13 18501	27 81	- 265	-7₹e9 *	15.35613	05.32	キィラニク	- SI32	21.73237	04.70	+4311
5304	13 03610	00 EE		⁶⁸ Zn ⁴	16,98122	18.57	- 949	⁶⁶ 7n ³	21.97575	27-81	-0157
4013	13 30080	22.22	-22 FL	sı _V 3	16,98133	99.75	- 955	39574	21.97650	82.56	-1847
40 0 3	13 30080	77.50	- a a s = = =	34 _S 2	16.98393	ó4.22	-1118	447,22	21.97775	02.06	
- ∪a 40-⁄-3	13 30133	20.97	10823	170	16,99913	00.037		22110	21,99138	08.82	+1612
30 C + 43	17.76122	00.012	+202J 1753	1 SOH	17,00274	99.747	+4709	[€] 1.10	22.00001	07.40	+ 683
244-53	17.30500	78 70	+3202	14NH2	17.02655	99.593	+ 320	10 PC	22.01294	19.39	+ 625
Mig	12.2505	10.10	TJEVE			100 000		118	22.01861	64.63	+ 574
⁶⁷ Zn ⁵	13.38543	04.11		^{>} Mn ^{>}	17.16814	T00.000		=			
5 6 ₇ e 65	13.42439	91.66		31p53	17.20765	100.000		>0T143	22.19768	05.34	- 773
54(Jr4	13.48472	02.38	-2230	23 Na32	17.24234	100.000		SC Cr43	22.19824	04.31	- 738
547e4	13.48490	05.82	-2298	52Cr ³	17.31350	83.75		Ca_53	22.20143	_96.97	- 339
27 A12	13.49077	100.00		39K43	17.31720	93.10	+4579	8974	22.22643	100.00	
18032	13.49937	00.204	+1569	-				°′Zn ³	22.30905	04.11	



90Zr4	22.47608	51.48	-12E3	⁵⁰ Ti ⁵³ 500753	27.74710	05.34	-39E3	³⁸ Zn ²	32.96302	27.81	-3907
45 Sc ² 30 St 32	22.47796	100.00		567 <u>6</u> 2	27 267/17	04.51 01.88		99 Ru3	32.96868	12.72	-6812 -12E3
68 Zn3	22.64162	18.57	79524	63 Cu43	27.96871	91.00 69.09	-3404	335 13284	32.97146	00.76	
⁹¹ Zr ⁴ 41 _K 53	22.72633	11.22		84 Sr ³	27.97050	56.90	-4351	32 SH	32.97989	95.0	+3911
з9 _{Са} з	22,97524	60.4	-1581	2851	27.97693	92.21		³³⁰ 2	32.99405	00.075	+1460
92Zr4	22.97617	17.11	-1689	²⁷ AlH ¹² CO	27.98936	99.985	+2251	100 Ru ³ 100 Mo ³	33.302/	12.62	-20E4
*°T1 ² 45Ca ²	22.97632	08.00	-1708	14N2	28,00615	90.66 99.269	+1556 + 957	87 Zn2	33.46357	04.11	
23 Na	22.98978	100.00		¹² C ₂ H ₄	28.03130	97.75	+ 524	¹³ *Ba* 101 _{Bu} 3	33.47606	02.42	+2679
23BC 7L10	23.00931	79.72	+1177	⁹⁵ Rb ³ ⁵⁴ 7n ⁴³	28.30401	72.15		135 Ba 4	33.72639	06.59	
52Cr43	23.08467	83.76	12009	57 Fe ²	28.46770	02.19		⁶⁸ Zn ²	33.96243	18.57	-6256
93Nb4	23.22642	100.00		esgr3	28.63645	09.86		102 Ru3	33.96786 33.96791	04.22 31.61	+68E4
⁷⁰ Ge ³	23.30800	20.52	+5955	52 Cr 53	28.35584	83.76	+50E)	102 Pd3	33.96829	óo.96	+79E3
⁷⁰ Zn ³ 47m42	23.30845	00.62	+52E3	590u*5	28.35679	30.91	+30E3	33SH	33.97928	07.81	$+412^{\circ}$ +2974
94Zr4	23.47691	17.40	+23E3	58 Ni2	28.96666	00.33 69.18	-2948 -3289	3402 10PC	33.99408	00.407	+1295
53Cr43 7163	23.52918	09.55		⁸⁷ Sr ³	23.96966	07.02	-4242	DU2	34.01294	19.10	+ 10-
54 Cr 43	23.97283	02 38	-1064	29 S1	28.97649	04.70	-4312	103 Rh3	34.30152	100.00	
54 Fe ⁴³	23.97316	05.82	-2019	²⁸ SiH	28.98475	92.20	+3508	⁶⁹ Ga ² 4 6 ₇₁ 32	34.46286 34.46447	60.4 08.00	
′~Ge³ 48∏12	23.97386	27.43	-2145	12C170	28.99910	00.037	+1282	138 Ba4	34.47622	71.66	+2580
48 Ca2	23.97626	00.185	-2731	12 CHO 29N	29.00274	98.64	+1104	104Pd ³ 104 _{P1} 3	34.63443 34.63474	10.97 18.58	+11E4
32 _S 32	23.97733	02.80 95.0	-3111	12 C2 H5	29.03912	97.74	+ 463	139 La 4	34.72651	99.911	
² ⁴ Mg	23.98504	78.70		зэкза	29.22278	93.10		⁷⁰ Ge ²	34.96200	20.52	-5105
²³ NaH ¹² Ca	23.99760	99.985	+1910 +1603	385r ³ 536553	29.30200	82.56		105 Pd3	34.96267 34.96827	22.23	-5650 -60E3
73 _{Ge} 3	24.30778	07.76		59 Co2	29.46659	100.00		35Cl	34.96885	75.529	
55 Mn 43	24.41691	100.00	-8690	89 Y3	29.63524	100.00		¹⁴⁰ Ce ⁴	34.97560 34.97632	88.48	+468]
**Ca>3 +9T12	24.41972	02.06		⁶⁰ N1 ² 54Cr ⁵³	29.96538	26.23	-3577	23NaC	34.98978	98.89	+1669
74 Ge3	24.64033	36.54		54Fe ⁵³	29.96645	05.82	-4100	3502	34.99829	99.75 1.4E4	+1188
567e43	24.64085	00.87 91.66	+47E3	$^{90}Zr^{3}$ $^{40}Ca^{32}$	29.96881	51.48 96.97	-5305 -16E3	35BC2	35.00931	79.05	+ 861
^{so} Ti ²	24.97239	05.34	-1858	30Si	29.97376	03.09		47 T1 ³² 108043	35.21382	07.29 27.33	
50Cr ² 50772	24.97302	04.31	-1949	²⁰ S1H ¹⁴ NO	29.98451 29.99799	04.70 39.39	+2841 +1237	10 °Cd 3	35.30198	01.215	+35E3
⁷⁵ As ³	24.97390	100.00	-2038	120180	29.99916	00.202	+1180	⁷¹ Ga ² 142 _{Ce} 4	35.46241	39.6 11.07	+2377
25Mg	24.98584	10.13		15 N2	30.00000	94.57	+1133	107 Ag3	35.63495	51.35	
25 C2	25.00336	02.189	+2559 +1426	12CH2O	30.01056	99.63	+ 315	⁷² Ge ² 48m432	35.96080	27.43	-5718
⁹ BeŌ	25.00711	99.759	+1175	°L1C2 ¹² C2He	30.01500	97.73	+ 727	38 <u>5</u>	35.96709	00.014	
57⊐-43	25.00/02	91.100		91 _{Zr} 3	30.30177	11.22		зед 108 рдз	35.96755	00.337 26.71	+79E: +49E3
^{7 a} Se ³	25.30643	02.19	-38E3	81 _{N1} 2 551-53	30.46554	01.19		1H35C1	35.97568	75.52	+3750
⁷⁶ Ge ³ 51172	25.30710	07.76		69 Ga 4 3	30.63365	60.4	-25E3	23Na13C	35 . 90504	01.107	+1378
34532	25.47590	04.22	+6515	92Zr ³ 92Mo ³	30.63489	17.11 15.84	 12483	3 # C3	36.00000	96.71	+1097
51 _{C4} 4377;53	25.50502	5.4E4	+ 771 + 445	41K32	30.72137	06.88	14,47	109 _A -3	36 30154	48.65	+)) -
77 Se ³	25.64000	07.58		62 12	30.96417	03.66	-7230	⁷³ Ge ²	36.46167	07.76	
58Fe43	25.74814	00.33		31p	30.96855	100.00	-5945	110 Cd 3 110 Pd 3	36.63443 36.63482	12.39 11.81	+94E
52Cr ² 78583	25.97026	83.76	-2107	30 SiH	30.98158	03.09	+3961	74762	36,96050	36.54	-6846
⁷⁸ Kr ³	25.97340	00.354	-2927	15CE	30.99840	98.893	+1457	74 Se ²	36.96127	60.87	-7981
^{с 5} Мд 25 Ман	25.98259	11.17	+2347	1300	31.00251	00.002	+1077	1117da	36.96809	12.75	+17 E
12 CN	26.00307	98.54	+1269	³¹ L1C2	31.01600	90.70	+ 733	^{а а} зн 37 н С	36.97491	00.014	+5120
10 BO	26.00571	19.56	+1029	¹² CH ₃ O	31.01839	98.62 01.66	+ 694	773	37.00336	03.25	+ 987
12C2H2	26.01565	97.77	+ 786	94 _{M0} 3	31.30198	09.04	-55E3	12 Co H	37.00782	96.70	+ 882
⁴⁷ T1 ⁵³ 597-43	26.08431	07.29	- 760	94Zr ³	31.30255	17.40		112Cd ³	37.30102	24.07	
35C132	26.22664	75.529		ea Ca	31.50502	00.0013	3	50T132	37.45859	05.34	-17E
⁷⁹ Br ³ 53Cr ²	26.30613	50.537		57 Fe53	31.63078	02.19	-7849	50Cr ³² 7542	37.45954	04.31	-28E3
60 Ni 43	26.63590	26.23	-9123	64 M 4 2	31.06308	01.08	-3952	¹¹³ In ³	37.63477	04.28	
^{so} Se ³ so _K ,3	26.63882	49.82	+67E4	⁸⁴ Zn ²	31.96457	<u>48.89</u>	-4263	113Cd3 85Pb43	37.63482	12.26 72.15	+75E4
48T153	26.63775	73.98	-25E3	^{9 6} Мо ³ 9 6 _{В11} 3	31.96832 31.9696	16.53	-8526 -13£3	78 _{Se} 2	37.95964	09.02	-12E3
54Cr ²	26.96944	02.38	-2230	9 SZr ³	31.96977	02.30	-14E3	^{7 6} Ge ²	37.96065	07.76	-18E
STFe [∠] 81 _{Br} 3	26.96980 26.97214	05.82 49.463	-2870	зеS зірн	31.97207 31.98158	99.985	+3362	114Cd ³	21.96273 37.96785	28.86	+7415
27Ă1	26.98154	100.00		1802	31.98983	99.52	+1800	114 Sn ³ 1 r ³⁷ cn	37.9680	00.66	+720
- ~ MgH 12 (15 N	26.99041	11.11 00.362	+1453	12 _{CH4} 0	32.00176 32.02613	01.11 99.60	+1077 + 591	³⁸ MgC	37.98269	11.16	+1910
11B0	27.00422	80.20	+1190 +1084	58 _{Fe} 53	32.18517	00.33		²⁵ Mg ¹³ C 197_	37.98920	00.112	+1434
12 C2 Ha	27.00643	97.762	+ 643	97 MO3	32.30207	09.46		3873	38,00670	00.036	+ 863
⁸² Kr ³	27.30448	11.56	-26E3	130 Ba4	32.47656	00.101	+2562	$^{12}C_{2}$ ¹⁴ N	38.00307	97.43	+ 943
82 Se ³	27.30554	09.19		⁹⁸ Мо ³ 98 р.,3 (С)	University	of Pretor	1 <u>2</u> 2083	03 M2	JU-U1905	20.09	<i>⊤ (</i> ⊥(
⁸³ Kr ³	27.63802	11.55		74Ge43	32.85378	36.54	.2007				



115 Sn ³ 115 In ³ 77 Se ² 118 Sn ³ 118 Cd ³ 52 Cr ³² 78 Se ² 78 Kr ² 39 K 117 Sn ³ 27 ALC 23 NaO 26 Mg ¹³ C	38.30112 38.30120 38.45999 38.63406 38.63500 38.95530 38.95530 38.95810 38.96371 38.96371 38.96371 38.98154 38.988605 38.988605	00.35 95.530 14.55 07.530 07.55 03.55 03.62 97.68 97.68 90.12 90.28 90.12 90.1	-48E4 +41E3 -4678 -7777 -11E3 +9765 +2190 +1856 +1748	43 Ca 42 CaH 129 Xe3 31 PC 27 AlO 30 S113 C 25 Mg180 12 C2 19 F 11 BO2 C 219 F 11 BO2 C 25 H7 130 Ba 130 Ba	42.95373 42.96645 42.96825 42.97376 42.97711 42.997911 42.99884 42.999913 43.005477 43.30117 43.30208	00.146 00.64 26.44 93.76 00.021 97.00 97.50 97.57 00.03 97.58 00.101	+5601 +42860 +2332 +1065 +1450 +1450 +1065 + 748 -4853	3 6 SC 144 Nd3 24 Mg23 144 Sm3 35 Cl13 C 30 St13 26 O3 24 MgC2 12 C4 145 Nd3 97 Mo2 37 C3	47.96709 47.967093 47.97055 47.972202 47.972202 47.972292 47.973200 47.973200 47.973200 47.973200 47.973200 47.938500 47.938500 48.0000 43.345311 48.50168	00.013 23.85 61.34 03.09 00.34 09.006 93.28 76.97 95.63 03.30 03.46 07.25	+2505 +2167 +2122 +1977 +1914 +1294 +1294 + 921
¹² C ₂ ¹⁵ N ⁷ LiO ₂ ¹³ C ₃ ¹² C ₃ H ₃ ³⁸ Sr ⁴³	39.00011 39.00581 39.01005 39.02347 39.06934	00.362 92.13 01.4E4 96.70 82.56	+1070 + 926 + 841 + 652	130 Te3 58 Fe32 87 Sr2 87 Rb2 131 Xe3 88 cm2	43.30232 43.44999 43.45450 43.45465 43.63503	34.48 00.33 07.02 27.85 21.18	+18E4 -9635 +29E4	49Ti 98M02 48TiH 37C1C	48.63756 48.69584 48.94787 48.95299 48.95577 48.95577	17.22 30.91 05.51 23.78 73.97 24 20	+ 834 +9560 +6196 +2715
¹¹⁸ Sn ³ ⁷⁹ Br ² ⁸⁹ Y ⁴³ ¹¹⁹ Sn ³ ⁵³ Cr ³² ⁹⁰ 7 x ⁴³	39.30068 39.45920 39.51365 39.63438 39.70549	24.03 50.537 100.00 08.58 09.55	7800	44Ca 43CaH 132Ba3 132Xe3 28S10	43.95550 43.95550 43.966837 43.96837 43.96837 43.96835 43.97184	52.56 02.06 00.146 00.097 26.89 91.99	-1885 +3960 +3415 +3502 +2690	49 SO 49 Mg2 147 Sm3 98 Ru ² 49 MgC ₂ 49 O ₂	48.96540 48.97088 48.97150 48.9777 48.98584 48.98584	00.80 15.95 14.97 01.87 11.63	+2641 +2127 +2071 +1680 +1290
soSe2 soKr2 40A 40Ca 40K 120Sn ³ 120Te ³	39.95824 39.95824 39.95830 39.96239 39.96259 39.96250 39.96740 39.96740	49.82 02.27 99.60 96.97 00.012 320	-7320 -9187 -9315 -20E4 +28E3 +8308 +7175	52 SC 31 p13 C 2 6 Mg 13 O CO2 C2 H4 O C3 H8 59 C0 32	43.97207 43.97711 43.98175 43.98983 44.02621 44.06260 44.19989	94.0 01.107 00.023 97.8 97.51 96.62 100.00	+2653 +2026 +1674 +1280 + 622 + 410	49 C4 12 C4 H 148 Sm ³ 148 Nd ³ 99 Ru ² 149 Sm ³	49.00336 49.00782 49.30481 49.30549 49.45303 49.63893	04.29 95.62 11.24 05.73 12.72 13.83	+ 382 + 316 +73E3
39 KH 29 S1C 24 MgO 27 Al 13 C 12 C2 O 12 C3 H4	39.97153 39.97693 39.97693 39.97996 39.98489 39.99491 40.03130	93.09 91.19 78.60 98.89 97.56 95.60	+4470 +2993 +2301 +1791 +1236 + 582	1330s ³ a9 y ² 134 Ba ³ 134 Xe ³ a0 Xi ³² 90 Zr ²	44.30171 44.45286 44.63475 44.63514 44.94808 44.95217	100.00 100.00 02.42 10.44 26.23 51.46	+1124 -5734 -1223	50 Ti 50 Cr 50 V 100 Ru ² 100 M0 ² 49 TiH 34 SO	49.94479 49.944605 49.94716 49.953 49.95326 49.955269 49.955569 49.955569	05.34 04.31 00.22 02.63 03.63 05.51 04.21	+40E3 +21E3 +6083 +5897 +4582 +2776
121503 54Cr32 54Fe2 31Br2 122Te3 122Sn3 52Kr2 32Sr2 41K	40.30124 40.45415 40.45471 40.45820 40.63449 40.634652 40.95832 40.95832 40.95833	57.25 02.38 05.82 49.46 04.72 17.11 11.56 09.88	-9965 -12E3 -21E4 -8032 -12E3	44 CaH 135 Ba3 29 SiO 45 SC 27 AlO \$5 CO2 12 C2 HsO 136 Ba3 136 Ce3	44.99675142 444.99675142 444.9967750 444.9969710 444.9969710 444.9969710 445.9997 445.9997 445.445 455.4545.45 455.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.45455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.45 455.4545.45 455.4545.45 455.45 455.4545.4	02.06 06.59 04.69 01.80 00.204 01.175 97.50 07.81 00.193	+6075 +3568 +2902 +2305 +1314 +1207 + 575 	50 Mg2 37 ClC 23 NaAl 130 Sm ³ 150 Nd ³ 50 MgC2 50 O ₃ 12 CF2 50 C4 12 C Ha	49.9672301 49.977301 49.977301 49.977301 49.9988880 49.9988880 49.9988880 49.9988880 49.9988880 50.0055	18.61 00.27 100.00 07.44 05.62 11.16 00.61 98.89 00.61	+2187 +2041 +1883 +1815 +1733 +1321 +1320 + 9806 + 705
123 Sb ³ 123 Te ³ 40 CaH 40 KH 41 SiC 23 Na ¹⁸	40.96806 40.9681 40.97041 40.97182 40.97649	42.75 00.37 96.96 00.012 05.67	+6575 +6533 +4774 +4100 +2792 +1508	136 Xe3 $91 Zr2$ $137 Ba3$ $92 Zr2$ $4 3Ti$	45.30240 45.45286 45.63519 45.95234 45.95234	08.87 11.22 11.32 17.11 03.00	+48E3	151 Eu3 101 Ru2 152 Sm3 152 Sd3	50.30651 50.453 50.63979 50.63981	47.32 17.07 26.72 00.20	F . CJ
12 C2 17 0 12 C2 HO 9 BeO2 12 C3 H5 55 Mp 32	40.99910 41.00274 41.0020 41.0391	00.037 97.55 99.52 96.66	+1099 +1001 +1020 + 530	4 5 C 4 9 2 Mo 2 4 5 S C H 3 4 S C 1 3 5 E a 3		03.7E3 15.84 99.935 04.17 71.66	+43625 +426360 +430625 +30625 +30655	102 542 102 542 50 774 50 774 50 774 50 774 102 542 50 774 102 542 50 774 102 542 50 774 102 542 50 774 102 542 50 774 102 542 102 544 102 544 100 544 1000 1000 1000 100000000000000000000	50.45957 50.45957 50.455267 50.455267 50.45571	99.78 71.61 00.76 05.74 05.74 05.74	+6457 +6029 +5903 +5151 +2582
124Te3 124Sn3 124Sn3 124Xe3 33Kr2 125Te3 94Zr43	41.30104 41.30175 41.30204 41.45703 41.63487 41.73673	04.61 05.94 00.096 11.55 06.99 17.40	-58E3 +14E4	50 S10 135 Ce3 135 L18 25 S1 23 Na2 14 NO2 C2 H 60	45.56800 45.568000 45.568000 45.568000 45.568000 45.5680000 45.56800000000000000000000000000000000000	03.08 00.25 00.089 00.138 100.00 99.15 97.49	+2365 +2863 +2863 +1956 +1706 +1741 + 515	³³ ClO ²⁴ MgAl ²⁸ SiNa ⁵¹ Mg2 ¹⁵³ Eu ³ ²⁷ AlC2 ¹⁹ FO2	50.96376 50.966571 50.966743 50.96643 50.9735 50.96345 50.96542	- 70 - 70 - 20 - 20 - 20 - 20 - 20 - 20 - 20 - 2	+2576 +2254 +2241 +2034 +1726 +1358 +1152
537632 34Kr ² 84Sr ² 42Ca 128Te ³ 128Xe ³ 41mu	41.95120 41.95576 41.95663 41.95863 41.968363 41.968363 41.968363 41.968363	91.66 56.90 00.56 00.64 18.71	-5647 -15E3 -20E3 -4497 +4497	139 La ³ 93 Nb ² 140 Ce ³ 47 Ti 94 Zr ² 94 Vo ²	46.30201 46.45283 46.53509 46.95176 46.95582	99.911 100.000 33.48 07.29 17.40	+2323	13 CF2 51 C4 C4H3 154 Gd3 154 Sm3 103 5%2	51.00016 51.01005 51.02346 51.30698 51.30731	01.11 05.4E4 95.61 02.15 22.71	+ 207 + 771 + 641 -16E4
⁴² SiC ²⁶ Mg0 ²⁴ Mg ¹⁸ 0 ¹² C ₂ 180 ⁸⁴ C ⁷	41.96965 41.97649 41.97751 41.98420 41.99916 42.00000	06.00 03.11 11.11 00.16 97.56 92.48	+2766 +2222 +1641 +1035 +1014	4°TiH 31P0 35ClC 141Pr3 29Sii80	46.96045 46.96872 46.96885 46.96916 46.97565	09.04 08.00 99.76 74.69 100.00 00.01	+5403 +2763 +2763 +2747 +26981 +1961	208004 155043 89322 207 Fb4 5207	51.49361 51.6409 51.69428 51.74397 51.94051	23.6 14.73 60.4 22.6 83.76	+1245 + 967
12 BO2 12 C2H2O 12 C3H6 127 I3 85 Rb2 85 C2	42.00274 42.01056 42.04695 42.30155 42.45601 42.50168	19.52 97.54 96.64 100.00 72.15 07.25	+ 951 + 808 \ + 475	- NaC2 15NO2 - 3Cu ³² 142Nd ³ 142Ce ³ 95M0 ²	46.98978 46.98991 47.19720 47.30249 47.30310 47.45222	97.80 00.36 69.09 27.11 11.07 15.72	+1234 +1231 -78E3	104Pd ² 51VH 104Ru ² 28SiMg 36SO 40CaC	51.95180 51.95180 51.95211 51.96197 51.96200 51.96259	10.97 99.935 13.53 72.57 00.014 95.90	+4667 +4601 +4478 +2420 +2417 +2352
128 Xe ³ 128 Te ³ 57 Fe ³² 88 Sr ² 86 Kr ²	42.63450 42.63518 42.70155 42.95468	01.919 31.79 02.19 09.86	-63E3 	14313 64Zn ³² 48Ti 96Mo2 48Ca	47.94686 47.94686 47.94795 47.95248 47.95253	12.17 48.89 73.98 16.53 00.185	-44E3 +11E3 +10E3	² ⁶ Mg ₂ ² ⁵ MgAl ⁵ ² KC ¹⁵ ⁶ Dy ³ ¹⁵ ⁶ Gd ³	51.96518 51.96738 51.96706 51.971/ 51.97409	01.25 10.13 01.04 00.052 20.47	+2105 +1933 +1956 +1704 +1547
43 Ca	42.95878	00.146		⁹⁶ Ru ² ⁹⁵ Zr ² 47TiH 32SO	47.9544 Univer: 47.95959 47.96699	05.51 of Prefor 94.8	+7434 147156 44123 +2518	²⁰⁸ Pb ⁴ ¹² C ₃ O ¹² C ₄ H ₄	51.99416 51.99416 51.99492 52.03128	90.18 52.3 96.48 95.60	+1427 + 968 + 955 + 572





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SOVO	65.94207	00.24	+4115	70	60 02700	20 52		57 5 61			
³³ S ₂	65.94293	00.006	+3906	70Zn	69.92534	00.82	+5283	50 CmC	71.95814	02.19	+4323
Jacris C	65.94401	00.106	+3673	⁷⁰ FeC	69.23331	00.35	+7503	74040	72.04065	04.22	+3762
43m+180	65.94525	93.10	+3434	69 GaH	69.93353	60.4	+7330	5851-0	73 34560	05.04	+3107
1221 2	65.94711	00.151	+3132	⁵⁴ CrO	69.93379	02.38	+7135	42 CaO-	73 01813	00.21	+2005
132p-2	65.95205	26.89	+2533	54FeO	69.93452	05.31	+6540	74Mg	73 06268	37.18	+2077
34 co	02·95256	00.097	+2487	70 S2	69.93495	05.001	+6380	148 m2	73.95721	11 24	+20/11
50102	02.95/69	104.20	+2024	53NiC	69.93535	68.41	+6155	148 _{Nd} 2	73.95823	05 77	+1086
M320	07.96254	15.50	+1809	35 CT_	69.93771	56.05	+5097	2 6MgOs	73.96732	11.00	+1507
27 Mg20	65.96659	01.03	+1626	57 Fe ¹³ C	89.93 <u>976</u>	00.024	+4734	74 Møn Ch	73.96763	18.54	+1585
AL2C	65.96308	98.90	+1780	52 Cr180	69.93967	00.171	+4451	74 MgC	73.93259	11.11	+1200
138 243	65.97576	03.14	+1381	7051-0	69.95069	05.95	+2619	74Ce	74.00670	00.176	+ 863
1981-3	65.97.58	0.4.51	+1381	46080	63 95%69		+035Å	12 CaHa	74.01564	93.50	+781
12 A2	65.90592	10.02	+1049	4 6T1C2	69.95263	07.82	+2442	149 0-2		17 07	
U11 C U	66.00000	85.45	+ 891	27 Å] 2	69.95799	99.75	+2053	Sm	74.45840	13.83	
CSH6	66.04692	94.50	+ 545	70 SC	69.96786	04.10	+1592	⁷⁵ As	74.92171 :	100.00	
199 _{Hg} 3	66.32274	16.84		CaHio	70.0782	94 45	+ 453	⁵⁹ CoO	74.92809	99.76	+12E3
133Cs ²	66.45257	100.00		NapCp	69.97976	97.80	+1254	7⁴GeH	74.92882	36.53	+11E3
133 3211	66.50168	10.90	+1353	947.32			,	⁴⁸ TiAl	74.92949	73.98	+9630
200 _{Hg} 3	66.65611	23.13		141p.2	70.40070	1/.40		^{es} CuC	74.92959	68.33	+9506
ອອ _ບ ເຊ	66.67929	105.05	+2876	- Pr	10.45274	T00.00	+9062	SeH	74.93036	00.87	+8661
67 7		01 77		⁷¹ Ga	70.92482	39.6		57Fe ¹⁸ O	74.93457	00.004	+5812
667nH	65.92714 66.03387	04.11		⁷⁰ GeH	70.93181	20.52	+10E3	2 TAC ⁵	74.94398	97.56	+3364
551000	66 07805	27.01	+9945	⁵⁵ MnO	70.93297	99.76	+8702	(PMgg	74.95347	05.34	+2359
5100	66.97005	93.09	+6124	59 CoC	70.93318	98.89	+8484	²⁵ Mg3	74.95752	00.01	+2092
57 5-	66 03033	99.52	+5596	44CaAl	70.93654	02.06	+6052	150 Sm ²	74.95845	07.44	+2039
28 a + 39 v		00.054	+5490	58Fe ¹³ C	70.93666	03.7E3	+5990	⁴³ CaO ₂	74.95858	00.145	+2032
54 cm 13 c	66.94064	05.05	+4950	SeNi ¹³ C	70.93370	00.766	+5110	150Nd2	74.96041	05.63	+1936
54 m 13 c	66.94222	00.026	++++>0	530r130	70.93981	00.019	+4735	35 KCa	74.96371	90.04	+1784
40002711	66.94296	00.064	+4251	°*FeOH	70.94231	05.81	+4055	27A103	74.96627	99.25	+1681
49 ma 18 0	66.94440	90.97	+2070	' TiC ₂	70.95176	07.31	+2633	2'AlC4	74.98154	95.65	+1253
1342,2	66 05013	00.011	+>>/0	KO2	70.95351	92.65	+2472	С _в Нз	75.02346	93.48	+ 736
134 _{Vo} 2	66 05217	102.42	+25(0		70.95374	27.11	+2452	^{isi} Eu ²	75.45977	47.32	
35010	50.952/1 66 05865	75 17	+2010	11°Cer	70.95465	11.07	+2378	760			
67 CaCa	66 05878	12.11	+2124	23 NaO3	70.97451	36.72	+1427	'SSe	75.91925	09.02	0
31p7_	66 97376	06 72	+2110	- NaC4	70.98978	92.62	+1091	four o	15.92019	07.76	+2082
201473	65 92010	70.12	+1063	C5H11	11.02605	94.44	+ 440	54 N10	(5.92560	26.1/	+1252
134 ~2	67.00336		+ 879	143Nd ²	71.15479	12.17		647mC	75.92190	18 25	+0745
$C = H_{\pi}^{\cup 11}$	67.05474	00.011 04.40	+ 525	7200	71 00150	07 113		75 A o U	75.92914	00.086	+7107
202- 2				56500	71 00085		11/27	76701	75.92952	27 08	+7300
135502	67.52354	29.30		60 N 4 C	71 03077	91.77 05 04	+7935	63 0, 13 0	75 03202	00 765	+5566
307.32	67.45278	06.59		720100	71 92071	4J•77 01 93	+6956	52 CrC2	75 94051	81.92	+3576
203m-3	67.42025	51.46		71Gou	71 0306h	30 6	+6500	32 S.C	75.94414	39.25	+3054
- <u>-</u> -	01.0010	29.50		360_	71 03418	29.0 3 OF6	+5713	44CaOa	75.94529	02.05	+2919
⁸⁸ Zn	67.92486	13.57		7201	71 37478	36.97	+5461	7 SMZa	75.95023	03.29	+2453
5°FeC	67.93194	90.64	+9594	590,130	71 03953		1,1817	152 Sm ²	75.95968	26.72	+1879
⁸⁷ ZnH	67.93496	Q4.11	+6725	540,130	71 07303	01.107	-++OI4	152 Jd2	75.95971	00.20	+1878
⁵² CrO	67.93543	33.56	+6426	54 - 180	71 05377			28 S10a	75.96166	91.54	+1~91
58 S2	67.93573	00.204	+6249	72040-	71 04705	72 50	T0405	⁴⁰ CaCa	75.96259	93.79	+1753
SiÇa	67.93979	39.42	+4550	2951002	71 24977	74.33	+2646	28SiC4	75.97693	38.19	+1318
^{oo} Mn ¹ ^o C	67.94140	01.107	+4107	4º CaOo	71.25230	36.5 <u>0</u>	+2335	¹² CO4	75.97964	97.94	+1259
* KAI	67.94337	C6.88	+\$670	43 Ca.Ca	71.95253	00.181	+2325	12CgH4	76.03123	33+47	+ 378
50 T1 50	57.94/95	00.011	+2553	144 Nd ²	71.35490	23.35	+2154	1532	78 - 203	52 13	
	67.94521	00.009	+3339	24.23	71.05513	13.71	+2144			JC•10	
1350-2	01.40219		+2405	144 Šm2	71. 5533	03.09	+2101	Se	<u>78.91998</u>	07.55	
136v.2	01.92224	00.195	+2000	^{2 4} MgO ₃	71.03977	78.13	+1407	<u>3</u> 1110	73.92600	01.19	++;;;;;;
2804 0	01.90000 07.05780	31 00	+2262	^{2 4} Mg ₂ C ₂	71,97003	30 . 53	+1+35	~~tet	10.15/10		+1122
44000	27 0 = = 00	02.015	+22=2	24 MgC ₄	71.93504	75.27	+113-	7 âg au	70.141.0	10.9. 17. Te	+9062
3290	67 07207	02.01	+1430	⁷² Ca	72.00000	93.52	+ 717	85 77	79.92001	30.27	17260
204 Dh3	67 00103	91.93	+1027	145 NJ2	70 15203	08 30	_	647513 r	70.22110	00 54	+9062
204 _{Ur} 3	67 30116	06 35	+1025	14502_	72 50188	11 78	±1637	53777	76 34065	00.34	+3709
Ca Ha	63.06256	<u>34</u> 44	+ 403	~12		ر. •مد - مع	· (·	520,250	76.04387	01.37	+-220
205		70 70		- 3 Ge	72.92334	07.73		45 Sc0,	73.94752	99.52	+2793
137 D-2	55.5246	/0.50		JeH 570	72.92941	27.47	+12E3	77.53	76.95102	66. <u>3</u> 8	+2475
20 6 m 3	67.492/9	11.52		7 3 X 4 9	72.05052	02.19	+1022	1547,12	76.26047	02.15	+1900
	00.00010	27.5		5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5	72.72107 70.52107	01.4/ 01.5/	オジャワト	154 5 2 2	73.98097	22.71	+1877
⁶⁹ Ga	63.92571	60.4		551180	/2.35464 70 02701	00 00 h	+0400 15001	29 SiOa	76.96122	04.87	+1865
92Zr ³²	68.92850	17.11	+25E3	73T*A	12.30121 70 01707	00.204	〒フビロ上 エンハママ	41%Ca	73.36183	36.65	+1333
⁶⁸ ZnH	68.93268	18.57	+9889	1102 7301_0	12034101 70 04833	03.57	+2019	77 SiC4	76.27649	08.45	+1361
5°Fe ¹³ C	68.93529	01.015	+ 7194	41K0-	72 05163	16.35	+2573	13C04	76.)3300	01 .1 0	+1221
FeC	68.93541	02.166	+7106	73 _{Mar}	72.05502	18-32	+22=3	12C6H5	77.03910	97.45	+ 643
⁵³ CrO	68.93556	09.53	+6998	1461742	72,35635	17.22	+2209	232mh3	77 3480	100 00	
69S2	65.93855	02.E4	+5368	37 C1C2	72.23590	23.67	+1713	1557,32	77.4614	14.73	
¹³⁸ Ba ²	69.95244	71.66	+2579	25 _{M2} 02	72.97057	10.06	+1544		it• ∘≎π⇒	ш. • _ ́	
rae Ces	68.95302	00.25	+2524	73 Mg Co	72.57088	16.96	+1534	/ªSe	77.91739	27.52	
- ³⁵ La ^e	65.95337	00.089	+2487 `	73 MgCa	72.23584	13.07	+1167	/ [°] Kr	77.92019	00.35-	+2353
Si2C	68.95342	09.50	+2487	730 -	73.00336	06.29	+ 911	N10	17.92325	05.84	+13 E3
3′C102	68,95570	24.35	+2298	12CeH	73.00782	93.51	+ 363	~~ZnC 397	11.92605	21.50	+0999
45 ScC2	69.•95592	97 . 80	+2282	147 -2	73 12705	1/1 017	-	41x37 ~7	77.92742	36.68	+//60
SCa	68.97542	03.83	+1387	5m-	12.70120	⊥+•≯{		77 Satt	11.927()	01.60 01.60	+1500
eu'Pb'	68.99196	22.6	+1040	74Ge	73.92100	36.54		000 65 0,13 0	11.42/30		+1405
CsHə	69.0704	94.46	+ 476	′_⁴Se	73.92254	00.87	+4853	780m0	11.49110 77 5207	00.54	+25/1
208 _{Pb} 3	69.32555	52.3		⊃¤FeO	73.92822	00.33	+10E3	54 240	77 03041	05 50	+3027 13507
¹³⁹ La ²	69.45302	<u>99.911</u>		' NiC	73.92834	03.63	+1053	785.0	77 03003	07 05	+2007 17160
209 _{Bi} 3	69.65978 :	100.00		2°NiQ	73.93026	69.01	+7983	4 °T10~	ィイ・ブノブブフ 77、ロムクルド	07 98	+/*/ +3110
70 ₀₀	69.02300	20 53		737 Fe ¹⁸ 0	73.93110	00.137	+7319	78 _{Møs}	77.04777	00 14	+2266
50	~~~ <i>~~~</i> /77	20.72		GeH	73.93116	07.76	+7276	15 6 Dv2	77.957/	00.052	+1967
				39 v 21 🕜 🚺	versityedf	Pretoria	+6838	y	11.02217	00.092	F7201
				VCT	12.7256	10.52	+0295				



³⁰ SiO3 ⁴² CaC3 15 ⁶ Gd ² ³¹ P ₂ O ²⁷ Al ₂ C2 ²³ Na ₂ O2	77.95849 77.95863 77.96113 77.96244 77.96308 77.96938	03.07 00.62 20.47 99.76 97.80 97.52	+1895 +1889 +1781 +1730 +1705 +1499	³⁴ SO ₃ ⁴ ⁶ TiC ₃ ⁵⁰ Mg ₂ O ₂ 164Dy ² 164Er ²	81.95261 81.95263 81.95745 81.9643 81.9649	04.19 07.74 18.53 28.18 01.56	+2277 +2275 +2007 +1718 +1697	¹⁷⁵ Lu ² 56Fe ³² S 88Sr 40Ca ⁴⁸ Ti 72Ge0	87.471/ 87.90401 87.90601 87.91081 87.91650	97.41 87.08 82.56 71.74 27.37	-44E3 +18E3 +8372
78 SiC4 14NO4 12C13 12C6H6 235U3	77.97376 77.98271 78.00000 78.04692 78.3476	03.16 98.67 86.49 93.45 00.72	+1382 +1193 + 943 + 602	165 _{H0} 2 56FeA1 83Kr 26S155Mn	81.96786 82.46455 82.91348 82.91405 82.91405	04.04 100.00 91.66 11.55 92.21	+1599 -15E4 	88Ca2 87SrH 87RbH 76SeC 76GeC	87.91653 87.91681 87.91712 87.91928 87.92129	00.40 07.02 27.85 08.92 07.67	+8348 +8139 +7912 +6624 +5753
157 _{Gd} 2 157 _{C13} 79 _{Br}	78.4621 78.50168 78.91839	15.68 12.60 50.537	+1982	⁶⁷ ZnO ⁸³ Ca ₂ ⁸² SeH 71 GaC	82.92205 82.92278 82.92445 82.92445	04.10 00.28 09.19	+092) +1023 +9498 +7973	^{5 6} FeO2 ⁸⁸ Si3 ⁶⁴ ZnC2 ⁶⁴ NiC2	87.92174 87.92445 87.92914 87.92796	91.22 00.28 47.81 01.06	+5505 +4767 +3801 +4003
⁵² CrAl ³³ CuO 78SeH 79ZnC 79K-	78.92205 78.92451 78.92521 78.92714	83.76 68.92 23.52 04.42	+22E3 +13E3 +12E3 +9019	⁵⁹ CoC2 ⁵¹ VO2 ⁸³ TiC3 ³⁵ ClO3	82.93318 82.93378 82.95176 82.95355	97.80 99.28 97.31 74.98	+4334 +4202 +2199 +2099	52 CrC3 28 Si202 32 S2C2 40 Ca03	87.94051 87.94368 87.94414 87.94414	81.01 84.62 88.26 96.27	+2547 +2333 +2305 +2114
⁵⁵ MnC ₂ ⁴⁷ TiO ₂ ³¹ PO ₃	78.92941 78.93805 78.94156 78.95849	00.31 97.80 07.25 99.28	+7168 +4014 +3406 +1968	¹⁸⁸ Er ² ³⁵ ClC ₄ 167 _{Er²}	82.9644 82.96885 83.4653	33.41 72.24 22.94	+1647 +1513	² ⁴ MgO ₄ ¹⁷ ⁸ Hf ² ¹⁷ ⁸ Lu ² ¹⁷ ⁸ Lu ²	87.96468 87.9704 87.9710 87.97136	92.75 77.94 05.20 02.59 12.73	+1365 +1365 +1352 +1345
79 CaC3 158 Dy2 158 Gd2 31 PC4	78.95878 78.96200 78.9622 78.97376	00.161 00.09 24.87 95.65	+1954 +1810 +1801 +1425	84Kr 84Sr 57FeAl	83.91325 83.91325 83.91695	56.90 00.56 02.19	-48E3 +23E3	¹² C7H4 177Hf ² 897	88.03128 88.4713 88.90572	92.46 18.50 100.00	+ 702
158 _C 2 C ₆ H 7 239 _U 3	79.00335 79.05474 79.3495	00.847 93.44 99.274	+ 929 + 579	⁶⁸ ZnO 72GeC 52CrO2	83.91808 83.91977 83.92159 83.93031	18.53 27.13 83.36	+1785 +1383 +1083 +4919	57 Fe ³² S 88 SrH 73 GeO 89 SeC	88.90748 88.91383 88.91825 88.91998	02.08 82.55 07.73 07.60	+51E3 +11E3 +7095 +6235
^{ao} Se ^{so} Kr ²⁸ Si ⁵² Cr	79.46244 79.91647 79.91659 79.91744	100.000 49.82 02.27 77.24	+ 703 +67E4 +82E3	⁶⁰ NiC ₂ ⁸⁴ TiC ₃ ⁴⁸ CaC ₃ 168 Tr	83.93079 83.93078 83.94795 83.95253 83.95253	78.40 25.65 71.79 00.18	+4784 +4787 +2418 +2136 +1609	89 S13 57 FeO2 65 CuC2 89 CrC3	88.92401 88.92521 88.92778 88.94065	00.013 02.18 30.23 11.96	+4861 +4562 +4030 +2545
⁸⁴ N10 ⁸⁴ Zn0 ⁸⁰ ZnC ⁴⁰ Ca ₂	79.92287 79.92405 79.92486 79.925517	01.08 48.77 18.41 93.45	+13E3 +11E3 +9525 +9186	168 <u>7</u> 62 12 _{C7} 169 _{Tm} 2	83.96695 84.00000 84.46717	00.135 92.48 100.00	+1563 + 967	³ Si ₂ O ₂ ⁴ KO ₃ ⁴ KC ₄ ²⁵ MgO ₄ 178 Hf ²	88.94324 88.94563 88.96183 88.96548 88.9715	08.62 06.83 06.58 10.03 27.14	+2370 +2228 +1584 +1488 +1352
H ⁷⁹ Br ^{5 5} FeC2 ^{5 5} Mn ²⁵ C2	79.9252 79.92622 79.93194 79.94141	50.52 89.64 02.19	+8197 +5166 +3204	85S1Fe 85Rb 58TeAl	84.90843 34.91202	06.33 72.15	-24E3	¹² C ₇ H ₅ ¹⁷⁹ Hf ² ⁹⁰ 7r	89.03910 89.4726 89.90433	92.45 13.75 51.46	+ 667
$32 S_2 O$ $48 Ca O_2$ $28 Si_2 C_2$ $44 Ca C_3$ $32 SO_3$	79.93775 79.93905 79.94233 79.95386 79.95500 79.95602	90.03 90.184 83.16 01.99 94.32	+3735 +3539 +3090 +2137 +2074 +1981	⁸⁴ SrH ⁸⁵ GeC ⁸⁵ Si ₃ ⁵³ CrO ₂ ⁸⁵ N1C2	84.92107 84.92334 84.93035 84.93045 84.93109	00.39 00.56 07.97 11.99 09.50 01.73	+9383 +9383 +7501 +4632 +4607 -± ⁴⁴ 53	45 SC2 89 YH 7 4 GeO 90 SeC 7 4 SeO 59 B 00	89.91184 89.91354 89.91591 89.91591 89.91739 89.91745 89.92311	100.00 99.985 36.38 23.32 00.87	+12E3 +9762 +7764 +6884 +6852 +4787
²⁴ Mg2O2 150Dy2 160Jd ² 32SC4 12CgHa	79.95990 79.9620 79.96361 79.97207 80.06256	61.64 02.294 21.90 92.77 93.43	+1840 +1755 +1695 +1437 + 547	³⁷ ClC ₃ ³⁷ ClC ₄ 170Yb2 170Er ² ⁸⁵ C7 12C7	84.94787 84.96590 84.967/ 84.9678 85.00336	07.73 02.40 03.03 14.38 07.25	+2369 +1576 +1544 +1522 + 930	58 NiO2 532nC2 39 K2C 90 CrC3 54 FeC3	89.92515 89.92605 89.92742 89.93887 89.93961	68.85 27.20 85.72 02.61 05.63	+4318 +4139 +3894 +2602 +2548
¹⁶¹ Dy ²	80.4629	18.88		171Yb ²	85.468/	92.49 14.31	+ 505	⁹⁰ Si202 ²⁸ Mg04	89.94051 39.96223	05.89 11.06	+2485 +1553
54FeAl 65CuO 80SeH 69GaC 81FeC2	80.92115 80.92269 80.92269 80.92429 80.92571 80.93541	05.82 30.84 49.81 59.73 04.15	+17 E3 +13E3 +10E3 +8710 +4261	⁸ ⁶ Sr ⁸ ⁶ Kr 54 Fe ³² S 70 GeO 85 RbH 79 70	85.90935 85.91079 85.91168 85.91390 85.91984	09.86 17.37 05.53 60.3 72.14	+60E3 +37E3 +8996 +3190	²⁷ Al ₂ C ₃ 180 W2 180 Ta ² 180 Hf ² 12 C ² 5 12 C - H	59.96308 59.9723 59.973/ 59.9731 90.00000 90.04692	96.72 00.135 00.012 35.24 84.58 92.43	+1530 +1323 +1309 +1307 + 940 + 631
²⁷ Al ₃ ⁸¹ S1 ₂ C ₂ ⁴⁹ Mg ₂ O ₂	80.93767 80.94462 80.95342 80.96070	05.48 100.00 12.12 15.87	+3808 +2869 +2187 +1827	8 * GeC 7 * SeC 8 * Si3	85.92100 85.92254 85.92762	36.23 00.87 08.49	+7374 +6513 +4702	$181Ta^{2}$ $181C^{2}_{15}$	90.4729 90.50168	99.988 14.22	+3144
162 Dy ² 162 Er ² 12 C ₆ H9 163 Dy ²	80.9628 80.96436 81.07038 81.4639	25.53 00.136 93.41 24.97	+1745 +1688 + 526	54 CrO2 54 CrO2 54 FeO2 8 STIC3 50 CrC3 27 AloO2	55.92594 85.92867 85.92941 85.94479 85.94065 85.95289	02.37 05.79 05.34 04.17 99.52	+4924 +4446 +4283 +2424 +2341 +1973	90ZrH 75As0 79BrC 59CoC2 .91ZpCa	90.90592 90.91215 90.91662 90.91839 90.92298 90.922714	51.45 99.76 49.98 97.80 04.63	+13E3 +8045 +6955 +5148 +4166
²⁸ Si ⁵⁴ Fe ⁸² Se ⁵⁵ MnAl ⁸² ZnO ⁸² Caa	81.91345 81.91654 81.91663 81.91959 81.92096	11.56 05.37 09.19 100.00 27.74	-26E3 -91E4 +28E3 +19E3	172 YD2 $31 P_2 C_2$ $8 C_7$ $12 C_7 H_2$ 173 YD2	85.9626 85.96753 86.00670 86.01564	21.32 97.80 00.244 92.48	+1612 +1477 + 382 + 808	55MnC3 54Fe ³⁷ C3 27AlO4 192W2 182C15	90.93805 90.94297 90.96114 90.9730 91.00335	96.72 00.189 99.04 26.41 01.115	+2777 +2414 +1629 +1343 + 927
⁴¹ K ₂ ⁷⁰ GeC H ⁸¹ Br ⁷⁰ ZnC	81.92366 81.92399 81.92425 81.92534	00.47 20.29 49.44 00.63	+12E3 +11E3 +11E3 +9405	87 Sr 87 Rb 88 SrH 71 GaO	86.90899 86.90930 86.91717 86.91973	07.02 27.85 09.86 39.50	+28E4 +11E3 +8092	183 _W 2 40Ca ⁵² Cr ⁹² Zr ⁴⁶ T12	91.4741 91.90337 91.90467 91.90526	14.40 81.22 17.11 00.64	-71E3 +16E4
Ga+3C 82 FeC2 50 TiO2 58 NiC2 88 S2O 50 CrO2 82 SisCo	01.92906 81.93331 81.93459 81.93535 81.93585 81.93585 81.95069	00.669 00.368 05.31 67.66 08.00 04.29 05.98	+6590 +4911 +4561 +4376 +4498 +4262 +2405	75ASC 74Ge13C 55MnO2 87S13 39KO3 174Yb2 38VC	86.92171 86.92436 86.92785 86.92718 86.94841 86.96287	98.89 00.40 99.52 00.81 92.43 31.84	+6832 +5654 +4608 +4773 +2205 +1615	92 Mo 91 ZrH 78 SeO 76 GeO 80 SeC 80 SeC 80 N102 92 75 C	91.90855 91.91314 91.91419 91.91620 91.91620 91.92057 91.92057	15.84 11.22 09.01 07.75 49.27 26.10 18.25	+24E3 +11E3 +9654 +7971 +7789 +5780 +4552
			/	^{17 4} Hf ² ¹² C ₇ H ₃	87.02346	92.47	+1425 + 759	21102	J =+ J = + 00		

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4°Ca ₂ C	91.92517	92.42	+4483	967 rH	26 21712	02 80	18882	539.0	100 005-0		
44CaO3	91.94023	02.05	+2584	65 CuOs	96.91758	30.76	+8523	es curda	100.92538	09.48	+4951
² Si ₂ C ₃	91.95386	32.24	+1868	97GeC2	96,92334	ó8.19	+5657	101020	100.92775	29.09	+4450
	91.95550	01,97	+1908	<u>97</u> Si3Č	96.93035	12.73	+4014	202 Hg2	100.98531	29.80	+1256
184002	91.95657	91.35	+1771	, NiCs	96.93109	02.00	+3895	C _B H ₅	101.03910	91.42	+ 752
184 _{W2}	91.9745	30.84	+1245	271103	96.93257	05.47	+3676	135 _{Ba} 32	101.17216	06.59	
185 0 2		20.84	+1010	97 T1 C	96.99952	99.76	+2908	203 m	101.4360	29,50	
Re-	92.474	37.07		194p+2	96.94/0/ 96.9817/	32 3	+2526 ±1284	1020	101 99050	27.00	
93Nb	92.90566	100.00		194 ČŽ	97.00335	01.26	+ 398	51m	101.00695	07.22	-0920
772rH	92.91249	17.11	+14E3	97 Cs	97.00335	08.20	+ 998	1025	101.00795	39.54	-0+50
albrC	92.91489	07.57	+10E3	¹² C ₈ H	97.00782	91.45	+ 954	3 5 C O	101.90575		
61NtO	92.91642	40.92	+5634	195 _{Pt} 2	97,4831/	33.8		907rC	101.90425	0 9. 04	+1954
⁶⁹ GaC2	92.92571	59.07	+6100	98m.		22.00	7790	102 pd	101 20486	00.96	+1, L,
93FeC3	92.93530	05.10	+3134	98M0	97.09273	05.20	-7.589	89v13r			+19F3
27AlgC	92.94462	98.89	+2385	9 55rC	97.90990	00 75	±29.53	⁷⁰ Ge02	101.91379	20.42	+10E3
³ P3	92.95129	100.00	+2036	⁹² SeO	97.91154	09.18	+18E3	102 SeCa	101.91739	23.15	+7460
29 CI2C3	92.95342	11.14	+1945	⁹⁷ MoH	97.91403	09.46	+12E3	¹⁰² Si30	101.92253	08.47	+5420
18602	92.95613	04.65	+1841	98S3.	97.91201	11.43	+16E3	54CrQ ₃	101.92360	02.36	+5129
1850-2	92.9124	20.41	+1352	^{BS} Rb ¹³ C	97.91545	00.80	+10E3	°⁴FeO3	101.92434	05.78	+4944
187- 2	92.910/	01.59	+1721	³³ ZnO ₂	97.91585	27.68	+9920	^{CC} ZnC ₃	101.92605	26.90	+4566
1870-2	93.477/	62.93		745eC-	97.92100 97.92100	25•91 00 85	+6510	102 CrC4	101.92025	07.51	++1)1
08-	92.4(0/	01.64	+94 83	98SiaC	37.92762	08.53	+4524	54FeC4	101.93961	05.57	+2840
40 Ti2	93.90058	12.37	-1353	98 NiCa	97.92834	03.58	+4379	27A1203	101.94781	99 . 28	+2312
T ^o CaFe	93.90247	05.64	-13E3	⁵⁰ TiO3	97.92952	05.30	+4159	204 Pb2	101.98654	01.48	+1231
94/7m	93.90594	09.04	-55E3	50 CrO3	97.93078	04.28	+3948	204 Hg ²	101.98674	Q6.85	+1228
785e0	92.90764	17.40	100 53	SOCIC4	97.94479	05.35	+2523	12C17	102.00000	32.72	+1059
93NbH	93.91348	- <u>6</u> 0 - 97	+2023	34co	97.94605	04.12	+2445	Caris	102.04692	91.41	+ 712
82 SeC	93.91663	09.09	+10E3	98 ₂₁ ,	91.94102 07 0541	01 87	+2039	205T12	102.4869_	70.50	
⁶² N102	93.91814	03.64	+8944	31 P2Ca	97.96753	96.72	+1591	205C17	102.50168	15.75	+6934
³⁹ K ₂ O	93.92233	86.47	+6393	196Hg2	97.98291	00.146	+1273	13'Ba32	102.67918	11.32	
GeC2	93.92399	20.07	+5744	19 SPt2	97.9836	25.3	+1261	103Cr2	102.88670	00,82	-5765
58 N# C	93.93331	00.39	+3658	95Ca.	98.00670	00.321	+ 972	87 SrO	102.90390	07.00	-16E4
4 ⁶ TtO ₂	92.92222	07 04	+2209	- Ce Hz	98.01564	91.44	+ 893	a7 RDO	102.90421	27.78	- 30 E4
94SiaCa	93,950.69	06.01	+2181	¹⁹⁷ Au ²	98.4836	100.00		103Rh	102.90455	100.00	
46T1C4	93.95263	07.65	+2087	⁹⁹ Tia	38.89266	00.59	-7387	¹⁰³ Zr C	102.90532	11.67	+13E4
³⁰ SiO4	93.95340	03.06	+2052	99 Ru	28.90605	12.72		$\frac{71}{2}$ GaO ₂	102.91462	39.41	+10E3
31P202	93.95735	99.52	+1890	99SrC	98.90899	07.05	+34 E3	[BrC ₂	102.91839	49.42	+7435
-000s2	93.9785/	13.3	+1325	87 RbC	98.90930	27.54	+30E3	103 grad	102.92278	99.28	+5645
¹⁸⁹ 0s ²	94.4793/	16.1		⁹ ³ MoH	98.91380	23.78	+13E3	55Mm C	102.92714	04,00	++>>>>
95 min	a4 80070	11 67	-2073	~' <u>1</u> n02	98.91694	04.09	+9082	3970.	102.90000	92.21	+2652
40 CaMn	94,90091	96.97	-27 53	63 Cu C-	38 32350	97.00	+6216	20 6ph2	102,98722	23.6	+1245
95 _{Mo}	94.90444	15.72		35C104	98,94849	74.80	+2330	CaH ₇	103.05474	91.40	+ 685
⁷⁹ BrC	94.91330	50.42	+11E3	198 Pt2	96.9823	07.21	+1297	207 Dh2	103 48704	22.6	
MoH	94.91376	09.04	+10E3	¹⁹⁸ Hg ²	98.98337	10.02	+1279	138 Ra 32	103.42866	71.66	1746
ZrH	94.91546	17.40	+8615	CsH3	99.02346	91.43	+ 842	1040	107 20100	70 37	hees
40 ca Fa	25 80480	88 88	-661)	¹⁹⁹ Hg ²	99.48411	16.34		38 G MO	103.00102	30.36	-4623
9eria	95.39539	56.38	-7152	50m4.	00 88058	00.00	= =	104 DA	107 20328	10 07	
9 ^e Mo	95.90496	16.53	-2223	50 Cr2	99.39210	00.19	-4233	104 P11	107,90422	13.58	+1124
⁹ [€] Ru	95.9087	05.51	-16E4	100 _{R11}	99,905/	12.52	-87 53	1047rC	103, 20467	17.04	+75Ë3
9 ⁶ Zr	95.90930	02.30		100570	99.90610	31.7×	-25E4	[∋] 2MoC	103.90355	15.66	+20E3
SeO	95.91138	49.71	+46E3	100 _{Mo}	99,90651	09.63		72 GeO2	103.91139	27.30	+13E3
B4gnC	95.91226	15.72	+ ラビビラ	⁸⁴ SrO	39.30816	00.56	+60 E3	30 SeC2	103.91647	48.72	+7877
325	95.91622	85.74	+1453	a7 Rb13C	99.91265	27.54	+16E3	Jereos	103.91664	91.00	+/////
64 NiO2	95 . 91776	01.07	+1123	^{co} ZnO ₂	99.91266	18.43	+1253	40 Ca - C-	103.32517	21.30	44747
64Zn02	95.91896	48.65	+9928	Tage C2	99.91928	08.52 .	+7324	567eC4	103.93194	37.67	+3625
$^{40}Ca_{2}O$	95.92008	93.22	+8397	52 CrO-	29.92129	83 16	+5/50 16340	28 Siz03	103.93859	34.42	+2943
GeC ₂	95.92159	26.83	+7804	23 Sta0	39.92521	78.21	+5203	⁴⁰ Ca04	103.94250	96.04	+2649
28 Ci C	95.93077	25.40	+4467	39 K2 C2	99.92742	84.77	+4778	208 Pb2	103.93333	52.3	+1222
48mi0-	95.95079	((・)) フェール5	++++02	⁶⁴ NIC3	<u>99</u> .92796	01.04	+4655	CsHa	104.06256	91.39	+ 652
³² SaOa	95.93396	89.82	+3889	³⁴ ZnC ₃	99.92914	47.28	+4415	¹³⁹ La ³²	104.17952	99.911	
∂°TiC4	95.94795	71.07	+2481	SecrC4	99.94051	20.11	+2938	²⁰⁹ 3i ²	104.43967	100.000	
³² S04	95.95173	94.09	+2260	200 <u>1 -</u> 2	99.94414 00 08/12	01.29	+2504	105 ₀₋₀₀	104.38159	16.00	-4516
+340s ²	95.9811/	41.0	+1336	C-H-	100-03128	2/•1/ 91.42	+ 801	səyo.	104.90063	99.76	-25E3
Pt ^e 12 <i>0</i>	95.9824/	00.78	+1312	201 2		, <u> </u>		105 Pd	104.90492	22.23	
U8 193- 2	96.00000	91.46 	+1057	Hgf	100.48515	T2•55		⁹³ NbC	104.90566	93.39	+13E4
 19362	96.4834/	62.7		101 Ru	100.905/	17.07		⁷³ Ge02	104.91314	07.72	+13E3
∪īe	96.50168	⊥4•99	+5278	39YC	100.90572	<u>9</u> 8.89	+1424	³¹ BrC ₂	104.916-2	48.37	+9044
Tia	96.89581	08.93	-9318	⇒ RbO	100.90693	71.98	+5253	P FeO3	104.92011	02.17	+6861
CaFe	96.89827	02.12	-12E3	100	100.90945	00.914	+とうどう	105 mg/	104.92896	30.40 0 = 02	++246
MO Blb-0	96.90621	09.46		69 COO	100.91433	09.00 60 11	+1772)	57 St - 0	104.03815	08.60	+7147
-bru 35 brc	70.71133	49.54	+1983 ±1753		100,01008	07 - 61	+6736	27 41 - 0-	104 044460	37.80	+2636
● ^M OH	96.91278	16-53	+15E3	101Sia0	100.92526	11.96	+4981	AT305	<u></u>	-1 -	,20,0
97 Sg	96.91561	02.06	+10E3		2 . 2	-	-	10 °Cr2	105.37938	04.90	-4501
								² ZrO	105.59924	51.34 27 33	-29E3
								Pa	100.90591	e(•22	



10 8 Pd	105,90291	27.33		113-				10 -			0
10602		- 01 - 01 -		Fe ₂	112.86735	04.02	-3056	* Ca ₃	119.88776	90.34	-8303
	102.90292	01.217	+25522	⁹⁷ MoO	112.90112	00 46	3653	88 Sr0a	119.89592	82.16	-19F3
⁹ "MoC	105.90594	08.94	+35E3	113 -	110 00 120		- 7027	104 740			30 53
947rC	105,90764	17.21	+2253	2 2 2 ¹¹¹	112.90450	04:28		Pau	113.03013	10.94	- 30 E 3
93 130				113Cd	112,90446	12.26	+71E4	¹⁰ * RuO	119.89914	18.53	-39E3
NDC	102.90901	01.10/	+17 ビラ	119 _{Ru}	112 005	17 00	1.000	120 cm	110 00000	30 85	
¹⁰⁶ FeC₄	105.93331	00.41	+3484	89	112.905	11.02	+T0F4	Sn	119.90220	22.02	
58 NIC	105 03525	66 17	12005	YC ₂	112.90572	97.80	+80E3	¹⁰⁰ PdC	119.90347	26.41	+94E3
	105.92525	00.11	+2265	⁸¹ BrOa	112 00622	10 22	LEO EZ	108 040	110 00407	00 865	LELES
°°Si203	105.93542	05.88	+3258	65 2. 2	112.90022	77.22	モンタニノ	120-000	119.90.01		+0+57
			. / _ / 0	CuOs	112.91251	30.69	+14E3	Te	119.90449	00.089	+52E3
107 Cr ₂	106.87592	00.46	-4224	49 T104	112,92751	05.46	14867	120 MoCa	119.90496	16.41	14383
917.0	106 00003	11 00	0777	65 m. m			++007	960.0			
10410	108.90025	TT. 20	-2555	27.0404	116.96110	29.56	+4809	- RuC2	119.9007	05.29	+10ピン
10' MoC	106,90444	10.68	-27 E4	~'Alg02	112.93444	99.52	+3746	⁹ ⁶ ZrC ₂	119.90930	02.74	+17E3
107 4	100 00007					,,,, <u>,</u> _		5600	110 01168	00 78	11353
Ag	106.90403	51.35		114Fea	113.86525	00.66	-2974	37	119.91150	90.70	
947 n130	106.01000	00 103	±17 🖬 3	57		00000		≤′Al₄C	119.92616	98,89	+5004
75 1 2	100091099			rez	112.01002	00.05	-3481	28 StaCa	119.93079	75.83	+4104
' ASO2	106.91151	99.52	+16E5	9°MoQ	113.90089	23.72	-43E3	120-303			1.1.0.0
54				11401	117 00755			010	150.00000	09.44	+T556
J ^T Cr ₂	107.87774	00.06	-4194	Ca	113.90355	28.86		1 3 1			0000
5400	107 87000	00 74		¹¹⁴ RuC	113,90373	31.45	+63E4	¹²¹ Ni2	120.86186	00.62	-2889
C. Les	101.01922	00.54	-4450	114	117 0070			1217	100 99777	07 70	7700
J2r0	107.89958	17.07	-28E3	ao_ ^{on}	112.90.59	00.66	+シンピ4	K3	120.00/2/	01.52	-1,299
92 _{M00}	107.00346	15.80	-10 86	³ [°] ZrC ₂	113.90433	50.33	+15E4	eg XO2	120.89552	99.52	-15E3
108-1	1010/10	1).00	- 10 10	102 PAC	113,00486		18753	105 040	120 80073	55 18	_ ਤੁਹੇਸ਼ਤੇ
- Pd	107.90347	26.71		82 - 2				ruo	120.09917	~~• <u>1</u> 0	
108 CA	107 00407	00 875	18 FL	Se02	113.90645	09.17	+39E3	121Sb	120.90371	57.25	
108.00	101.30401	00.079	-TO P-	5°T104	113,92443	05.29	+5455	109 100	IZO OOLEI	18 11	エコスアは
+ O o MoC	107.90496	16.47	+72E3	50 0 00	113 005 00			121.000	120.90401		
96 _{Bu} C	107 9087	05 45	101 83		117.92009	04.21	+2142	MCC2	120.90621	09.61	+40ビン
782.0	107.9001		+2107	<u> </u>	113.92605	26.60	+5062	⁵⁷ Fe0₄	120.91505	02.17	+11E3
_ SeO₂	107.90910	08.98	+19E3	98 Ru0	113.040/	01.87	12452	12104 0	120 03035	1 1 1 1 1	11538
96ZrC	107.90930	02.77	+19E3	12 2				1212130	3120.97075	14.14	77970
78000		07 70	11/177	019	114.00000	00.09	+TTOT	15_1C10	121.00335	10.02	+1512
deu2	101.91111	01.12	+1+0)	99	111 00000	10.00	1	122		07 1.2	000
°°SrC⊳	107.91325	00.55	+11E3	Ruo	114.90096	12.69	-43E3	122 Ni2	121.85911	03.41	-2784
27 41.	107 02613	100 00	14762	115 Sn	114,90335	00.35	-4464	110 FeaC	121.87155	10.55	-3888
£0	107.92017	100.00	++/02	115 -				551 2			jug ho
~~N1C₄	107.93077	25.09	+2953	10°° TU	T14.2020T	22. (2		Mn2C	TST.0(010	70.09	-4549
28 Sta Ca	107.93079	76.67	+3050	¹⁰³ RhC	114.90455	98.89	+12E4	122 Caa	121,88435	01.79	-6572
440.0				1157 n.C.	174 00530	1210	6753	907.0			1/1777
-∵ca0₄	107.93514	02.04	+2411	90-2102	117.900022	12.10	+0(1)	2702	121.09412	51.21	-1462
¹² Ca	108.00000	90.44	+1118	ZrfSC	2114.90769	01.13	+28E3	^{10 e} PdO	121.89782	27.26	-24E3
09	100.00000			F 0			-	108040			- 50 83
217 C2	108.50168	16.50		°°Ni2	115.87070	47.86	-3681	- Cuu	121.90004	UI•CI	- 79-27
018	100. 00100	10.00		58 80-	116 86662	00 001	3258	¹²² Te	121,90290	02.46	
93 mbo	108 00057	00 76	07 E3	P 4 5 5 5	119.00002	00.001	- 72.50	110		10.05	
108.00	100.90097	22.10	-2127	°⁻Sr0₂	115.90305	00.56	-14E4	++ CaC	121.90329	15.52	+ウエビ4
10° Ag	108.90461	48.65		100 Bu	115,900	12.50	-5383	110 PdC	121,90447	11.68	+78E3
109 100	108 00621	00 51	16853	100100				122120		07 117	1002
77	100.90021	09.07	+001	MOO	115.90142	09.61	-1554	- MOC2	121.90590	27.41	+40 57
(SeO ₂	108,90980	07.54	+21E3	118 _{Sn}	115,90219	14.30		^{e e} SrC ₃	121,90935	09.54	+19E3
85 RbCa	108.91202	70.56	+1583	104 010		10.02		58 TAN.	121 01205	00 33	+12E3
967	100.01000			Pac	TT2+20,250	T0.02	+1154	58.04			
- Zrisc	100.91265	00.051	+1462	104 RuC	115.90422	18.37	+57E3	³⁰ N104	121.91499	60.52	+10E2
- ^{IUS} SiaC	<pre>>108.93035</pre>	13.50	+4231	1167.0	115 00467	16 66	ルファス	12251-0	-121.92762	08.60	+4931
109 ~	100 00336	00 10	1103	110000	119.90407	10.90		980.730		01.83	10386
⊂a	109.000000	09.12	+110)	Cd	115.90499	07.58	+41E3	, Ruce	121.95-7	01.07	+2,000
110	100 97155	10 67	7107	92MoCa	115,90855	15.49	+18E3	144C10	122.00670	00,505	+1174
re2	109.07100	10.01	-2462	522.0		Số cố		123	122 88678	<u></u> Ω	-7063
^{J J} Mn ₂	109.87611	100.00	-4044	-Cr04	115.92015	02.90	+0+22	91	122.00010		1 1 1 7 7
94Ma0	100 00085	00 02	1653	28 Sta0a	115.92061	78.02	+6298	² ZrO ₂	122.89512	11•1 <i>(</i>	-14E2
MOU	109.90005	09.02	-4262	1167-0	115 02/86	17 04	16113	107 AgO	122.89974	51.23	-28E3
¶ 4Zr0	109,90255	17.36	-15E4	ZnC4	112.92400	11.94	モンエン	100			/
110 04	100 00300		-	* CapCa	115.92517	90.38	+5044	±≤ Sb	122.90418	42.75	
ca	103.30253	16.22		232mh2	116 0100	100.00	+1185	123 CAC	122.00428	12.75	+1255
¹¹⁰ Pd	109.90447	11.81	+93E3	111	110.0190	100.00		1230	122.90420		+12 10
110MoC	100 00508	23 62	⊥น้ำ ธ่3	397	116 80113	80 70	-9766	Te	122.9043	00.07	+T0E2
78 2.0	109.90590			1013			70.07	¹²³ RuC ₂	122.90605	12.48	+66E3
SeO2	109.90721	22.42	+20E2	101 RuO	116.9000	17.022	-2052	123 cmC-	122 20802	07 11	+26F3
^{ae} SrC ₂	109.90935	09.64	+18E3	85 BDO2	116.90182	71.80	-91E3	2 DI 03	122.90099	01.11	
397		86.26	17878		110190100			^e RbCa	122.90930	26.94	+24E3
_ V505	109.91/24	00.20	+1010	¹¹⁷ Sn	116.90310	07.61		1230	ີ 27 ຄຳຄໍຄິ	05	+1161
¹¹⁰ SiaC	- 109 . 92763	08.55	+4515	117010	110 00190	20 10	10953	V10	12/01000	00.01)	1 7 7 9 7
4 6 T 1 0	100 03227	07.02	±3702	Pac	116.90462	22.10	+6052	124.	103 35873	00 57	-2664
31-04	109.97221			⁹³ NbCa	116,90566	97.80	+46E3	- N12	12/0000	00.57	-2004
- P203	T03.92555	99.20	+2244	8501 0	116 02017	11 03	<u>re848</u>	⁵⁶ FeaC	123.86388	83.09	-3000
98 RuC	109.954/	01.85	+2167	01302	110.92011		10000	12400	103 88070	05 70	-5053
1100	110 00670		1063	⁵³ CrO₄	116.92029	09.46	+600T	a_3	122.000/2	02.19	- 10 - 10
C9	TT0.00010	00.409	+106)	27 41-0-	116,94462	96.72	+2816	⁹² ZrO ₂	123.39447	17.03	-12E3
1117	110 97500	00 26	3700	23410		05 653	008	92M00-	123.89835	15.76	-18E3
Fe2	TTO 01205	00.20	-2790		111.0202	05.057	÷ 330	108-10			1957
95MoO	110.89935	10.73	-23E3	2352	117 6014	00 70		PdO	142.09020	<0.30	-1053
11100		10 76		- u-	111 • 7414	00.12		TOB COO	123.89898	00.871	-20E3
- ua	TTO-20458	14.(5		118	117 96010	36 00	-3081	124 CAC	123.00306	23.04	-57 E3
99 Run	110.00605	12.58	+6353	°Ni2	TT(*00015	J0.29	- <i>Je</i> 01	124~		51.37	25.22
79				59 Co-	117.86636	100.00	-3304	''e	TSD•A09T5	04.6L	- ウダ やう
Br02	TTO . 20013	20.29	+2017	102 5.0	117 8096	31 63	- 35 57	124 RuCo	123.905	12.32	-50 E4
¹¹¹ SrC-	110.90899	07.09	+24E3	HuO	111.02004	21.22	-2222	1240	107 0000	OF OF	
87 02 7	110 00030	27 34	エククデネ	^{ee} Sr0,	117.89915	09.81	-4⊥E5	· Sn	122.90524	UD•94	
63	TTO . 202.20	- I •		102 040	117 80077	00.96	-52E3	1240-0	123 00010	80 08	<u> ተ</u> ገ և ም ሥ
°° CuOa	110.91432	68 . 59	+11E3	Fau	TT1 . 02211			- SrUg	T57.700T0		
63 0 1 0	110 62050	86.08	+4382	118 Sn	117.90205	24.03		⁺≃⁴Xe	123.90612	00.01	+14E4
47	110 76707		11202	118	117 00001	07 00	11200	100MAC-	123.00651	09.42	+98E3
T104	110.93140	06.97	+4089	PdC	117.90291	21.28	+1+54	80			
111 _{Ca}	111.01008	00.011	+1048	10 0 CAC	117.90593	01.20	+30 E3	°∼NiO₄	123.91041	25.90	+2453
~ 9			· · -	841-0	117 00601	08 84	+30 83	27A1.0	123.92107	99.76	+7827
112 Po-	111.86388	84.0e	-2856	- MOU2	111.20274					,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	
112-22			27717	∃*ZrC>	117.90764	17.02	+とエビク	113 Fe- 0	124.86735	03.97	-3351
Fez	TTT.0(595	00.04	-2(12	8801-0-	117,01744	08.45	+7661	93			ייים ול ר
9 6MOO	111 80087	16.40	-35 83	542 2		~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	17163	I NDO2	124.09546	72.25	-14E3
1100	102201		رشار ر	_⁼Cr0₄	117.91851	02.00	*(<u>+</u> <u>2</u> 2	109 AgÕ	124.89952	48.53	-25E3
TTE Cd	111.90306	24.07		54Fe0.	117.91925	05.76	+6855	113720	104 00412	04 52	- 30 11
9 6 BILO	111 00361	05.50	+2014					128		37.57	
967 -				119 Ni-	118.86644	01.65	-3239	⁺f°CdC	124.90446	15.09	-70E4
^o ^o ZrO	111.90421	02.19	+91E2	110			QEE II	125 To	124 004A2	06.99	
112 RuC	111.905	12.62	+58E3	тт ^р Ка	118.88925	17.09	-0224	125 - ~	10/ 000	16 07	12250
112		00.00	16553	87 Smn-	118.80870	06.99	-27E3	RuC2	124.905	10.97	キククビ4
sn	TTT•202T	20.30	T2252	87			-3053	an -	10F 0F0	1	<u> </u>
112 SrCa	111.9061	80.89	+37E3	- RbO2	TT0.02775	< 1 • 1 Z		os Cu2	125.85918	47.73	-2017
80	111 00000	40 36	+3552	103 RhŌ	118.89946	99.76	-32E3	1235 0	125 86525	00.65	-3260
100002	TTT. 20052	77.20		110-		00 -0		re20			
+00MoC	111.90651	09.52	+2253	÷∸° Sn	110.90315	00.50		° [™] MoO>	125.89574	09.00	-16E3
28 4	111 00770	72-30	+24E3	1194-0	118 00111	10.72	+9283	947-0	125 80711	17.32	-20 83
40		72.52	10000	MOU2		±2.15		110102		きん・イラ	
~~Ca202	111.91554	92 .5 0	+0901	+0" AgC	118.90483	50.78	+(155	++°CdO	125.59820	12.36	-2253
48 11 1 1	111.92759	73.27	+4562	55Mnn	118.01760	99.04	+8178	110 PAO	125.89938	11.78	-28E3
*64 7 ~ ~		16 70	Lunn	238		66°	- dei	128			- 20-2
~~ZnC4	TTT•75(ÃQ	40.0		~ J O U2	LLY.0245	770214	- 70I	÷€°CdC	125.90355	20.60	- 29 54
³² S=0a	111.92887	89.60	+4336	120		11 01	2010	128R1C-	125.90373	31.28	-90E4
				- Niz	119.06154	11.94	-2777	12 8m-	125 00287	18 71	
				-				T.e	10/05+70/01		

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12 600	125 00397	18 71		1 4 -	177 25001	10 00	0510	14104	10 85031	02 63	-2555
114900	125 20320	00 65	14025	87 m	122.35091	10.50	-2510	9311-0	140.00204	20.22	-2250
907-0	125.90 00	10.77	+0750	~ _n₂	137.35423	00.17	-2680		140.59059	19.20	1153
12 Arts	125.90435	49.11	+27 5.4	110 7-2C2	133.87155	10.43	-4094	125 AgU2	140.09441	40.42	1957
102 DIG	125.90445	00.09	+2224	⁵⁵ Mn ₂ C ₂	133.87610	97.80	-4757	141	140.59952	05.70	-1052
PdC2	125.90406	00.94	+1254	102 Ru02	133.89353	31.46	-13E3	f SnC2	140.9051	07.19	-2422
- J- C2 1	125.00000	(9•⊥4	+1010	³⁶ SrO ₃	133.89410	09.79	-13E3	12 TeC	140.90555	21.44	
⁹⁵ MoO2	126.89424	10.71	-12EB	118 SnO	133.39696	23.97	-18E3	SSN6C4	140.,0555	90.00	-(10)
111CdO	126.80919	12.72	-23EF	¹²² TeC	133.9029	02.43	-99E3	141 Pr	140.90743	100.00	
115 SnC	126,90335	00.35	- 27 मई	110 CdCa	133.90329	12.12	-14E4	140CeH	140.91310	38.47	+25E3
115 TnC	126.00361	94.66	-1274	122 SnC	133,00346	04.67	-17 ± 4	142 7	141 34558	11 23	-2227
103 BhCa	126.90455	57. Sõ	-7295	134 _{B2}	133 00425	02 12		xe2	141.040	-1	-2227
127 7	126 00466	100.00		110 010	177 00427	11 55		144Ti3	141.54853	14.51	-2335
127720	126 00532	12 52	10F4	Bee e	100.90447	11.55	+6124	' ¹ Ga ₂	141.84964	15.68	-2379
63 0.00	126 00023	68 <u>1</u> 3	12853	sec. o	122.90925	09.42	+2613	110 Fee0a	141.86137	10.62	-2961
254 22	127 00335	02 085	1296	1340	177.91275	00.45	+1(E)	⁵⁵ Mn ₂ 0 ₂	141.86592	99.52	-3271
647n	127 85502	23 21	-2527	011	194.006/0	00.611	+1207	107 AgCl	141.87368	38.78	-3984
128 0.	107 85737	20.91	0855	135~02	134.85200	01.53	-2519	⁹⁴ ZrÕ3	141.89237	17.27	-8382
	127.05727	42.11	-2000	87 SrO-	134 80372	06.07	_1153	110 Cd02	141.89309	12.33	-8754
⁵⁶ Fe ₂ O	127.35879	83.81	-2735	87 800-	134 80403	27 65	-1283	¹¹⁰ Pd0 ₂	141.89427	11.75	-9442
¹²⁸ Ca ₃	127.33053	00.64	-5112	103 500-	134 80435		-1253	^{12 a} TeO	141.89878	13.65	-14E3
52 Cr2 C2	127.88102	68.61	-5214	119 0-0		27•J2	1007	142 SnC2	141.00205	23.67	-20E3
^{9 6} MoO ₂	127.89476	16.45	-12E3	123010	174.09006	00.56	-1057	130 BaC	141,90623	00.100	-46E3
9 °Ru02	127.8985	05.48	-18E3	135616	124.90410	42.20	-90E2	130 TeC	141,90695	34.10	-60E3
112Cd0	127.89797	23.95	-17E3	LOO CAC2	194.90420	T5.90	-1124	142 _{Nd}	141.90748	27.11	-78E3
⁹ €ZrC₂	127.89910	02.79	-20E3	135 Ea	134.90555	06.59		947rC4	141.90764	16.64	-86E3
112 Sn0	127.9000	00.95	-23E3	27A15	134.90770	100.00	+63E3	142	141.00030	11.07	
116SnC	127,90219	14.14	-38E3	68 7	175 84070	oz he	01.87		1 1. 0		- 1
104 PdCa	127,90329	10.73	-56E3	1127. 0	155.04912	02.45	-2407	IZ IO	142.89957	99.76	-14E3
128 Xe	127.90351	01.917	-6323	40 0 - 0	2122.06000	02.20	-2226	5 SnC2	142.90315	02.92	-22E3
104 R110-	127,90422	18.17	-GÁES	T CagO	1000267	90.12	-0203	143Nd	142.90958	12.17	
128 ZrCa	127.00467	16.91	-1554	Se SrOg	125.39082	ST.96	-1083	142NdH	142.91530	27.11	+25E3
116 ₀₄₀	127 00400	07.50	-2354	10 FPdO2	135.89308	10.92	-12E2	¹⁴² CeH	142.91712	11.07	+19E3
1280-	107 00555	31 70		104RuO_2	135.89402	18.49	-1353	7200	1/12 8/1218	07 50	-2160
40 a - 0	127.90000	21.19	100 23	120 Sn0	135.89711	32.77	-19E <u>3</u>	144m2	147.04710	11.17	2182
10 Ca203	T51.90330	92.10	+2950	¹²⁰ TeO	135.89940	00.089	-27 E3	1447.	142.04200	22 51	-5105
97100	108 80201		1077	124TeJ	135.89898	04.56	-25E3	Je2	142.04499	22·91	-2220
113700	128 90001	00.07		136CdC2	135.90306	23.82	-10E4	3°Fe202	143.555/0	32.6L	-2565
113240	108 90027	10 07	-2020	¹³⁶ Ba	135.90437	07.81		AgCl	143.57346	12.57	-2682
129 0. 0	120.09997	12.20	-2452	ll2SnC2	135.9051	00.94	+19 E4	to Ca3C2	147.88776	38.35	-6529
129	120.9051	07.69	-(942	124SnC	135.90524	05.87	+16E4	112CdO2	143.39286	23.95	-8495
129 D 10	125.904/4	25.44		¹³⁶ SrC ₄	135.90610	79.26	+79E3	TeO	143.90046	31.70	-15E3
PaC2	128.90482	51.98	+1655	¹³⁶ Ce	135.90707	00.193	+50E7	111 SnC2	143.9022	32.32	-19E3
NbCa	128,90764	96.72	+4523	¹³⁶ Xe	135.90721	08.87	+48E3	13Z BaC	143.90512	00.096	-31E3
~′Al ₃ O ₃	128,92935	99.23	+5233	137	170 00075		7 7 7 0	144Nd	143.90980	23.35	
130-	100 Pellon	07 00	01 50	101 Hez Ca	2106.06735	05.77	-2535	<u>1</u> 4 4 Sm	143.91185	03.09	+78E3
EE.	129.35401	27.20	-2452	ag Yog	136.39042	99.28	-9037	27A14C3	143.92616	26.72	+8800
Jug	129.35556	09.55	-2228	105 Pd02	136.89462	22.12	-13E3	C15	100000	57.46	+1595
³ MoO ₂	129.39578	23.67	-12E3	121SbO	136.89862	57.11	-20E3	145710	144.24377	10.78	-2122
114CdO	129.39846	28.79	-15E3	¹¹³ InC ₂	136.90430	04 .1 9	-11E ⁴	145 200	144,84403	04.15	-2159
114Sn0	129.3983	00.66	-18E3	137 CdC2	136.90446	12.52	-1254	113 700-	122 83210	04 26	-80.60
¹³⁰ SnC	129.90205	23.92	-27 E3	137 TeC	156.90462	06.96	-14E4	113040-	100 37036	12 20	-8141
130 Pd C2	129.90291	27.22	-32 E3	137 Ba	136.90557	11.32		121ch/2	122.0 220	55 00	-1753
¹³⁰ Хе	129.90350	04.08	-37E3					133720	144 00513	22.22	-2123
10 °CdC2	129,90593	01.19	-13E ¹	59 Ga2	137.35142	36.48	-2530	- 45		90.09	
¹³⁰ Ba	129.90823	00.1Ĉ1	-13E4	ZrOg	137.33906	51.09	-3717	= 10 IId	144.91208	05.30	
¹³⁰ Te	129.90695	34.43		- PdO ₂	137.59271	27.20	-1233	145 712	145.00335	11.78	+1587
94ZrCa	120.90764	13.83	+19E4	ty 20d0a	137.39573	01.21	-15E3	148-1	a 1 = 21 0 00		2007
131~	170 37710		0.000	tffTeO	137.99781	02.45	-20E3	1480-	1 2 . 2 . 0	07.04	-2027
10 1	100.00010	JUZ	-2519	tffSn0	137.39837	04.71	-21E3	1021227	+-2· *-27	22.32	-2001
F RuO2	130.39505	12.66	-14E3	130CdC2	137.90355	23.49	-10E4	114040	- Teb. 105T		-2-22
115 SnO	130.39326	00.35	-19E5	137TeC	137.90387	13.55	-1-E-	132 - 0202		20. 2	-,2-2
113 InO	170.39852	22.40	-20E3	-14SnC2	137.9039	00.65	-14E4	1307-0	1-2.50130 1-2.50130		-1222
131SnC	130.90315	03.73	-68E2	$g_0 ZrC_4$	137.90433	49.22	-25E4	122-00	142.90100	24.20	-1422
131 AgC2	130.90485	20.25	-25252	¹³⁸ Ba	137.90488	71.66		122000	1 = 50352	02.41	-1922
Xe	130.90508	21.13		¹³⁸ Ce	137.90603	00.25	+1254	1345.0	1-7.10.40	04.02	-1020
1327n-	131,35080	25 80	-2522	138 La	137.90674	00.039	+7+E3	==================================	1,5 01045	02+29 17 00	-エ(コン
40 00 0	131 92776	20.27	-7508	317 0	170 20000		0.05.0	d	1-2.41269	T1.55	
100 p	171 8010	J7•)4 10 = 0	-1000 -1722	- ZrOg	T22.20005	11.14	- : : : : : : : : : : : : : : : : : : :	17512	1-8.00670	00.725	+1552
100100	121 80071	12.50		123 AU02	158.89463	51.10	-1422	147742	148.94081	01.30	-1989
116002	171 90710		-1027 1077	123500	138.89909	42.02	-56.52	147 200	748, 2447E	05.57	-2094
116040	171 20000	14.21		12°TeO	135.8992	00.87	-20E2	115 Tr.O.	148.30741	25.26	-69.69
1320-0	171.099990	20 23	16722	1 SnC2	138.90335	00.25	-52=2	123576	148.00419	41.B1	-1423
108 040	171 00220	22.50		113 InCa	138.90361	93.61	-57 E2	147 BaC	148.00555	06.55	-1653
108 040	131 20107	20.12	-00 ±5	139 IC	138.90466	98.89	-1024	134 ta 13	d 46.20760	00.026	-21E3
132V2	131 00016	26.30	-1/24 1//24	139 TC4	158.90532	12.94	-20 E4	2741=C	146.00770	28.39	-2253
120mar	131 00000	20.09	ーエッジャ - フィント	139 La	120.90603	99.911		147 cm	146 01440	14 07	/
132-	1)1.90449	00.037		тгг∋ан	138.91540	71.65	+20E3	147 0	1 7 01002	20.007	. 1677
Ba	191.90512	00.097		⁷⁰ Gep	139.34798	04.21	-2442	C12	T+1:0T003	00.027	+100%
- S1303	121.91552	77.33	+15E3	140 345	139.35053	47.84	-2555	148Tia	147.33752	00.68	-1874
- Al ₄ C ₂	191.92616	97.80	+6269	140	139 85321	01.40	-2697	148 Geo	147.34200	17.81	-1987
C ₁₁	T25.00000	80 . 45	+1390	28312	139,88465	66 66	-6733	5 6 7 6 2 Ca	147.86388	31.26	-2317
1337n-	132.85318	02.29	-2558	923r0a	179,33040	16.00	-8810	118Sn0a	1-7.39199	14.23	-6045
1010.0	130 8018	16.00	 _1 3 5 3	103 240-	139, 99327	26 68	-1253	1130405	147.39479	07.54	-6826
85phA	130 2069	10.77 71 67	-1683	124TeO	139,89803	04 É8		124TeC-	147.39898	00.139	-8462
117 0003	132 80801	07 50	-1057	1245n0	139,90015	05.03	-1959 -2753	132Ba0	147.90003	00.097	-9000
13300	132 00513		-1767	11eSnC-	139,90219	13.00	-45 23	148 EaC	147.00437	07.79	-12E3
109/ -7	130 00/21	100.00 17 28	-26Fh	1407-0				135 _{Ba} ĭ3	c 47.90891	00.07	-20E3
B5 pr a	130 01000	-1.50 60 01		116020	170 00467	16.34	-23E4	124 SnC-	147.90524	05.81	-13E3
85 0 4	130 01608	11 00		14000	130 00E0P	07.41 gg 10	-4024	138CeC	147.90707	00.191	-16E3
1337	172 · 7100		+1353	128 Ter	130 00555	31 11	15050	¹⁴⁸ Sm	147.01442	11.24	-73E3
611		10.90	1-10-1	139 _{1.2} H		00 00	T7254	148Nd	147.91646	05.73	
				27 41.00	Louvaroite	DProtori	TLOL)			-	
				···⊥4∪29	MIN MULDHY U	110001	いーエフトレフ				



149Ge2	148.84463	01.20	-2063								
^{as} Rb0₄	148.89170	71.46	-5933	12.0	0.			144 cmC	167 01165	03 00	87.00
117 SnO2	148.89290	07.57	-6230	TeO2	157.89367	18.62	-5139	156D.C	167.91105	09.02	-0169
¹³³ CsO	148.90004	99.76	-8885	NdO	157.90239	27.04	-7175	152 Sm()	167 01427	26 66	-99990
149 TeC2	148.90462	06.94	-12E3	134 CeO	157.90421	11.04	-7822	152040	167.01434	20.00	-1057
¹ ³ BaC	148.90557	11.28	-13E3	158N4C	157.90425	02.37	-7837	168GdC	167.92226	20.40	-21E3
149 BaC	148.90772	00.086	-16E3		157.91269	17.12	-14E3	168 Er	167.9308	27.07	
- + Sm	148.91680	13.83		158 Qu	157.92401	00.09	-4124	168 Yh	167.93390	00.135	+54E3
150 Geo	149.84229	05.67	-1909	158 g	157.9244	24.87		12 C14	168.00000	85.55	+2427
75A50	149.84342	100.00	-1937	13	150.000005	00.847	+2000	1 49 -			
865r04	149.38899	09.77	-4712	158 Cr3	158.82003	01.23	-1516	137 Fea	168.79929	05.52	-1251
134 BaO	149.89916	02.35	-6921	¹⁵⁹ Se ₂	158.83661	01.39	-1800	169 BaO2	168,89537	11.27	-4225
150 TeCa	149,90387	18.45	-8845	143 NdO	158.90449	12.14	-7794	NdC2	168.91206	08.64	-7582
150 BaC	149.90488	71.00	-0405	159 BaC2	158.90555	06.50	-8221	¹⁵⁵ EuO	168.91551	52.05	-8972
138 CeC	149,90603	00.25	-1053	147 SmC	158.91449	14.80	-15E3	+ °° GdC	168.9241	15.74	-17E3
138 LaC	149.90674	00.088	-1153	159 Tb	158.92488	100.00		105 Tm	168.93434	100.00	
150 Sm	149.91690	07.44	-3883	¹⁵⁹ C13	159.01008	00.038	+1865	189C14	169.00335	13.42	+2448
150Nd	149.92082	05.62		160 00	150 8300%	00 14	1000	170 Fea	169.80319	00.96	-1283
87	1,9,9,2002	0,02		160 0	159.02294	29.14	-1696	170 Sra	169.82260	00.11	-1504
Sr04	150.88863	06.95	-4883	5 6 T 0		49.99	-1751	85 Rh2	169.82404	52.06	-1527
° (RbO ₄	150.88894	27.58	-4932	1280.0	159.04061	02.41	-20,55	138 BaOa	169.89468	71.32	-4157
¹¹⁹ SnO ₂	150.89295	08.54	-5676	160 7-0		21.64	-21/0	138 CeO2	169.89585	00.25	-4275
135 BaO	150.90046	06.57	-7909	144 Mac	159.90457	07.70	-7000	138 a0a	169.89654	00.089	-4351
27A150	150.90261	99.76	-8914		159.90477	22.79	-7127	134 Ba Ca	169,90425	02.34	-5421
IZ/IC2	150.90466	97.80	-10E3	136g.g	159.90656	05.00	-7745	148NdCa	169.91269	16.84	-7418
151BaC	150.90824	00.79	-13E3	160 CeC2	159.90707	00.109	-7941	154640	169.91585	02.14	-8604
¹⁵¹ Eu	150.91954	47.82		148 MAG	159.91442	11.29	-1252	154 SmO	169.91684	22.66	-9058
152 Cm	151 83261	00 47	-1751	1 60 D	159.91646	05.67	-1552	158 DVC	169.924	00.089	-15E
152 3	151 93856	01 22	-1880	1 60 0 1	159.9259	02.294	-40E2	170640	169.9244	24.76	-15E
40 Ca+0-	151 87758	80 01	-3636	- Ga	159.92721	21.90		170 YD	169.934/	03.03	-11E4
88570	151 88574	81 77	- 2020	161 BaCo	160,90557	11.36	-7994	170 Er	169.9356	14.88	
120000	151 80200	32 60		145 NdO	160.90697	08.28	-8592	170 Č. 4	170.00670	00.977	+2390
1362-0	151 80008	07 70	- 7566	^{1 61} SmC	160.9168	13.80	-18E3	171-			
1400-0	151 005920	87 50	-1300	181Dv	160.9257	18.88		135r2	170.82224	00.079	-1503
1287-7	151 00555	31 00	-1157	81-	101 07004	01 1-	a m h c	173 La02	170.89583	97.43	-425
1521-0	+7+•90000	JT.09	-1553	- Br2	161.00204	24.47	-1/46	- BaCa	170.90555	06.45	-5614
152 cm	151 01030	01.105	-1959	130 Se2		09.15	-1(51	- SmC2	170.91449	14.64	-7947
152 da	151 01017	20.12	100 FE	130m	161.09603		-54/6	153GdO	170.91761	14.69	-9295
Ga	151.91945	00.20	+20E5	27.1°TeO2	161.89675	34.31	-5613	To Los Loc	170.92488	98.89	-15E3
¹⁵³ Se2	152.83926	01.37	-1880	Ale -	161.88924	100.00	-4452	TTYD	170.936/	14.31	
S9Y04	152.88536	99.04	-4339	102 BaC2	161.90488	70.33	-7815	171C14	171.01008	00.044	+2307
121Sb02	152.89351	56.97	-5645		161.90603	00.245	-8274	172 Sra	171.81935	01.90	-1624
¹³⁷ Ba0	152.90048	11.29	-7600	1 of SmC	161.9169	07.51	-19E3	172 Bh	171.82132	40.19	-1655
¹⁴¹ PrC	152.90748	98.89	-12E3	LESSNAC	161.92082	05.56	- 24 52	140 CeO2	171.89508	88.05	-5708
¹⁵³ CeC	152.90863	00.979	-13E3	1 of Dy	161.9256	25.52		1 60 DVC	171.9239	02.27	-13E4
¹⁵³ Eu	152.9206	52.18		+ SE Er	161.92875	00.136	+5253	172 BaCa	171.90437	07.76	-8251
154 Cm-	153 82707	00 07	-1623	163 BaCz	162.90824	01.57	-8330	156Dv0	171,909	00.052	-11E3
15650-	153 83667	05.68	-1805	138 LaC2	162.90603	99.71	-7884	172 SmCa	171.91442	11.31	-1677
90720	153 88307	50.07	-4055	147 SmO	162.90940	14.93	-8855	148NdC	171,91646	05.60	-20E3
122 04	153 8927	02.45	-5266	¹⁵¹ EuC	162.91954	47.29	-20E3	158Gd0	171.91717	20.42	-21E
122 SnO+	153,8933	04.70	-5376	¹⁶³ Dy	162.9278	24.97		1 80 GdC	171.92721	21.66	-86E
138 BaO	163.80070	71 40	-6952	1641	1 CT 91/15	00 03	2 1 2 1	172Yb	171,9252/	21.82	
138120	153,90165		-7590	16 4 0-	102.01412	00.99	1701	173 -			- 1.1
138 CeO	153,90094	00.25	-7333	132 Boo.	163 80403	00.04	-1882	141 D.0	172.01034	01.58	-1445
130 BaCa	153,90623	00.099	-9804	140 000	163 00528	86 63	-7060	173D-02	172.09720	99.52	-424/
130 TeCa	153.90695	33.72	-10E3	148 cm0	163 00033	11 21	-8661	1730-0	172.90557	11.20	-5222
142NdC	153.90748	26.81	-11E3	148 140	167.90977	06 72	-0575	157 C10	1/2.9100		-0107
142CeC	153,9093	10.95	-12E3	152 SmC	163 01036	26.42	-1853	1730.00	172.91901	12.04	-9107
154Gd	153,92094	02.15	-16E4	152 CdC	163 91950	00 108	-1853	17372	172 2397	10.70	-1485
154Sm	153.92193	22.71		164Dvr	163 9285	28 18	-1019	10	1/2.990/	10.12	
1550		00.07	1 000	184 Fr	163.0208	01.56	+13E3	58N13	173.80605	33.11	-1455
155 c.	154.52/21	02.07	-1022	101°	10/09290			174Sr2	173.81545	16.77	-1579
917-0	154.00()() 151 22100	02.20	-1010 -1010	³ ^{Mn} 3	164.81415	100.00	-1435	174 Rb2	173.81860	07.76	-1625
123 01 0	151 20700		-+100	2 ⁰³ CaO2	164.89493	99.52	-4827	142 NdO2	173.89728	26.98	-614]
1397-0	154.09090	→ ∠ • 24	-2234	¹ ¹ PrC ₂	164.90748	97.80	-7629	142 CeO2	173.8991	11.02	-6563
155 LaU	154.90094	77.01		- SmO	164.91171	13.80	-9484	,, † BaC₃	173.90488	69.68	-8394
1550-0	154 01065	107 107	-1583	EuC	T64•9506	51.60	-1953	5 SmC2	173.9169	07.58	-20E3
155 du	154,91205	11:73	-1007	185 CeCa	164,90864	01.94	-8061	T22DAO	173.919	00.09	-26E3
Dr	174.9661	17.12		185HA	164.9291	100.00		+==GdO	173.91931	24.81	-58E3
158Cr3	155.82153	59.40	-1548		, ,_,_			174 NdC2	173.92082	05.50	- <u>36</u> E3
158Se2	155.83575	14.68	-1802	¹⁶⁶ Fe ₃	165.80349	14.67	-1325	DyC	173.9256	25.46	INF.
92Zr04	155.88431	16.95	-4108	134 BaO2	165.89405	02.41	-4789	+(*YЪ	173.9256	31.84	
40 CaaCa	155.88776	87.37	-4519	142 NdC2	165.90748	26.51	-7819	+ ° < ErC	173.92873	00.134	+56E3
124TeO2	155.88878	04.59	-4657	142CeC2	165.90930	10.83	-8553	⁺' * Hf	173.939	00.18	+13E3
124 Sn02	155.89504	05.91	-5728	150 SmO	165.91181	07.42	-9824	175 Sra	174.81509	11.59	-1378
132 BaC2	155.90512	00.095	-9097	150 NdO	165.91573	05.61	-13E3	143Nd0-	174 89938	12.11	-4105
15 °NdC	155.9098	23.72	-13E3	154GdC	165.92094	02.13	-21E3	139 LaC	174.90603	96.63	-4864
144SmC	155.91165	03.06	-15E3	154SmC	165.92193	22.46	-44E3	151 EuCa	174.91954	46.77	-7789
¹⁵⁶ Gd	155.92226	20.47		¹⁸⁸ Er	165.9287	33.41		159 Tb0	174.91979	99.76	-7877
¹⁵⁶ C13	156.00000	86.49	+2006	1 87 For	166-80005	00.70	-1385	175DyC	174.9278	24.97	-12E3
157 m	156,82167	20 10	-1532	135 Ban-	166.89535	06.56	-4749	175 Lu	174.942/	97.41	
157 86-	156,83616	07 55	-1700	1 67 NAC-	166.90958	12.40	-7979	17 8m.	175 90117	37 60	1010
93NDO	156,88530	aa 01	-4044	167 CeC-	166.91265	00.242	-9352	1760-	175 81000	21.00	-1246
125 Ten-	156, 80 ^{±±} 2	06 06	-5287	151 EnO	166-91445	47.70	-10E3	-3r2 144m20	175 8000	00.10	-1246
133 000	156,00513	97.80	-8272	1 67 GAC	166-9227	14 50	-21E3		175 001 15	2J.14	-4000
141 0.502	156.00230	90.76	-7228	187 87	166.9305	22.04	/	140 C- C	175 00500		-4263
145 NAC	156,01206	08.47	-1583	1-201			a. c. l. l.	1607-0	175 01997	02.20	-+099
157 14	156,9241	15.68		Feg	167.79582	77.12	-1244	152 0-0	175 01070	02.29	-1254
157 0 2	157.00335	12.60	+1980	5°517	167.86158	26.60	-2426	52 CAC	175 01047	20.17	-1002
~⊥3 158 <i>a</i> .		07 77	1517	136D-0	167.07249	07.59	-200U	180 3402	175,02212	21.85	-8541
158 c -	157 97799	01.21	-1011	1360-0	101.09411	00.100	-4000	17 5DVC	175.9285	28.15	-1253
79 2	157 93070	02.29 25 El	-1800	168 M (P)	101.0700(F Dropow		164 ErC	175.9298	01.54	-1483
947	157 22700	40.04 17 07	-1002	IAOCA	oneversity 0	I FPCIOIT	a-1770	<u> </u>			
<i>⊔Г</i> ∪4	-j1.00120	11 · C 7	-マビン(



	17 SHf 17 SLu 17 SYb	175.92212 175.9419 175.94272	05.20 02.59 12.73	-8541 -2223	173 EuO2 185 BaC4 185 DyCa	184.9140 184.90557 184.9257	51.93 11.17 18.52	-4919 -4359 -8294	193 _{CU3} 193 _{MO2} 181 _{DVO2}	192.78515 192.81042 19 2. 9155	19.80 10.60 18.79	-1063 -1235 -3769
	⁵⁹ CO3 177Ni3 145NdO2	175.79954 176.90179 176.90186	100.00 01.71 08.26	-1238 -1257 -4354	1 89 TmO 185 YbC 185 Re	184.9292 184.938 184.948	99.76 16.37 37.07	-9843 -19E3	169 TmC2 177 HfO 181 TaC 193 Ir	192.9343 192.9374 192.9458 192.9667/	97.80 18.46 98.88 62.7	-5956 -6586 -9233
	161Dy0 165HoC 177Hf	176.9206 176.92061 176.9291 176.9425	18.83 98.89 18.50	-5080 -8083 -13E3	¹⁸⁵ Ni ₃ ⁹³ Nb ₂ ¹⁸⁶ Zr ₂ ¹⁸⁶ Mo2	185.78501 185.81132 185.81231 185.81449	00.09 100.00 08.83 02.86	-1122 -1334 -1344 -1365	193C18 194Zn3 194M02	193.00335 193.78197 193.81094	14.99 19.95 10.49	+5265 -1070 -1273
	¹⁷⁸ N13 89Y2 146NdO2 162DYO 1542dC	177.79689 177.81144 177.90249 177.92051	19.53 100.00 17.14 25.47	-1218 -1353 -4393 -7912	138 BaO3 188 BaC4 154 GdO2 154 SmO2 188 YbC	185.88961 185.90488 185.91074 185.91173 185.9256	71.14 70.03 02.14 22.60 31.67	-3044 -4058 -4653 -4772 -7408	194 Ruz 162 DyOz 170 YbCz 170 ErCz 178 HfO	193.86270 193.9154 193.934 193.9356 193.9379	00.21 25.41 02.96 14.55 27.07	-1928 -4049 -6620 -7002 -7636
	154 SmC ₂ 162 ErO 166 ErC 178 U	177.92193 177.92364 177.9287	22.21 00.136 33.04	-8445 -9191 -12E3	186DyC2 162ErC2 170Yb0 170Er0	185.9256 185.92873 185.9290 185.9356	25,38 00,133 03,02 14,84	-7408 -8464 -8569 -12E3	182WC 194Pt 194C16	193.9460 193.9633/ 194.00670	26.12 32.9 01.26	-11E3 +4469
	179 _{Ni3} 147 _{SmO2} 179 _{3dCa}	178.79720 178.90429 178.9227	27.14 01.30 14.90 14.73	-1209 -4374 -7953	174HfC 186W 186OS	185.939 185.9507 185.952	00.18 28.41 01.59	-16E3 +14E4	195 MO2 195 Ru2 183 DyO2 195 Yb C-	194.73506 194.81219 194.81475 194.91760	02.95 07.53 01.40 24.85	-1067 -1266 -1237 -4012
	163 DyO 179 ErC 179 Hf	178.92271 178.9305 178.9452	24.86 23.05 13.75	-7957 -12E3	187 M02 187 Zr2 139 LaO3 155 GdOa	186.78738 186.81299 186.81462 186.89076	00.003 04.98 00.63 99.19 14.66	-1129 -1335 -1351 -3004 -4516	179HfO 195WC 195Pt 195C18	194.9401 194.9401 194.9481 194.9662/ 195.01008	14.08 13.72 14.53 33.8 00.066	-9490 -7470 -11E3
	100 N13 90 Zr2 148 SmO2 148 NdO2 180 GdC2	179.79446 179.80866 179.90422 179.9065 179.92226	07.37 26.48 26.48 05.70 20.34	-1187 -1309 -4297 -4544 -7548	187 DyC2 171 Yb0 175 LuC 187 Re	186.9278 186.9310 186.942 186.953/	24.98 14.28 96.33 62.93	-7419 -8498 -17E3	198Zn3 198M02 198Ru2 28S17	195.78078 195.81196 195.31370	24.65 08.84 01.43	-1052 -1263 -1277 -1524
	164 DyO 164 ErO 180 ErC 168 YbC 180 W	179.92341 179.92471 179.9308 179.9339	28.11 01.56 27.02 00.134	-7931 -8413 -12E3 -15E3	188Nis 188Nis 188Zr2 188Mo2	186.956/ 187.78463 187.81528 187.81188	01.64 00.014 03.99 06.05	+62E3 -1091 -1327 -1311	164 ErO2 164 DyO2 196 YbC2 180 WO	195.91960 195.92340 195.9252 195.9394	01.55 23.04 21.35 00.135	-4126 -4484 -4677 -7075
	180 Ta 180 Hf 12 C15	179.945/ 179.945/ 179.9461 180.00000	00.012 35.24 84.58	-16E4 -13339	140 CeC4 156GdO2 172YbO 188 DyCa	187.90528 187.91206 187.9201 187.9285	84.63 20.37 21.76 28.11	-2010 -3641 -4192 -5108 -6618	180 TaO 1840sC 196WC 196Hg	195.9410 195.9399 195.946/ 195.9489 195.96583	00.012 00.018 30.46 00.146	-7205 -9288 -1123 -1524
	1812r2 149SmO2 165H00 1813dC2	130.79262 130.30965 130.9066 180.9241 180.9241	00.43 11.56 13.76 99.76 15.78	-1181 -1329 -4616 -8339 -8339	164 ErC2 176HfC 188 LuC 176YbC	187.9298 187.9408 187.9419 187.94272	01.53 05.14 03.64 12.59	-6936 -12E3 -13E3 -13E3	19 SPt 197 Zn3 197 MO2 197 Ru2	195.9671/ 196.78115 196.81272 196.81370	25.3 03.35 01.82 02.36	-1059 -1275 -1283
	169 TmC 181 Ta 181 C15 182 N4	180.9343 180.9458 181.00335	98.89 98.988 14.22	-16E3 +3144	⁶³ Cu ₃ ¹⁸⁹ MO ₂ ²⁷ Alz	187.9569 188.78877 188.81476 188.87078	02.59 32.98 05.84	-1113 -1315 -2154	¹⁹⁷ Si7 185H002 197 YbC2 181Ta0	196.83806 196.9189 196.938/ 196.9407	20.22 99.52 15.24 99.747	-1525 -4078 -6745 -7432
	182Zr2 134BaO3 134BaC4 150SmO2	191.90907 191.90900 181.88898 191.90425 191.90670	13.87 02.40 02.31 07.40	-1328 -3191 -4358 -4630	157 GdO2 185 HOC2 173 YbO 189 HfC	188.91390 188.9291 188.9330 188.9425	15.60 97.30 16.09 18.36	-4237 -6427 -7410 -1223	198 Zn3 198 Ru2	196.9672 196.9672 197.77814 197.81243	100.00 17.99 05.57	-1062 -1298
	150 NdO2 165ErO 182 GdC2 170 YbC	131.91062 181.92361 181.924 181.934/	05.59 33.33 24.66 03.00	-5143 -8126 -8270 -15E3	¹⁹⁰ Nis 190Mo2 1907ra	188.9585 189.78425 189.31453 189.81694	16.1 00.001 12.99	-1057 -1271 -1291	198517 198517 134BaO4 185ErO2 199VbC-	197.81249 197.83533 197.88390 197.9185	04.00 16.39 02.40 33.25	-1301 -1531 -2453 -4294
	182 ₀ 182 ₀ 183 ₂ 272	191.9356 191.9460 182.00670 182.80999	14.72 26.41 1.115 03.84	-18E3 +2997 -1325	158Gd02 174Yb0 188ErC2 174Hf0	189.9142 189.9205 189.9287 189.9339	24.75 31.76 32.67 00.18	-3815 -4367 -5381 -6311	174HfC2 182WO 186WC 186OSC	197.939/ 197.9409 197.9507 197.952/	00.75 26.65 28.10 01.57	-7735 -8353 -1453 -1653
	183 Nis 135 BaO3 182 BaC4 159 TbC2	132.79019 182.89028 182.90555 182.92488	00.12 06.54 06.40 97.80	-1159 -3164 -4300 -7879	190 HfC 190 Pt 191 Cu3	189.9430 189.964 190.78696	27.04 00.013 44.26	-9046 	198 Pt 198 Hg 199 Zng 199 Pul-	197.9646 197.96675 198.77996	07.21 10.02 03.19	+9253
	187 ErO 183 YbC 183 W 183 C ₁₅	182.92541 182.9360 182.9481 183.01008	22.88 14.18 14.40 00.054	-8063 -15E3 +2952	159 TbO2 191 ErC2 175 LuO 191 HfC	190.80940 190.91468 190.9305 190.9369	06.91 99.52 23.16 97.18 13.90	-1240 -3920 -5804 -7206 -1153	199 S17 135 BaO4 167 ErO2 175 LuC2	198.83489 198.88519 198.9203 198.942/	04.33 06.53 22.83 95.27	-1492 -2397 -4152 -7588
	¹⁸⁴ Ni ₃ ¹⁸⁴ Zr ₂ ¹⁸⁴ MO ₂ ¹³⁶ BaO ₃	183.78744 183.80934 183.31710 183.88910	00.49 20.83 02.51 07.75	-1139 -1318 -1396 -3076	⁶⁴ Zn ₃ ¹⁹² MO2	190.9634 191.78388 191.81192	37.3 11.69 13.05	-1077 -1277	193W0 187 ReC 187 OsC 199 Hg	198.9430 198.953/ 198.956/ 198.96822	14.33 62.23 01.62 16.84	-7889 -13E3 -16E3
•	160 BaC4 160 DyC2 152 SmO2 184 YbC 168 FrO	183.90437 183.9239 183.90916 183.9252 183.9257	07.73 02.24 26.59 21.74 27.00	-4131 -7358 -4629 -7762 -7932	¹⁹² Ru2 ¹⁶⁰ DyO2 ¹⁶⁰ GdO2 ¹⁹² ErC2	191.81860 191.81740 191.9137 191.91703 191.9308	00.078 00.31 02.28 21.30 26.97	-1337 -1326 -3958 -4250 -6113	200Zn3 200Ru2 200M02 200S17	199.77696 199.81110 199.81302 199.83216	10.01 09.16 00.93 01.37	-1045 -1263 -1288 -1469
	160 GdC2 168 Yb0 1840s 184W	183.92721 183.9288 183.946 183.9489	21.41 00.135 00.018 30.64	-8481 -9156 -63E3	168YbC2 176Hf0 176Lu0 176Yb0	191.9339 191.9357 191.9368 191.9376	00.132 05.19 02.58 12.70	-6783 -7244 -7558 -7803	¹³⁶ BaO4 168 ErO2 176 HfC2 200 LuC2 176 VLC	199.88401 199.92060 199.9408 199.9419	07.73 26.94 05.09 04.56	-2371 -4190 -7264 -7317
	185Ni3 185Zr2 137BaO3	184.78776 184.81296 184.89030	00.03 03.91 11.24	-1154 -1370 -3205	180WC 180TaC 192HfC 192Os 192P +	191.9445 191.945 191.9461 191.9622	00.134 00.012 35.00 41.0	-11E3 -11E3 -12E3 -12E3	-1002 1840s0 184W0 1880sC 200Hg	199.9409 199.9409 199.9438 199.9569 199.96833	12.45 00.018 30.57 13.2 22.13	-7290 -7290 -8152 -1823
					¹² C ₁₈	117561218 Ot	Riefdus	+5078	-		-	



201 201 137 169 201	Zn ₃ Ru ₂ BaO ₄ TmO ₂ HfC ₂	200.7780 200.80978 200.88521 200.9241 200.9425	5 01.36 3 12.35 1 11.21 99.52 18.20	-1045 -1252 -2362 -4351 -7232	1860sCz 194Pt0 198PtC 211HgC	209.952 209.9582 209.9646 209.96675	01.55 32.8 07.13 16.76	-34E3 +33E3 +25E3	232 Sn2 232 Cd2 232 PbC2 232 Th	231.80638 231.80998 231.97665 232.0380	03.05 00.57 51.6 100.00	-1002 -1018 -3782
201 201	ReO OsC Hg	200.943/ 200.9585 200.97209	36.98 16.0 13.22	-7364 -17E3	187 ReC2 195 PtO 199 HgC	210.80773 210.953 210.9611 210.96822	12.15 61.54 33.7	-1376 -27E3	²³³ Sn ₂ ²⁰⁹ B1C ₂ ²³⁴ Sn ₂	232.80529 232.97934 233.80424	02.46 97.80 08.04	+1338 - 991
202	Zn ₃ Ru ₂ Ba04	201.77577 201.8087 201.88452	03.45 11.58 70.97	-1037 -1247 -2346	212Pd2 180Hf02 196P+0	211.80582 211.9359	13.55 35.07	-1357 -8121	234U 235 Sn2 23511	234.0403 234.80515 235.0428	00.0056	; - <u>-</u> - - 989
170	YbO2 ErOa	201.9238 201.9254	03.03	-4313	212HgC	211.96833	25.2	+34E3	2365na	235.80439	16.65	,
202 186	HfC ₂	201.9430	26.95	-7311	213Pd2	212.80829	11.88	-1385	237 Sn2	236.80530	09.16	-1497
202 202	wo OsC Hg	201.9458 201.9548 201.97063	20.35 26.3 29.80	-8071 -13E3	197Au0 213HgC	212.9556 212.9621 212.97029	99.51 99.76 13.33	-8036 +26E3	205 T102 238 Sn2	236.9636 237.80425	70.20 17.95	- 974
203	Zn3	202.77685	00.47	-1041	214Pd2	213.80638	17.19	-1378	238U	237.96424 238.0486	23.5 99.2739	-2022
203	Ru2 Yb02	202.8087/	15.52	-1244 -4403	187 WO2	213.80966	26.37 26.28	-1408 -8274	239 Sna	238.80535	06.40	-1490
203 187	HfC ₂	202.9452	14.04	-7602	¹⁹⁸ Pt0 198 _{Hg0}	213,9595	02.19	-99E3	207 Pb02	238.96568	22.5	
187	Os0	202.940/	62.78 01.64	-8493 -9712	214HgC	213.97063	29.62	+24E3	²⁴⁰ Sn ₂ 208 PhOn	239.80440	14.76 52.0	-1227
203	IrC Tl	202.9634	37.3 29.50	-24E3	215 Pd2	214.80695	05.25	-1397	240C20	240.00000	79.99	
204	Zna	203.77451	00.84	-1027	199 HgO	214.96313	16.80	-0520	²⁴¹ Sn ₂ 241Coo	240.80661	01.71	-1225
204 140	Ru ₂	203.80746	14.68	-1232	203T1C	214.9719	29.17	+25E3	²⁴² Sn ₂	241.80566	05.96	-1204
172	Yb02	203.9150	21.71	-2514 -3512	218Ag2	215.80944	49.96	-1134	242C20	242.00670	01.91	
180	WC2 TaC2	203.9445 203.9458	00.132	-7137 -7477	¹⁸⁴ W02 200 Hg0	215.9387 215.96323	30.49 23.07	-3524 -5874	²⁴³ Sn ₂ 243Cao	242.80839	01.02	-1205
204 192	HfC_2	203.9461	34.76	-7560	204 PbC 204 HgC	215.97308	01.46	-8024 -8142	²⁴⁴ Sn ₂	243.80692	04.13	
192	PtC	203.9648	00.77	-19E3 -25E3	15 ^{C18}	216.00000	81.80		232 ThC	244.0380	98.89	
204	Pb Hg	203.97308	01.48 06.85	 +52E4	217 Cd2 186WO	216.81021	00.31	-1124	232ThO 238UC	248.0329 250.0486	99.76 98.175	
12C:	17	204.00000	82.72	+7577	205T1C	216.9738	69.72	-7344	252C21	252.00000	79.14	
2052	Zng Rug	204.77505	00.067	-1031 -1245	218 C18	217.00335	16.50		254Ca	252.00555	02.09	
173	rb0 ₂	204.9278	16.05	-4456	218 Pd2	217.80794	06.31	-1097	238U0	254.0435	99.035	+5930
189	$1a0_2$ 0s0	204.9458	97.79 16.1	-7320 -10E3	²¹⁸ Ag2 202 _{Hg} O	217.80922	23.67 29.73	-1104 -5295	²³² ThC ₂ 238UC ₂	256.0380 262.0486	97.80 97.088	
205	IrC Fl	204.9667 204.9738	62.0 70.50	-29E3	20 8 PbC	217.97444	23.3	-6758	232 ThO2	264.0278	99.52	9496
205(317	205.00335	15.75	+6937	219 Cdo	218.80835	00.52	-1086	²⁶⁴ C ₂₂	264.00000	78.26	
2062	Zna	205.77505	00.067	-1033	203T10	218.9668	29.43	-5060	² ⁶⁶ C22	265.00335	19.29 02.27	
2061	Pd ₂	205.80814	00.21	-1239	219 _{C18}	219.01008	00.094	-6404	238U02	270.0384	98.796	
174	Rh2 7b02	205.80910	100.00 31.69	-1246 -3489	220 Cd2	219.80658	02.66	-1363				
182 V 190		205.9460	25.83	-7242	204Pb0	219.80894	01.39 01.48	-1983				
194	PtC	205.9633	32.5	-18E3	²⁰⁴ Hg0 220PhC	219.96838	06.83 52.0	+57 E4 +25 E3				
2080	20 217	205.97444	26.4 01,41	+6385	2 2 1Cd2	220.80757	03.37	-1371				
207 E	2d2	206.80968	00.43	-1245	²⁰⁵ T10 209B1C	220.9687 220.97934	70.3 98.89	+2183				
207 M	LuO2 IC2	206.9318 206.9481	96.94 14.66	-4695 -7451	222 _{Cd2}	221.80635	08.28	-1362				
191] 207 -	[r0 r0	206.9583	37.2	-12E3	²⁰⁶ Pb0	221.96935	23.5					
207 F	γõ	206.97588	22.6		207 Pb0	222.80734 222.97080	08.27 22.5	-1364				
2080	17	207.01008	00.079	+6052	224Cd2	223.80684	16.20	-1360				
208 F	d ₂	207.80656	01.73	-1223	²²⁴ Sia 208Pb0	223.81544 223.97156	52.27 52.1	-1435				
208F 176H	lu ₂ : If0 ₂ :	207.80844 207.9306	03.45 05.17	-1236 -4516	75A53	224.76513	100.00	-1076				
178 176v	.u02 /	207.9317	02.58	-4627	20° B10	224,80783	13.26 99.76	-1352				
208 W		207.9489	30.29	-7495	228Cd2	225.80661	17.27					
192 P	t0 2	207.9571	40.9	-11E3 -13E3	²²⁷ Cd ₂	226.80801	09.01					
208 F	rtC 2 b 2	207.9671	25.37 52.3	-22E3	228 Ud2 228 In2	227.80710	08.19	-1188				
soab	de 2	208.80810	04.88	-1220	204 PbC2 228 C12	227.97308 228.00000	01.45 80.89	-8470				
177 H 185 p	$f\bar{0}_2$	208.9323	18.41	-4443	229 Cd2	228.80945	01.86	-1181				
193 I 197 (rO	208.9616	62.5	-12E3	²²⁹ C ₁₉	229.00335	17.22					
209B	uc 2 1 2	200.9672 208.97934	98.89 100.00	-17E3	230 In2 230 Cd2	229.80722 229.80854	91.62 04.38	-⊥153 -1161				
210 p	d ₂	209.80619	11.45	-1381	230C19 231D17	230.00670	01.74					
18 6W	C_2	209.80964 209.9507	27.78	-82 66 -28E3	PDU2	230.9(500)	cc.b	io				
						· · · · · · · · · · · · · · · · · · ·	PERCIPATION	1 M M M				





APPENDIX C

COMPARISON OF EXPERIMENTAL ANALYTICAL DATA TO EXPECTED VALUES FOR SELECTED ELEMENTS USING VARIOUS ANALYTICAL TECHNIQUES

Laboratory

Analytical Method

Α	Inductively	coupled	plasma	(ICP)	optical
	emission sp	ectroscop	oy (OES))	

- B Spark-source mass spectrometry (SSMS)
- C Inductively coupled plasma (ICP) optical emission spectroscopy (OES)
- D Atomic absorption spectroscopy (AAS)
- E Arc emission spectroscopy (AES) (AgC1 buffer)
- F Arc emission spectroscopy (AES) (NaC1 buffer)
- G Direct current emission spectroscopy

Experimental and expected values are given in the units μ gX/gU. The dotted lines depict expected concentrations.



































Dedicated to my wife

DENISE

and my children

GAVIN, NICOLE AND EDWIN

for their love, support and understanding



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ACKNOWLEDGEMENTS

The author would like to express sincere thanks to:

PROFESSOR R G BÖHMER for his guidance, assistance and helpful comments.

DR W C A VAN NIEKERK for his motivation, guidance, unfailing support and many valuable discussions.

MR M T S BRITTON for his valuable comments.

MR J J VAN ROOYEN for his assistance and guidance.

MR P A SPIES for performing many of the supplementary analyses.

MRS S M SWART and MISS A M M OOSTHUIZEN for their patience in typing this script.

THE ATOMIC ENERGY CORPORATION OF SOUTH AFRICA LIMITED for the opportunity of conducting this study.

MY COLLEAGUES for their support.

AND THOSE who contributed in any way and who were involved in performing any of the supplementary analyses required for the completion of this dissertation.



ii

SUMMARY

Spark-source mass spectrometry is used exclusively for the analysis of metal samples and other solid-state materials. Non-conducting powders are mixed with either silver or graphite as conducting medium, and pelleted into electrodes which are then mounted in the ion source. The dc-spark forms a plasma from which the ions are extracted and accelerated down a flight tube. The ion beam is defined by an electrostatic analyser and recorded on a photographic plate, after passing through a magnetic field which separates the ions according to their mass-tocharge ratio. The line blackening on the photoplate is measured using a microdensitometer. The data is interpreted using specialised compu-A major advantage of photoplate detection in sparkter software. source mass spectrometry is that the entire periodic table of elements can be recorded from a single analysis.

Reference standards are not available in South Africa for uranium com-A method of spiking the conducting material with trace impuripounds. ties was developed after testing various graphite powders. Precision tests confirmed the homogeneity of the standards and the feasibility of using these for quantitative analyses. A comprehensive range of standards containing up to 34 elements, each using yttrium as an internal A complete set reference, were prepared and analysed quantitatively. of calibration graphs was compiled, providing relative sensitivity factors (RSF's) for these elements in a U_3O_a /graphite matrix. For most of these elements, both the singly and doubly charged states were considered so as to obtain a correlation between the various ion yields. The accuracy obtained at a concentration level of 10 µg/gU is better than 20% for most of the elements determined. The UF_4 /graphite matrix was also studied.

This method was assessed by comparison with ICP, AA, spectrographic and spectrophotometric methods. Excellent agreement was confirmed.

KEYWORDS: spark-source mass spectrometry, U_3O_8 /graphite matrix, UF_4 / graphite matrix, uranium compounds, relative sensitivity factors, photoplate detection, low-voltage discharge.



iii

OPSOMMING

Vonkbronmassaspektrometrie word uitsluitlik vir die ontleding van metaalmonsters en ander vastestofmateriale gebruik. *Nie-geleidende* poeiers word met silwer of grafiet as geleidende medium vermeng en in elektrodes gedruk wat dan in die ioonbron gemonteer word. Die gelykstroomvonk vorm 'n plasma waaruit die ione uitgeneem en in 'n vlugbuis versnel word. Die ioonbundel word deur 'n elektrostatiese analiseerder gedefinieer en op 'n fotografiese plaat opgeneem nadat dit deur 'n magneetveld beweeg het, waar ione volgens die massa-tot-ladingsverhouding geskei is. Die lynverswarting op die fotoplaat word deur 'n mikroverswartingsmeter gemeet. Die data word met gespesialiseerde rekenaarprogrammatuur vertolk. Die hoofvoordeel van fotoplaatdeteksie in vonkbronmassaspektrometrie is dat die hele periodieke tabel van elemente met 'n enkele ontleding opgeneem kan word.

Verwysingstandaarde van uraanverbindings is nie in Suid-Afrika beskik-'n Metode van toevoeging van spooronsuiwerhede tot die geleibaar nie. dende materiaal is ontwikkel nadat verskeie grafietpoeiers uitgetoets is. Presisietoetse het die homogeniteit en die bruikbaarheid daarvan vir kwantitatiewe ontledings bevestig. 'n Omvattende reeks standaarde met tot 34 elemente, wat elk yttrium as interne verwysing bevat, is voorberei en kwantitatief ontleed. 'n Volledige stel kalibrasiegrafieke is opgestel, wat relatiewe sensitiwiteitsfaktore (RSF's) vir hierdie elemente in die U₃O₈/grafietmatriks verskaf het. Vir die meeste van hierdie elemente is beide die enkel- as dubbelgelaaide ladingstoestande beskou om 'n verband tussen die verskillende ioonopbrengste vas te stel. Die akkuraatheid wat by 'n konsentrasievlak van 10 µg/gU bereik is, is beter as 20% vir die meeste van die elemente wat bepaal is. Die UF4/grafietmatriks is ook ondersoek.

Die metode is deur vergelyking met IGP, AA, spektrografiese en spektrofotometriese metodes geëvalueer. Uitstekende ooreenstemming is bevestig.

SLEUTELWOORDE: Vonkbronmassaspektrometrie, $U_3O_9/grafietmatriks$, $UF_4/gra-fietmatriks$, uraanverbindingsersityelapieweia sensitiwiteitsfaktore, foto-plaatdeteksie, laespanningontlading.



CHAPTER ONE

INTRODUCTION

1.1 Introductory review

The double-focusing spark-source mass spectrometer Varian SM1B-F is well known for the analysis of trace impurities in solids such as conductors, semi-conductors and insulators. An electric discharge is generated between two electrically conducting electrodes which are made partly or wholly of the sample substance and mounted in a high vacuum. The electrode substance is evaporated and simultaneously ionised in the discharge. The ions emitted from this discharge are accelerated into the analyser, filtered according to their energy in the electrostatic analyser and analysed according to their mass-to-charge ratio, m/e, by deflection in the magnetic field. Ion-sensitive photographic plates are used to detect the ions and provide a permanent mass spectrum of the sample.

All elements with concentrations in the detection range may be analysed simultaneously in a single analysis. The complete mass range of interest is then recorded on a single photographic plate. This emphasises the selectivity and power of spark-source mass spectrometry in solid-state analysis. Very small sample The minimum mass of a non-conducting powder sizes are required. sample for a single analysis is only 0,1 grams which is then mixed with a conducting medium such as graphite powder. The physical size of a conducting metal or alloy sample for a single analysis is a piece one millimeter square with a ten millimeter length, which can be cut off from the bulk sample. The sensitivity with which a given element in a sample can be detected is in the same order of magnitude for almost all elements. Generally, it can be stated that the detection limit for almost all elements


is in the parts per billion (ppb) range. Some difficulties are, however, encountered in the quantitative determination of certain elements below the parts per million (ppm) concentration.

If a sample has a completely unknown composition, the sparksource mass spectrum allows the analyst to carry out a quick and standard-independent survey of the composition of the sample, qualitatively or semi-quantitatively. This survey analysis provides the concentrations of practically all elements in the sample to as far down as the ppb range, with a deviation from the absolute value not exceeding at the most, a factor of 3. A major advantage in the analysis at trace levels is the fact that samples can be analysed without any preliminary chemical treatment. This eliminates possible direct, as well as indirect, sources of contamination.

For many of the analysis problems in industry, particularly in trace analysis, a qualitative or semi-quantitative analysis of the sample is sufficient. If, however, a greater degree of accuracy is required, then the amount of endeavour required to carry through an analysis is correspondingly higher and the duration of the analysis that much longer. It is then necessary to measure the transmission factors of the spectral lines of the elements of interest. Concentration values relative to the concentration of one or several internal or external reference elements are hence obtained. The precision which may be achieved using graphical evaluation methods is in the order of approximately 20 per cent.

The work involved in high precision analyses is more arduous and exacting. The analyst must rigorously apply a precisely defined method of analysis in the evaluation of photographically recorded



mass spectra. The large amount of spectral information must then be fully utilized [1]. This can be achieved only with computerised data interpretation methods. The program provides spectral line transmission values along with the necessary corrections such as isotope abundances, line surfaces, photographic sensitivity, background and loss of sensitivity of the photoplates through background [2].

At present, the precision cannot be increased to values of better than approximately 20 per cent. This is largely due to the properties of commercially available photoplates. The statistical distribution of the silver grains on the photoplate surface as viewed through the microdensitometer slit gives the precision obtainable in mass spectrometric analyses of solids, an upper limit of 20 per cent. The percentage surface covering of the silver grains is a measure for the transmission factor for the relevant mass lines.

1.2 Motivation and scope of the thesis

Uranium compounds are produced to nuclear grade specifications by the Atomic Energy Corporation of South Africa Ltd. Maximum permissible levels are defined for a large number of elements in uranium oxide, U_3O_8 . The spark-source mass spectrometer and various other techniques and methods are used to analyse these compounds. However, these techniques have limiting factors, such as sample treatment, standard addition and spectral interferences, which are not applicable to the spark-source mass spectrometer.

In order to perform quantitative analyses on the trace level impurities in uranium compounds, specifically U_3O_8 and UF_4 , making use of the internal reference standard method, the spark-source mass spectrometer first had to be characterised by deter-



mining relative sensitivity factors (RSF's) for these impurities in the particular matrices.

At the start of this characterisation stage of the project, no suitable standards were available. The existing standards were incomplete in that they did not contain all the relevant impurity elements. The non-availability of international U_3O_8 standard reference material (SRM) further complicated the situation. Due to these limitations, graphite standards containing all the required impurity elements were prepared.

After this characterisation phase had been completed, the sparksource mass spectrometer was used to standardise a series of internal U_3O_8 working standards. This technique can also be used in other applications in the nuclear industry where contamination must be controlled through a quality control programme.

This investigation had as its aim to conduct a comprehensive evaluation of the method of relative sensitivity factors for the determination of trace elements in U_3O_8 . The project also afforded the opportunity to study the UF4 matrix where the effects of an excess of fluoride ions in the plasma had a marked effect on the ions recorded on the mass spectrum. This part has been studied in lesser detail. The evaluations were carried out to a point where routine analyses could be performed on the basis of the documented procedures. It was of prime importance to incorporate safeguards for reliable data acquisition and interpretation when doing routine analyses. This thesis should serve as a useful reference manual for the application of spark-source mass spectrometry in the nuclear industry. It contains extensive guide-lines for spectrum identification in uranium oxide and fluoride matrices. Data for fluoride matrices has never been published in the open literature.



CHAPTER TWO

THE FUNDAMENTALS OF SPARK-SOURCE MASS SPECTROMETRY

2.1 <u>The physics of plasma formation</u>

The most commonly used method of generating ions in the analysis of solids is with the radio frequency (RF) spark. However, this type of ion source has proved to be deficient in many respects as will be discussed below.

In the Varian SM1B-F spark-source mass spectrometer, the triggered low-voltage discharge (secondary spark) is used to generate ions. This low-voltage discharge is generated in turn by an external high-voltage impulse (primary spark) [3].

The major differences between the low-voltage spark and the RF spark can be summarized as follows:

The energy width of ions emitted from the triggered low-voltage discharge is much smaller than for the ions generated by the RF spark. This means that more ions pass through the entrance to the electrostatic analyser for the low-voltage spark. Due to this factor the time taken to determine an element in a sample at a given concentration with the same sample consumption is considerably reduced for the low-voltage spark compared to the RF spark.

When high-voltage electric spark-overs occur in the ion source due to too great a distance between the two electrodes, and also during the low-voltage discharge, some of the electrode substance is transferred from one electrode to the other. With the RF spark the polarity of the electrodes alters so that particles of



the electrode substrate flow in both directions. With the lowvoltage discharge, the polarity of the electrodes does not alter, therefore during each discharge a new amount of the cathode is evaporated, partly ionised and condensed on the anode so that the volume of the anode increases and that of the cathode decreases. The flow of electrode substrate particles in the same direction eliminates the possibility of some components of the electrode substance becoming preferentially evaporated, a process which happens in the RF spark.

The ratio of multiply charged ions to singly charged ions is not constant in the case of the RF spark. The constant ratio in the case of the low-voltage discharge offers an advantage in that the quantitative analysis of a sample is not restricted to evaluating lines of singly charged ions, but also multiply charged ions [1]. This is useful, especially in cases where the line of a singly charged elemental ion is interfered with by a line from another elemental ion such that the first element cannot be quantified. Then a multiply charged ion of the same element can be used to quantify.

Ions formed in the ignition phase (primary spark) of the impulse low-voltage spark exhibit characteristics making them unsuitable for quantitative analysis which resemble those obtained with the RF spark. By using time resolved mass spectrometry [4] with the SM1B-F, all these unwanted ions formed in the ignition phase are rejected and only ions generated during a.selected burning time interval of the low-voltage discharge arc are allowed to pass through the mass spectrometer where they are analysed according to their mass-to-charge ratio and detected photographically.



Various processes occur between the two electrodes in the ion source. The electrode material is first evaporated/volatilised. Thereafter the vapour is selectively atomised and subsequently ionised [5, 6]. This resulting collection of charged particles is called a plasma. The above processes occur during the lowvoltage arc discharges (secondary sparks) which are induced by high-voltage ignition pulses (primary sparks). Eventually the ions are accelerated into the mass spectrometer due to the 20 kV acceleration voltage. The plasma can thus be seen to be floating at this voltage. The formation of ions in this manner lead to ions found only in the elemental atomic stage. No molecular species are formed, except clusters which are formed due to recombinations within the plasma.

The primary and secondary sparks are controlled by pulse statistics and spark parameters. This means that the plasma created between the two electrodes in the ion source (and ultimately also the ion beam) can be controlled by the spark parameters.

Arc discharges are generated between the two electrodes in the ion source in order to evaporate the samples to be analysed. The spark repetition rate of individual discharges can be set in steps of 10, 30 or 100 Hz by adjusting the frequency. The voltage of this arc discharge is approximately 850 V and is set. Each discharge is induced by a high-voltage ignition impulse and subsequently maintained for a specified period of time as a lowvoltage discharge with a constant current. This discharge current of the low-voltage arc can be set in 10 equal stages between approximately 3 and 10 A. The high-voltage ignition impulse used to induce discharges has a maximum ignition voltage of approximately 64 kV with +32 kV on the one electrode and -32 kV on the other electrode. The energy of the ignition spark can be set to 3 different intensities.



The above spark parameters are directly related to the results obtained in respect of atomisation and ionisation of the electrode material.

Ions generated during the burning interval of the discharge and subsequently accelerated into the flight tube of the mass spectrometer can be deflected in front of the entry slit. This means that ions are only allowed to reach the entry slit during a certain pre-selected time in the burning interval and the ion current is completely cut out during selected dead times (impulse statistics). In this way the ion beam can be controlled.

2.2 Mass spectrometer design features

A simplified block diagram of the Varian SM1B-F spark-source mass spectrometer is given in Figure 2.1. The instrument makes use of a triggered low-voltage direct current (d.c.) discharge in the ion source region where ions are generated. The ion beam then undergoes double-focusing on entering the analyser, comprising the electrostatic analyser (ESA) and magnetic sector with Mattauch-Herzog geometry. A photographic plate is used to detect the ions.

The generation of ions in the ion source region of the mass spectrometer has been discussed in Section 2.1. All parts in close proximity of the actual spark i.e. the acceleration plate and the shield plate, are made of tantalum and can be cleaned easily by chemical or mechanical means. Electrical focusing is not possible because of the relatively large initial energy dispersion. The design of the ion source is therefore relatively simple, consisting only of the acceleration system and a deflection condenser.

 * Varian MAT, now Finnigan MAT, GmbH, Postfach 14 40 62, D-2800 Bremen 14, Federal Republic of Germany.
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An important feature of the instrument is that all original tube electronic units have been replaced by units using solid-state electronic components. The vacuum system has also been updated. Two large turbo-molecular pumps are used to achieve a working vacuum of 10⁻⁴ Pa in the ion source region of the mass spectrometer. Two ion-getter pumps are used in the analyser region (electrostatic analyser (ESA) and magnetic sector) to obtain a vacuum down to 10⁻⁷ Pa. One small turbo-molecular pump is used to obtain a vacuum of 10⁻³ Pa in the photoplate lock.

The ion optical system of the SM1B-F mass spectrometer is given in Figure 2.2, which shows the path of the ion beam. In the ion source, particles of the substance to be investigated are ionised, accelerated through a system of electrostatic lenses by means of a stable 25 kV Spellman^{*} high-voltage d.c. supply unit, and focused into a narrow beam. This ion beam must be so aligned that it hits the centre of the object slit (exit slit of the ion source). To achieve this, the ion source can be aligned in all three directions.

The object slit (entrance slit of the ion optical system) defines the width of the ion beam so that the desired resolution can be set. In order to meet the requirements of quantitative analysis and the separation of doublets, the ion source is equipped with a pair of slits having entry slit widths of 30 and 300 μ m. With a slit width of 300 μ m the aberrations of the ion optics is negligibly small. Since the slit is evenly illuminated at the same time, rectangular-shaped line blackenings are obtained with the wider slit width on the photoplate.

* Spellman High Voltage Electronics Corporation, Plainview, New York, 11803, U.S.A.



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spark-source mass spectrometer



The formula used to determine resolution (R) is given by:

$$R = \frac{M_o}{\Delta M}$$

where:

 M_{\odot} is the nominal mass of the particular element, and ΔM is the difference between the mass defect of the element under scrutiny and the mass defect of the interfering element (see also page 41).

The resolutional requirement is given in the fourth column of Appendix B on page 177. The resolving power is defined as that resolution required to resolve two mass spectral lines lying adjacent to each other as a doublet on a photoplate.

The resolving power of the SM1B-F mass spectrometer is up to 10 000 and depends on the position on the photoplate, the magnet strength setting as well as the object and exit slit settings. Practical resolving powers obtained during this investigation range between 2 000 and 5 000.

The electrostatic deflection field between the plates of the curved analyser produces an energy dispersion and a direction focusing. Ions of selected energy are thus directed in one parallel beam on emergence from the electrostatic analyser.



The potential difference between the ESA plates is kept very stable and is supplied by two 5kV Spellman high-voltage d.c. supply units. The energy band of ions leaving the ESA is defined by a narrow band within the Boltzman natural distribution of the energy population shown in Figure 2.3.



Figure 2.3: Shaded area represents energy band of ions selected on leaving the ESA

On leaving the ESA, the ion beam is defined vertically, called z-direction. The direction of the ion beam emerging from the the ESA can be controlled and correctly adjusted, so that the beam passes the monitor lens plates symmetrically and enters the magnetic field horizontally. The casing of the z-monitor acts as a shield against influences from the magnetic field as does the so-called Herzog lens. This lens creates a magnetic short circuit and ensures that the area within the z-lenses is not disturbed by the stray field of the separating magnet. At the end of the Herzog lens, the energy slit is mounted just in front of the magnet chamber. The energy-defining slit determines the point of entrance of the ion beam into the magnetic field and can be shifted horizontally, called the r-direction. The position



of the ion beam can also be controlled in the r-direction prior to its entrance into the magnetic field. The path of the ion beam through the Herzog lens and z-and-r-monitors is shown schematically in Figure 2.4.



<u>Figure 2.4</u>: Path of ion beam through Herzog lens and z- and r-monitors

The ion beam, which is defined in the r- and z-directions, enters the magnetic field produced by an electromagnet, whose current is supplied by a stable solid-state magnet power supply unit. The double-focusing plane (the plane in which ions of equal m/e



ratio are focused with respect to direction and energy) lies outside the magnetic field. Due to this location of the plane outside the field, it is possible to use a slit collector positioned in front of the photoplate for the measurement of the total ion current. The ions entering the magnetic field are bent according to their mass-to-charge (m/e) ratio and recorded on the photoplate.

2.3 <u>Ion detection and measurement</u>

In the quantitative analysis of solids, it is not only customary but necessary, in order to cover as large a concentration range as possible, to bring a staggered series of exposures of the same mass spectrum onto one photoplate. The selection of such an exposure pattern is discussed on page 21. Aspects of the ionsensitive photographic plates are discussed on page 22.

Since the ion current emitted from the ion source fluctuates with time, a slit aperture detector is used to record a fraction of the total ion current. This ion current is integrated over time to provide a measure of the total ion current falling onto the photoplate during each exposure.

In the SM1B-F spark-source mass spectrometer the electrodes of the slit aperture detector are positioned directly in front of the photoplate, i.e. at the exit boundary of the analyser's magnetic field. The ion current integrator permits the exact measurement of the charge down to 0,01 picocoulomb (pC).

There are a number of publications in existence on general measuring techniques used in conjunction with double-focusing mass spectrometers with a spark-source [1]. The measuring technique used in this work required specialised hardware and software



[7, 8] specifically designed and developed to evaluate spectral lines on ion-sensitive photoplates.

Besides photoplate recordings, ions can also be recorded with an ion collector utilizing a Faraday cage or a secondary electron multiplier (SEM) as electrical detection systems. Two focusing plates positioned behind the exit slit direct the ion beam onto the ion collector. Further plates located in front of the exit slit are connected to a saw-tooth generator. The ion beam can therefore be made to pass at intervals before the slit. Connected to the SEM of the ion collector, the ion beam can be displayed as a peak on an oscilliscope screen. Alternatively, the ion beam can be recorded with a Faraday cage which can be exchanged for the SEM.

The SM1B-F spark-source mass spectrometer used by this laboratory does not make use of electrical detection as this facility has been removed from the instrument.

The advantages of utilizing photoplate detection can be summarized as follows:

Photographic plates provide a permanent record of the spectrum obtained for a sample. Once the analyst has analysed the photoplate, it can be stored and re-used at a later stage to obtain additional information. The complete spectrum of impurity elements present in the sample is obtained on a photoplate. This helps the analyst when eliminating possible interferences on a specific spectral line.

Sophisticated hardware and software exist for the reading and interpretation of mass spectrographic ion-sensitive photoplates. The sensitivity of the emulsion layer on Ilford Q plates meets the requirements for the detection of ions of low concentration levels.



CHAPTER THREE

EXPERIMENTAL

3.1 <u>Mass spectrometer operation</u>

3.1.1 Operation of the instrument

The operation of the instrument, from the time the sample is loaded in the ion source of the mass spectrometer until the photoplate has been exposed and removed to the dark room for development, is comprehensively described in the operating manual [9] and will not be repeated in this thesis.

3.1.2 Preparation of electrodes

Solid-state compounds which are analysed with spark-source mass spectrometry can be divided into two groups: The first group, metals and alloys, are electrically conducting and analysis can be performed directly on a piece of the material. The second group, powders, can be divided into conducting and non-conducting materials. For powder samples, electrodes have to be pelleted. However, for non-conducting powders, a conducting medium such as silver or graphite must first be mixed with the sample before electrodes can be pelleted.

For non-conducting powder samples, these are first ground using an agate mortar and pestle to ensure homogeneity of the sample. Thereafter, the sample is weighed and combined with graphite in the appropriate dilution ratio, using yttrium as an internal standard. The preparation of graphite standards and the use of yttrium as an internal standard are discussed on pages 26 and 28, respectively.

Two or three glass beads are then placed into the polyethylene vial with the sample/graphite mixture to promote good mixing using a Retsch^{*} Type MM2 agitator/mixer or a Wig-L-Bug[#] mixer, serial no. Y56737. A cylindrical high-density polyethylene pill (called a slug), with two holes through it, is then placed into a stainless steel holder. This holder is specially manufactured to accommodate the pill and also has a sample loading facility. Using a small spatula, the sample mixture is carefully inserted into the holes of the pill through the sample loading facility of the holder. A plunger is used to compact the sample. The exercise requires gentle action in order to produce an electrode. The pill is then placed in a die and compacted to 22 - 25 tons using a Spex Industries 25 ton hydraulic bench press. The pill is subsequently placed on a perspex support and a stainless steel plunger is used to press out the two electrodes. The tips of each electrode are carefully broken off to expose a representative new surface for analysis. The electrodes are finally clamped in tantalum electrode holders and mounted in the ion source of the mass spectrometer.

3.1.3 Spark generator parameters

It was important in this investigation to keep all the instrument parameters constant throughout the experiments so as to eliminate possible differences from one photoplate to the next. However, as a result of the wide concentration range employed in the graphite standards, certain parameters were changed slightly to suit the particular analysis. The various instrument parameters are given in Table 3.1.

- * F. Kurt Retsch KG, 5657 Haan, Neuer Markt 25, Germany.
- # Wig-L-Bug, Crescent Dental MFG. Co., Chicago, Illinois, 60616, U.S.A.
- @ Spex Industries Inc., Metuchen, N.J., 08840, U.S.A.



Table 3.1: Instrument parameters

Vacuum conditions:			
Electrostatic analyser	10-6 Pa		
Magnetic analyser	10-7 Pa		
Ion source (when sparking)	10-* Pa		
Photoplate lock	10-3 Pa		
Slit settings:			
Object slit width	10 – 20 µm		
Analyser entrance slit width	0,6 mm		
Energy-defining slit width	0,8 mm		
Potentials:			
Ignition spark voltage	32 kV		
Low d.c. discharge voltage	850 V		
Electrostatic analyser voltage	± 750 V		
Accelerating voltage	± 20 kV		
Magnet settings:			
Magnetic field	14 000 Gauss		
Magnet current	4,6 A		
Mass range covered	5 - 165 Daltons		
Spark parameters:			
Low voltage discharge current	2 – 4 A		
Spark pulse duration	20 µsec		
Spark pulse repetition frequency	30 Hz		
Ignition voltage intensity	Medium (No 2 setting)		



It is imperative to wait until the desired vacuum has been reached in the various sections of the mass spectrometer before starting with the analysis. Poor vacuum conditions could cause short circuiting in the ion source region and vacuum banding across the photoplate in the magnetic analyser region.

The various slit width settings of the mass spectrometer were unchanged throughout the investigation. The ignition spark and low d.c. discharge voltages were also kept constant. These two potentials are set and fixed in the pulse statistics unit. The electrostatic analyser voltage could be changed with a 2 - 3 volt tolerance, but the positive and negative voltages were kept in perfect balance so as not to deflect the ion beam passing through the two slits. The accelerating voltage could also be changed with a small tolerance as it was used to direct the ion beam through two ion source slits in order to balance the ion beam monitors.

The magnet settings of the mass spectrometer were kept constant throughout an experiment to ensure that the various exposure spectral lines were directly aligned beneath each other on the photographic plate. Adjustments can be made on the microdensitometer to correct skewness which results from slight misalignment of the photoplate mounting in the detection compartment.

Most of the spark parameters, as set out in Table 3.1, were kept constant. The spark pulse duration was fixed in the pulse statistics unit, whereas the other settings could be set externally. Whenever very short exposures were required, especially for samples with high concentration levels of impurity elements, use was made of beam chopping whereby only certain portions of the ion beam were allowed through the lenses, making it easy to capture short exposures on the photoplate. The low-voltage discharge



current was constantly changed in order to maintain the ion beam. This parameter has a direct influence on the ionisation that is taking place within the plasma generated in the ion source.

The polarity configuration of the two electrodes mounted in the ion source depends on the type of sample. The ion current differs from a metal sample to a powder sample. In order to achieve the optimum ion current the polarity must be changed to suit the sample type.

Possibly the single most important setting that must be constantly adjusted throughout an analysis is the spark gap between the two electrodes. The position of the two electrodes relative to the aperture of the ion source is also very critical. The positioning of the two electrodes during sparking is directly related to the ion current monitored. This spark gap must be kept constant throughout the analysis by repeated resetting of the gap as the electrode material is being depleted.

3.1.4 Exposure pattern selection

The exposure pattern to be used to analyse a sample depends on concentration range of impurity elements present. The ion the beam is recorded as a charge which is measured in picoCoulombs For unknown samples, a standard exposure pattern is (pC). However, for samples which have very high concenimplemented. tration levels of impurity elements, very short exposures must be selected to be able to obtain a workable transmission curve. Similarly, for samples that have very low concentration levels of impurity elements, very long exposures are needed to detect these low concentrations. The exposure pattern is based on a natural logarithmic scale due to the large range of the exposures (one to 20 000 pC). Three exposure patterns were compiled to cater for © University of Pretoria



the range of graphite standards prepared. These standards and preparation methods are discussed on pages 26, 103 and 122. The U_3O_8 sample used for the acquisition of the blank data required a very long exposure pattern.

There are normally 32 positions which can be utilized on a photographic plate. The analysis time is totally dependent on the exposure pattern selected. For an exposure pattern of up to 20 000 pC, the average analysis time is of the order of two hours, depending on the spark parameters. However, replacing short exposures by long exposures, to ensure detection of very low concentrations, increased the analysis time up to seven hours using the same ion current and sparking parameters. Exposure patterns should be chosen in relation with the lifetimes of electrodes.

3.1.5 Detection

Ion-sensitive photographic plates Ilford^{*} Q plates, are used in the photographic detection system [10].

Silver bromide (AgBr) crystals embedded in a gelatine matrix, which is the emulsion layer covering the glass plate, are reduced to metallic silver (Ag) during the development stage. This takes place on the photoplate only where ions from impurity elements in the sample have fallen, forming clusters of silver atoms, called latent image centres. During the fixation stage, the remainder of the AgBr crystals are removed, leaving only the characteristic spectral lines on the emulsion with varying degrees of blackening, according to the exposure pattern and concentration of impurity element ions. The developing procedure for these Q plates is a standard method [7]. Whenever a photoplate

* Ilford Limited, 14 - 22 Tottenham Str, London, W1POAH England.



has to be developed, it is a cardinal rule that fresh solutions of developer and fixer must be used. This is necessary to eliminate the possibility of under-developing the photoplate and also to remove all of the residual silver halide crystals so as to have a clear background transmission of light on the photoplate. A hardener is also added when rinsing the photoplate off, to aid image formation.

Hereafter, the photoplate is placed in a specially designed water tower with running demineralised water for half an hour. This step ensures that no fixing agents remain on the photoplate which, with time and light, darkens the background emulsion. Α wetting agent is finally added which aids rapid and uniform drying. The glass side of the photoplate is then dried off and the photoplate placed in a specially designed dust-free black box where the emulsion is allowed to dry before the photoplate is inspected under the microscope. It is very important to follow the standard developing procedure so as to minimise differences in photoplate data due to differences in the photographic development procedure. The sensitivity of the photoplates in a particular batch is very similar. Slight variations do not influence the results as an internal reference standard normalises the data.

3.2 Preparation of Standards

3.2.1 Reagents

The reagents used to prepare the standards consist of two parts, namely the graphite powder and the solution containing the impurity elements of known concentration.

Various graphite powders were evaluated for this application. The most important consideration was the number of and



concentration levels of impurity elements present. Graphite powder with the least background spectral lines should be selected to act as conducting medium in the spark-source mass spectro-Another prerequisite was that the powder should be meter. wettable and pelletable, wettable in the sense that it would be able to adsorb drops of the standard solution and pelletable in the sense that electrodes could be pressed from the graphite Ringsdorff * spectrographic powder, Grade RW-A, has very powder. good pelletability, but is not very compatible with an aqueous Another graphite powder tested was a French spectrosolution. graphic carbon Ref 9900-208-17 387, from Le Carbone[#], which was also not wettable. The only two graphite powders suitable were a spectroscopic powder from Union Carbide Corporation[@] (UCAR). Grade SP-1, Lot Number B92, Catalogue No. L 4100. and an Ultra 'F' purity electrode graphite from Ultra Carbon Corporation $^{\diamond}$, Material UCP-1-200 powder, Lot Number 112-6-37. The Ultra 'F' graphite formed pellets (electrodes) which produced a better ion signal and had a cleaner background spectrum than UCAR SP-1 graphite, although it was slightly more difficult to wet. Both. however, were most suitable graphite powders to use in preparing standards.

The choice of impurity elements in U_3O_8 matrix was limited to those listed for nuclear grade specification for trace impurities

- * Ringsdorff Werke, GmbH, Bad Godesberg Mehlem.
- # Le Carbone, Lorraine, Paris, France.
- @ Union Carbide Corporation, Carbon Products Division, New York, N.Y., 10017, U.S.A.
- \$ Ultra Carbon Corporation, P.O. Box 747, Bay City, Michigan, 48706, U.S.A.



in uranium reactor fuels. The choice of impurity elements in a UF₄/graphite matrix is discussed on page 81. Impurity elements whose isotopes interfered with other element isotopes in such a way that they could not be measured, could not be evaluated using this method.

It was possible to obtain $Spex^*$ custom plasma standard solutions with concentrations of either 1 000 or 10 000 µg/ml for most of the selected impurity elements which are used in inductively coupled plasma (ICP) optical emission spectroscopy. These standards are referred to as "ICP standards" in the text below. It has been shown that the relative sensitivity factor for an impurity element is the same irrespective of a nitrate or oxide matrix [11]. Appropriate volumes of the standard solutions were added together to form a solution containing all the impurity elements, which was subsequently added to the graphite powder to prepare standards.

A set of Spex diluted powder standards, denoted G-7, containing 49 common elements over seven concentration ranges using In as internal standard, were also analysed with base U_3O_8 material which contained very low levels of impurities (see Table 5.1 on page 106). These standards were found unsuitable for a number of reasons, of which the most important is their inhomogeneity. The concentration of the internal standard, In, is also too high for spark-source mass spectrometry applications. The powder does not form suitable electrodes when pelleted.

* Spex Industries Inc., Metuchen, N.J., 08840, U.S.A.



3.2.2 Preparation of standards in a graphite matrix

The desired volume of a specific ICP standard was chosen depending on the final concentration and the total mass of graphite standard required. The approach is demonstrated by the following example:

- Final concentration of graphite standard for element X relative to uranium: 10 μg X /gU.
- Concentration expressed relative to graphite: 40 μg X /gC (ratio of U to graphite is 4:1).
- Total mass of graphite standard required: 5 grams.
- Concentration then becomes: 200 µg X /5gC.
- Concentration of ICP standard: 1 000 μg X /m1.
- Expressed in microlitres : 1 000 μg X /1 000 μ1.
- By extracting 200 μ1 from the ICP standard, the required concentration of 200 μg X /5gC is obtained.

The above procedure was adopted for each of the graphite standards prepared with the concentration range given on page 103 for U_3O_8 , and on page 122 for UF₄.

Approximately 1 ml of a 1 000 μ g/ml ICP standard for the various elements of interest was obtained in a clean pill vial. The necessary volume for each of the graphite standards was extracted from the pill vial using an appropriate Eppendorf^{*} Varipette and placed carefully in a clean 50 ml Erlenmeyer flask containing deionised water and methanol (which was used to break the surface tension of the resultant solution). The concentration levels of impurities in the methanol were very low. Pb and Sn are the only elements which could interfere with the spectrum interpretation (see page 51). This procedure was followed for each of the

 * Eppendorf Gerätebou, Netheler & Hinz, GmbH, Postfach 65 06 70, 2000 Hamburg 65, Germany.
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impurity elements, each time using a clean nib on the varipette.

Five grams of graphite powder was weighed off into a clean platinum crucible large enough to take the volume of graphite, using a clean stainless steel vibration spatula and a Mettler^{*} HlOT mass balance.

The wet doping technique was used to prepare the graphite stan-The standard solution is added to the graphite powder dards. using a clean dropper until the powder is uniformily wet. Great care must be exercised when doing the addition, so as not to get any of the solution against the sides of the platinum crucible. as this could result in selective crystallisation during drying. The crucible is then placed under a 250W infrared lamp for about 20 to 30 minutes to dry the powder before the next addition is In total 15 to 20 such additions of the standard solution made. are made to the graphite powder with repeated washing down of the flask sides with a 30% methanol solution to ensure complete transfer from the flask to the platinum crucible. A glass rod is used after each drying to break up any lumps or crust that may have formed in the graphite powder and to mix the powder, in Once the standard solution has order to promote homogeneity. been completely transferred to the graphite powder, it is then dried in a vacuum oven at 80°C for 48 hours. After cooling down, the graphite standard is carefully transferred from the platinum crucible to a pill vial and capped. During the evaporation stage under the infrared lamp, the crucible is covered with a large-enough watchglass so as to prevent contamination from dust.

Mettler Analytical and Precision Balances, CH-8606,
Greifensee - Zurich, Switzerland.



3.2.3 Internal Standard Method

The general method used to quantify an unknown sample is to use the same photoplate for both the sample and a relevant standard [12]. In this way one eliminates slight differences from one photoplate to the next, e.g. photoplate response, differences in development, etc. A deciding disadvantage of such a method, especially if the sample turnover is great, is that the standard material becomes depleted. The time it takes to analyse both sample and standard is also impractical, especially when pumpdown time is also taken into account. For these reasons, the use of an internal standard [13, 14] is far more desirable.

Yttrium (Y) was included in the preparation of graphite standards as an internal reference standard whereby differences between photoplates could be monitored.

The choice of Y as an internal standard was based on the following properties:

- it is an element which is not present as an impurity in nuclear fuels;
- both the 1+ and the 2+ spectral lines fall within the mass range of interest;
- Y is a mono-isotopic element having a mass-to-charge ratio of 89 in the singly charged state and 44,5 in the doubly charged state.

The general formula used to express a relative sensitivity factor (RSF), as shown by equation (3) on page 99, is reproduced to include Y as the internal standard (IS):



 $\frac{\frac{x}{Q_{y}^{-}}}{\frac{C_{y}}{C}}$ RSF = -

where:

 Q_y^- is the mean exposure value of Y for the charge states 1+ and 2+, C_y^- is the concentration of the internal standard Y added to the graphite standards, Q_x^- is the exposure value at 50% transmission of element X, and C_x^- is the concentration of an element X.

It can be shown, statistically, that it is advantageous to use the mean exposure value of two charge states, Q_y^- , when expressing an impurity element's exposure value relative to the internal standard, Y.

The internal standard is also used as a control for photoplate evaluation and possible rejection by using the ratio between singly and doubly charged species as well as the mean exposure value between singly and doubly charged species, Q_y^- . It has been found for Y in a U_3O_8 /graphite matrix that the Y⁺/Y²⁺ ratio lies between 3 and 4, with an average of 3,56 determined over 30 photoplates (n = 30). For a UF₄/graphite matrix the Y⁺/Y²⁺ ratio lies between 1 and 2, with an average of 1,57 determined over 46 photoplates (n = 46). The mean exposure value, Q_y^- , for Y in a U_3O_8 /graphite matrix can be coupled to the Y concentration in the following manner:



 μg Y /gC : $Q_{y}^{-} = 4$ 895 where n = 31 μg Y /gC : $Q_{y}^{-} = 7$ 098 where n = 14 μg Y /gC : $Q_{y}^{-} = 9$ 384 where n = 12 μg Y /gC : $Q_{v}^{-} = 20$ 066 where n = 37

The Q- value for Y in a UF_4 /graphite matrix is $Q_- = 1$ 386, determined over 46 photoplates, and the Y concentration 100 μ g Y/gC.

These values of Y^*/Y^{2*} ratio and $Q_{\overline{y}}$, for both U_3O_8 and UF_4 matrices, have been determined over a period of 10 months as the value of n indicates, and can be used to control the quality of analyses. Possible reasons for photoplate rejection are that the photoplate has not been developed properly, or that the sparking conditions used to analyse the sample are inadequate, or general instrument problems. This quality assurance approach is a new contribution to the methodology of spark-source mass spectrometry.

3.3 Sample preparation: dilution ratio's

Uranium compounds such as U_3O_8 and UF_4 are electrically non-conducting. For spark-source mass spectrometry analysis these have to be mixed with a conducting medium such as graphite or silver. The ratio between the conducting medium and the uranium compound determines the yield of impurity element ions. The mixing ratio depends on the conductance of the sample and is not subject to any generally applicable ruling.



Tests were conducted using different mixing ratios of Merck^{*} nuclear grade U_3O_8 , LAB 6344513, and graphite powder, as well as for a stoichiometric UF₄ sample and graphite powder. The number of mass spectral lines on the photoplate, using the appearance level method, was counted for the same element isotopes and charge states using different dilution ratios of sample to graphite. This method is based on the number of spectral lines which can be observed on a photoplate according to a specific exposure pattern for a particular impurity element, and is discussed on page 132.

For UF_4 , it was found that a ratio of 1:1 between UF_4 and graphite by mass, yielded the most lines for the majority of the elements selected. Ratios up to 5:1 for UF_4 and graphite by mass were also analysed, yielding fewer lines for certain elements.

For U_3O_8 it was found that a ratio of 5:1 between U_3O_8 and graphite, by mass, yielded the most lines for most of the elements selected. Ratios from 1:1 for U_3O_8 and graphite, by mass, were also analysed. These ratios yielded fewer lines for all of the elements. The ratio of 4:1 for U_3O_8 and graphite by mass yielded for certain elements more lines than for a ratio of 5:1. The ratio of 5:1 between U_3O_8 and graphite implies a ratio of 4:1 between uranium (U) and graphite by mass as there is approximate-ly 85% U in U_3O_8 . When preparing electrodes with U_3O_8 and graphite the ratio of 5:1 by mass was used.

The different optimum dilution ratios between U_3O_8 and UF_4 can be ascribed to the fact that these compounds have different matrices resulting in different plasma conditions.

* E Merck, Frankfurter Strasse 250, D-6100 Darmstadt 1, Federal Republic of Germany.



3.4 Data acquisition and processing

3.4.1 <u>Microdensitometer</u>

Once mass spectral lines have been identified on the photoplate as being solely representative of a particular impurity element in the sample, data capture is performed using a computer-controlled microdensitometer^{*}, Model MD 100 [15]. Operating procedures are fully documented [16]. Data acquisition is performed using a Zenith[#] Data Systems microprocessor with dual auxiliary floppy disk drives, colour monitor and an OKI[®] Microline 292 printer.

The microdensitometer settings are as follows:

Slit	width	15	μm
Slit	height	1,0	mm
Scanr	ning speed	1,0	mm/sec

These settings are fixed from the outset and are determined by the characteristics of the spectral lines on the photoplate with regard to width and height.

- * VEB Carl Zeiss JENA, DDR.
- # Fabriqué Par, Zenith Radio Corp., Springfield, Missouri, 65801, U.S.A.
- @ OKI Electric Industry Co. Ltd., Tokyo, Japan.



The basic function of the microdensitometer is to measure the percentage light from a photocell that passes through the mass spectral line on the photoplate. The 100% setting is done using two clear plate regions at the low and high mass ends of the photoplate. It is thus imperative that all the emulsion is removed from these two regions. Transmission curves are drawn up from these transmission values used on the mass spectrometer. A limiting factor with the standard microdensitometer software is that the data manipulation matrix is dependent on the number of exposures utilised and the number of spectral lines to measure. The large number of impurity elements in a U_3O_8 / graphite matrix, and the fact that some elements were measured both in the singly and the doubly charged state, created the need to compile two matrices.

The most time consuming exercise is the preliminary setting up of the microdensitometer. This includes photoplate alignment on the carriage, obtaining relevant spectral line co-ordinates and the setting of windows around doublets and triplets. The last task is of utmost importance, especially for elements that occur only as doublets or triplets. This is discussed on page 45 for magnesium in a U_3O_8 /graphite matrix.

The actual data acquisition is done rapidly, with the x- and y-motor drives activated under computer control. After each scan, the analyst must ensure that the y-motor has moved the carriage accurately from the preceding spectral line to the next and that the slit is correctly positioned over the spectral line on the photoplate. In this way, all the exposure spectral lines are scanned for the composition of a transmission curve.



The background noise correction transmission value is of extreme importance, especially for very light spectral lines. This value is subtracted from the emulsion background transmission which is measured on either side adjacent to the relevant spectral line of interest. If this background noise correction value is too high, it will result in the corrected emulsion background value being lower than the actual spectral line transmission value. This exposure point will then be rejected from the transmission curve.

Various factors affect the background noise correction value, amongst others, dust on the photoplate and ordinary electronic noise. The electronic units have to be kept well ventilated because if the analogue-to-digital converter gets warm, the background noise correction value becomes too large to work with. Ideally, this value should fall between 2 - 4%.

The data acquired is stored on floppy disk for further reduction and interpretation.

3.4.2 Linearisation functions

A second microcomputer and data processing software [7] are used for the data reduction and interpretation. The analyst is required to quantitatively determine the composition of the sample from the blackening of the mass spectral lines on the photographic plate. Plate blackening, which is measured by the light transmission through the emulsion, is not linearly related to the number of ions striking the emulsion. The plot of plate blackening against the natural logarithm of the number of ions striking the emulsion is an S-shaped curve dependent upon exposure conditions, ion momentum and plate development technique and is called the emulsion response curve or transmission curve.



The transmission curve is first investigated for possible outliers. Ideally, the curve should have a shape as in Figure 3.1 where there are a few saturated points as well as a few light points. The correct exposure pattern selected will ensure that such a transmission curve is obtained.



Figure 3.1: Typical good quality transmission curve

Transmission curves were linearised using the Hull function [8, 17]. Other functions that can also be used are the Seidel and Wagner functions [7]. However, these are more applicable to special applications and were not employed for this investigation. Although the semi-empirically derived Hull formula is not universally suitable for treatment of all data, it represents an approach which is adequate, provided that the exposure range is appropriate to the concentration of the particular element under investigation. For the Hull function plot, a gradient after



linearisation of between 0,7 and 1,7 is acceptable. Points far outside the effective range for the Hull function were removed. Transmission values between 10 and 75% best fitted the Hull function, providing straight lines having correlation coefficients near unity. This is best illustrated in Figure 3.2. The final choice of acceptable data points for the Hull function plot depends on the assessment of the analyst and is based on experience rather than on any firm statistical approach.



Figure 3.2: Typical Hull function plot

When quantifying, the intercept at a 50% transmission of the transmission curve gives an exposure value which is coupled to the concentration of that particular impurity element. Thus, the exposure value of an element, X, expressed as Q_X , at 50% transmission on the Hull function plot, is used as the intercept from which the concentration of element X is determined.



Natural logarithms are determined for the exposure values of element X and the internal standard, Y. A ratio of Q_x/Q_y^- is then calculated and used for calibration graphs to determine relative sensitivity factors (RSF's) [18]. (See pages 29 and 98).

Once relative sensitivity factors have been determined, these are stored in the software. The standard data reduction and interpretation software has been updated in this laboratory to perform the necessary calculations to determine concentrations using the relevant RSF's, exposure ratios and the internal standard concentration.


CHAPTER FOUR

QUALITATIVE SPECTRUM INTERPRETATION

4.1 U₃O₈/graphite matrix characteristics

4.1.1 General principles

Once a spectrum has been recorded on a photographic plate, each spectral line must be assigned a nominal mass. Thereafter, the lines must be related to the elements present in the sample as impurities.

The first step in assigning nominal mass values to the spectral lines is to identify the major elements. In the case of the U_3O_6 /graphite matrix, majors are uranium, oxygen and carbon. A knowledge of the fingerprint spectrum of uranium is required, and is listed in Table 4.1.

Table fill habb byccclum of dianta	<i>Table</i>	4.1:	Mass	spectrum	of	uranium
------------------------------------	--------------	------	------	----------	----	---------

Charge state	Isotope	m/e	Charge state	Isotope	m/e
1+	238 235 234	238,00 235,00 234,00	4+	238 235 234	59,50 58,75 58,50
2+	238 235 234	119,00 117,50 117,00	5+	238 235 234	47,60 47,00 46,80
3+	238 235 234	79,33 78,33 78,00	6+	238 235 234	39,67 39,17 39,00



By examining the plate through a microscope, two distinct sets of spectral lines are observed in the upper half of the plate. These are distinguished as "A" and "B" in Figure 4.1. The major line of each set is due to the 238-isotope of uranium. The magnet range must be known in order to ascertain what charge state to relate to each set. In the case of Figure 4.1, the magnet range is from mass 10 to 165. Thus, from the data in Table 4.1, "A" can be assigned the mass 79,33 and "B" the mass 119,00.

At the lower end of the photoplate, a major line with dispersion due to over-saturation is noted. This line "C" is due to carbon, another major component, with mass 12. The line "D" in Figure 4.1 is due to oxygen, another major element, with mass 16.

The line marked "E" is due to the formation of the carbon dimer ${}^{12}C_2^+$ with mass 24. The line marked "F" in Figure 4.1 is due to the formation of ${}^{12}C^{16}O^+$, the major isotopes of both carbon and oxygen, which are main components. The formation of such a species is not uncommon for a $U_3O_8/graphite$ matrix.

Once the main elements have been identified on the photoplate and nominal masses assigned to these spectral lines, these are used as markers to calibrate the rest of the data simply by filling the masses in between. It is noted that the distance between two masses at the lower end of the photoplate is larger than that obtained between two masses at the upper end. This is due to the fact that the position of a spectral line relative to any arbitrary figure is proportional to the square root of the mass-tocharge ratio, m/e [19].

A fundamental principle in the identification of spectral lines on a photoplate is to eliminate the possibility of interference



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Figure 4.1: Photoplate spectrum of a U₃O₈/graphite matrix

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from other elements [19]. The photoplate must be thoroughly examined so as to gain an overall impression as to which elements are present in the sample. Each element is then identified in terms of its isotopes and charge states. To positively confirm if an element is present, it must be possible to assign spectral lines on the photoplate to the elements' isotopes, as well as the various charge states. Doublets and triplets on the photoplate can be resolved on the basis of mass-defect data.

The mass defect in milli-mass units (mmu) is defined as the difference between the accurate mass and the mass number or nominal mass of an isotope. Mass-defect values for all the isotopes of the elements are relative to carbon 12 having a mass defect of zero.

Bearing in mind that the ultimate purpose is to measure the transmission of spectral lines for the quantitative determination of the elements present, it is imperative to ascertain that a spectral line is totally representative of that particular element's concentration. The importance to rule out any interference from other elements cannot be over-emphasised.

The plasma generated in the ion source is such that primarily elemental ions are formed in the U_3O_8 /graphite matrix. The formation of molecular species can largely be avoided. This simplifies matters as far as the spectrum is concerned.

The plasma temperature must be of such a magnitude so as to prevent the formation of oxide species of the various impurity elements. When the spectrum becomes more complicated as in the



case where 34 elements are present in the U_3O_{θ} /graphite matrix, special care must be taken when assigning spectral lines with elemental names, eliminating all possibilities of interferences.

4.1.2 <u>Selection of elements</u>

Thirty four elements were selected from nuclear fuel specifications and are listed in Table 4.2 (see page 75). These were added to graphite powder in various ranges of concentration. The method followed for the preparation of the standards is discussed in Chapter 3 on page 26. The procedure to ascertain, firstly, whether each of these elements is present on the photoplate and, secondly, at what mass line to measure the elements present quantitatively is discussed in the following paragraphs.

4.1.3 <u>Boron (B)</u>

Box	ron	Isotopes		
Maaa	1+	10	11	
Mass	2+	5	5,5	
Abundance (%	()	19,65	80,35	
Mass defect (mmu)		+12,9	+9,3	

B is positively identified at masses 10 and 11. These lines should also occur in the correct natural isotopic abundance ratios. Lines at masses 5 and 5,5 are unique to the doubly charged species of B. However, these lines are at the low-mass end of the spectrum and are not readily observed. The mass range is determined by the magnetic-field strength (H) and is selected so as to record a practical range on the photoplate.



Possible interferences at mass 10 could be the hydride species of beryllium 9 ('BeH'), the doubly charged gaseous neon 20 (''Ne'') species or the triply charged silicon 30 (''Si'') of small isotopic abundance (3,09%). If the concentration level of Ca is very high in the sample, the multiply charged 4+ ion of the major isotope *°Ca can be detected at mass 10. However, each of these interferences appears as a doublet or triplet at mass 10, which can be resolved using the mass defect differences in milli-mass units.

Interferences at mass 11 could be the hydride species of ${}^{10}B$, the doubly charged gaseous Ne 22 species (${}^{22}Ne^{2+}$), the triply charged sulphur 33 (${}^{33}S^{3+}$) of low isotopic abundance, as well as the multiply charged 4+ ion of ${}^{44}Ca$. The mass defect of ${}^{11}B$ and these interferences are sufficient to resolve any doublets or triplets at mass 11. ${}^{11}B$ is the major isotope. The only interference of importance is the possibility that the background percentage transmission of light for the longer exposures of ${}^{11}B$ could be affected by the clouding around the longest exposures of the major component, ${}^{12}C$, at mass 12. This is clearly manifested in Figure 4.1 at "C". To quantify B, mass 11 is the most suitable line to use.

4.1.4 <u>Sodium (Na)</u>

Sodi	um	Isotopes
Mass	1+	23
	2+	11,5
Abundance (%)		100
Mass defect (mmu)		-10,2



Na is very similar to K in that the element does not readily form multiply charged species. This is probably due to the fact that Na has only one valence electron to lose in its 3s orbital to reach the noble gas structure. Being mono-isotopic also has its disadvantages in that there is no way in which to positively identify the presence of Na other than the line at mass 23. Possible interferences could be the heterogeneous species ''B''2C or the *****⁶Ca doubly charged isotope which has a low isotopic abundance (0,0037%). The most likely interference at mass 23 is the doubly charged isotope of titanium 46 (*'Ti'). The presence of this isotope of Ti can be verified by the presence of a line at mass 23,5 due to the 4'Ti' ion of similar isotopic abundance. However, this doublet can be resolved using the mass-defect value.

4.1.5 <u>Magnesium (Mg)</u>

Magne	Isotopes			
Mass	1+	24 25		26
	2+	12	12,5	13
Abundance (%)		78,84	10,08	11,09
Mass defect (mmu)		-15,0	-14,2	-17,4

The only way to positively establish whether Mg is present as an impurity is the presence of a line at mass 12,5. This line is due to the doubly charged ion of ²⁵Mg and is unique for this isotope of Mg.

Figure 4.2 represents the typical spectral lines obtained on a photoplate with Al and Mg present as impurities in a U_3O_8/gra -phite matrix.





<u>Figure 4.2</u>: Triplet spectral lines where Mg and Al are, amongst others, present in a U_3O_8 /graphite matrix (m/e 27 staggered to show overlapping).

All four spectral lines are triplets. The intensity of the blackening, which relates to the isotopic abundance of the various elemental isotopes, has also been shown. Using the reference table in Appendix B at page 180, the triplets can be resolved using the mass-defect values.

At mass 26, the light central line is due to ^{26}Mg , an isotope of small abundance. The dark left-hand line is due to the major isotope of Cr, namely $^{52}Cr^{2+}$, and the dark right-hand line could be either the hydride species of the ^{25}Mg isotope, the dimer $^{13}C_2$, or the hydrocarbon, $^{12}C_2H_2$.

At mass 25, the darker central line is due to the ²⁵Mg isotope of abundance similar to ²⁶Mg. The light left-hand line is due to the ⁵⁰Cr²⁺ isotope of small abundance (4,38%). There are three possibilities for the darkest right-hand line: it could be the hydride species of the major isotope of Mg, namely ²⁴MgH (a strong possibility), or the C dimer ¹²C¹³C, or the hydrocarbon ¹²C₂H.



A very strong triplet appears at mass 24. There are a number of species which could give rise to this line. The most noteworthy would be the dimer of ${}^{12}C$, the isotope of highest abundance, and the fact that C is one of the main components of the sample. The formation of C clusters is well known [20]. Other species are the doubly charged main isotope of *0 Ti, the main isotope of singly charged ${}^{2*}Mg$, or the doubly charged low abundance isotope of ${}^{*0}Ca$. When resolving this triplet, the central line is due to ${}^{2*}Mg$, the left-hand line due to the C dimer and the right-hand line due to *0 Ti²⁺.

All three isotopes of Mg appear as the central lines of the triplets at masses 24, 25 and 26. Because we are unable to measure the background transmission next to these lines of Mg, it is impossible to measure Mg in the singly charged state.

The close proximity of the ²⁵Mg²⁺ line at mass 12,5 to the line of the main component, C, at mass 12, makes the measurement of Mg unreliable because of fogging of the plate at long exposures. This affects the background transmission readings for ²⁵Mg²⁺ at mass 12,5.

4.1.6 Aluminium (A1)

Aluminium		Isotopes
Mass	1+	27
	2+	13,5
Abundance (%)		100
Mass defect (mmu)		-18,5



Similar to Mg, the only way to positively identify A1 as an impurity in the sample is the presence of a spectral line at mass 13,5. This line is due to the doubly charged ion of the mono-isotopic '7A1. In Figure 4.2 the spectral line m/e 27 represents '7A1 in the singly charged state. The dark central line is due to A1, the lighter left-hand line overlapping the A1 line is due to a combination of $5 \cdot Fe^{2+}$ and $5 \cdot Cr^{2+}$, each isotope of low abundance. The lighter right-hand line is due to the hydride species of 26 Mg or the formation of the hydrocarbon $1^{2}C_{2}H_{3}$. In this instance, it will be impossible to measure the central A1 line because of interference from $5 \cdot Fe^{2+}$ and $5 \cdot Cr^{2+}$, as well as the fact that the microdensitometer requires a clear region on either side of a spectral line in order to measure background transmission values.

The only way to measure the mono-isotopic Al would be at its doubly charged species at mass 13,5.

Silicon		Isotopes			
Mass	1+	28	29	30	
	2+	14	14,5	15	
Abundance (%)		92,23	4,68	3,09	
Mass defect (mmu)		-23,1	-23,5	-26,2	

4	ι.	1	7	Silicon	(Si)

The presence of Si is indicated by a line at mass 14,5 due to the ²⁹Si²⁺ isotope. This line is unique to Si only if the Ni concentration in the sample is very small. The multiply



charged 4+ isotope of ⁵Ni interferes with the ²Si²⁺ line at mass 14,5. The difference in mass defect of these elements is so small that the two lines cannot be resolved.

At mass 28 on the photoplate a triplet is observed. Each of these lines can be resolved. The left-hand line is due to the doubly charged species of ⁵⁶Fe, which is the major isotope of Fe. The central line is due to the singly charged species of '*Si, also the major isotope of Si. The right-hand line is somewhat lighter than the adjacent two lines. Two possible species could give rise to this line. The hydride species of the mono-isotopic 'Al ion is the more probable, although the monoxide species of '2C should not be discounted as C and O are both major components in the sample.

At mass 29 a weak triplet is observed. The left-hand line is much darker than the other two lines. This line is due to the doubly charged species of ⁵ Ni, which is the major isotope of Ni. The central line is the singly charged isotope of ² Si, with small isotopic abundance. The right-hand line is probably due to the hydride species of the major isotope of ² Si, although various other species contribute to this line, such as ¹³CO and ¹²CHO.

The possibility of quantitatively measuring Si in the singly charged state arises at mass 30, where a doublet is observed. These two lines can be resolved. The left-hand line is due to two species, namely the doubly charged species of $^{\circ}$ Ni, having an isotopic abundance of 26,78%, and the triply charged species 9 Cr³⁺, which is from the major isotope of Zr. The difference in mass defect of these two elements is so small that these two lines making up the left-hand line cannot be resolved. The right-hand line of the doublet is due to the singly charged species of 3 Si. It has been observed at times that a third



line at mass 30 appears on the upper side of the ³°Si line, especially noticeable at very long exposures. This line could be the formation of a number of species involving C, O and H, for example ${}^{12}C^{18}O^{+}$, or the hydride species ${}^{29}Si$ (see reference table in Appendix B at page 180).

In order to measure the ³°Si line the area to the right of this line must be free of any interfering lines in order to be able to take background transmission readings. The third line does not hinder the measuring of the ³°Si line as it is present only at the very long exposures where the line transmission of the ³°Si line is in any case saturated. As the exposures get shorter, this third line fades out completely, hence enabling the measurement of the ³°Si line.

4.1.8 Phosphorus (P)

Phosphorus		Isotopes
Maaa	1+	31
Mass	2+	15,5
Abundance (%)		100
Mass defect (mmu)		-26,2

A line at mass 15,5 is unique to the doubly charged species of mono-isotopic ³¹P. The singly charged species of P at mass 31 can be identified by a very dark line at long exposures. A doublet is observed, where the left-hand line is due to ³¹P. The right-hand line, which is very low in intensity, is due to



the hydride species of ³°Si. However, this line fades out as the exposures become shorter, as is the case at mass 30 with Si. The only possible interference with the ³1P line could be from the triply charged species of the mono-isotopic Nb (⁹3Nb³⁺). The concentration of Nb in the sample would, however, have to be very high in order to interfere with the ³1P line. Before measuring the line at mass 31 for P, the presence of Nb must first be positively identified.

4.1.9 <u>Calcium (Ca)</u>

Calciu	1111	Isotopes					
Maga	1+	40	42	43	44	46	48
nass	2+	20	21	21,5	22	23	24
Abundance (%)		96,94	0,65	0,14	2,08	0,0037	0,181
Mass defect (mmu)		-37,4	-41,4	-41,2	-44,5	-46,3	-47,6

There is no unique line for Ca on the photoplate. The only significant isotopes of Ca are at masses 40 and 44. The isotopic abundances of these isotopes are high enough, 96,94% and 2,08% respectively, to be used to identify the presence of Ca. However, interferences from other elements present in the sample hinder the measuring of these lines.

A triplet appears at mass 40. The left-hand line is the darkest in intensity and is due to the singly charged species of ⁴°Ca, the isotope with the highest abundance. This line is not unique to Ca, especially if K is also present in the sample. The line



of the singly charged *°K isotope overlaps with that of *°Ca to the extent that the two lines cannot be resolved using the massdefect values. The central weak line is due to the formation of two possible species. Pb and Sn are added to the standards as impurity elements originating from the reagents used to prepare the standards. The triply charged species of the 120Sn isotope, which is also the isotope of highest abundance, is one of the possible species. The other is the hydride of 39K, which is also the isotope of the highest abundance. The right-hand line could be due to the formation of quite a few species, of which the main possibilities are 2°Si12C, 24Mg16O, 27A113C and 12C, 160. The presence of these species is verified by the fact that they are all present in the sample as impurities and that they are the major isotopes of these elements.

At mass 44 a strong doublet is observed. The intensity of the two lines is an indication that other elements are present. The left-hand line is due to two species, namely Sr and Ca. The line of the doubly charged ^{\$e}Sr isotope, which has the highest abundance, overlaps with that of ⁴⁴Ca to the extent that the two lines cannot be resolved. The right-hand line could be due to the formation of the monoxide species of ²⁸Si. However, the more likely species is ¹²CO₂, a matrix-derived component of the sample. It is thus not possible to measure Ca in the singly charged state.

When considering the doubly charged state of Ca, the only isotope of importance is the major isotope, ⁴°Ca. The minor isotopes of Ca have such low abundances that they can be ignored in the doubly charged state. The line at mass 20 is due to the doubly charged species of ⁴°Ca only if the concentration of Ni in the sample is relatively low. The triply charged species of ⁶°Ni, having an isotopic abundance of 26,78%, could interfere



with the line obtained from *°Ca²⁺. This interference can be verified by the presence of a line at mass 19,33 which is due to the triply charged ⁵ Ni, the major isotope of Ni (67,18%). If there is no line present at mass 19,33 it can be assumed with certainty that there is no interference at mass 20 by ⁶ Ni³⁺. Ca can hence be measured using the line at mass 20.

4.1.10 <u>Potassium (K)</u>

Potass	sium	Isotopes			
Magg	1+	39	40	41	
nass	2+	19,5	20	20,5	
Abundance (%)		93,26	0,012	6,73	
Mass defect (mmu)		-36,3	-36,0	-38,2	

K is very similar to Na in that the element does not readily form multiply charged ions. The line obtained at mass 19,5 is very light in intensity and is unique to the doubly charged ³, the major isotope of K (93,26%). This line serves as a positive identification of K in the sample.

At mass 39 a doublet is present. The left-hand line, which is dark in intensity, is due to the singly charged species of $3^{9}K$, also the isotope of highest abundance. However, the presence of Sn as an impurity interferes with this line due to the triply charged species of $11^{7}Sn$. The two lines cannot be resolved. The right-hand line is possibly due to the C cluster $13C_{3}$ or,



if the concentration of the mono-isotopic Na and Al is very high in the sample, the formation of 27Al12C and 23Na16O species.

A poorly resolved triplet appears at mass 41. The left-hand line is due to the singly charged ⁴¹K isotope with an isotopic abundance of 6,73%. The central line is the triply charged species ¹²³Sb³⁺ and the right-hand line is the hydride species of the major isotope of ⁴⁰Ca. It is thus necessary to exercise extreme care when measuring the left-hand line for K so as not to measure the central line.

Titan	Isotopes					
Mass	1+	46	47	48	49	50
	2+	23	23,5	24	24,5	25
Abundance (%)		7,99	7,42	73,63	5,56	5,40
Mass defect (mmu)		-47,4	-48,2	-52,1	-52,1	-55,2

4.1.11 <u>Titanium (Ti)</u>

Ti has several isotopes which overlap with those of Ca. However, their abundances are higher, thus making Ti easier to detect. Elements which hinder the measuring of Ti in the singly charged state are Zr, Mo and Ru. The presence of these elements makes it extremely difficult to measure Ti, as their doubly charged species interfere with the lines of Ti to such an extent that they cannot be resolved. The line of *6Ti has ⁹²Zr²⁺,



⁴⁶Ca⁺ and ⁹²Mo²⁺ as interferences. The line of ⁴⁷Ti has ⁹⁴Zr²⁺ and ⁹⁴Mo²⁺ as its main interferences.

At mass 48 a doublet occurs. The left-hand line is that of **Ti as well as of $96Mo^{2+}$, $48Ca^+$, $96Ru^{2+}$ and $96Zr^{2+}$. The right-hand line is due to the possible formation of two cluster ions, namely $12C_4$ and $24Mg_2$. 49Ti has $98Mo^{2+}$, $98Ru^{2+}$ and the hydride species of 48Ti as interferences. Similarly, the line of 50Ti has $50Cr^+$, $50V^+$, $100Ru^{2+}$ and $100Mo^{2+}$ as interferences.

The only way to positively identify the presence of Ti in the sample is to look for lines of the doubly charged species. Two isotopes of Ti, namely "Ti and "Ti, have lines at masses 23,5 and 24,5 respectively, which are unique to Ti. The only element which could possibly interfere with the line of "Ti at mass 23,5 is the multiply charged species of "Zr4". However, the probability of such an ion forming can be tested by looking for a line at mass 22,5, due to the multiply charged species of "Zr4", the major isotope of Zr. If no line is detected at mass 22,5, then the possibility of "Zr4" interfering at mass 23,5 is negligible. Thus, Ti can be quantitatively measured at either of these lines.

4.1.12 Vanadium (V)

Vanac	lium	Isotopes		
Maaa	1+	50	51	
Mass	2+	25	25,5	
Abundance	e (%)	0,26	99,74	
Mass defe	ect (mmu)	-52,8	-56,0	



V is positively identified by a line at mass 25,5 due to the doubly charged species of the major isotope of V, namely 51. The singly charged ion of V appears as a doublet at mass 51. The high intensity of the left-hand line is due to the ⁵¹V isotope. The light right-hand line is that of the doubly charged 10^2Ru^{2+} isotope. These two lines are only just resolved, thus care must be exercised when measuring the transmission of the V line so that no overlapping occurs.

4.1.13 Chromium (Cr)

Chromium		Isotopes				
Mass	1+	50	52	53	54	
	2+	25	26	26,5	27	
Abundance (%)		4,38	83,70	9,51	2,41	
Mass defect (mmu)		-53,9	-59,5	-59,3	-61,1	

Isotopes of Cr at masses 52 and 53 are used to identify and quantify Cr in the sample. The other two isotopes have interferences from Ti, V and Fe. The doubly charged species of 53 Cr at mass 26,5 is used to positively identify Cr as no interferences are present at this line. At mass 52 a clearly resolved doublet is present. The dark left-hand line is due to the major isotope of Cr, namely at mass 52. The light right-hand line could be the hydride species of 51 V or the doubly charged ion of 104 Ru. Various other species could also be formed in the plasma, but their influence is so small that they can be ignored (see reference table in Appendix B at page 181). When the Cr



concentration is too high, the line at mass 52 is too dark to measure. The only other alternative would be to measure the ⁵³Cr line. This is not advisable due to the contribution of ⁵²CrH species.

Manganese		Isotopes	Cobalt		Isotopes
Mass	1+	55	Maga	1+	59
	2+	27,5	mass	2+	29,5
Abundance (%)		100	Abundance (%)		100
Mass defect (mmu)		-61,9	Mass defect (mmu)		-66,8

4.1.14 Manganese (Mn) and cobalt (Co)

The mono-isotopic Mn and Co are both easily identified by their unique doubly charged ions at masses 27,5 and 29,5 respectively.

For the singly charged ⁵⁵Mn ion, the hydride species of ⁵⁴Cr and ⁵⁴Fe could interfere. However, the isotopic abundances of these two species are very small (2,41 and 5,90% respectively). A doublet at mass 55 is due to the doubly charged species ¹¹⁰Cd²⁺, one of the numerous isotopes of Cd with a percentage abundance of only 12,46%.

Similarly, for the singly charged ⁵°Co ion, the hydride species of ⁵°Fe and ⁵°Ni could interfere. A greater possibility of interference from ⁵°NiH⁺ exists as the ⁵°Ni isotope is the major isotope for Ni. This species would result in a line that overlaps slightly with the Co line. Extreme care must therefore be



exercised when measuring the Co line so as to not include the contribution from the ⁵ NiH⁺ species. A resolved doublet at mass 59 is the result of the doubly charged species of ¹¹ Sn, one of the impurity elements added by means of the reagents used.

When the concentration level of Mn and Co is too high in the sample and the exposure pattern is such that a 50% transmission value cannot be obtained from the Hull function, the lack of other isotopes of these two elements necessitates the use of the doubly charged species to quantify Mn and Co in the sample.

4.1.15 Iron (Fe)

Iron		Isotopes				
Mass	1+	54	56	57	58	
	2+	27	28	28,5	29	
Abundance (%)		5,90	91,60	2,18	0,32	
Mass defe	ect (mmu)	-60,4	-65,1	-64,6	-66,7	

Fe has only two isotopes of interest. The other isotopes overlap with those of Cr and Ni. The doubly charged ion of the ⁵'Fe isotope is used to positively identify the presence of Fe in the sample. A line at mass 28,5 is unique to the isotope of this element. Unreliable results are obtained when measuring this line at mass 28,5 due to $5'Fe^{2+}$. This occurs when the Fe concentration in the sample is not very high due to the low isotopic abundance of this isotope, namely 2,18%. It is thus



preferable to measure the singly charged ions of Fe at mass 56, which is the major isotope. As in the case of ⁵°Co⁺, the line of the hydride species of Mn overlaps slightly with the line of ⁵°Fe. Thus extreme care must be exercised when measuring the transmission of the Fe line so as not to include the contribution from ⁵⁵MnH⁺.

A doublet at mass 56 is caused by the doubly charged species of ¹¹²Cd and ¹¹²Sn. When the concentration level of Fe in the sample is very high, the line at mass 56 will be oversaturated. The only alternative, as in the case of Cr, would be to measure the line at mass 57. This is, however, not advisable due to direct interference from the hydride species of ⁵⁶Fe namely FeH⁺ at mass 57.

A doublet at mass 57 is due to the doubly charged species of ¹¹⁴Cd and ¹¹⁴Sn.

Nicke	1	Isotopes				
Mass	1+	58	60	61	62	64
	2+	29	30	30,5	31	32
Abundance (%)		67,18	26,78	1,24	3,80	1,01
Mass defect (mmu)		-64,7	-69,2	-69,0	-71,7	-72,0

4.1.16 Nickel (Ni)

A line at mass 30,5 is unique for the doubly charged ⁶ ¹Ni isotope. However, this line can only be used when the concentra-



tion of Ni in the sample is very high, because of the very small percentage isotopic abundance, namely 1,24%. In most cases, the only method to analyse Ni would be to use the singly charged species. The isotopes at masses 58 and 64 interfere with Fe and Zn respectively. The isotopes at masses 61 and 62 are of very low abundance, making them impractical to use. Ni can be measured at mass 60 using the ⁶ Ni isotope with a relative abundance of 67,18%. As in the case of Fe and Co, the hydride species of ⁵ Co interferes with the line of ⁶ Ni. The slight overlap of the two lines can be resolved. A distinct doublet at mass 60 is due to the doubly charged species of ¹² Sn, which is the major isotope of Sn.

4.1.17 Copper (Cu)

Cop	per	Isotopes		
Mass	1+	63	65	
	2+	31,5	32,5	
Abundance	e (%)	69,14	30,86	
Mass dei	fect (mmu)	-70,4	-72,2	

Cu can be positively identified if lines exist at masses 31,5 and 32,5. These lines are due to the doubly charged species of the two isotopes of Cu. No interferences occur at these masses. The singly charged species of Cu at masses 63 and 65 both have the hydride species of ⁶2Ni and ⁶4Ni respectively, as interfering species. However, the isotopic abundances of these two isotopes of Ni are very small (3,80% and 1,01% respectively),



thus lessening the effect their hydride species have on the Cu lines. The presence of Zn as an impurity in the sample could interfere with the line of ⁶⁵Cu, due to the formation of the hydride species of ⁶⁴Zn which is the major isotope of Zn. A doublet with slight overlapping occurs at mass 65, thus making the measuring of the Cu line unreliable. In this instance, the ⁶³Cu line should be used.

4.1.18 Zinc (Zn)

Zinc		Isotopes				
Mass	1+	64	66	67	68	70
	2+	3 <i>2</i>	33	33,5	34	35
Abundance (%)		48,89	27,77	4,12	18,59	0,638
Mass defect (mmu)		-70,9	-74,0	-72,9	-75,1	-74,7

The presence of Zn in the sample is positively identified if a line exists at mass 33,5 due to the doubly charged species of This isotope of Zn has a low isotopic abundance (4,12%). 67Zn. Therefore, when the concentration level of Zn in the sample is low, no lines are observed at this mass. The singly charged species of Zn will then have to be utilised to identify the pre-The ⁶⁴Zn isotope cannot be used due to interferensence of Zn. ce from ⁶ *Ni. These two lines cannot be resolved. Another interference is the ⁶³Cu hydride whose line will overlap with that of ⁶ ⁴Zn. This leaves only the isotopes at masses 66 and 68 to measure quantitatively as the isotopes at masses 67 and 70 have too low isotopic abundances (4,12% and 0,638% respec-



tively). The line at mass 66 has the hydride species of ⁶⁵Cu as interference. These two lines can be resolved using the mass-defect values. The mass-defect value for ⁶⁵Cu hydride is -64,4 mmu and for ⁶⁶Zn is -74,0 mmu. The line at mass 68 is a clearly resolved doublet. The right-hand line is due to the doubly charged species of ¹³⁶Ba.

4.1.19 Stronti	um (Sr)
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Strontium		Isotopes				
Mass	1+	84	86	87	88	
	2+	42	43	43,5	44	
Abundance (%)		0,552	9,87	7,00	82,58	
Mass defect (mmu)		-86,6	-90,7	-91,1	-94,4	

The identification of Sr is quite elementary. A line at mass 43,5 is due to the doubly charged species of *7Sr. However, if Rb is present in the sample, the doubly charged *7Rb line interferes with that of *7Sr to such an extent that the two lines cannot be resolved. If no line exists at mass 42,5 which can be uniquely assigned to the doubly charged *5Rb which is the major isotope of Rb, then the line at mass 43,5 is unique to *7Sr. The line at mass 88 is unique to the singly charged species of the major isotope of Sr. No interferences occur at this line.



4.1.20 <u>Yttrium (Y</u>)

Yttı	Isotopes		
Magg	1+	89	
	2+	44,5	
Abundance	100		
Mass defec	-94,6		

The choice of Y as the internal reference has been described on page 28. A line at mass 44,5 is unique for the doubly charged species of the mono-isotopic °9Y. Similarly, a line at mass 89 is unique for the singly charged Y. The hydride species of °°Sr could interfere with the line of Y at mass 89. This line of °°SrH⁺ is, however, very weak in intensity and only occurs at the very long exposures.

4.	. 1	2	1	Zir	coni	um	(Zr)

Zirconium		Isotopes				
Mass	1+	90	91	92	94	96
	2+	45	45,5	46	47	48
Abundance (%)		51,45	11,12	17,18	17,46	2,82
Mass defect (mmu)		-95,7	-94,8	-95,4	-93,9	-91,8

The presence of Mo and Ru in the sample makes the identification and measuring of Zr more complex as they have isotopes which overlap in mass. Furthermore, the doubly charged species of



W and Ta also interfere with the lines of these elements. The large number of isotopes, seven each for Mo and Ru and five for Zr, assists the analyst when assigning elemental names to these spectral lines.

Zr has a unique line at mass 45,5 due to the doubly charged ion of ⁹¹Zr. This line serves to positively identify the presence of Zr in the sample. The singly charged ⁹²Zr and ⁹⁴Zr isotope lines interfere with the lines of ⁹²Mo and ⁹⁴Mo. Similarly, the ⁹⁶Zr line interferes with the lines of ⁹⁶Mo and ⁹⁶Ru. These isotope lines of Zr cannot be resolved. A line at mass 90 is, however, unique for the singly charged ion of ⁹⁰Zr which is the major isotope of Zr(51,45%).

A clearly resolved doublet at mass 90 is due to the doubly charged species of ¹⁰^{OW} and ¹⁰^{OT}a, or the hydride species of ⁰^Y. The isotopic abundances of W and Ta are very small at these masses, thus their influence on the ⁹^OZr⁺ line is negligible. A line at mass 90,5 is unique for the doubly charged species of ¹⁰^TTa which is the major isotope of Ta. The presence of this line on the photoplate originates from the Ta present in the electrode holders.

4.1.22 <u>Niobium (Nb)</u>

Niol	oium	Isotopes
Mass	1+	93
	2+	46,5
Abundance	e (%)	100
Mass defe	ect (mmu)	-94,0



The mono-isotopic Nb has a unique line at mass 46,5 due to the doubly charged ion. No other lines appear at this mass, making it unique for Nb. A doublet at mass 93 indicates the presence of W in the sample. The dark left-hand line is due to the singly charged ion of °3Nb. The right-hand line is due to the doubly charged species of 1°6W. Another possible interference for the °3Nb line could be the hydride species of °2Zr, °2ZrH⁺. This line cannot be resolved by the mass-defect principle. However, the isotopic abundance of °2Zr is very small compared with that of the mono-isotopic Nb. Thus the °2ZrH⁺ line will disappear as the exposures get shorter.

Molybde	enum	Isotopes						
Mass	1+	92	94	95	96	97	98	100
	2+	46	47	47,5	48	48,5	49	50
Abundance	Abundance (%)		9,12	15,92	16,63	9,42	24,25	9,43
Mass defect (mmu)		-93,9	-95,3	-94,3	-95,5	-94,3	-94,5	-92,4

4.1.23 Molybdenum (Mo)

Lines at mass 47,5 and 48,5 are unique for the doubly charged species of ⁹⁵Mo and ⁹⁷Mo. In their singly charged state these two isotopes have no interferences from other elements. As previously mentioned, ⁹²Mo, ⁹⁴Mo and ⁹⁶Mo interfere with ⁹²Zr, ⁹⁴Zr and ⁹⁶Zr; and ⁹⁶Mo, ⁹⁶Mo and ¹⁰⁰Mo interfere with ⁹⁶Ru, ⁹⁶Ru and ¹⁰⁰Ru. The isotopic abundance of ⁹⁵Mo is greater than that of



⁹⁷Mo, thus the line at mass 95 is the more suitable to measure as there are more lines present. If there is no Ru present in the sample, then the line at mass 98 due to the major isotope of Mo can be measured.

4.1.24 Ruthenium (Ru)

Ruther			Is	sotopes				
Mass	1+	96	98	99	100	101	102	104
	2+	48	49	49,5	50	50,5	51	52
Abundance (%)		5,55	1,96	12,75	12,64	17,05	31,54	18,50
Mass defect (mmu)		-92,4	-94,5	-93,9	-97,0	-95,9	-96,3	-94,5

Ru can be positively identified by the presence of lines at masses 49,5 and 50,5 due to the doubly charged ions of "Ru and 101Ru respectively. No interferences occur at these masses. The isotopes of Ru at masses 96, 98 and 100 have Mo as interference in the singly charged state. These lines cannot be resolved. The same applies to the isotopes of Ru at masses 102 and 104, where the doubly charged ions of 204Pb and 200Pb interfere. However, these lines can be resolved using their mass-defect values. Therefore, the isotopes of Ru at masses 99, 101, 102 and 104 are unique and can be used to measure the singly charged ions of Ru.

The line at mass 102, which is from the major isotope of Ru (31,54%), gives a more reliable result because more exposure lines are present at this mass. The line due to ²⁰⁴Pb²⁺, which has an isotopic abundance of only 1,5%, occurs only at the very long



exposures. The presence of Pd in the sample interferes with the lines of ¹⁰²Ru and ¹⁰⁴Ru. Thus the ¹⁰¹Ru isotope would then be used to measure the concentration of Ru in the sample.

4.1.25 <u>Cadmium</u> (Cd)

Cadmi	lum	n Isoto,				es			
Mass	1+	106	108	110	111	112	113	114	116
	2+	53	54	55	55,5	56	56,5	57	58
Abundance	(%)	1,219	0,863	12,46	12,81	24,04	12,26	28,85	7,50
Mass defect(mmu)		-94,1	-96,0	-97,0	-95,9	-97,2	-95,4	-96,44	-95,0

The difficulty of quantitatively determining Cd as an impurity at very low concentration levels is greatly compounded by the fact that Cd has no less than 8 isotopes, the highest abundance being that of ¹¹⁴Cd at only 28,85%. Furthermore, most of the isotopes of Cd have other elements as interferences such that their lines cannot be resolved. Typically, the only isotope of Cd which can be used to positively identify the presence of Cd in the sample is the isotope at mass 111 with an abundance of only 12,81%. A line at mass 55,5 is unique for the doubly charged ion of this isotope of Cd. The line from the doubly charged ion of ¹¹³Cd at mass 56,5 overlaps completely with the line of the doubly charged ion $^{113}In^{2+}$, also present in the sample. These two lines cannot be resolved using the mass-defect values.

For the singly charged species of Cd, the isotopes at masses 106, 108 and 110 have direct interference from the same isotopes of Pd



if Pd is present in the sample. These lines cannot be resolved at these masses. The same applies for the isotopes at masses 112, 114 and 116, where direct interference is encountered by isotopes of Sn, one of the elements added indirectly to the standards as an impurity during the preparative stage. These lines cannot be resolved. The doubly charged ion of the mono-isotopic Th (232Th2+) produces a line at mass 116, resulting in a doublet at this mass which can be resolved. The ¹¹³Cd isotope has direct interference from the ¹¹³In isotope, as In is also present in the sample. Of the eight isotopes of Cd, the only isotope unique to Cd (in the singly charged state) is at mass 111, with an isotopic abundance of only 12,81%. If it can be positively shown that no Sn is present in the sample, then the lines from the 112Cd and 114Cd isotopes can be used to measure Cd in the singly charged state. These isotopes have isotopic abundances of 24,04% and 28,85% respectively, giving a more reliable result than that obtained from ¹¹¹Cd.

4.1.26 Indium (In)

Indiu	1111	Isotopes		
Mass	1+	113	115	
	2+	56,5	57,5	
Abundance	(%)	4,24	95,76	
Mass defec	ct (mmu)	-95,7	-95,9	

The presence of In in the sample can be identified by a line at mass 57,5. This line is due to the doubly charged ion of the major isotope of In, namely ¹¹⁵In. The contribution to this line



at mass 57,5 by the doubly charged ion of ¹¹⁵Sn is negligible as the ¹¹⁵Sn isotope has an isotopic abundance of only 0,35%. The line at mass 56,5 is due to the doubly charged ion of ¹¹³Cd which interferes directly with the line of the doubly charged ion of ¹¹³In. These two lines cannot be resolved. The isotopic abundance of ¹¹³In is in any case too small for the doubly charged ion of this isotope of In to be detected at mass 56,5.

The only singly charged isotope of In which can be used to quantify In in the sample is ¹¹⁵In. The line at this mass is dark in intensity, coinciding with the isotopic abundance of this isotope of In, namely 95,75%. However, the longest exposure lines have interference from the ¹¹⁵Sn isotope, with an isotopic abundance of only 0,35%. The 50% transmission intercept obtained for this line at mass 115 is unique for ¹¹⁵In and can be used to quantify In in the sample.

4.1.27 Antimony (Sb)

Antimo	ony	Isotopes		
Mass	1+	121	123	
	2+	60,5	61,5	
Abundance	(%)	57,25	42,75	
Mass defec	t (mmu)	-96,3	-95,9	

Sb has only two isotopes, namely at masses 121 and 123, with abundances that are roughly the same (57,25 and 42,75% respectively). This facilitates the detection of Sb as an impurity



in the sample. The doubly charged ions of both isotopes of Sb yield lines at masses 60,5 and 61,5 which are unique for Sb. If Te is present in the sample, the contribution from the doubly charged ion of ¹²³Te at mass 61,5, with an isotopic abundance of only 0,88%, can be considered negligible.

In the singly charged state, it is preferable to use the line at mass 123 instead of the line at mass 121, both due to the isotopes of singly charged Sb, because of fogging caused by the major isotope of uranium, one of the main components in the sample. The doubly charged ion of ^{230}U yields a very intense line at mass 119, causing the fogging. This is similar to what happens to $^{11}B^{+}$ and $^{25}Mg^{2+}$, caused by the fogging of ^{12}C . However, when Te is present and can be positively identified in the sample, there is no alternative but to measure the line at mass 121 in order to quantify Sb. The result so obtained would be more unreliable than that obtained if the line at mass 123 is measured.

4.1.28 Barium (Ba)

Bar		Isotopes						
Mass	1+	130	132	134	135	136	137	138
	2+	65	66	67	67,5	68	68,5	69
Abundance (%)		0,108	0,119	2,44	6,58	7,87	11,41	71,50
Mass defect (mmu)		-93,8	-94,9	-95,7	-94,4	-95,6	-94,4	-95,0



Lines observed at masses 67,5 and 68,5 are unique for the doubly charged ions of 135Ba and 137Ba, respectively. No interferences occur at these masses. It is preferable to measure the line at mass 68,5 instead of at 67,5, as 137Ba has a higher isotopic abundance than ¹³⁵Ba, providing more exposure lines on the photoplate. The line at mass 138 is used to quantify Ba in the This line is due to the singly charged ion of the major sample. isotope of Ba at mass 138, with an isotopic abundance of 71,5%. If La and Ce were present in the sample, they would interfere with the line of 138Ba. However, these two isotopes of La and Ce have very small isotopic abundances of only 0,089% and 0,258%, respectively, and their influence can be ignored. They would probably only interfere at the longest exposure lines, which would then in any case be saturated for Ba.

4.1.29 <u>Tungsten (W)</u>, bismuth (Bi) and thorium (Th)

For the next three elements, namely W, Bi and Th, the only way to positively identify and quantify their presence in the sample is to consider only their doubly charged species. This restriction is imposed because the mass range of the magnet has been chosen so as to only go up to mass 165 for the purpose of this investigation.

Tungst	ten			Isotopes	3	
Mass	1+	180	182	183	184	186
	2+	90	91	91,5	9 <i>2</i>	93
Abundance (%)		0,137	26,22	14,32	30,66	28,66
Mass defect (mmu)		-53,0	-51,7	-49,7	-49,0	-45,7



A line at mass 91,5 is unique for the doubly charged ion of ¹⁰³W. The isotopic abundance of this isotope is only 14,32%, making it unfavourable to use at low concentration levels in the sample. However, the other isotopes of W, at masses 182, 184 and 186, with isotopic abundances of 26,22%, 30,66% and 28,66% respectively, give clearly resolved doublets at masses 91, 92 and 93. These doublets can be resolved using their mass-defect values. As discussed earlier, the doublet at mass 91 would be ⁹¹Zr, that at mass 92 would be a combination of both ⁹²Zr and ⁹²Mo and that at mass 93 would be the mono-isotopic Nb. By carefully setting up the microdensitometer, each line of the doublet can be measured simultaneously, without any uncertainty of the result so obtained.

Bismut	th	Isotopes
Mass	1+	209
	2+	104,5
Abundance	(%)	100
Mass defec	ct (mmu)	-19,6

The presence of Bi in the sample can be positively identified if a line appears at mass 104,5. This line is due to the doubly charged ion of the mono-isotopic ²⁰⁹Bi and is unique for Bi.

Thor	ium	Isotopes
Mass	1+	232
	2+	116
Abundance	(%)	100
Mass defec	ct (mmu)	+38,2



A clearly resolved doublet at mass 116 indicates the presence of Th in the sample. The left-hand line is due to a combination of both the singly charged ion for ¹¹⁶Cd and the singly charged ion of ¹¹⁶Sn. The darker right-hand line is due to the doubly charged ion of the mono-isotopic ²³²Th. This line is unique and can be measured to quantify Th.

4.1.30 Samaria	ım (Sm)
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Samari	ım	Isotopes						
Mass	1+	144	147	148	149	150	152	154
	2+	72	73,5	74	74,5	75	76	77
Abundance(%)		3,03	14,92	11,21	13,81	7,39	26,84	22,97
Mass de- fect (mmu)		-88,4	-85,4	-85,4	-83,1	-83,0	-80,5	-78,0

Lines at masses 73,5 and 74,5 are unique for the doubly charged Sm isotopes 147 and 149 respectively. No interference from other elements occurs at these masses. In the singly charged state, the only isotopes unique for Sm are at masses 147 and 149. The isotopes with masses 144, 148 and 150, of relatively low abundance, can have Nd as interference. Similarly, the isotopes with masses 152 and 154, both major isotopes of Sm, have Gd as interference. Of the remaining two isotopes unique for Sm, the ¹⁴⁷Sm isotope is used to measure quantitatively because of the higher abundance, namely 14,92%.



4.1.31 Europium (Eu)

Europium		Isotopes			
Mass	1+	151	153		
	2+	75,5	76,5		
Abundance	(%)	47,79	52,21		
Mass defec	ct (mmu)	-80,4	-79,1		

Both the isotopes of Eu are unique for this element. No interferences from other elements occur. The presence of Eu in the sample is positively identified by the presence of lines at masses 75,5 and 76,5. These two lines are due to the doubly charged ions of the two isotopes of Eu, namely ¹⁵Eu and ¹⁵Eu, respectively. For Eu in the singly charged state, either of the lines at masses 151 and 153 can be used to quantify Eu as the abundances of these two isotopes are very similar.

4.1.32 Gadolinium (Gd)

Gadolinium		Isotopes							
Mass	1+	152	154	155	156	157	158	160	
	2+	76	77	77,5	78	78,5	79	80	
Abundance (%)		0,20	2,16	14,87	20,56	15,70	24,77	21,79	
Mass defect (mmu)		-80,5	-79,3	-77,4	-77,9	-76,1	-75,9	-72,9	


Gd is very similar to Sm in that it also has only two isotopes which are unique to it, namely ¹⁵⁵Gd and ¹⁵⁷Gd. The doubly charged ions of these two isotopes of Gd give lines at masses 77,5 and 78,5, respectively, which are used to identify the presence of Gd in the sample. No interference from other elements occurs at these masses.

When measuring the doubly charged state of Gd, it is preferable to use the line at mass 77,5, because the line at 78,5 is obscured by the line of $235U^{3+}$ at mass 78,33 (U being one of the main components in the sample.) In the singly charged state, 152Gdand 154Gd, both of low abundance, have Sm as interference. The three major isotopes of Gd, namely 156Gd, 150Gd and 160Gd, have Dy as interference. The isotope suitable to quantify Gd in the singly charged state is the 157Gd which has a higher abundance than 155Gd.

Dyspros	sium	Isotopes						
Mass	1+	156	158	160	161	162	163	164
	2+	78	79	80	80,5	82	81,5	82
Abundance ((%)	0,058	0,098	2,33	18,87	25,46	24,93	28,25
Mass defect	t (mmu)	-76,2	-76,0	-75,2	-74,3	-73,5	-71,6	-71,2

4.1.33 Dysprosium (Dy)

The doubly charged ions of Dy with masses 161 and 163 give lines at masses 80,5 and 81,5 which are unique for Dy. In the singly charged state the first three isotopes of Dy (namely at masses



156, 158 and 160), all with very low isotopic abundance, have Gd as interference. The remaining four isotopes of Dy, with abundances ranging from 18,87 % to 28,25%, can be used to quantify Dy in the singly charged state. However, the presence of Er in the sample would interfere at masses 162 and 164. ¹⁶³Dy would then be used as it is unique for Dy and has a higher abundance than ¹⁶¹Dy.

4.1.34 Selection of isotopes and charge states

The choice of isotopes used to identify and quantify each of the 34 elements present in the U_3O_8 /graphite matrix is summarised in Table 4.2.

<u>Table 4.2</u>: Isotopes and charge states used to quantify impurity elements in a U_3O_8 /graphite matrix

Element	Charge state	m/e	Isotope	Abundance (%)
В	1+	11	11	80,35
Na	1+	23	23	100
Mg	2+	12,5	25	10,08
Aļ	2+	13,5	27	100
Si	1+ 2+	30 14,5	30 29	3,09 4,68
Р	1+ 2+	31 15,5	31 31	100 100
Ca	2+	20	40	96,94
K	1+ 2+	41 19,5	41 39	6,73 93,26



Table 4.2: Continued

Element	Charge state	m/e	Isotope	Abundance (%)
Ti	1+	48	48	73,63
	2+	23,5	47	7,42
V	1+	51	51	99,74
	2+	25,5	51	99,74
Cr	1+	52	52	83,70
	2+	26,5	53	9,51
Mn	1+	55	55	100
	2+	27,5	55	100
Fe	1+	56	56	91,60
	2+	28,5	57	2,18
Со	1+	59	59	100
	2+	29,5	59	100
Ni	1+	60	60	26,78
Cu	1+	63	63	69,16
	2+	31,5	63	69,14
Zn	1+	66	66	27,77
Sr	1+	88	88	82,58
	2+	43,5	87	7,00
Zr	1+	90	90	51,45
	2+	45,5	91	11,12
Y	1+	89	89	100
	2+	44,5	89	100
Nb	1+	93	93	100
	2+	46,5	93	100
Мо	1+	95	95	15,92
	2+	47,5	95	15,92
Ru	1+	102	102	31,54
	2+	50,5	101	17,05
Cd	1+	111	111	12,81



Table 4.2: Continued

Element	Charge state	m/e	Isotope	Abundance (%)
In	1+	115	115	95,76
	2+	57,5	115	95,76
Sb	1+	123	123	42,75
	2+	61,5	123	42,75
Ba	1+	138	138	71,50
	2+	68,5	137	11,41
Sm	1+	147	147	14,92
	2+	73,5	147	14,92
Eu	1+	153	153	52,21
	2+	76,5	153	52,21
Gđ	1+	157	157	15,70
	2+	78,5	157	15,70
Dy	1+	163	163	24,93
	2+	81,5	163	24,93
W	2+	93	186	26,66
Bi	2+	104,5	209	100
Th	2+	116	232	100



4.2 UF₄/graphite matrix characteristics

4.2.1 <u>General principles</u>

The qualitative interpretation of a UF_4 /graphite matrix spectrum is far more complex than that of a U_3O_8 /graphite matrix. The over-abundance of fluoride ions generated in the plasma from UF, leads to fluorination and recombination of elemental ions present in the sample as impurities. When 0,004 moles of UF_4 is used to prepare electrodes with graphite, this mass of UF, yields a concentration of fluorine of 320 000 µgF/gU, compared with the total concentration of impurities in the UF_4 sample of perhaps up to 1 000 µg/gU. Because fluorine is so extremely reactive with other elements and, as indicated above, in total abundance, the chances of fluorination are greatly enhanced. This phenomenon complicates the interpretation of the mass spectrum of a UF₄/graphite matrix.

The procedures followed for assigning nominal mass values to the spectral lines on a photoplate exposed to a UF₄/graphite matrix are very similar to those for a U_3O_8 /graphite matrix. The major elements must first be identified. The fingerprint spectrum of uranium is given in Table 4.1 on page 38. By examining the photoplate through a microscope, several major lines are observed over the entire length of the photoplate. These lines are distinguished by A, B, C, D, E, F, G and H in Figure 4.3. The two distinct lines in the upper half of the photoplate, "A" and "B", are due to the major isotope of U, i.e. ²³⁸U. The magnet range in Figure 4.3 is from mass 10 to mass 130. Thus, from the data given in Table 4.1, "A" can be assigned the mass 119 and "B" the mass 79,33, which corresponds with the ions 238U2+ and 238U3+ respectively.



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Figure 4.3: Photoplate spectrum of a UF₄/graphite matrix



At the lower end of the photoplate, the strong line with dispersion, marked "C", can be assigned the mass 12. This is due to another major component, C. Similarly, the line marked "D" can be assigned the nominal mass of 19, due to a main component, F.

The lines marked "E" and "F" in Figure 4.3 are due to the clusters C_2^+ and C_3^+ respectively, at masses 24 and 36. The formation of carbon clusters is well known [20].

The lines marked "G" and "H" are due to the formation of fluorinated carbon species, CF^* and CF_2^* , with nominal masses 31 and 50, respectively. The formation of such species is not uncommon for a UF_4 /graphite matrix. By using the above markers on the photoplate, the rest of the lines can be assigned nominal mass values to calibrate the rest of the photoplate data.

The positive identification of an element as an impurity in a UF_4 /graphite matrix is not always possible. A vast number of fluorinated species of other elements could interfere with the lines of the element under investigation. This limits the use of singly charged species to quantify an element, unless a doublet or triplet can be satisfactorily resolved using mass-defect values.

Each element (X) present in the UF₄ sample, with all its isotopes, forms fluorinated species of up to $XF_{(n-1)}$, where n is the number of fluorine atoms present in that element's stable state, e.g. where X=P, we get PF₅ and where X=S, we get SF₆ [21, 22]. When too many elements are present in the UF₄, the qualitative interpretation of the spectrum obtained becomes too complicated as the interferences of fluorinated species do not permit the positive identification of a single line which is totally representative of a particular element. This is in stark contrast © University of Pretoria



to the analysis of a U_3O_8 /graphite matrix discussed in Section 4.1, where 34 elements of interest could be positively identified and measured. This was possible because of the formation of primarily elemental ions in the plasma, hence avoiding the great number of possible molecular ion interferences.

4.2.2 Selection of elements

Seven elements were identified in the study of reactions in the uranium fuel production process. The UF_4 -material had to be analysed qualitatively and quantitatively in the solid state, without prior chemical treatment. The spark-source mass spectrometer made a significant contribution to these studies.

The seven elements listed in Table 4.3 (see page 97) were added to graphite powder at five concentration levels. The method followed for the preparation of these standards is discussed in Chapter 3 on page 26.

4.2.3 Aluminium (A1)

Alumin	nium	Isotopes	
Maga	1+	27	
Mass	2+	13,5	
Abundance	(%)	100	
	A1F+	46	
species	A1F ₂ +	65	
	AlF ₃ +	84	



A line at mass 13,5 is unique for the doubly charged ion of the mono-isotopic ²⁷A1 and is used to measure A1 quantitatively. The singly charged ion at mass 27 appears as a triplet which can be resolved using the mass-defect values. Possible interferences at mass 27 are the doubly charged ions of ⁵⁴Cr and ⁵⁴Fe. The presence of these two elements in the sample can be verified by lines at masses 26,5 and 28,5 due to the doubly charged state of ⁵³Cr and ⁵⁷Fe respectively. Another possible interference could be the doubly charged ion of fluorinated chlorine (³⁵Cl), namely ³⁵ClF²⁺. By using the mass-defect value, it can be shown that the central line at mass 27 is due to the singly charged ion of A1, which cannot be used for quantification.

The formation of AlF⁺ is confirmed by a single line at mass 46. However, quite a few interferences could contribute to this line. The mono-isotopic ions of ⁴⁶Ca and ⁴⁶Ti could interfere, as well as the fluorinated species ⁵⁴FeF₂²⁺ and ³⁵ClF₃²⁺.

A doublet is observed at mass 65. Possible interferences at this mass, resulting in a doublet, could be from the ${}^{5}Cu^{+}$ ion, which must first be positively identified by the presence of lines at masses 31,5 and 32,5, due to the doubly charged ions of the two isotopes ${}^{5}Cu$ and ${}^{5}Cu$, respectively. Other interferences could be the fluorinated species of A1, namely ${}^{27}A1F_{2}^{+}$, and of Ca, namely ${}^{46}CaF^{+}$.

A light single line at mass 84 could be due to the formation of ²⁷AlF₃⁺. This line could also be from the fluorinated species of ⁶⁵Cu, namely CuF⁺.



4.2.4 Phosphorus (P)

Phosphoru	Isotopes	
Macc	1+	31
11255	2+	15,5
Abundance (%)	100	
	PF+	50
Fluorinatod	PF 2 +	69
species	<i>PF</i> ₃ +	88
Species	PF 4 +	107
	PF 5 +	126

The table below illustrates the fluorination of ${}^{12}C$, which helps to enlighten the interferences of these two elements.

Carbon		Isotopes	
Mass	1+	12	
Abundance (%)		98,89	
	CF+	31	
Fluorinated	CF 2 +	50	
species CF ₃ +		69	
	CF 4 +	88	



The doubly charged ion of the mono-isotopic ³¹P yields a doublet at mass 15,5. This doublet can be resolved using the massdefect values. The darker left-hand line is due to P²⁺ and the light right-hand line due to the doubly charged ion of ¹²CF²⁺. The only line of P which can be used to measure P in the sample is this left-hand line at mass 15,5.

The singly charged ion of P at mass 31 appears as a very dark unresolved doublet. The interference is due to the fluorinated species of C, namely ¹²CF⁺. Another species which could interfere at this mass is the doubly charged ion of ⁶²Ni, which can be positively identified as being present in the sample if a line appears at mass 30,5, due to ⁶¹Ni²⁺.

For the fluorinated species of P, lines are observed up to the formation of PF_4^+ . No line is observed at mass 126 due to PF_5^+ .

A doublet appears at mass 50, one line due to PF^+ and the other due to CF_2^+ . Similarly, a doublet appears at mass 69, one of the lines due to PF_2^+ and the other due to CF_3^+ . At masses 88 and 107, single lines are present. The line at mass 88 is due to the presence of PF_3^+ and the line at mass 107 is due to PF_4^+ . No interference from other fluorinated species occurs at these two lines, although the fluorinated carbon species, CF_4^+ , with a mass of 88, does interfere with the PF_3^+ ion.



4.2.5 <u>Calcium (Ca)</u>

Calcium			Isotopes				
Mana	1+	40	42	43	44	46	48
11455	2+	20	21	21,5	22	23	24
Abundance	(%)	96,94	0,65	0,1	2,08	0,0037	0,181
Fluorinated	CaF+	59	61	62	63	65	67
species	CaF ₂ +	78	80	81	82	84	86

The doubly charged ion of the major isotope of Ca, namely ${}^{\circ}Ca^{2+}$, appears as a doublet at mass 20. This doublet can be resolved using the mass-defect values. The strong right-hand line is due to the formation of HF⁺, a species which occurs readily in a UF₄/graphite matrix. The left-hand line, due to ${}^{\circ}Ca^{2+}$, is used to measure Ca quantitatively.

The *²Ca isotope is also used to measure Ca quantitatively. The result obtained is used as a guide to check whether the correct line of the doublet was selected at mass 20, as the two measurements should give the same result. It is not always possible to do this as the doubly charged ion of ⁴²Ca is only observed when the Ca concentration in the sample is fairly high. The isotopic abundance of ⁴²Ca is only 0,65%, yielding a very faint line at mass 21. However, this line is single and unique for ⁴²Ca. Lines at masses 21,5 and 22 can also be used to identify the presence of Ca in the sample. The line at mass 21,5 is too light



to measure (abundance 0,14%) and the line at mass 22 has interferences from $^{25}MgF^{2+}$ and possibly $^{12}C^{13}CF^{2+}$, (C_2F^{2+}), which cannot be resolved.

There are too many interferences to measure Ca in the singly charged state. For ${}^{40}Ca$ there is interference from ${}^{40}K$, the presence of which is identified by a line at mass 19,5, due to the ${}^{39}K$ doubly charged ion. For ${}^{42}Ca$, interference is in the form of ${}^{65}CuF^{2+}$ and NaF⁺. The presence of Na in the sample is confirmed by a strong line at mass 23. At mass 43, ${}^{43}Ca$ has interference from ${}^{24}MgF^{+}$ and ${}^{12}C_2F^{+}$. The formation of ${}^{24}MgF^{+}$ is confirmed by the presence of a line at mass 12,5 due to the doubly charged ion of ${}^{25}Mg$. Similarly, for ${}^{4*}Ca$, interferences are ${}^{25}MgF^{+}$ and ${}^{12}C^{13}CF^{+}$.

The isotopic abundance of ⁴⁶Ca is so small that this isotope can be ignored, although possible interferences are ²⁷AlF⁺ and ⁴⁶Ti⁺, the presence of which is confirmed by lines at masses 23,5 and 24,5 due to the doubly charged ions of ⁴⁷Ti and ⁴⁹Ti, respectively.

Furthermore, the interpretation of the Ca spectrum is made more complex by the fluorination of Ca to form CaF⁺ species with all the isotopes. The interferences on the lines of the CaF⁺ species is such that no line can be uniquely assigned. This is detailed below:

- The line at mass 59 is a doublet due to ⁵°Co⁺ and ⁴° CaF⁺;
- that at mass 61 is also a doublet due to ⁶ Ni⁺ and ⁴ CaF⁺;
- that at mass 62 a weak doublet due to ⁶²Ni⁺ and ⁴³CaF⁺; and
- that at mass 63 a doublet due to ⁶³Cu⁺ and ⁴⁴CaF⁺.



The line at mass 65 could be due to a combination of ${}^{\circ}Cu^+$, ${}^{\circ}CaF^+$, ${}^{\circ}TiF^+$ and ${}^{2}{}^{7}A1F_2^+$. Similarly, the line at mass 67 could be due to a combination of ${}^{\circ}{}^{7}Zn^+$, ${}^{\circ}CaF^+$, ${}^{\circ}TiF^+$ and ${}^{2}{}^{9}SiF_2^+$.

No line is observed at mass 78, which would indicate the formation of $4 \circ CaF_2^+$.

4.2.6 <u>Silicon (Si</u>)

Silicon		Isotopes				
Magg	1+	28	29	30		
11455	2+	14	14,5	15		
Abundance (%)		92,23	4,68	3,09		
	SiF+	47	48	49		
<i>Fluorinated</i>	SiF ₂ +	66	67	68		
species	SiF ₃ +	85	86	87		
	SiF ₄ +	104	105	106		

The presence of Si in the sample can be positively identified by a single line at mass 14,5 due to the doubly charged ion of ² ⁹Si. This line cannot be measured to quantify Si, as it is very weak in intensity because of the ² ⁹Si abundance of only 4,68%.

In the singly charged state the lines of the various Si isotopes have interferences to contend with. At mass 28 there are four overlapping lines which cannot be resolved using mass-defect values.



Apart from the line for ²°Si, other interferences are ⁵°Fe²⁺, ³⁷C1F²⁺ and ⁶⁵CuF³⁺. From the intensity of the central line it would appear as if this line is due to ²°Si, the major Si isotope. At mass 29 an unresolved triplet is observed, made up of the interferences of ⁵°Fe²⁺, ⁵°Ni²⁺ and possibly ³°KF²⁺, with the line of ²°Si. The presence of K in the sample can be verified by a line at mass 19,5 due to the doubly charged ion of ³°K.

A resolved triplet is found at mass 30. The left-hand line is due to the doubly charged ion of ⁶ Ni. The central line is due to ³ Si and the right-hand line is due to either ¹²C₅²⁺ or ⁴ KF²⁺. The formation of ⁴ KF⁺ is verified by the presence of a strong doublet at mass 60 due to ⁶ Ni⁺ and ⁴ KF⁺. The righthand line of the triplet at mass 30 is weak in intensity, thus it does not affect the measuring of the ³ Si central line. Only the saturated exposures of ³ Si have any interference from this weak right-hand line. This is the only Si line which can be measured to quantify Si.

Silicon forms several fluorinated species. For the formation of SiF⁺species the following lines are obtained:

- A doublet at mass 47 due to ² ⁸SiF⁺ and ⁴ ⁷Ti⁺;
- a doublet at mass 48 due to several possible species, e.g. 2°SiF⁺, ¹2C₄⁺, ⁴°Ti⁺, ⁴°Ca⁺; and
- a doublet at mass 49 due to ${}^{30}SiF^+$, ${}^{49}Ti^+$ and ${}^{12}C_3{}^{13}C^+$.

For the formation of SiF_2^+ species, the following lines are obtained which can be resolved using mass-defect values:

- A triplet at mass 66, where the left-hand line is due to 66Zn⁺:
- a weak central line due to 4'TiF'; and
- a strong right-hand line due to ² ^sSiF₂⁺.



At mass 67 a triplet is present, where

- the weak left-hand line is due to ⁶⁷Zn⁺ with small abundance;
- the strong central line is that of **TiF*, the major isotope of Ti combined with **CaF*; and
- the weak right-hand line is due to ²SiF₂⁺.

Similarly, at mass 68, a weak triplet is observed, where

- the stronger left-hand line is due to ⁶²Zn⁺;
- the weak central line is due to *'TiF'; and
- the weak right-hand line is due to ³°SiF₂⁺.

For the formation of SiF_3^+ species, the only line obtained is that of the major isotope of Si, which gives a single line at mass 85 due to the formation of ${}^{2}{}^{8}SiF_3^+$. No line is observed at mass 104 to confirm the presence of SiF_4^+ species.

4.2.7 Sulphur (S)

Su1phur		Isotopes				
Magg	1+	32	33	34	36	
nass	2+	16	16,5	17	18	
Abundance	(%)	95,0	0,76	4,22	0,01	
	SF+	51	52	53	55	
	SF 2 +	70	71	72	74	
Fluorinated	SF ₃ +	89	90	91	93	
species	SF 4 +	108	109	110	112	
	SF 5 +	127	128	129	131	
	SF 6 +	146	147	148	150	



For the formation of fluorinated S species, the table below illustrates the fluorinated species of ¹³C, and the interferences of these two elements.

Carboi	2	Isotopes
Mass	1+	13
Abundance	(%)	1,10
	CF+	32
Fluorinated	CF 2 +	51
species CF ₃ + CF ₄ +		70
		89

The doubly charged ion of the ³³S isotope gives a line at mass 16,5. However, no line is observed at this mass because the isotopic abundance of the ³³S is only 0,76%. This means that only the singly charged state of S can be used to quantify S in the sample.

At mass 32 there is a doublet which can be resolved. The main interference at this mass is from the major isotope of Zn, namely ${}^{64}Zn^{2+}$. Other possible interferences are ${}^{13}CF^+$ and ${}^{64}Ni^{2+}$. The right-hand line of this doublet is due to ${}^{32}S^+$, which is used to measure S.

The ³³S and ³⁶S isotopes both have very small abundances, with the result that their lines at masses 33 and 36 are so faint that they cannot be used. This is apart from the fact that ³³S also has ⁶⁶Zn²⁺ as interference and ³⁶S has the cluster ¹²C₃⁺ as interference.



A very weak doublet is obtained at mass 34 due to ${}^{3+}S^+$ and ${}^{6+}Zn^{2+}$. These two lines overlap to such an extent that they cannot be resolved on the basis of the mass-defect values.

Only the ³2S and ³4S isotopes are used to illustrate the fluorination of S to form SF_n^+ species, where n=1 and 2. For SF^+ a doublet is obtained at mass 51 due to ³2SF⁺, ¹³CF₂⁺ and ⁵¹V⁺, the presence of which in the sample can be identified by a line at mass 25,5, which is unique for ⁵¹V²⁺. Similarly, a doublet is obtained at mass 53 due to ³⁴SF⁺ and ⁵³Cr⁺. For the formation of SF_2^+ species, a doublet at mass 70 is due to ³²SF₂⁺, ¹³CF₃⁺ and the fluorinated species of V, namely ⁵¹VF⁺, as interferences. A doublet at mass 72 originates from ³⁴SF₂⁺ and ⁵³CrF⁺. In the same way that the fluorinated species of ¹²C interfered with the fluorinated species of P, the fluorinated species of ¹³C interfere with the fluorinated species of S up to the formation of ¹³CF₃⁺ species.

For the formation of further SF_n^+ species where n = 3, 4 and 5, only the major isotope, ${}^{32}S$, will be considered. At mass 89 a clearly resolved doublet is obtained. The dark line is that of the internal standard, the mono-isotopic 69 Y, and the very weak line is that of ${}^{32}SF_3^+$ which does not interfere with the 50% transmission intercept obtained for 69 Y, except at the longest exposures. A line at mass 108 is due to the formation of ${}^{32}SF_4^+$ and/or the formation of YF⁺. Similarly, a line at mass 127 is a combination of ${}^{32}SF_5^+$, ${}^{69}YF_2^+$ and ${}^{235}UF^{2+}$. No line is obtained at mass 146 to confirm the presence of SF_6^+ species.

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4.2.8 Chlorine (C1)

Chlorine	9	Isotopes		
Mass	1+	35	37	
	2+	17,5	18,5	
Abundance	(%) 	75,72	24,28	
	C1F+	54	56	
	C1F ₂ +	73	75	
Fluorinated	uorinated C1F ₃ +		94	
species C1F4+		111	113	
	C1F ₅ +	130	132	

No lines are readily observed at masses 17,5 and 18,5, which would be due to the doubly charged species of ³⁵Cl and ³⁷Cl respectively. The lines for Cl in the singly charged state are used to identify the presence of Cl in the sample, as well as to quantify Cl.

At mass 35 a weakly resolved doublet is observed. The strong left-hand line is due to ³⁵Cl, the major isotope of Cl. The faint right-hand line could be ⁷⁰Zn²⁺, or the species ¹⁶OF⁺. These interferences do not affect the measuring of the ³⁵Cl line as they only occur at the very long exposures.

At mass 37 there is a clearly resolved doublet. The weaker lefthand line is due to ${}^{37}C1^{+}$ and the strong right-hand line is due to the formation of the cluster ${}^{12}C_2{}^{13}C$ (C₃).

Both lines of Cl are measured, the ³⁷Cl line being used as a check for the ³⁵Cl line. The results obtained from each line should ideally be the same Diversity of Pretoria



The fluorination of C1 cannot be positively verified. This is a result of the numerous interferences of fluorinated species of Cr and Fe. The formation of C1F⁺ species would give rise to lines at masses 54 and 56. Interferences at mass 54 are 54 Cr⁺ and 54 Fe⁺, both elements having low abundance. At mass 56 the major isotope of 56 Fe results in a doublet with the 37 C1F⁺ species.

The formation of $C1F_2^+$ species would result in lines at masses 73 and 75. The single line at mass 73 could be due to ${}^{35}C1F_2^+$, ${}^{54}FeF^+$ or ${}^{54}CrF^+$. The doublet at mass 75 could be as a result of the formation of ${}^{37}C1F_2^+$ and the fluorinated species of the major isotope of Fe, namely ${}^{56}FeF^+$.

Similarly, the formation of $C1F_3^+$ species would result in faint lines at masses 92 and 94. Apart from ${}^{35}C1F_3^+$, the line at mass 92 could also be due to ${}^{54}FeF_2^+$ and ${}^{54}CrF_2^+$. The line at mass 94 could be the result of a combination of ${}^{37}C1F_2^+$ and ${}^{56}FeF_2^+$.

The formation of $C1F_4^+$ species cannot be positively verified as no lines are observed at masses 111 and 113. No lines appear at masses 130 and 132 to confirm the presence of $C1F_5^+$.

4.2.9 Zinc (Zn)

Zinc		Isotopes					
Mass	1+	64	66	67	68	70	
	2+	32	33	33,5	34	35	
Abundance (%)		48,89	27,77	4,12	18,59	0,638	
Fluorinated species	ZnF+	83	85	86	87	89	
	ZnF 2 +	102	104	105	106	108	



The doubly charged state of Zn is used to confirm its presence in the sample. A line at mass 33,5 is due to the doubly charged species of ⁶⁷Zn. This line can, however, not be measured to quantify Zn as it is too light in intensity, because the abundance of ⁶⁷Zn is only 4,12%.

For Zn in the singly charged state, the line obtained for each of the isotopes appears as a doublet or a triplet which can be resolved. Most of the interferences at these masses are due to the fluorinated species of the other elements present in the sample.

The line at mass 64 is very dark in intensity and is due to the major isotope ⁶⁴Zn. The only possible interference is from ⁶⁴Ni⁺. Because this isotope of Ni has a low abundance (1,01%), it does not affect the measuring of the ⁶⁴Zn⁺ line.

At mass 66 a resolved triplet is obtained. The left-hand line is due to ${}^{6}Zn^{+}$ and the other two lines are due to ${}^{2}{}^{6}SiF_{2}^{+}$ and ${}^{4}{}^{7}TiF^{+}$ as interferences.

Similarly, for the line at mass 67, the left-hand line of the resolved triplet is due to ${}^{\circ}7Zn^{+}$ and the other two lines are due to ${}^{\circ}9SiF_{2}^{+}$, ${}^{\circ}8TaF^{+}$ and ${}^{\circ}8CaF^{+}$ as interferences.

The resolved triplet at mass 68 has one strong line and two weak lines. The left-hand line, which is the strong line, is due to ⁶⁹Zn⁺. The two weak lines are due to ³⁰SiF₂⁺ and ⁴⁹TiF⁺, where the abundance of ³⁰Si and ⁴⁹Ti is very small.

It is apparent from the above discussion that Zn can be measured at any of its isotopes up to mass 68, as long as the upper window is carefully chosen so as not to include the interfering adjacent lines.



The doublet at mass 70 is due to a number of species, apart from $^{70}Zn^+$. These possible interferences are $^{32}SF_2^+$, $^{51}VF^+$ and $^{13}CF_3^+$.

A weak line is obtained at mass 83, which is due to the fluorinated species of the main isotope of Zn, namely $^{64}ZnF^{+}$. No line is observed at mass 102 to confirm the presence of ZnF_{2}^{+} .

4.2.10 <u>Yttrium (Y</u>)

Yttriu	Isotopes	
Mass	1+	
11255	2+	44,5
Abundance	100	
Fluoringtod	YF+	108
sposios	YF 2 +	127
species	YF 3 +	146

The single line at mass 44,5 is unique for the doubly charged ion of the mono-isotopic ⁸'Y. In the case of the singly charged ion, a doublet is obtained at mass 89, which can be resolved using mass-defect values. The strong left-hand line is due to ⁸'Y⁺ and the weak right-hand line is due to the fluorinated species of S, namely ³'SF₃⁺. The presence of this interference at mass 89 does not hinder the measuring of the Y line. Only the longest exposures are affected, which are in any case discarded



as saturated points. The 50% transmission intercept obtained for the Y line is thus a true value for Y in the singly charged state.

In a UF₄/graphite matrix the internal standard, Y, also forms fluorinated species, i.e. YF^+ . This is in contrast to the use of Y as an internal standard for a U₃O₈/graphite matrix. The difference obtained between the Y ratios, derived as the number of singly charged ions relative to the number of doubly charged ions, for the two types of matrices could be ascribed to the fact that Y also forms fluorinated species in a UF₄/graphite matrix.

The line obtained at mass 108 is due to ${}^{32}SF_4^+$ and ${}^{89}YF^+$. Similarly, the line at mass 127 is due to ${}^{32}SF_5^+$, ${}^{89}YF_2^+$ and ${}^{235}UF^{2+}$. No line is obtained at mass 146 to confirm the presence of YF_3^+ .

4.2.11 Uranium (U)

Apart from the normal fingerprint spectrum of uranium up to charge state 5, a number of other lines are also observed. The fingerprint spectrum of U is given in Table 4.1. on page 38. A strong line at mass 128,5 is due to the doubly charged ion of the fluorinated species of the major isotope of uranium, namely $^{236}UF^{2+}$. The line at mass 127 could be as a result of the combination of $^{235}UF^{2+}$ with $^{32}SF_5^+$ and $^{89}YF_2^+$. A weak line at mass 85,67 is due to the triply charged ion of fluorinated $^{236}UF^{3+}$.

The line observed at mass 125 is of interest as it can be related to the formation of a UC⁺ species. It would appear that the UF₄ molecule is in this case totally stripped of its fluoride ions within the plasma, leaving the U⁺ ion which recombines with a C⁺ ion, forming a UC⁺ species. At mass 125 the doubly charged species ²³⁶UC²⁺ is observed.



4.2.12 Selection of isotopes and charge states

A summary of the isotopes and charge states used to quantify each of the seven impurity elements in the UF_4 /graphite matrix is given in Table 4.3.

<u>Table 4.3</u>: Isotopes and charge states used to quantify impurity elements in a UF₄/graphite matrix

Element	Charge state	m/e	Isotope	Abundance (%)
A1	2+	13,5	27	100
Р	2+	15,5	31	100
Ca	2+ 2+	20 21	40 42	96,94 0,65
Si	1+	30	30	3,09
S	1+	32	32	95,0
C1	1+ 1+	35 37	35 37	75,72 24,28
Zn	1+ 1+	64 67	64 67	48,89 27,77
Y	1+ 2+	89 44,5	89 89	100 100